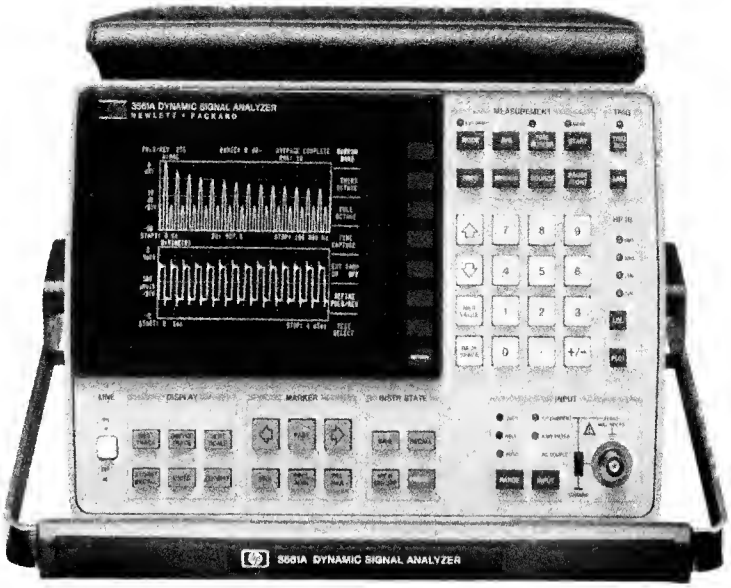
SERVICE MANUAL

3561A
DYNAMIC SIGNAL ANALYZER

VOLUME II



HEWLETT
PACKARD

HEWLETT PACKARD

SERVICE MANUAL

MODEL 3561A
DYNAMIC SIGNAL ANALYZER

Serial Prefix: 2338A

IMPORTANT NOTICE

This manual applies to instruments with the above serial number and greater. As changes are made in the instrument to improve performance and reliability, the appropriate pages will be revised to include this information.

WARNING

To prevent potential fire or shock hazard, do not expose instrument to rain or moisture.

Manual Part No. 03561-90010
Microfiche Part No. 03561-90060

P.O. Box 69, Marysville, Washington 98270 U.S.A.

HEWLETT PACKARD

CERTIFICATION

Hewlett-Packard Company certifies that this product met its published specifications at the time of shipment from the factory. Hewlett-Packard further certifies that its calibration measurements are traceable to the United States National Bureau of Standards, to the extent allowed by the Bureau's calibration facility, and to the calibration facilities of other International Standards Organization members.

WARRANTY

This Hewlett-Packard product is warranted against defects in material and workmanship for a period of one year from date of shipment [,except that in the case of certain components listed in Section I of this manual, the warranty shall be for the specified period] . During the warranty period, Hewlett-Packard Company will, at its option, either repair or replace products which prove to be defective.

For warranty service or repair, this product must be returned to a service facility designated by -hp-. Buyer shall prepay shipping charges to -hp- and -hp- shall pay shipping charges to return the product to Buyer. However, Buyer shall pay all shipping charges, duties, and taxes for products returned to -hp- from another country.

HP software and firmware products which are designated by HP for use with a hardware product, when properly installed on that hardware product, are warranted not to fail to execute their programming instructions due to defects in materials and workmanship. If HP receives notice of such defects during the warranty period, HP shall repair or replace software media and firmware which do not execute their programming instructions due to such defects. HP does not warrant that the operation of the software, firmware or hardware shall be uninterrupted or error free.

LIMITATION OF WARRANTY

The foregoing warranty shall not apply to defects resulting from improper or inadequate maintenance by Buyer, Buyer-supplied software or interfacing, unauthorized modification or misuse, operation outside of the environmental specifications for the product, or improper site preparation or maintenance.

NO OTHER WARRANTY IS EXPRESSED OR IMPLIED. HEWLETT-PACKARD SPECIFICALLY DISCLAIMS THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE.

EXCLUSIVE REMEDIES

THE REMEDIES PROVIDED HEREIN ARE BUYER'S SOLE AND EXCLUSIVE REMEDIES. HEWLETT-PACKARD SHALL NOT BE LIABLE FOR ANY DIRECT, INDIRECT, SPECIAL, INCIDENTAL, OR CONSEQUENTIAL DAMAGES, WHETHER BASED ON CONTRACT, TORT, OR ANY OTHER LEGAL THEORY.

ASSISTANCE

Product maintenance agreements and other customer assistance agreements are available for Hewlett-Packard products.

For any assistance, contact your nearest Hewlett-Packard Sales and Service Office. Addresses are provided at the back of this manual.

12/1/81

HEWLETT PACKARD

SAFETY SUMMARY

The following general safety precautions must be observed during all phases of operation, service, and repair of this instrument. Failure to comply with these precautions or with specific warnings elsewhere in this menual violates safety standards of design, manufacture, and intended use of the instrument. Hewlett-Packard Company assumes no liability for the customer's failure to comply with these requirements. This is a Safety Cless 1 instrument.

GROUNO THE INSTRUMENT

To minimize shock hazard, the instrument chassis and cabinet must be connected to an electrical ground. The instrument is equipped with a three-conductor ac power cable. The power cable must either be plugged into an approved three-contact electrical outlet or used with a three-contact to two-contact adapter with the grounding wire (green) firmly connected to an electrical ground (safety ground) at the power outlet. The power jack and mating plug of the power cable meet International Electrotechnical Commission (IEC) safety standards.

DO NOT OPERATE IN AN EXPLOSIVE ATMOSPHERE

Do not operate the instrument in the presence of flammable gases or fumes. Operation of any electrical instrument in such an environment constitutes a definite safety hazard.

KEEP AWAY FROM LIVE CIRCUITS

Operating personnel must not remove instrument covers. Component replacement and internal adjustments must be made by qualified maintenance personnel. Do not replace components with power cable connected. Under certain conditions, dangerous voltages may exist even with the power cable removed. To avoid injuries, always disconnect power and discharge circuits before touching them.

DO NOT SERVICE OR AOJUST ALONE

Do not attempt internal service or adjustment unless another person, capable of rendering first aid and resuscitation, is present.

USE CAUTION WHEN EXPOSING OR HANOLING THE CRT

Breakage of the Cathode-ray Tube (CRT) causes a high-velocity scattering of glass fragments (implosion). To prevent CRT implosion, avoid rough handling or jarring of the instrument. Handling of the CRT shall be done only by qualified maintenance personnel using approved safety mask and gloves.

DO NOT SUBSTITUTE PARTS OR MODIFY INSTRUMENT

Because of the danger of introducing additional hazards, do not install substitute parts or perform any unauthorized modification to the instrument. Return the instrument to a Hewlett-Packard Sales and Service Office for service and repair to ensure that safety features are maintained.

DANGEROUS PROCEDURE WARNINGS

Warnings, such as the example below, precede potentially dangerous procedures throughout this manual. Instructions contained in the warnings must be followed.

WARNING

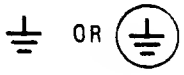
Oangerous voltages, capable of ceusing deeth, ere present in this instrument. Use extreme caution when handling, testing, end adjusting.

SAFETY SYMBOLS

General Definitions of Safety Symbols Used On Equipment or In Manuals.

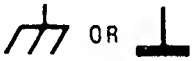
Instruction manual symbol: the product will be marked with this symbol when it is necessary for the user to refer to the instruction manual in order to protect against damage to the instrument.

Indicates dangerous voltage (terminals fed from the interior by voltage exceeding 1000 volts must be so marked).



Protective conductor terminal. For protection against electrical shock in case of a fault. Used with field wiring terminals to indicate the terminal which must be connected to ground before operating equipment.

Low-noise or noiseless, clean ground (earth) terminal. Used for a signal common, as well as providing protection against electrical shock in case of a fault. A terminal marked with this symbol must be connected to ground in the manner described in the installation (operating) manual, and before operating the equipment.



Frame or chassis terminal. A connection to the frame (chassis) of the equipment which normally includes all exposed metal structures.

Alternating current (power line).

Direct current (power line).

Alternating or direct current (power line).

The WARNING sign denotes a hazard. It calls attention to a procedure, practice, condition or the like, which, if not correctly performed or adhered to, could result in injury or death to personnel.

The CAUTION sign denotes a hazard. It calls attention to an operating procedure, practice, condition or the like, which,if not correctly performed or adhered to, could result in damage to or destruction of part or all of the product.

NOTE: The NOTE sign denotes important information. It calls attention to procedure, practice, condition or the like, which is essential to highlight.

TABLE OF CONTENTS

SECTION I
GENERAL INFORMATION

SECTION II
PERFORMANCE TEST

SECTION III
ADJUSTMENTS

SECTION IV
REPLACEABLE PARTS

SECTION V
BACKDATING

SECTION VI
FAULT ISOLATION

SECTION VII
SCHEMATICS/SERVICE

LIST OF TABLES

LIST OF ILLUSTRATIONS

SECTION VII
SCHEMATICS/SERVICE

SECTION VII
SERVICE

7-1 INTRODUCTION

The information contained in this section is used for troubleshooting a circuit board to the component level. The following information is given for each board: circuit description, troubleshooting procedures, component locator, and schematic diagram. A complete list of schematic diagrams is given in Table 7-1.

The equipment needed to perform the troubleshooting procedures is listed in Table 1-5. If the recommended equipment is not available, a substitute may be used which meets or exceeds the critical specifications listed in the table.

NOTE

After completing a test or repair, check that all jumpers have been returned to the NORMAL or RUN position and that all cables have been re-connected.

CAUTION

Do not remove or replace any circuit boards when the LINE power switch is ON.

CAUTION

To protect the -hp-3561A circuits from static discharge, remove or replace circuit boards only at static protected work stations.

Table 7-1 Schematic Diagrams

Schematic/ Assembly Number	Number of Schematics	Board Description
A10	2	Input Amplifier
A15	2	Digitizer
A20	4	Digital Filter
A30	2	FFT/RAM
A40	4	Processor/ROM
A50	3	Local Oscillator/Noise Source
A60	3	Digital Display Driver
A65	1	CMOS/Bubble Memory
A66	1	CMOS Memory
A70, A71, A72	2	Power Supply
A80, A81	1	Keyboard
A82	1	Rear Panel
A90	1	Analog Display Driver

7-2 SAFETY CONSIDERATIONS

WARNING

Maintenance described herein is performed with power supplied to the instrument and with the protective covers removed. Such maintenance should be performed only by service-trained personnel who are aware of the hazards involved.

Any interruption of the protective grounding conductor inside or outside the instrument, or disconnection of the protective earth terminal, is likely to make the instrument hazardous.

WARNING

±170 Volts are present on the A70 and A71 Assemblies. ±170 Volts are present on the heat sinks on the A70 Assembly. This voltage is exposed whenever the protective power supply cover is removed. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

WARNING

Capacitors in the power supply will remain charged to ±170 Volts dc for at least three(3) minutes after power is removed from the instrument. Do not remove the power supply assemblies (A70, A71, A72) or disconnect cables W70 or W71 for at least three(3) minutes after power is removed from the -hp-3561A.

WARNING

Only fuses with the required current rating and of the specified type should be used for replacement. The use of repaired fuses or short circuiting the fuse holder is not permitted. Whenever it is likely that the protection offered by the fuse has been impaired, the instrument must be made inoperative, and secured against any unintended operation.

WARNING

The protective power supply covers are removed exposing ±170 Volts while troubleshooting the A66 CMOS Memory Assembly or the A65 CMOS/Bubble Memory Assembly. Be extremely careful when working in this area, the high voltage could cause serious personal injury if contacted.

WARNING

+8000 Volts are present in the CRT AT ALL TIMES, EVEN WHEN POWER IS REMOVED FROM THE INSTRUMENT! Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

7-3 SCHEMATIC NOTES

1. PARTIAL REFERENCE DESIGNATIONS ARE SHOWN. PREFIX WITH ASSEMBLY DESIGNATION FOR COMPLETE DESIGNATION.

2. COMPONENT VALUES ARE SHOWN AS FOLLOWS UNLESS OTHERWISE NOTED.
   RESISTANCE IN OHMS
   CAPACITANCE IN MICROFARADS
   INDUCTANCE IN MILLIHENRIES

3. DENOTES EARTH GROUND
   USED FOR TERMINALS WITH NO LESS THAN A NO. 18 GAUGE WIRE CONNECTED BETWEEN TERMINAL AND EARTH GROUND TERMINAL OF AC POWER RECEPTACLE

4. DENOTES FRAME GROUND
   USED FOR TERMINALS WHICH ARE PERMANENTLY CONNECTED WITHIN APPROXIMATELY 0.1 OHM OF EARTH GROUND.

5. DENOTES GROUND ON PRINTED CIRCUIT ASSEMBLY (ELECTRICALLY CONNECTED TO FRAME GROUND.)

6. DENOTES ISOLATED (I) OR SIGNAL(S) CIRCUIT GROUND.

7. DENOTES ASSEMBLY

8. DENOTES MAIN SIGNAL PATH

9. DENOTES FRONT PANEL MARKING

10. DENOTES REAR PANEL MARKING.

11. DENOTES SCREWDRIVER ADJUST

12. AVERAGE VALUE SHOWN. OPTIMUM VALUE SELECTED AT FACTORY. THE VALUE OF THESE COMPONENTS MAY VARY FROM ONE INSTRUMENT TO ANOTHER.

13. DENOTES RF SHIELD

14. ALL RELAYS ARE SHOWN DEENERGIZED. ALL ANALOG SWITCH IC'S ARE SHOWN NOT ACTIVE.

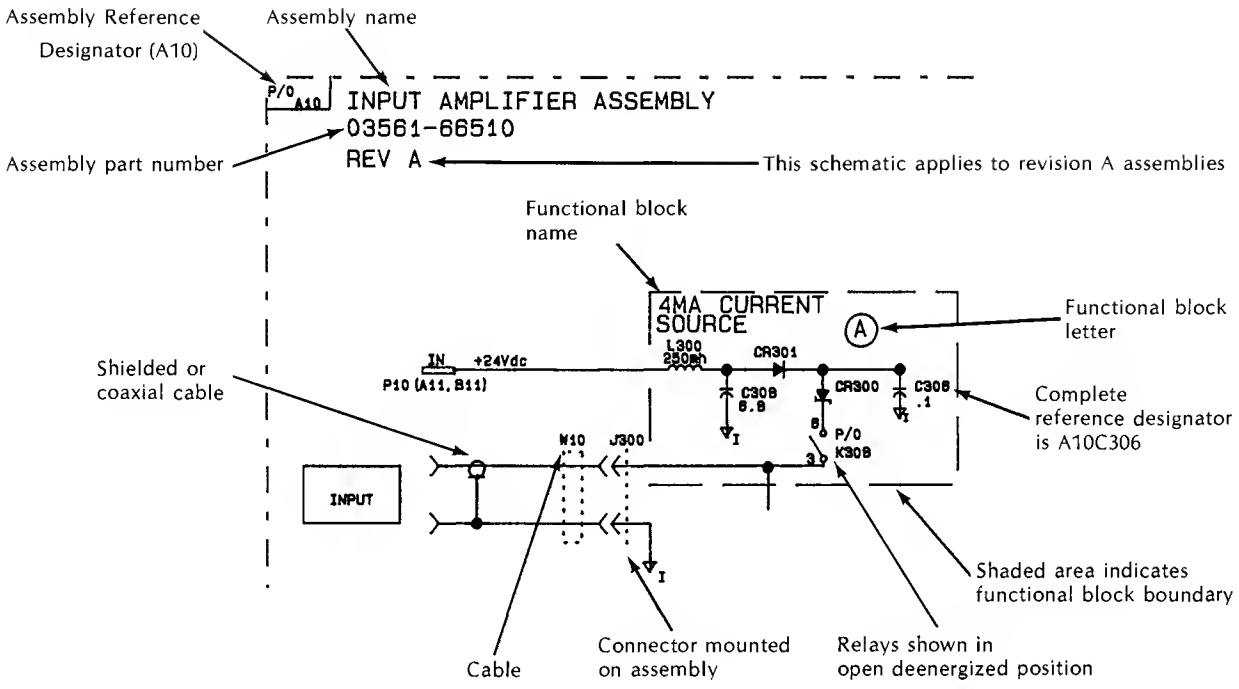
15. RP1 DENOTES RESISTOR PACK

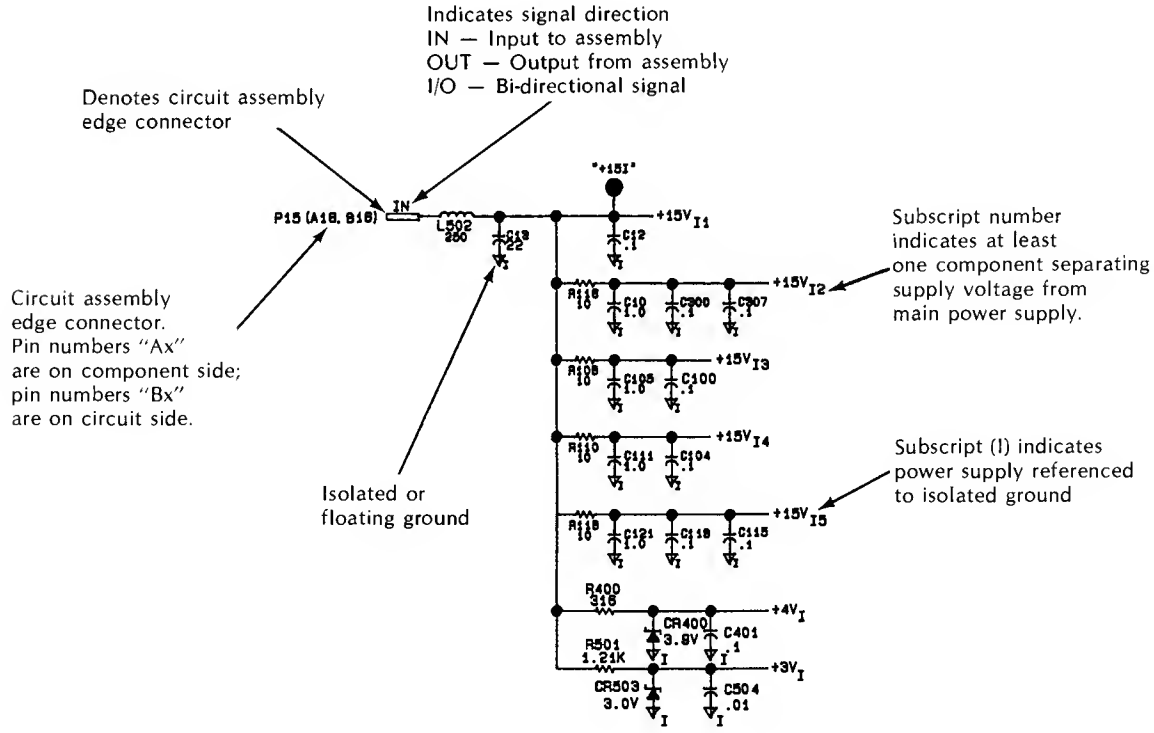
16. ALL WAVEFORMS SHOWN ARE MEASURED WITH A 10:1 OSCILLOSCOPE PROBE UNLESS OTHERWISE NOTED. ALL DC VOLTAGES ARE MEASURED WITH A 1:1 PROBE AND A DVM.

17. R3 0 MAY BE LOADED WITH A ZERO OHM RESISTOR OR A JUMPER WIRE.

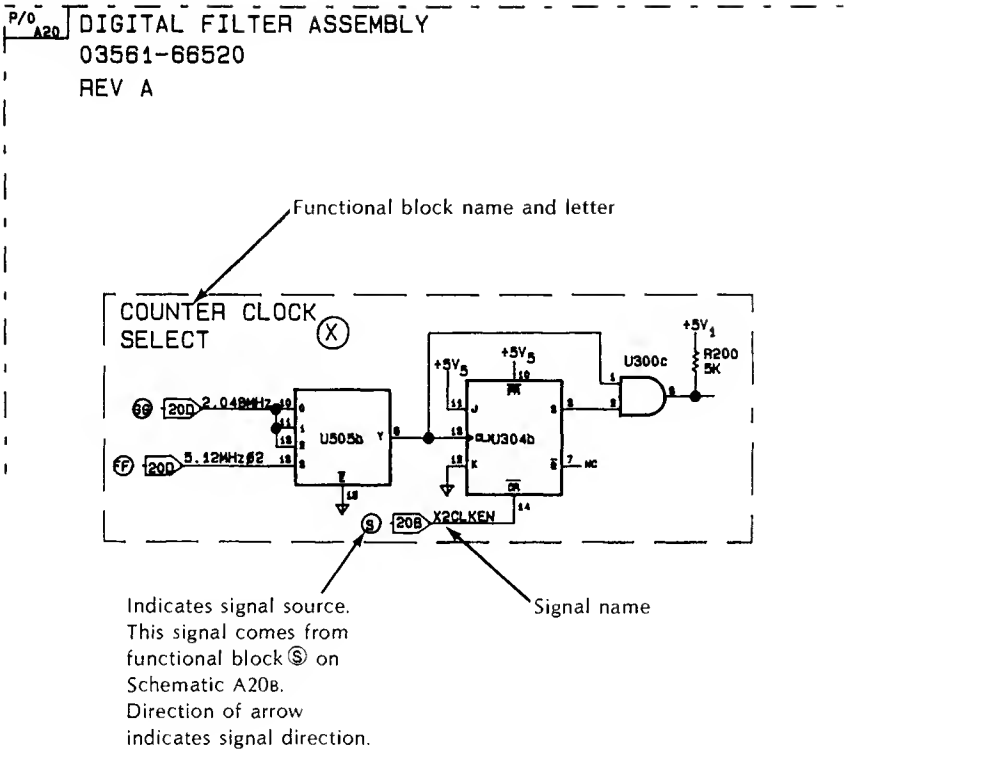
18. T MOVEABLE JUMPER. N INDICATES NORMAL OR RUN POSITION; T INDICATES TEST POSITION.

W3 N

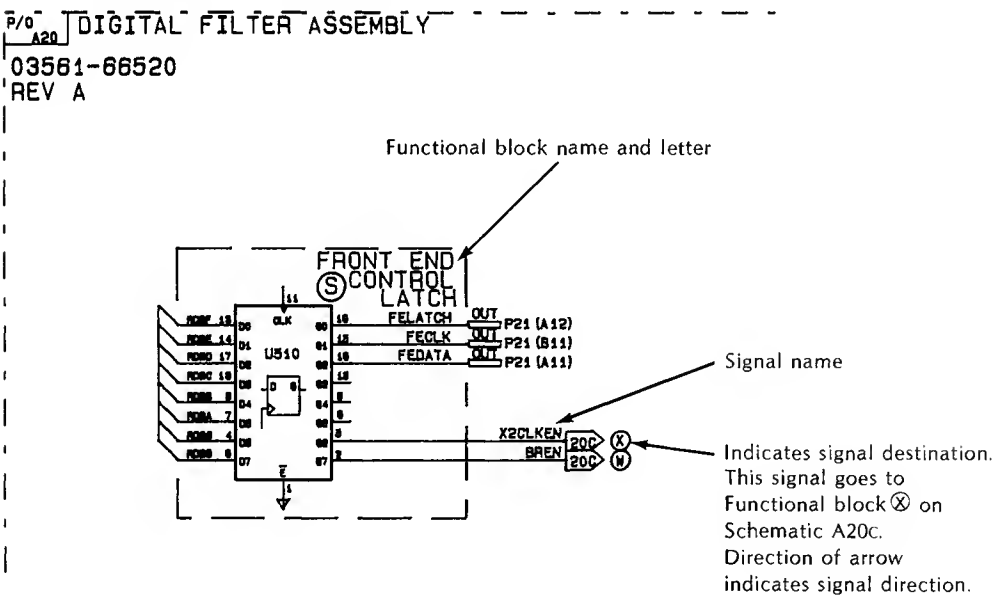

Assembly Reference Designator (A10)
Assembly name
P/O A10
INPUT AMPLIFIER ASSEMBLY
03561-66510
REV A
Assembly part number
This schematic applies to revision A assemblies
Functional block name
4MA CURRENT SOURCE
A
Functional block letter
Shielded or coaxial cable
IN +24Vdc
P10 (A11, B11)
L300 250mh
CR301
C308 6.8
CR300
C306 .1
Complete reference designator is A10C306
W10
J300
P/O K308
INPUT
Shaded area indicates functional block boundary
Cable
Connector mounted on assembly
Relays shown in open deenergized position

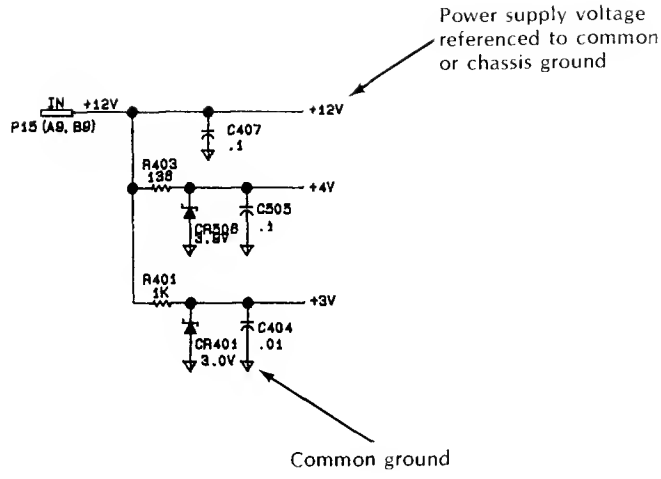

Indicates signal direction
IN — Input to assembly
OUT — Output from assembly
I/O — Bi-directional signal
Denotes circuit assembly edge connector
"+15I"
P15 (A16, B16)
IN
L502 250
C13 22
+15V I1
C12 .1
R116 10
C10 1.0
C300 .1
C307 .1
+15V I2
Subscript number indicates at least one component separating supply voltage from main power supply.
R108 10
C105 1.0
C100 .1
+15V I3
R110 10
C111 1.0
C104 .1
+15V I4
R118 10
C121 1.0
C118 .1
C115 .1
+15V I5
Subscript (I) indicates power supply referenced to isolated ground
Circuit assembly edge connector. Pin numbers "Ax" are on component side; pin numbers "Bx" are on circuit side.
Isolated or floating ground
R400 316
CR400 3.8V
C401 .1
+4V I
R501 1.21K
CR503 3.0V
C504 .01
+3V I

Schematic A20c



Schematic A20B




Power supply voltage
referenced to common
or chassis ground
IN +12V
P15 (A9, B9)
+12V
C407
.1
R403
13Ω
+4V
CR505
3.6V
C505
.1
R401
1K
+3V
CR401
3.0V
C404
.01
Common ground

7-4 A10 INPUT AMPLIFIER ASSEMBLY

7-5 Input Amplifier Circuit Description

GENERAL

The main function of the Input Amplifier Assembly is to implement the RANGE function. This function allows the -hp-3561A to measure signals of different amplitudes. The range setting specifies the maximum input amplitude which will not overload the -hp-3561A. Other circuitry on the A10 Assembly includes the Auto-Zero DAC, Trigger Level DAC, and A-Weight Filter.

[A] 4 mA CURRENT SOURCE, FRONT PANEL GROUND SWITCH

When signal ICP ON/OFF is TTL high, relay K308 closes, and a 4 milliamp current is delivered to the center conductor of the BNC input connector.

The front panel ground switch determines the ground reference for the the input connector. When the ground switch is in the FLOAT position, signal FEISO is pulled low to tell the processor the position of the ground switch for HP-IB access.

[B] CAL SIGNAL GENERATOR, [O] CAL SIGNAL CONTROL

These circuits produce a signal with a precise amplitude of 195 mVrms (-14.2 dBV) which is used to calibrate the amplitude accuracy of the -hp-3561A. The cal signal frequency, which is set on the A20 Assembly, is 4 kHz when the cal signal is selected by pressing the INPUT key and selecting CAL SIG ON. To isolate the front panel input connector when the cal signal is enabled, BNC1 goes low to open K305 and K307 and BNC2 goes high to close K306. For more information, see the "Self Calibration" paragraph in Section 6 of this manual.

[C] ATTENUATOR #1,[F] ATTENUATOR #2, [H] ATTENUATOR #3,[J] ATTENUATOR #4

These attenuators are programmable through the front end control register to the attenuation values specified on the schematic. The equivalent attenuation in linear terms is also given on the schematic. The attenuators are used to scale the input signal to a nominal level for the A/D converter. Table 7-2 lists all of the attenuator setting as a function of the instrument RANGE setting.

[K] A-WEIGHT FILTER

The A-Weight Filter is enabled by the AWHT ON/OFF signal from the front end control register. The A-Weight Filter implements ANSI Standard S1.4-1971. A table of filter gain verses frequency is given in Table 7-3.

Table 7-2 Attenuator Settings vs. Range Settings

RANGE (DBV)	ATTENUATOR#1 (dBV)	ATTENUATOR#2 (dBV)	ATTENUATOR#3 (dBV)	ATTENUATOR#4 (dBV)
+27	40	12	12	14
+26	40	13	10	14
+25	40	12	10	14
+24	40	13	8	14
+23	40	12	8	14
+22	40	13	6	14
+21	40	12	6	14
+20	40	13	4	14
+19	40	12	4	14
+18	40	13	2	14
+17	40	12	2	14
+16	40	1	12	14
+15	40	0	12	14
+14	40	1	10	14
+13	40	0	10	14
+12	40	1	8	14
+11	40	0	8	14
+10	40	1	6	14
+9	40	0	6	14
+8	40	1	4	14
+7	20	12	12	14
+6	20	13	10	14
+5	20	12	10	14
+4	20	13	8	14
+3	20	12	8	14
+2	20	13	6	14
+1	20	12	6	14
0	20	13	4	14
-1	20	12	4	14
-2	20	13	2	14
-3	20	12	2	14
-4	20	1	12	14
-5	20	0	12	14
-6	20	1	10	14
-7	20	0	10	14
-8	20	1	8	14
-9	20	0	8	14
-10	20	1	6	14
-11	20	0	6	14
-12	20	1	4	14
-13	0	12	12	14
-14	0	13	10	14
-15	0	12	10	14
-16	0	13	8	14
-17	0	12	8	14
-18	0	13	6	14
-19	0	12	6	14
-20	0	13	4	14
-21	0	12	4	14
-22	0	13	2	14
-23	0	12	2	14
-24	0	1	12	14
-25	0	0	12	14
-26	0	1	10	14
-27	0	0	10	14

Table 7-2 Attenuator Settings vs. Range Settings (Cont'd)

RANGE (DBV)	ATTENUATOR#1 (dBV)	ATTENUATOR#2 (dBV)	ATTENUATOR#3 (dBV)	ATTENUATOR#4 (dBV)
-28	0	1	8	14
-29	0	0	8	14
-30	0	1	6	14
-31	0	0	6	14
-32	0	1	4	14
-33	0	0	4	14
-34	0	1	2	14
-35	0	0	2	14
-36	0	1	0	14
-37	0	0	0	14
-38	0	1	0	12
-39	0	0	0	12
-40	0	1	0	10
-41	0	0	0	10
-42	0	1	0	8
-43	0	0	0	8
-44	0	1	0	6
-45	0	0	0	6
-46	0	1	0	4
-47	0	0	0	4
-48	0	1	0	2
-49	0	0	0	2
-50	0	1	0	0
-51	0	0	0	0

[L] AUTO-ZERO DAC

The auto-zero DAC is programmed through the front end control register to zero the dc offset in the input circuitry. An auto-zero is performed whenever a calibration is performed or the instrument range is changed. This function can be disabled by moving jumper A10W100 to the test position.

[N] DIGITAL CONTROL INPUT AND ISOLATION

The FEDATA, FECLOCK and FELATCH signals work together to input, clock, and latch digital information from the processor into the front end control register. These three signals are transformer coupled to maintain isolation between the chassis ground and the isolated ground.

[P] FRONT END CONTROL REGISTER

The front end control register is a serial in parallel out register which latches and stores A10 Assembly programming data. Data stored in the front end control register is only updated when an instrument front panel control is changed which requires a change in the setup of the A10 Assembly or the A15 Assembly.

Table 7-3 A-Weight Filter Characteristics

Frequency (Hz)	Amplitude Gain (dB)	Tolerance (dB)
10.0	-70.4	±4.0
12.5	-63.4	±3.5
16.0	-56.7	±3.0
20.0	-50.5	±2.5
25.0	-44.7	±2.0
31.5	-39.4	±1.5
40.0	-34.6	±1.5
50.0	-30.2	±1.0
63.0	-26.2	±1.0
80.0	-22.5	±1.0
100	-19.1	±1.0
125	-16.1	±1.0
160	-13.4	±1.0
200	-10.9	±1.0
250	-8.6	±1.0
315	-6.6	±1.0
400	-4.8	±1.0
500	-3.2	±1.0
630	-1.9	±1.0
800	-0.8	±1.0
1000	0	±1.0
1250	0.6	±1.0
1600	1.0	±1.0
2000	1.2	±1.0
2500	1.3	±1.0
3150	1.2	±1.0
4000	1.0	±1.0
5000	-0.5	+1.5,-2
6300	-0.8	+1.5,-2
8000	-1.1	+1.5,-3
10000	-2.5	+2,-4
12500	-4.3	+3,-6
16000	-6.6	+3,-∞
20000	-9.3	+3,-∞

[Q] TRIGGER LEVEL DAC

The Trigger Level DAC is used to set up the voltage level at which the -hp-3561A will trigger on the input signal. The trigger level is established by the DEFINE % OF RNG soft key. A trigger level of 100 % of range corresponds to a DAC output of 1.29 Vdc regardless of the range selected. The DAC output for other percentage settings may be directly calculated by taking the percentage selected of 1.29 Vdc (eg., .645 Vdc for a 50 % setting).

Table 7-4 A10 Assembly Signal Descriptions

Signal Name	Description
AC/DC CPL	AC/DC CouPLing: TTL high for dc coupling of the input signal, low for ac coupling.
ATTN1 - ATTN4	ATTeNuator #1 through ATTeNuator #4: These signals program the attenuation of the four input attenuators.
BNC1	Isolates the front panel BNC connector when the CAL BNC2 signal is enabled.
COMP OUT	COMPare OUTput: This signal is used on the A15 Assembly to generate the over-range, under-range, and input trigger signals.
FE CAL	Front End CALibration: TTL signal from the A20 Assembly which sets the frequency of the CAL signal used for self calibration.
FE CALG	Front End CALibration Gated: FE CAL gated by CAL ON/OFF Signal.
FECLOCK	Front End CLOCK: Clocks the FEDATA signal into the front end control register.
FEDATA	Front End DATA: Serial data which programs all circuits on the A10 Assembly when latched into the front end control register.
FEDATAIC	Front End DATA Isolated Continue: A continuation of the FEDATA signal. This signal contains programming information for the A15 Assembly.
FELATCH	Front End LATCH: Latches the FEDATA signal into the front end control register.
TRIG0-7	TRIGger bus (0-7): Programs the trigger level D/A converter.
0DAC0-7	0 Digital to Analog Converter bus (0-7): Programs the auto zero D/A converter.

7-6 Troubleshooting the Input Amplifier

CAUTION

Before removing the A10 Assembly, remove the bottom cover and disconnect the input cable (W10).

GENERAL

The primary method for troubleshooting this assembly is to input a sine wave to the -hp-3561A and check the signal at each amplifier stage. Table 7-5 lists the signal amplitudes at the AMP1, AMP2, and AMP3 test points and at the A10 output (J200) for an input sine wave with an amplitude equal to the -hp-3561A range setting.

All signal amplitudes listed have a tolerance of ±5% (±.4 dB)

[C] ATTENUATOR #1,[E] AMPLIFIER #1,[F] ATTENUATOR #2,[G] AMPLIFIER #2, [H] ATTENUATOR #3,[I] AMPLIFIER #3,[J] ATTENUATOR #4,[M] AMPLIFIER #4

To check these circuits, place the A10 Assembly on an extender board and use a BNC to SMB adapter cable to input a 1 kHz, 1 Vrms (1.414 Vpeak) sine wave into A10J10. Set the -hp-3561A controls as follows:

PRESET
RANGE . . . . . DEFINE RANGE . . . . . 0 dBV

Verify the signal amplitudes listed in the 0 dBV range column of Table 7-5. This test can be repeated at the other range settings listed.

Table 7-5 Signal Amplitudes vs. Range Setting

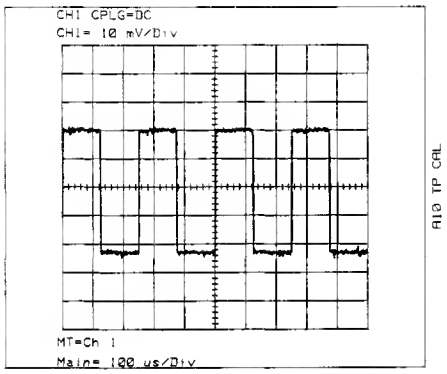
-hp-3561A RANGE SETTING		+9	0	-5	-36	-51
	dBV					
	Vrms	2.818	1.00	.5623	.0158	.0028
	Vpeak	3.985	1.414	.7952	.0223	.0039
TP AMP1	dBV	-21.46	-10.46	-15.46	-26.46	-41.56
	Vrms	.085	.300	.168	.047	.0085
	Vpeak	.120	.424	.238	.066	.012
TP AMP2	dBV	-11.92	-13.92	-5.92	-17.92	-31.92
	Vrms	.254	.201	.506	.127	.025
	Vpeak	.359	.284	.716	.180	.035
TP AMP3	dBV	-8.37	-8.37	-8.37	-8.37	-22.37
	Vrms	.381	.381	.381	.381	.076
	Vpeak	.539	.539	.539	.539	.107
OUTPUT	dBV	-12.83	-12.83	-12.83	-12.83	-12.83
	Vrms	.228	.228	.228	.228	.228
	Vpeak	.323	.323	.323	.323	.323

[B] CAL SIGNAL GENERATOR, [O] CAL SIGNAL CONTROL

To check these circuits, set the -hp-3561A controls as shown below, and use a digital voltmeter to check for .216 Vac at the CAL test point. Verify the CAL signal as shown in Figure 7-1.

PRESET
INPUT..... AUTO CAL OFF
CAL SIG ON

Figure 7-1 CAL Signal Waveform



Probe: 10:1

Ch1: Connection- A10 TP CAL
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

Troubleshooting for Distortion

To troubleshoot for distortion failures, a low distortion oscillator, which meets the required characteristics listed in Table 1-5, is used to input a sine wave to each of the test points AMP1, AMP2, AMP3, and to A15J1. The -hp-3561A display can then be monitored for distortion introduced by each amplifier stage.

1. Set the -hp-3561A controls as follows:

   PRESET
   INPUT..... AUTO CAL OFF

2. Disconnect cable W15 from connector A15J1 and move test jumper A10W100 to the TEST position.

3. Using a BNC to SMB adapter cable and the low distortion oscillator, input a 1 kHz, .228 Vrms(±5%) sine wave into A15J1. If all harmonics are greater than 80 dB below the 1 kHz fundamental, the -hp-3561A main measurement path through the A15, A20, and A30 Assemblies is operating correctly. This main measurement path can now be used to test the A10 Assembly. If a full scale 1 kHz sine wave does not appear on the display, or the harmonic signals are less than 80 dB below the fundamental, troubleshoot the A15, A20, and A30 Assemblies before troubleshooting distortion on the A10 Assembly.

4. Reconnect cable W15 to connector A15J1.

5. Set the -hp-3561A controls as follows:

   RANGE ..... DEFINE RANGE .. ..-51 dBV

6. Connect a 50Ω termination to A10J300 through a BNC to SMB adapter cable.

7. Using a clip lead or a shielded connector, input a 1 kHz, 76 mVrms (±5%) sine wave to the AMP3 test point. If all harmonics are greater than 80 dB below the 1 kHz fundamental, the circuits between the AMP3 test point and A10J200 are operating correctly.

8. Set the -hp-3561A controls as follows:

   RANGE ..... DEFINE RANGE .. ..-36 dBV

9. Using a clip lead or a shielded connector, input a 1 kHz, 127 mVrms (±5%) sine wave to the AMP2 test point. If all harmonics are greater than 80 dB below the carrier, the circuits between the AMP2 test point and A10J200 are operating correctly.

10. Set the -hp-3561A controls as follows:

    RANGE ..... DEFINE RANGE .. ..-5 dBV

11. Using a clip lead or a shielded connector, input a 1 kHz, 169 mVrms (±5%) sine wave to the AMP1 test point. If all harmonics are greater than 80 dB below the 1 kHz fundamental, the circuits between the AMP1 test point and A10J200 are operating correctly.

12. Move test jumper A10W100 back to NORM position, and reconnect cable W15 to connector A15J1.

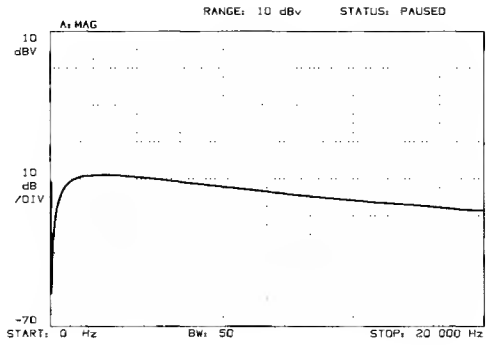
[K] A-WEIGHT FILTER

To check the A-Weight Filter for proper operation, connect the -hp-3561A noise source output to the -hp-3561A input connector and set the -hp-3561A controls as follows:

PRESET	
WINDOW	UNIFORM
SOURCE	PERIODIC NOISE
	DEFINE ATTEN... .....0 dB
FREQuency	DEFINE SPAN ....20 kHz
INPUT.....	A WT FLT ON
FORMAT	SINGLE

Check the frequency response by varying the -hp-3561A frequency span. To check for distortion or noise, input a sine wave rather than the noise signal to the -hp-3561A. Table 7-3 lists the A-Weight Filter gain for various frequencies.

Figure 7-2 A-Weight Filter Response



[A] 4 mA CURRENT SOURCE

To check the 4 mA ICP Current Source for proper operation, terminate the -hp-3561A input port with a 50Ω load and set the -hp-3561A controls as follows:

PRESET
INPUT..... ICP CURR ON

Use a digital voltmeter to check the voltage across the 50Ω load for approximately .2 Vdc. If the voltage is incorrect, check the +24 V power supply and the current source circuitry.

[Q] Trigger Level DAC

The output of the trigger level DAC may be monitored at the TRG test point. To troubleshoot the DAC, set the -hp-3561A controls as follows:

RESET
RANGE..... AUTO RNG OFF
TRIGger SELect... INPUT TRIGGER
SETUP SELECT ...DEFINE % OF RNG.....100 %

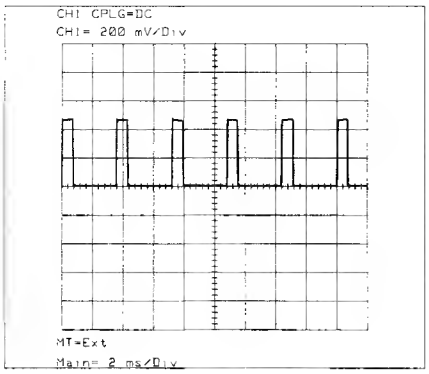
The DAC output should be 1.29 ± .13 Vdc. Vary the % of range selected and check the corresponding DAC output voltage (eg: a trigger level of 50 % of range will result in a .645 Vdc output).

[N] Digital Control Input and Isolation, [P] Front End Control Register

To check the these circuits, select self test 110 as follows, and check the waveforms shown in Figure 7-3.

PRESET
MODE ..... TEST SELECT.....DEFINE TEST NUM.....110 ENTER
START CONT TEST

Figure 7-3 Front End Control Register Waveforms

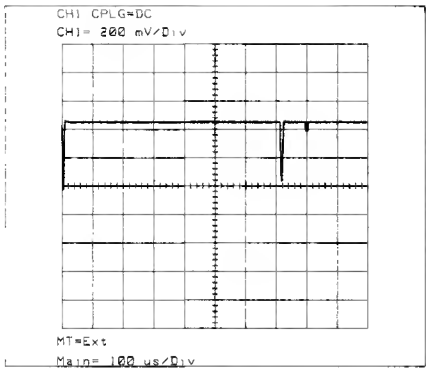


Probe: 10:1

Ch1: Connection- A10 U400(10) "FELATCHI"
Coupling- dc
Ground- Center Graticule

Trigger: External- A20 J200(5)
Slope: Positive

Bandwidth Limit: OFF

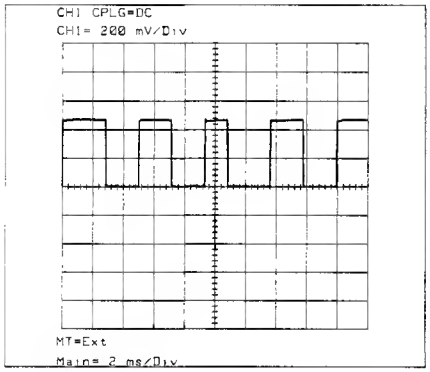


Probe: 10:1

Ch1: Connection- A10 U402(9) "FECLKI"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope: Negitive

Bandwidth Limit: OFF

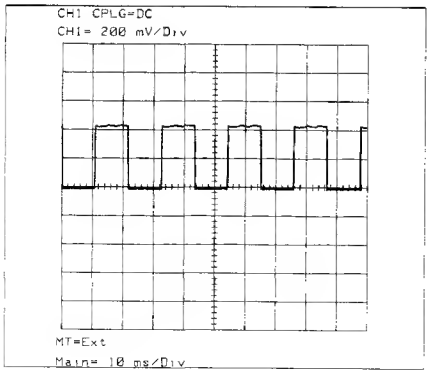


Probe: 10:1

Ch1: Connection- A10 U402(13) "FEDATAI"
Coupling- dc
Ground- Center Graticule

Trigger: External- A20 J200(5)
Slope: Positive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection-
This waveform is available at any of the following connection points. The waveform will be shifted in time relative to the external trigger at each different connection point.

U401(4,5,6,7,11,12,13,14)
U201(4,5,6,7,11,12,13,14)
U105(4,5,6,7,11,12,13,14)
U107(4,5,6,7,11,12,13,14)

Coupling- dc
Ground- Center Graticule

Trigger: External- A20 J200(5)
Slope: Positive

Bandwidth Limit: OFF

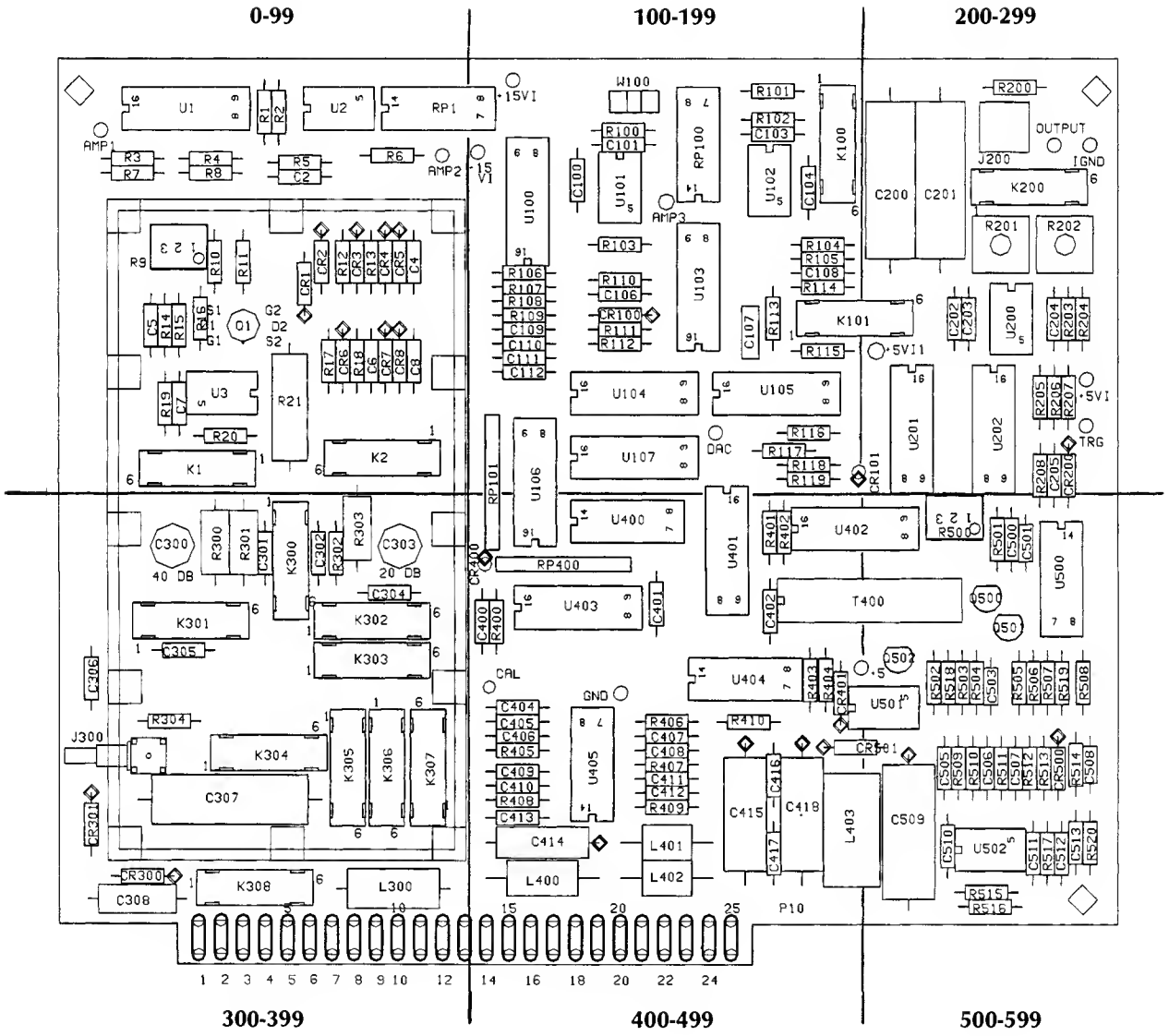
Table 7-6 A10 Assembly Signal Connections

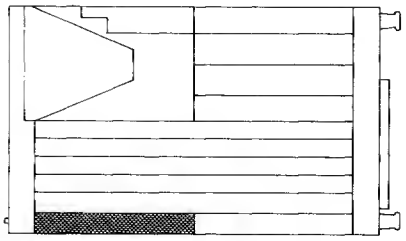
INPUTS

Signal Name	Functional Block	Connector Number	Origin Assembly
FE CAL	N	P10(A15)	A20
FECLOCK	N	P10(A16)	A20
FEDATA	N	P10(B16)	A20
FELATCH	N	P10(B15)	A20
INPUT	A	J10	Front panel
+24 V	A	P10(A11)	A99

OUTPUTS

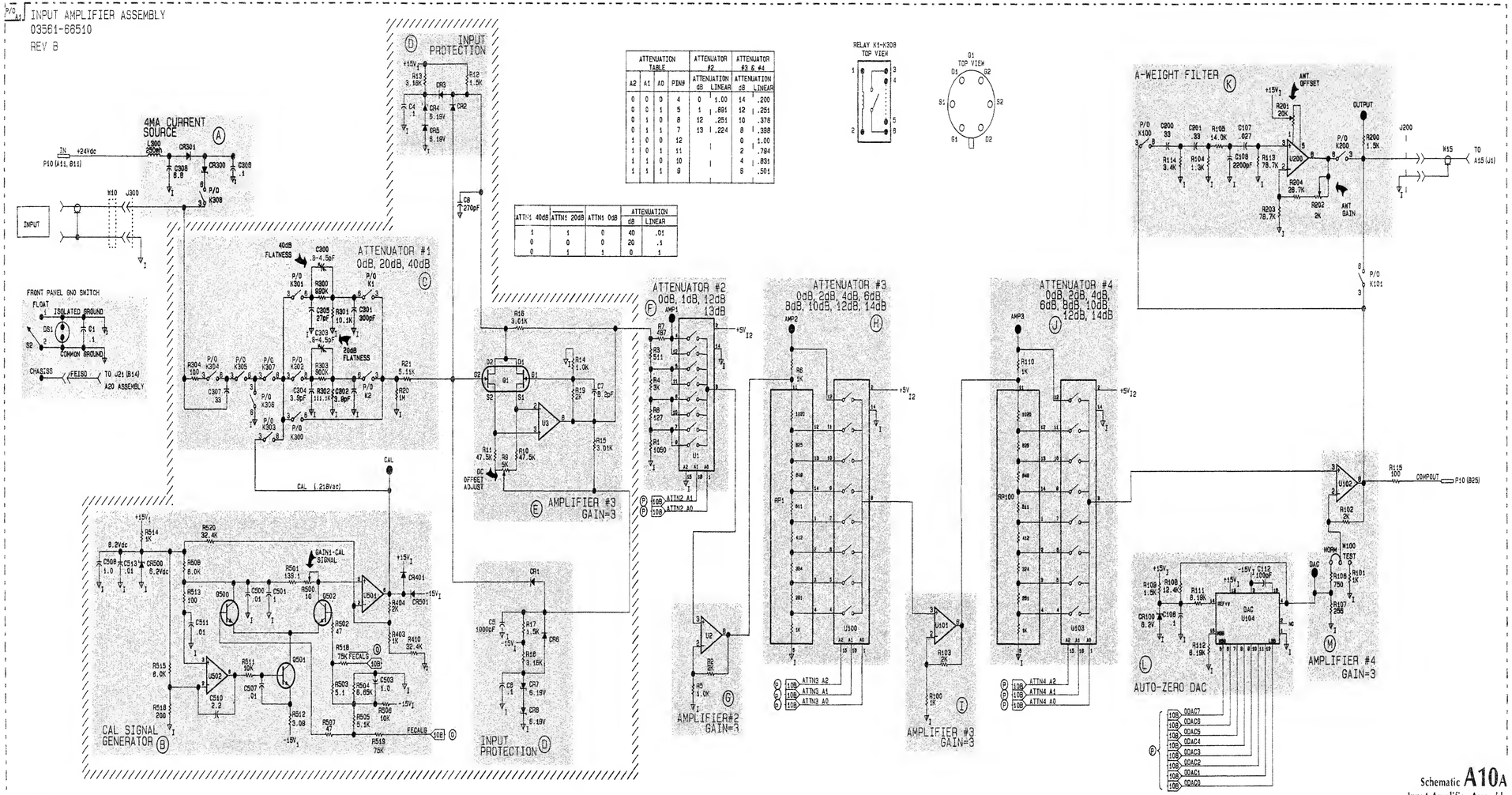
Signal Name	Functional Block	Connector Number	Destination Assemblies
COMP OUT	M	P10(B25)	A15
FECLK	P	P10(A24)	A15
FEDATA	P	P10(A25)	A15
FEISO	A	A99 J11	A20
FELATCH	P	P10(A23)	A15
SIGNAL OUT	K	J200	A15


0-99
100-199
200-299
300-399
400-499
500-599
U1
U2
RP1
W100
R100
C101
RP100
R101
R102
C103
K100
R200
OUTPUT
J200
IGND
K200
C200
C201
R201
R202
AMP1
R3
R7
R4
R8
R5
C2
R6
AMP2
15VI
15
VI
U100
C100
U101
AMP3
U102
C104
R103
R104
R105
C108
R114
R110
C106
CR100
R111
R112
U103
C107
R113
K101
C202
C203
U200
C204
R203
R204
R115
5VI1
R9
R10
R11
CR1
CR2
R12
CR3
R13
CR4
R14
CR5
C4
C5
R15
R16
S1
G1
Q1
G2
D2
S2
R17
CR6
R18
C6
CR7
R19
C7
U3
R21
CR8
C8
R20
K1
K2
R106
R107
R108
R109
C109
C110
C111
C112
U104
U105
U201
U202
R205
R206
R207
5VI
TRG
DAC
R116
R117
R118
R119
CR101
R208
C205
CR200
RP101
U106
U107
U400
U401
R401
R402
U402
R500
R501
C500
C501
U500
C300
40 DB
R300
R301
C301
K300
C302
R302
R303
C303
20 DB
C304
K301
K302
K303
C305
C306
CR400
RP400
C400
R400
U403
C401
C402
T400
050
050
CAL
GND
U404
R403
R404
CR401
U501
C502
R502
R518
R503
R504
C503
R505
R506
R507
R519
R508
R410
CR501
C404
C405
C406
R405
C409
C410
R408
C413
U405
R406
C407
C408
R407
C411
C412
R409
C414
L400
L401
L402
C415
C416
C417
C418
L403
C509
C505
R509
R510
C506
R511
C507
R512
R513
CR500
R514
C508
C510
U502
C511
R517
C512
C513
R520
R515
R516
J300
R304
K304
K305
K306
K307
C307
CR301
CR300
C308
K308
L300
P10
1 2 3 4 5 6 7 8 9 10 12 14 16 18 20 22 24



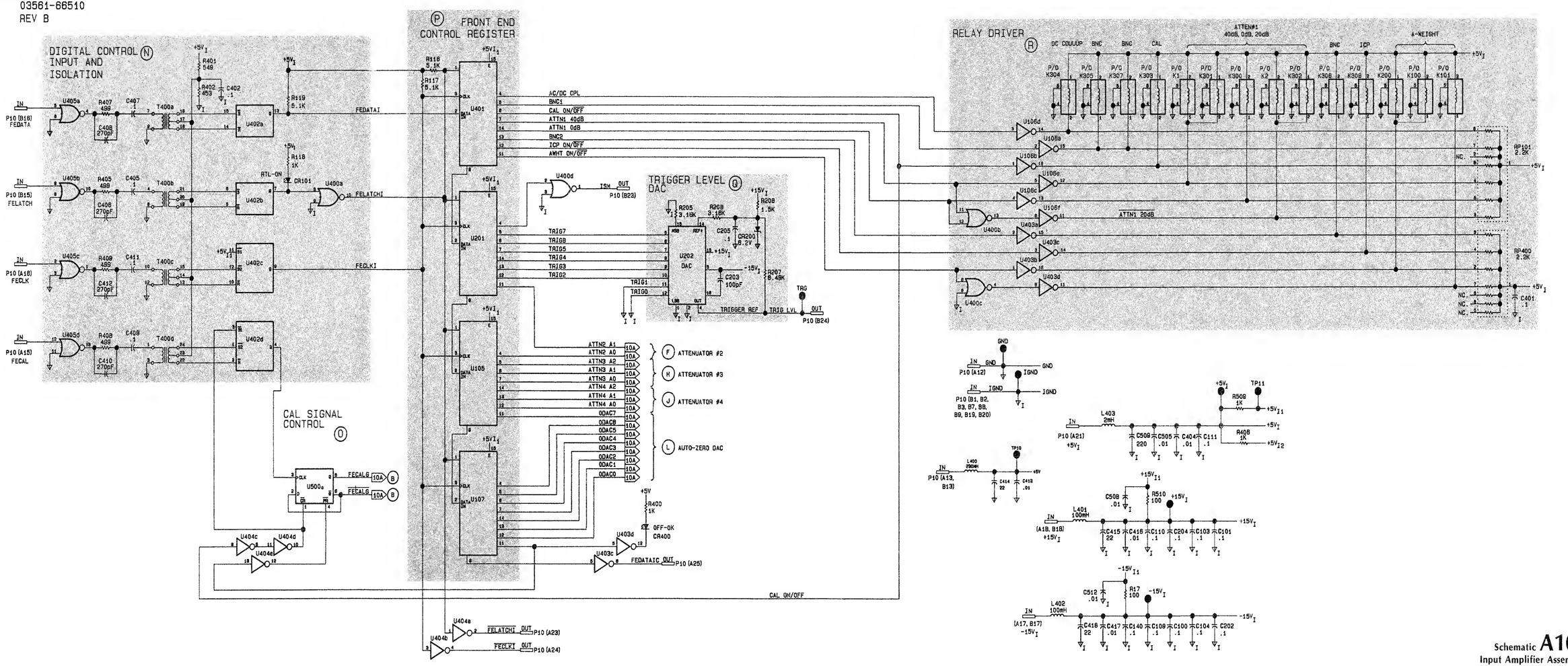
A10 Assembly

	+15V$_I$	+15V$_{II}$	-15V$_I$	-15V$_{II}$	+5V$_I$	GNDI	+5V	GND	By-Pass Capacitors
U1	13		3						C110, C109
U2	7		4						
U3	7		4						C101, C100
U100	13		3						C103, C104
U101	7		4						
U102	7		4						C202
U103	13		3						
U104	13		3						
U105					16	8			
U106					9	8			
U107					16	8			
U200	7		4						C204
U201					16	8			
U202	13		3						
U400					14	7			
U401					16	8			
U402					16	8			
U403					9	8			
U403					14	7			
U405							14	7	
U500					14	7			
U501	7		4						
U502		7		4					



Schematic **A10A**
Input Amplifier Assembly
7-19/7-20

A10 INPUT AMPLIFIER ASSEMBLY
03561-66510
REV B



Schematic **A10B**
Input Amplifier Assembly
7-21/7-22

7-7 A15 DIGITIZER ASSEMBLY

7-8 Digitizer Circuit Description

GENERAL

The A15 Assembly uses a "two-pass residue" type A/D converter to digitize the analog input signal into a 13 bit digital output. A track and hold circuit samples the input signal and holds it long enough for the analog to digital conversion to take place. In addition the A15 Assembly contains a 100 kHz low-pass filter to attenuate higher frequency signals which may interact with the measurement. Other circuits on the assembly include the over-range and half-range comparators, the trigger level comparators, a test register, and a ground isolation interface.

Figure 7-4 gives a timing diagram of the complete analog to digital conversion process. The heart of the A15 Assembly digitizer is a single chip, 8 bit A/D converter which will be referred to as the "8 bit ADC". Each complete analog to digital conversion consists of two passes of data through the 8 bit ADC. In the first pass, the track and hold output signal is input to the 8 bit ADC. The result of the first pass conversion is an 8 bit digital approximation to the analog track and hold output. The timing and control circuit then transfers this 8 bit digital signal to the second pass input circuit. In the second pass, the result of the first pass conversion is converted back into an analog signal and subtracted from the analog track and hold output, resulting in a signal that is equal to the error between the first pass 8 bit approximation and the track and hold output. This error signal is multiplied by 32 and input to the 8 bit ADC. The second pass conversion is then scaled back down by 32 and added to the first pass conversion to obtain a final 13 bit digital result.

Between each conversion, the 8 bit ADC is reset by passing a fixed dc voltage of .34 volts through it. The dc voltage is derived from the the 6.2 volt reference and is selected by the ADC input switch.

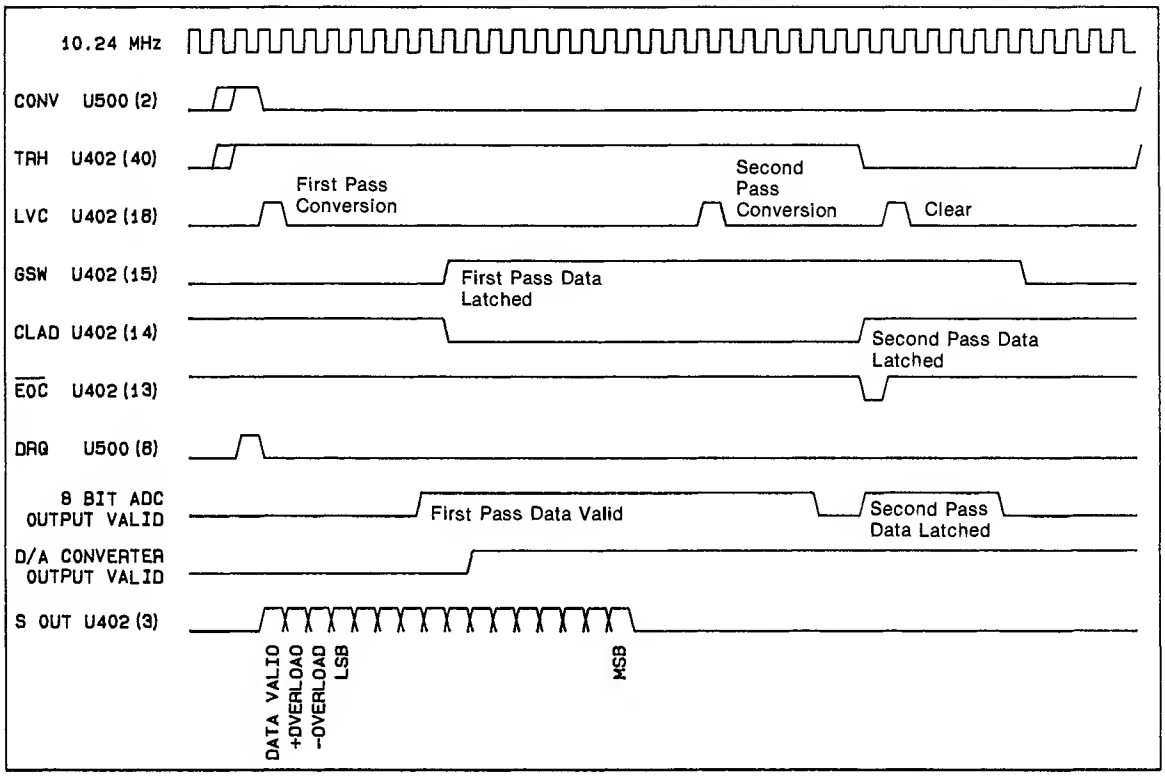
[A] 100 kHz LOW PASS FILTER

The 100 kHz low pass filter is a 4 stage filter with a gain of 0.557 and zeros at 371 kHz, 166 kHz, 151 kHz, and 214 kHz.

[F] TIMING CONTROL ISOLATION INTERFACE, [N] DATA OUTPUT ISOLATION INTERFACE, [T] STATUS ISOLATION INTERFACE, [U] TRIGGER ISOLATION INTERFACE

The isolation interface circuits use transformer coupling to isolate the floating ground from the chassis ground. Move the -hp-3561A front panel ground switch to the CHASSIS position to short the two grounds together. All of the transformer coupled interfaces are non-inverting.

Figure 7-4 A/D Converter Signal Timing



[G] TRACK AND HOLD

The track and hold circuit is controlled by the TRH signal generated in the ADC timing and control circuit. When the TRH signal is high, this circuit is an inverting unity gain amplifier. When the TRH signal goes low, the track and hold circuit samples the input signal and holds the sampled value until the TRH signal goes high again. The track and hold circuit samples the input data at a 256 kHz rate.

[H] SECOND PASS ADC INPUT

The Second Pass ADC input circuit consists of a 13 bit D/A converter, and a summing amplifier. The D/A converter outputs an analog signal which is equal to the first pass 8 bit ADC conversion. This signal is then subtracted from the actual track and hold output signal in U205 resulting in a signal which is equal to the error between the first pass 8 bit digital approximation, and the actual track and hold output. This error signal is multiplied by 32 and then input to the 8 bit ADC for the second pass conversion.

[I] TEST REGISTER

The test register is an extension of the front end control register on the A10 Assembly. The FEDATAIC signal is clocked into the register with the FECLKI signal. When the register is full the $\overline{\text{FELATCHI}}$ signal latches the data. The test register output programs the ADC timing and control circuit.

[K] A/D INPUT SWITCH

The A/D input switch selects which signal will be input to the 8 bit ADC. The GSW and CALD signals generated in the A/D timing and control circuit control the position of the ADC input switch as shown in Table 7-7.

Table 7-7 ADC Input Switch Control

GSW	CLAD	Input Selected
1	0	Second Pass Input
1	1	.34 Vdc Reference
0	0	First Pass Input
0	1	First Pass Input

[L] A/D TIMING AND CONTROL

The A/D timing and control circuit performs four major functions. First, the A/D timing and control circuit generates the control signals which coordinate the two passes of data through the 8 bit ADC, and control the track and hold circuit. Second, it transfers the first pass 8 bit ADC output to the D/A converter in the second pass input circuit. Third, it divides the second pass 8 bit ADC output by 32 and adds the result to the first pass 8 bit ADC output to obtain a final 13 bit result. Finally, the timing and control circuit transfers the 13 bit digital data to the digital filters on the A20 Assembly.

The digital filter on the A20 Assembly controls the A/D converter through the CONV and DRQ signals. The CONV signal is used to initiate an A/D conversion, and the DRQ signal is used to request the resultant data. Data is transferred to the digital filter with every DRQ, however, if the A/D conversion is not yet complete, the data will be invalid. The digital filter reads the DATA VALID bit of the transferred data to determine whether it should use the data or request the data again by sending another DRQ.

To improve the linearity of the A/D converter, the timing and control circuit adds 5 bits of noise to the first pass result, and then subtracts this noise back out of the second pass results.

[O] ANALOG TO DIGITAL CONVERTER (8 BIT ADC)

This circuit is a single chip 8 bit A/D converter. An analog to digital conversion is initiated on the rising edge of the LCV signal and data is valid 600 nSec later. The 8 bit ADC has an operating range of +0 volts to -1.0 volts.

[P] OVER-RANGE/HALF-RANGE

This circuit compares the input signal to a fixed voltage reference to generate the overload (OVLD), and half-range (6dB+,6dB-) signals. Comparator outputs are high when tripped by a fault condition.

Table 7-8 A15 Assembly Signal Descriptions

Signal	Description
CLAD	CLear 8 bit ADC: Selects a .34 Vdc signal as the input to the 8 bit ADC between the first and second pass conversions to clear the 8 bit ADC.
COMP	COMPare input: Identical to the main signal input from the A10 Assembly. This signal is used to generate HALFR, OVERR, and FETRIG.
CONV	CONVert: This signal initiates the two pass A/D conversion process.
DATAOUT	DATA OUTput: 13 bit serial data transferred to the digital filter LSB leading plus two bits to indicate overloads, and one bit to indicate data valid.
DRQ	Data ReQuest: Tells the A/D converter that the digital filter on the A20 Assembly is ready for new data.
EOC	End Of Conversion: Signifies that the two pass A/D conversion is complete.
$\overline{\text{FECLKI}}$	Front End CLOCK: Clocks the FEDATA signal into the test register.
FEDATAIC	Front End DATA: Serial data which, when latched into the test register, programs the A/D timing and control circuit.
FELATCHI	Front End LATCH: Latches the FEDATA signal in the test register.
FETRIG	Front End TRIGger: Triggers a measurement when the instrument is in the input trigger mode.
GSW	Gate SWitch: Goes low to select the first pass ADC input circuit and goes high to select the second pass ADC input circuit.
HALFR	HALF-Range: Goes high when the input is more than 6 dB below the range setting.
LCV	Local ConVert: Initiates an A/D conversion in the 8 bit ADC. Two 8 bit ADC conversions and one clear are needed for each complete A/D conversion.
OVERR	OVER-Range: Goes high when the input signal is greater than 2.8 dB above the range setting.
OFERQ	Over-FREQuency: Goes high when the external sample frequency is greater than 256 kHz.
SSTAT	Serial STATus: Serial data which outputs the status of the HALFR, OVERR, OFREQ, and FEDATA signals to the digital filter.
TRH	TRack/Hold: Goes high to place the track and hold circuit in the track mode and low to place the track and hold circuit in hold mode.
TRIG LVL	TRIGger LeVeL: Sets the trigger level for the input trigger.

[R] STATUS LATCH

Three status bits are generated for each A/D data output, half-range (HALFR), over-range (OVERR), and over-frequency (OFREQ). HALFR is high when the input signal is between 0dB and 6dB below the range setting, and OVERR is high when the input

signal is greater than 2.8 dB over the range setting. OFREQ is high when the external sample frequency is greater 256 kHz. In addition, the status word contains one bit of the FEDATA signal. This allows the processor to read the front end programming data to verify proper programming. The status data is transferred to the digital filter when a data request (DRQ) signal is received.

[S] TRIGGER LEVEL COMPARATOR

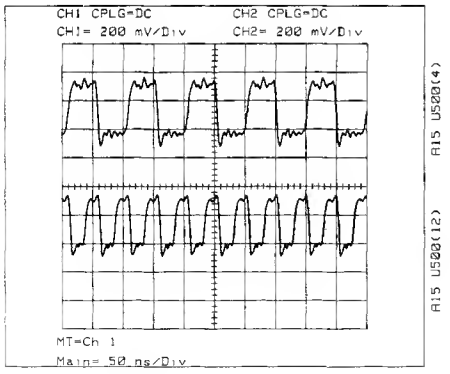
This circuit compares the input signal to the trigger level signal generated on the A10 Assembly. When the input signal exceeds the trigger level signal, the comparator output goes low. A trigger level of 100 % of range results in a 1.29 Vdc ±.12 Vdc signal at the TRIG LEV test point.

7-9 Troubleshooting the Digitizer

GENERAL

Troubleshooting the A15 Assembly should be performed in two steps: analog troubleshooting and digital troubleshooting. The primary method for troubleshooting the analog circuitry is to input a sine wave into A15J1 and then check the signal at each of the analog circuit blocks. The primary method for troubleshooting the digital circuitry is to check the control signals against the timing diagram given in Figure 7-4. Move the front panel ground switch to the CHASSIS position and verify the 20.48 MHz and 10.24 MHz clocks shown in Figure 7-5 before troubleshooting this assembly.

Figure 7-5 A15 Assembly Clock Waveforms



Probe: 10:1

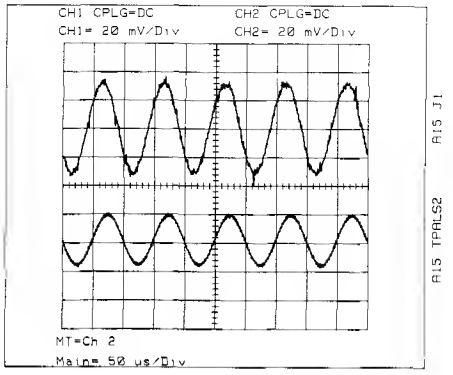
Ch1: Connection: A15U500(4) 10.24 MHz
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A15U500(12) 20.48 MHz
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth limit: ON

Figure 7-6 A15 Assembly Analog Waveforms in Test 115



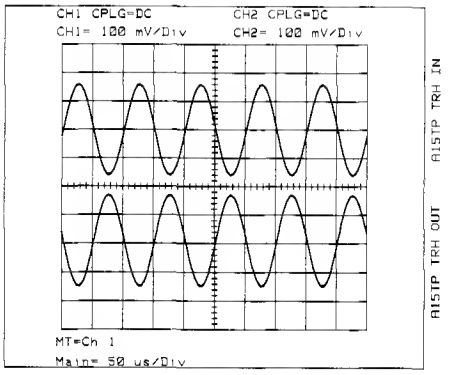
Probe: 10:1

Ch1: Connection: A15J1
(.23 ±.01 Vrms)
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A15TP"ALS2"
(.135 ±.006 Vrms)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch2
Slope- Negative

Bandwidth limit: ON



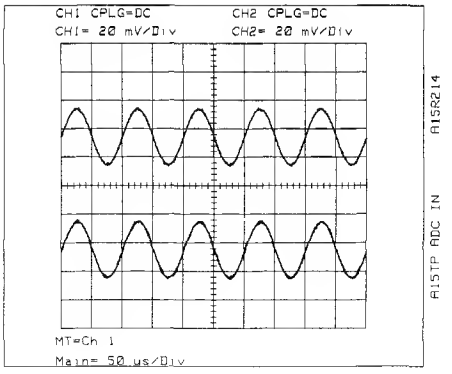
Probe: 10:1

Ch1: Connection- A15TP"TRH IN"
(1.1 Vrms)
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A15TP"TRH OUT"
(1.1 Vrms)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A15 R214
(.14 ±.01 Vrms)
Coupling- dc
Ground- Second Graticule From Top

Ch2: Connection- A15TP"ADC IN"
(.14 ±.01 Vrms)
Coupling- dc
Ground- Fourth Graticule From Bottom

Trigger:- Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

[A] 100 kHz LOW PASS FILTER, [B] X3 AMPLIFIER, [C] 482 kHz LOW PASS FILTER, [D] X3 AMPLIFIER, [G] TRACK AND HOLD, [H] SECOND PASS ADC INPUT, [M] ADC INPUT BUFFER

To check these circuits, set the -hp-3561A controls as follows:

PRESET
RANGE . . . . . DEFINE RANGE . . . . . .0 dBV
MODE . . . . . TEST SELECT. . . . .DEFINE TST NUM . . . . . .115 ENTER
START SNGL TST

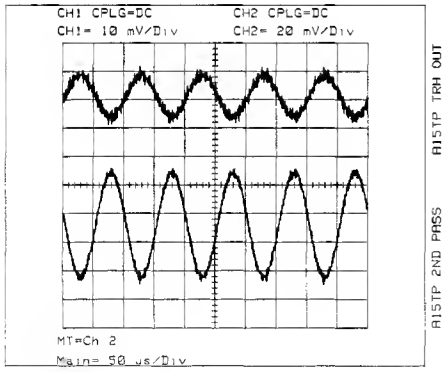
In this test the TRH signal is held low, causing the track and hold circuit to operate as a unity gain inverting amplifier. In addition, Test 115 programs the ADC input switch to select the first pass ADC input circuit as the input path to the 8 bit ADC.

1. Remove cable W15 from A15J1. Use the frequency synthesizer and a BNC to SMB adapter cable to input a .228 Vrms, 11 kHz sine wave into A15J1. Terminate the frequency synthesizer with 50 Ω.

2. Verify the waveforms shown in Figure 7-6. The signals shown in the figure are listed in the order of signal flow.

3. If all the signals in Figure 7-6 are correct, reduce the amplitude of the input sine wave to 10 mVrms, and verify the signals as shown in Figure 7-7. In Test 115, the output of the D/A converter (U102) is set to zero.

Figure 7-7 Second Pass ADC Input Waveforms In Test 115



Probe: 10:1

Ch1: Connection- A1STP"TRH OUT"
(1S ±1 mVrms)
Coupling- dc
Ground- Second Graticule From Top

Ch2: Connection- A1STP"2ND PASS"
(5S ±3 mVrms)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch2
Slope- Positive

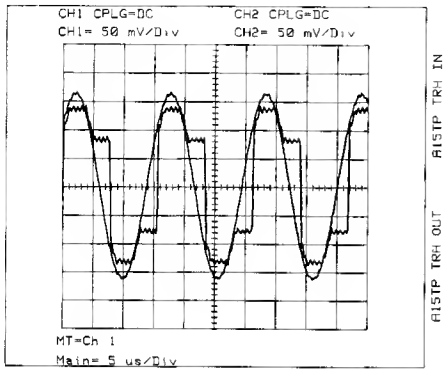
Bandwidth Limit: OFF

[G] TRACK AND HOLD

To check the track and hold circuit for proper operation, press the -hp-3561A PRESET key. When the preset is complete, use a frequency synthesizer, and a BNC to SMB adapter cable to input a 64 kHz, .228 Vrms sine wave into A15J1. Terminate the frequency synthesizer with 50 Ω. Check the TRH IN and TRH OUT test points for

the waveforms shown in Figure 7-8 to verify that the track and hold circuit is sampling the sine wave. Check for excessive DC offset or overshoot of the sampled signal. If there appears to be a problem in the track and hold output signal, check the TRH and FETG signals for the waveforms shown in Figure 7-8.

Figure 7-8 Track and Hold Waveforms



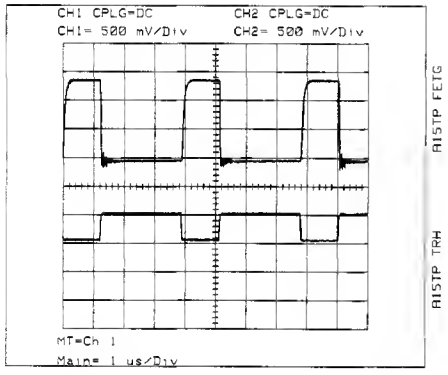
Probe: 10:1

Ch1: Connection- A15TP"TRH IN"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A1STP"TRH OUT"
Coupling- dc
Ground- Center Graticule
Invert Ch2

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A1STP"FETG"
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A1STP"TRH"
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Positive

NOTE

Adjust the frequency of the frequency synthesizer to within .5 Hz of 64 kHz to stabilize the waveform.

TROUBLESHOOTING DISTORTION

Distortion may be isolated to either the 100 kHz filter and X3 amplifiers, or the track and hold and A/D converter circuits. Use a low distortion oscillator, which meets the required characteristics listed in Table 1-5, when making any distortion or noise measurements.

1. Press the -hp-3561A PRESET key. When the preset is complete, use the low distortion oscillator and a BNC to SMB adapter cable to input an 11 kHz, 0.228 Vrms sine wave into A15J1. Terminate the low distortion oscillator in 600 Ω. If any of the harmonics are less than 80 dB below the 11 kHz fundamental, proceed with step 2.

2. Remove jumper J100 on the A15 Assembly, and input a 11 kHz, 1.14 Vrms (1.61 Vpeak) sine wave into the TRH IN test point. This removes circuit blocks A through D from the signal path.

   If any of the harmonics are less than 80 dB below the 10 kHz fundamental, the distortion failure is most likely in the track and hold circuit or the A/D converter.

   If all of the harmonics are now greater than 80 dB below the 10 kHz fundamental, the distortion failure is most likely in the 100 kHz low pass filter or the X3 amplifiers.

[F] TIMING AND CONTROL ISOLATION INTERFACE, [L] ADC TIMING AND CONTROL

To check these circuits, press the -hp-3561A PRESET key, and verify the control signals as shown in Figure 7-4.

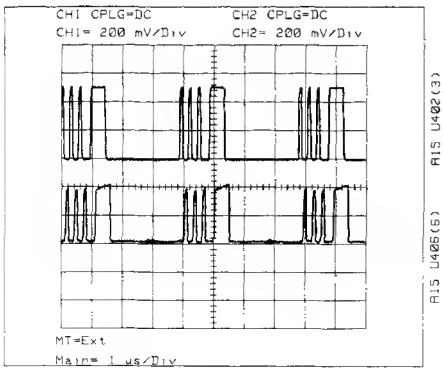
[N] DATA OUTPUT ISOLATION INTERFACE

To check this circuit, set the -hp-3561A controls as follows:

PRESET		
RANGE	DEFINE RANGE	.0 dBV
MODE	TEST SELECT	DEFINE TEST NUM . . . . . .112 ENTER
		START SNGL TST

In this test, the timing and control circuit outputs a test pattern as shown in Figure 7-9.

Figure 7-9 Test pattern Output in Test 112



Probe: 10:1

Ch1: Connection- A15U402(3)
Coupling- dc
Ground- Fourth Graticule From Top

Ch2: Connection- A15U406(6)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: External- A15TP"DRQ"
Slope- Positive

Bandwidth Limit: ON

BREAKING THE SECOND PASS FEEDBACK LOOP

Test 113 is provided to isolate failures to either the first pass circuit or the second pass circuit. To initiate this test, set the -hp-3561A controls as follows:

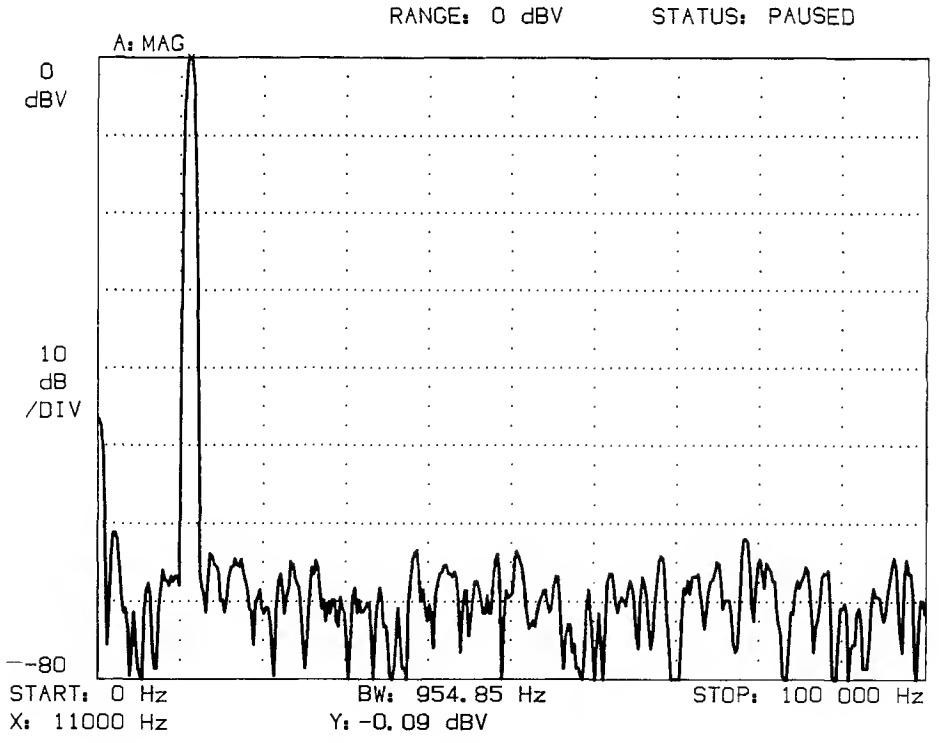
PRESET		
FORMAT	SINGLE	
RANGE	DEFINE RANGE	0 dBV
MODE	TEST SELECT.....	DEFINE TEST NUM.....113 ENTER
		START SNGL TST

When the "TEST #113 IS COMPLETE" message is displayed, press the MODE key. In this test, data is not passed through the second pass ADC input circuit, thus, if a failure appears, it is most likely in the 8 bit ADC, or the timing and control circuit. Use the frequency synthesizer and a BNC to SMB adapter cable to input an 11 kHz, .228 Vrms sine wave into A15J1. Terminate the frequency synthesizer in 50 Ω. Check the -hp-3561A display for a full scale sine wave as shown in Figure 7-10.

NOTE

Because the second pass circuit is not operating, noise and harmonics will be 50 to 70 dB below the amplitude of the 11 kHz fundamental. The test is failing if either the noise or harmonics are less than 50 dB below the fundamental.

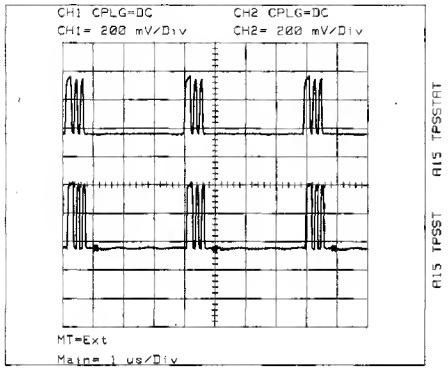
Figure 7-10 -hp-3561A Display in Test 113



[R] Status Latch, [T] Status Isolation Interface

To check these circuits, press the -hp-3561A PRESET key, disconnect the input signal, and verify the waveforms shown in Figure 7-11.

Figure 7-11 A15 Status Output



Probe: 10:1

Ch1: Connection: A15TP"SST"
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection: A15TP"SSTAT"
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: External- A15TP"DRQ"
Slope- Positive

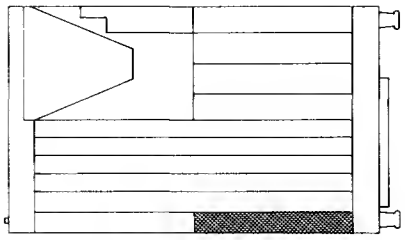
Table 7-9 A15 Assembly Signal Connections

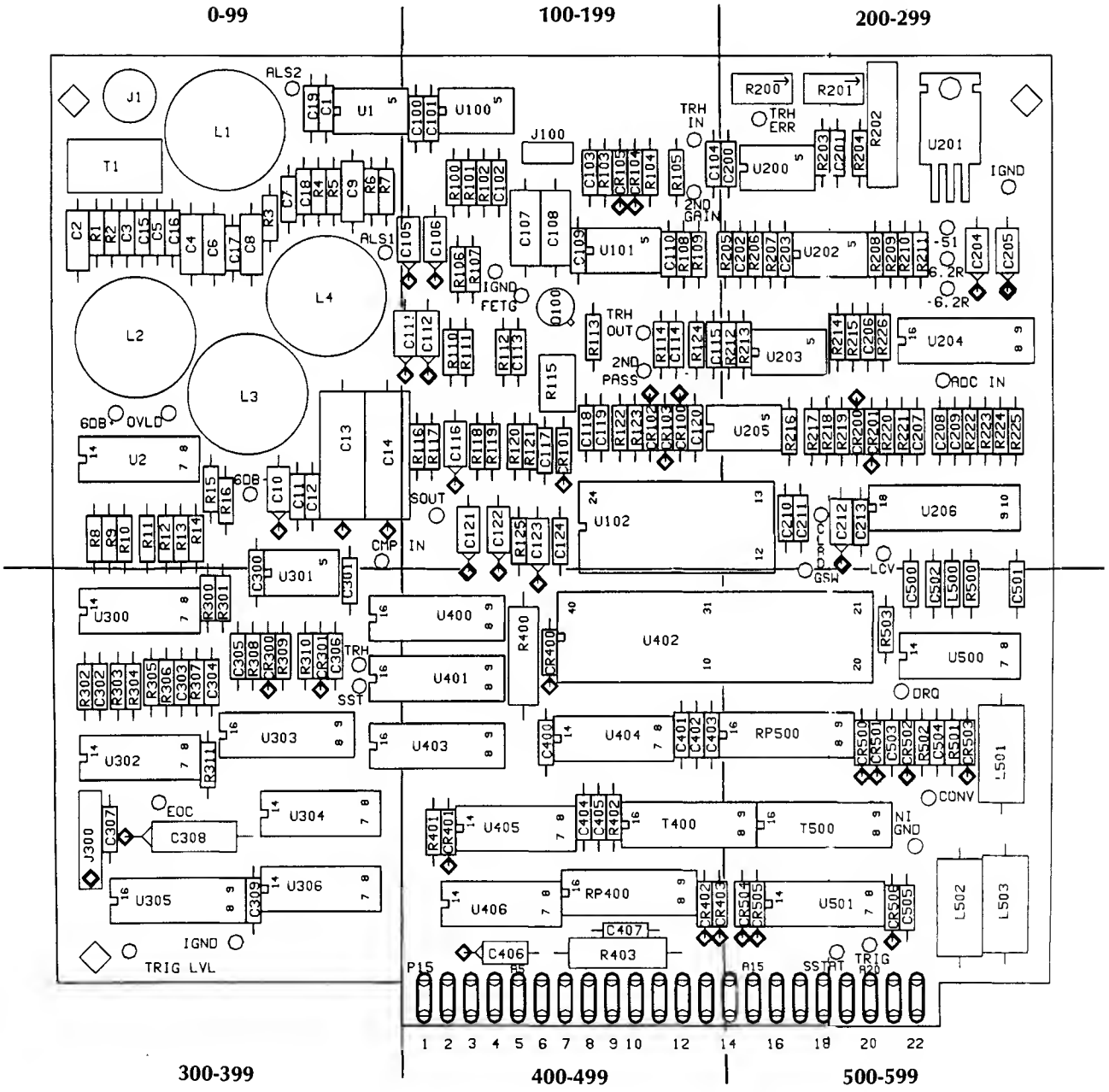
INPUTS

Signal Name	Functional Block	Connector Number	Origin Assembly
COMP	Q	P15(B1)	A10
CONVERT	F	P15(B16)	A20
DATA REQ	F	P15(B14)	A20
FECLOCK	I	P15(A2)	A10
FEDATA	I	P15(A1)	A10
FELATCH	I	P15(A3)	A10
ISM	L	P15(A6)	A20
SIGNAL INPUT	A	J1	A10
TRIGLVL	S	P15(B2)	A10
10 MHz	F	P15(A15)	A20
20 MHz	F	P15(B15)	A40

OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assemblies
SSTAT	T	P15(A14)	A20
FETRIG	U	P15(A13)	A20
A/D DATA	N	P15(B13)	A20

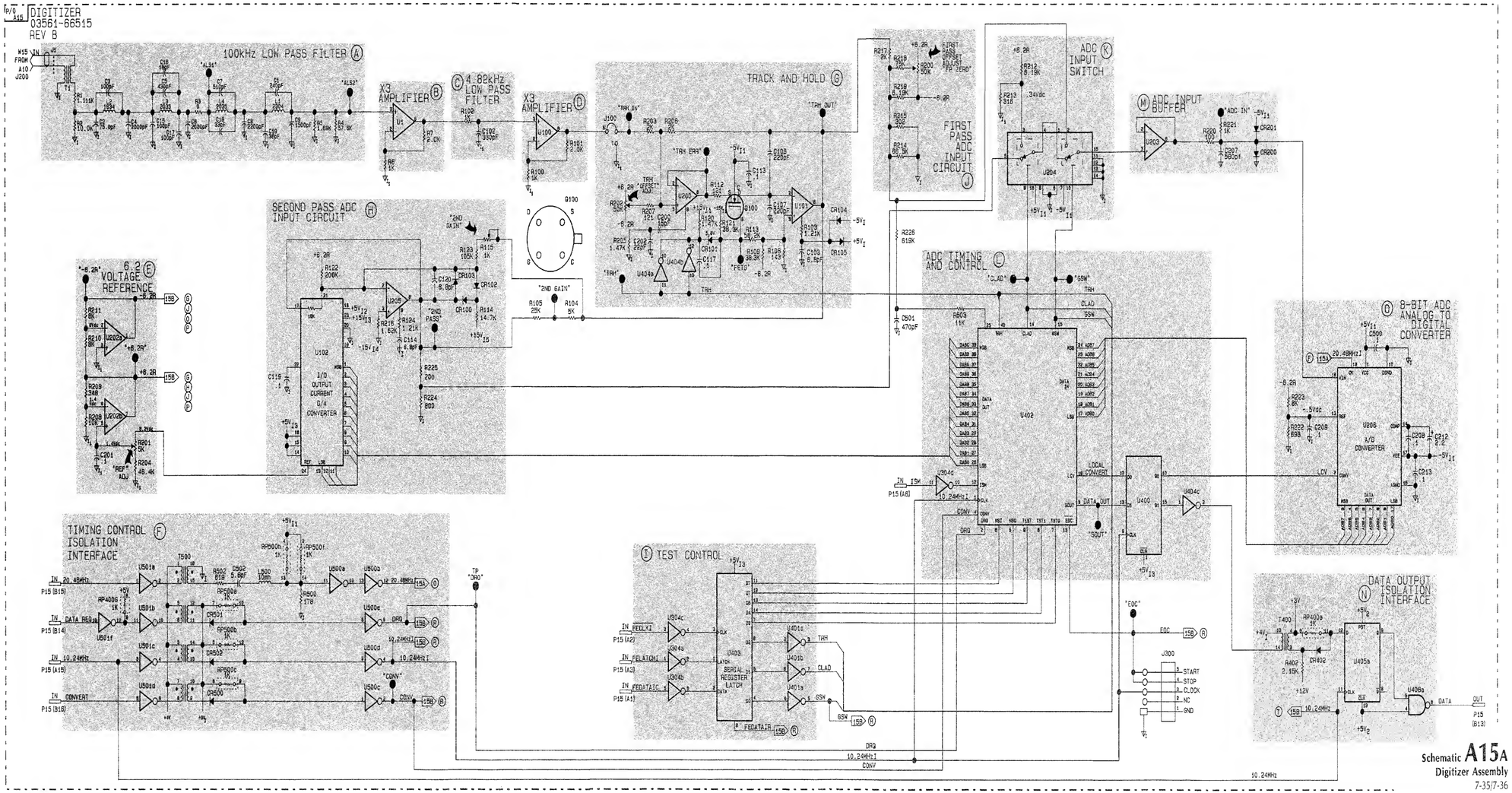



0-99
100-199
200-299
300-399
400-499
500-599
J1
L1
T1
L2
L3
L4
ALS2
ALS1
U1
U100
J100
U200
U201
U202
U203
U204
U205
U206
U101
U102
R200
R201
R202
TRH IN
TRH ERR
IGND
FETG
D100
TRH OUT
2ND PASS
ADC IN
6DB
OVLD
U2
SOUT
U301
U300
U400
U401
U402
U403
U404
U500
U302
U303
U304
U305
U306
RP500
RP400
U405
U406
U501
T400
T500
R400
R403
C407
C406
EOC
C308
CONV
DRQ
TRIG LVL
P15
1 2 3 4 5 6 7 8 9 10 12 14 16 18 20 22

A15 Assembly

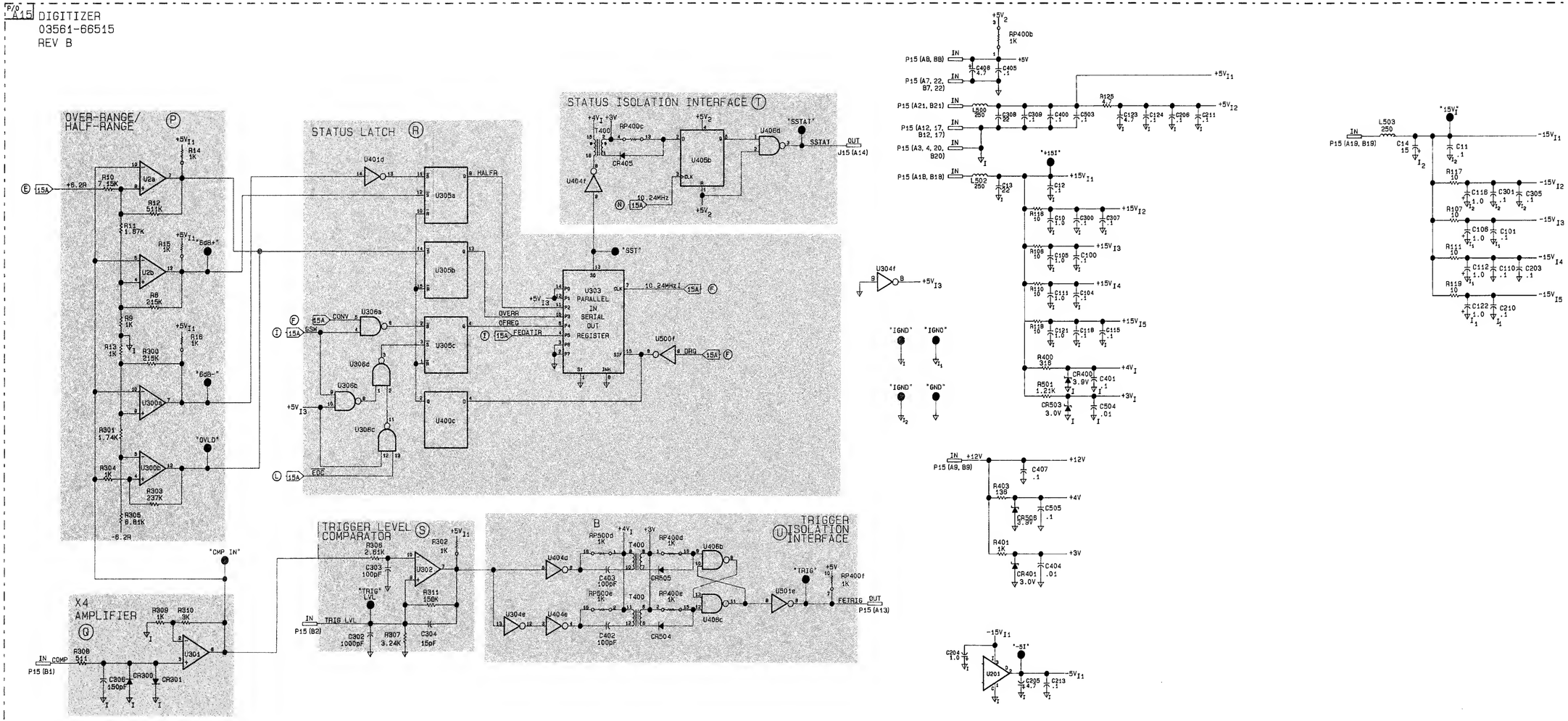
	+15V$_{I2}$	+15V$_{I3}$	+15V$_{I4}$	+15V$_{I5}$	-15V$_{I2}$	-15V$_{I3}$	-15V$_{I4}$	-15V$_{I5}$	+5V$_{I}$	+5V$_{I2}$	-5V$_{I}$	GNDI
U1		7				4						
U2	11				6							
U100		7				4						
U101	7						4					
U102				23				19			18	
U200			7				4					
U201												
U202				8				4				
U203				7				4				
U204										7	16	
U205				7				4				
U206									1	17		
U300	11				6							
U301	7				4							
U302	11				6							
U303									16			8
U304									14			7
U305									16			8
U306									14			7
U400									16			8
U401									16			8
U402									30			10
U403									16			8
U404									14			7
U500									14			7

	+5	GND
U405	14	7
U406	14	7
U501	14	7



Schematic **A15A**
Digitizer Assembly
7-35/7-36

F/O A15 DIGITIZER
03561-66515
REV B



7-10 A20 DIGITAL FILTER ASSEMBLY

7-11 Digital Filter Circuit Description

GENERAL

The primary purpose of the digital filter is to provide anti-alias filtering when the -hp-3561A frequency span is less than 100 kHz. The digital filter receives input data from the A/D converter, it then processes the data and stores the results directly into the instrument RAM. Other circuits on the A20 Assembly include the timing and control counter, the A/D converter interface, and the direct memory access (DMA) counters which interface the digital filter with the instrument RAM.

DIGITAL FILTER CHANNEL DESCRIPTIONS

The digital filter can store output data into two independent 1024 data point buffers in RAM, channel R, and channel G. Addressing is accomplished through the channel R and channel G direct memory access (DMA) counters. Each channel is set to one of three data modes. The data mode for a channel defines what type of data is transferred from the digital filter into RAM on that channel. In mode one, the digital filter outputs "real part" data (filtered by U1 only); in mode two, the digital filter outputs "imaginary part" data (filtered by U401 only); and in mode three, the digital filter outputs unfiltered A/D data directly. More than one type of data can be stored in a channel at the same time (e.g., in zoom mode, 512 real part and 512 imaginary part data samples are stored in channel G). Table 7-10 lists the data mode settings for each -hp-3561A measurement mode.

[B] CHANNEL R DMA COUNTER, [D] CHANNEL R ADDRESS BUS LATCH

The output of this counter defines the address in RAM where channel R data is stored. The channel R bus grant signal latches the counter output onto the RAM address bus, and increments the counter by one. The channel R counter clocks through 1024 positions and then issues a DONER signal to indicate that the channel R buffer in RAM has been filled and is ready to be processed by the FFT processor.

[C] CHANNEL G DMA COUNTER, [E] CHANNEL G ADDRESS BUS LATCH [L] CHANNEL G COUNTER PRESET

The output of this counter defines the address in RAM where channel G data is stored. The channel G bus grant signal latches the counter output onto the RAM address bus and increments the counter by one. The channel G DMA counter clocks through up to 40,960 positions before a DONEG signal is issued. The exact number is programmed by the central processor through the channel G preset circuit.

[H] DMA CONTROL LATCH, [J] DMA CHANNEL CONTROL

Through this register, the central processor programs the data mode for channel R and channel G, the number of counts for the channel G DMA counter, the trigger state, and the digital filter test mode. On the falling edge of the DIS1-3 signals, the digital filter processes one time record (1024 data points).

[I] RAM BUS INTERFACE, [K] DMA CHANNEL SELECT

The digital filter issues a RAM bus request whenever it is ready to store a data point in RAM. The particular bus request issued depends on the data mode the digital filter is operating in. When the digital filter receives a bus grant from RAM, the DMA channel select circuit issues a bus grant to the selected DMA counter, which then transfers the data onto the RAM data bus.

[M] DIGITAL FILTER

The digital filter consists of three integrated circuits, U1, U4, and U401. The actual digital filtering occurs in U1 and U401, which are identical and interchangable. The digital filter control circuit, U4, is primarily an interface and data selector. The digital filter receives three data inputs: A/D DATA and the local oscillator inputs, COSINE, and -SINE. The local oscillator inputs which are only active during zoom operation are multiplied with the A/D DATA signal within the digital filter. The digital filter control circuit, based on the -hp-3561A front panel settings, selects the type of data (mode one, mode two or mode three) which is output to the RAM data bus. Table 7-10 lists which digital filter ICs are active in each -hp-3561A measurement mode.

Table 7-10 Digital Filter Operation

-hp-3561 Front Panel Setting	Digital Filter Circuits in Use	Channel G Data Mode	Channel R Data Mode
Baseband -Magnitude -Phase -Time	U4, U1	1	not used
Zoom -Magnitude -Phase -Time	U4, U1, U401	1	not used
Third Octave	U4, U1, U401	1	2
Full Octave	U4, U1, U401	1	2
Input Time	U4	not used	3
Input Magnitude	U4	not used	3

[O] A/D STATUS LATCH, [Q] DATA REQUEST/SYNC2 SIGNAL GENERATOR [U] DIGITAL FILTER INPUT DATA LATCH

These circuits comprise the A/D converter and local oscillator interface. To initiate an A/D data transfer, the digital filter issues a SHIFT1 signal which triggers a $\overline{\text{DATA REQ}}$ signal. On receipt of a $\overline{\text{DATA REQ}}$ signal, the A/D converter transfers one 13 bit data sample into the digital filter through the digital filter input data latch, and one 4 bit status word into the digital filter through the A/D status latch. If the A/D does not yet have a new data sample, it will transfer invalid data. The digital filter reads the first bit of the A/D data to determine if the data is valid. If the data is invalid, the digital filter will continue to request data at a 512 kHz rate. When valid data is received, the digital filter will continue to request new data samples at a 256 kHz rate.

For each valid A/D data sample received, the digital filter issues a SYNC2 signal, which is a data request to the local oscillator. On receipt of a SYNC2 signal, the local oscillator transfers one 16 bit COSINE value and one 16 bit -SINE value to the digital filter.

[P] CONVERT SIGNAL TIMING, [T] CONVERT SIGNAL SELECT

The CONVERT signal establishes the sampling rate of the -hp-3561A. On receipt of a CONVERT signal, the A/D converter samples the input data and initiates an A/D conversion. In internal sample mode, the $\overline{\text{DATA REQ}}$ signal is selected to trigger a CONVERT pulse and in external sample mode, the rear panel "EXT SAMP" input is selected to trigger a CONVERT pulse.

[Y] TIMING AND CONTROL COUNTER, [X] COUNTER CLOCK SELECT [V] TRIGGER TIMING, [W] PHASE COUNTER CLOCK

All of these circuits provide inputs to the multi-function counter, U202. The multi-function counter contains six counters which can each be programmed to use any one of the four clock inputs. The central processor programs the multi-function counter to determine the timing relationship between the various activities within the -hp-3561A. It then uses this information to calculate phase corrections for the input signal.

[CC] CAL SIGNAL/TRIGGER CONTROL [EE] TRIGGER SELECT, [DD] CAL SIGNAL SELECT

Through these circuits, the central processor programs the correct trigger and calibration signal for the current front panel setting. The resulting trigger signal, NSTRIG, is syncronized to the internal 10.24 MHz clock in the trigger timing circuit, and used to trigger a measurement.

Table 7-11 A20 Assembly Signal Descriptions

Signal	Description
BGG	RAM Bus Grant channel G: Clocks the channel G DMA counter output onto the RAM address bus and increments the counter by one.
BGR	RAM Bus Grant channel R: Clocks the channel R DMA counter output onto the RAM address bus and increments the counter by one.
BREN	Bus Request ENable: Enables the channel G bus request signal to be input to the multi-function counter.
CAL GEN	CALibration signal GENerator: A square wave with a frequency programmed by the central processor (4 kHz when the front panel cal signal is selected).
CAL TRIG	CALibration signal TRIGger: Triggers a measurement at the start of the PRN cal signal.
CHGCNT	CHannel G CouNT: Used by the central processor to read the position of the channel G DMA counter over the RAM address bus.
$\overline{\text{CLRTRIG}}$	CLeaR TRIGger: Clears the current instrument trigger state.
CONVERT	A/D CONVERT: Initiates a data sample in the A/D converter and establishes the instrument sample rate.
$\overline{\text{CTRRS}}$	CounTeR Read Select: Used by the central processor to read data from the multi-function counter.
$\overline{\text{CTRWS}}$	CounTeR Write Select: Used by the central processor to write programming data to the multi-function counter.
$\overline{\text{DATA REQ}}$	A/D DATA REQuest: Causes the A/D converter to transfer its current data to the digital filter.
$\overline{\text{DF1BG}}$ $\overline{\text{DF2BG}}$ $\overline{\text{DF3BG}}$	Digital Filter 1-3 Bus Grant: RAM bus grant for data mode one, two, or three.
$\overline{\text{DF1BR}}$ $\overline{\text{DF2BR}}$ $\overline{\text{DF3BR}}$	Digital Filter 1-3 Bus Request: RAM bus request for data mode one, two, or three.
$\overline{\text{DFIS1}}$	Digital Filter Input Status: Used by the processor to address the digital filter status word.
$\overline{\text{DFOS1}}$ $\overline{\text{DFOS2}}$ $\overline{\text{DFOS3}}$	Digital Filter Data Strobe: Used by the processor to load data directly from the RAM data bus into the digital filter for processing (data mode one, two, or three).
DIS1 DIS2 DIS3	DISable data mode 1-3: Disables data mode one, two, or three in the digital filter.
DONEG	DONE with channel G count: Triggers a DMA interrupt to the central processor to indicate that the channel G RAM buffer is full.
DONER	DONE with channel R count: Triggers a DMA interrupt to the central processor to indicate that the channel R RAM buffer is full.
EXTSAMP	EXTernal SAMPle clock: Rear panel external sample input signal.
FECLK	Front End CLocK: Clocks the FEDATA signal into the front end control register on the A10 Assembly.

Table 7-11 A20 Assembly Signal Descriptions (Cont'd)

Signal	Description
FEDATA	Front End Data: Data to program the relays and other circuits on the A10 and A15 Assemblies.
$\overline{\text{FECS}}$	Front End Control Select: Clocks data into the front end control latch and the cal signal/trigger select circuits.
FELATCH	Front End LATCH: Latches the front end data into the front end control register on the A10 Assembly.
G0S, G1S	Channel G Data Mode Select: Data Mode G0S G1S Mode 1 0 0 Mode 2 0 1 Mode 3 1 0
HALFR	HALF Range: Input Signal is between 0 dB and 6 dB below the range setting.
OFREQ	Over FREQuency: External sample frequency is greater than 256 kHz.
OVERR	OVER Range: Input signal is greater than 2.8 dB above the range setting.
R0S, R1S	Channel R Data Mode Select: Data Mode R0S R1S Mode 1 0 0 Mode 2 0 1 Mode 3 1 0
$\overline{\text{SETTRIG}}$	SET TRIGger: Used by the processor to trigger a measurement when the -hp-3561A is set to internal trigger.
SSTAT	A/D Serial STATus: 4 bit serial data which indicates the status of the current A/D DATA signal. SSTAT is transferred to the digital filter when a $\overline{\text{DATA REQ}}$ signal is received by the A/D converter.
SYNC2	Issued by the digital filter to request data from the local oscillator.

7-12 Troubleshooting the A20 Assembly

GENERAL

Troubleshoot the circuits on the A20 Assembly in the order given in Table 7-12. In this table, level one circuits must be operational before level two circuits can be tested, and so on. Table 7-13 list some failure symptoms and the most likely cause of the failure. In addition, Table 7-14 lists all of the return codes for diagnostic self tests 13, 14, and 18. With the return code is given an error description and the most likely cause of the error. For the return code descriptions to be accurate, the diagnostic self tests should be run in numerical order.

Table 7-12 A20 Troubleshooting Order

Level	Functional Blocks
1	Clocks: FF GG
2	Processor Address Decoder: F
3	Processor Data Latch: S H N CC
4	Counter Clocks and Cal Signal Generator: V X AA
5	Timing and Control Counter: W Y Z DD EE
6	Digital Filter and Channel R DMA Counter: B D I K M
7	DMA Counters: C E G L
8	CONVERT Signal Timing: P Q T

Table 7-13 A20 Failure Symptoms

Symptom	Most Likely Cause of Failure
Instrument operates incorrectly in Input Time or Input Magnitude measurements only.	B Channel R DMA Counter
Instrument operates correctly in Input Time or Input Magnitude measurements only.	C Channel G DMA Counter Y Timing and Control Counter
Instrument operates incorrectly in zoom mode only.	U4 or U401

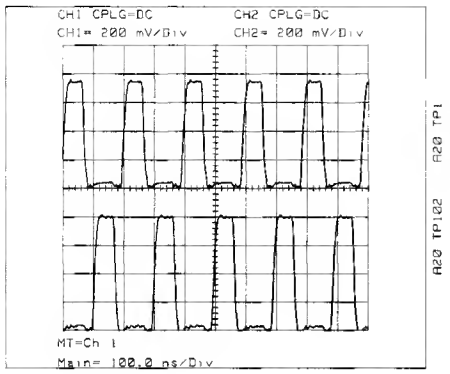
Table 7-14 A20 Diagnostic Test Return Code Descriptions

Return Code	Description	Most Likely Cause of Error
13 1 00 through 13 1 05	The processor is unable to program the timing and control counter.	U202 or U600, U300
13 6 00 through 13 6 02	The timing and control counter returns incorrect data.	U202 or X Counter Clock Select V Trigger Timing
14 2 00 through 14 2 02	The channel R DMA counter has not requested a data transfer in the allotted time.	B Channel R DMA Counter K DMA Channel Select I RAM Bus Interface or U1, U4, U401
14 2 03 through 14 2 10	The channel R DMA counter has not requested a data transfer in the allotted time.	U1 or U4: Odd numbered error code. U401 or U4: Even numbered error code.
14 5 00 through 14 5 10	The digital filter indicates a data overload.	U1 or U4: Odd numbered error code, or error code 00. U401 or U4: Even numbered error code.
14 6 00 through 14 6 02	Incorrect Data transferred to RAM.	B Channel R DMA Counter or U1, U4, U401
14 6 03 through 14 6 10	Incorrect Data transferred to RAM.	U1 or U4: Odd numbered error code. U401 or U4: Even numbered error code.
14 2 11 14 5 11 14 6 11	Data Incorrect or overload in zoom mode only.	U4
18 1 01 through 18 1 06	Timing and control counter error.	U202
18 3 01 through 18 3 07 Y	Incorrect Trigger.	J DMA Channel Control W Phase Counter Clock Timing and Control Counter
18 5 01	Digital filter indicates a data overload.	U1, U4, U401
18 9 01 through 18 9 04 or 18 6 01 18 6 02	Channel G DMA address error.	C Channel G DMA counter E Channel G Address Bus
18 8 00 through 18 8 15	Channel G DMA address error when using the channel G counter preset circuit.	E Channel G Address Bus L Channel G Counter Preset

[FF] CLOCK GENERATOR, [GG] LOW FREQUENCY CLOCK GENERATOR

Verify the clock waveforms with the waveforms given in Figure 7-12. The other clock signals can be checked against the frequencies listed on the schematic.

Figure 7-12 A20 Clock Waveforms



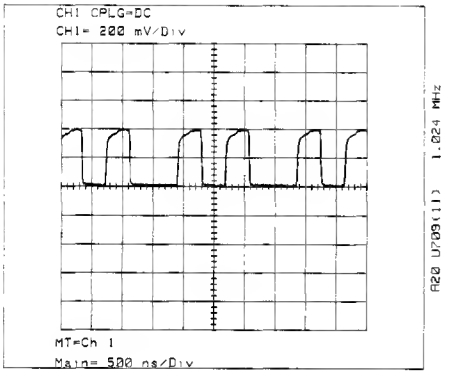
Probe: 10:1

Ch1: Connection- A20 TP1 "DFCLKφ2"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 TP102 "DFCLKφ1"
Coupling- dc
Ground- Bottom Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A20 U709(11) "1.024 MHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

[F] PROCESSOR I/O ADDRESS DECODING, [H] DMA CONTROL LATCH [N] DIGITAL FILTER DATA BUS LATCH, [S] FRONT END CONTROL LATCH [CC] CAL SIGNAL/TRIGGER CONTROL

1. Turn the -hp-3561A LINE power switch OFF.
2. Move jumper A40W1 on the A40 Assembly to the test position, and place the A20 Assembly on an extender board.
3. Turn the -hp-3561A LINE power switch ON.
4. When the "BLT TEST ROUTINE" message is displayed on the CRT screen, check the signatures given in Table 7-15.

NOTE

The A60 Assembly may be removed during this test to disable the beeper, however, this also disables the display so the "BLT TEST ROUTINE" message will not be displayed. The signatures will be valid when the front panel LEDs begin to blink.

Table 7-15 A20 Processor Interface Signatures

Signature Analyzer Setup

Signal	Polarity	Connection
Clock	⌐‾	A20J200(3) "$\overline{\text{RIOS}}$"
Start	⌐‾	A40J100(5)
Stop	⌐‾	A40J100(4)

+5 V Signature - H7PC

Processor I/O Address Decoding	
U106(6)	1590
U306(7)	400C
U306(9)	P86U
U306(10)	PHPP
U306(11)	571U
U306(12)	F4H9
U306(15)	8HFP
U307(7)	5250
U307(9)	4712
U307(12)	PH40
U307(13)	18CU
U307(14)	962P
U307(15)	C068

Front End Control Latch	
U510(2)	5A72
U510(5)	5C31
U510(6)	5C31
U510(9)	H6A8
U510(12)	H6A8
U510(15)	0143
U510(16)	+5 volts
U510(19)	8H99

Counter Data Bus Latch	
U600(11)	4746
U600(12)	7PHA
U600(13)	4746
U600(14)	PCFU
U600(15)	4746
U600(16)	H253
U600(17)	PCFU
U600(18)	PCFU

DMA Control Latch	
U501(2)	0 volts
U501(5)	0 volts
U501(6)	C829
U501(9)	C829
U501(12)	32F5
U501(15)	6UF2
U501(16)	0 volts
U501(19)	0 volts
U506(2)	6UF2
U506(5)	5H07
U506(6)	32F5
U506(9)	32F5
U506(12)	P52P
U506(15)	P52P
U506(16)	5H07
U506(19)	32F5

Cal Signal Trigger Control	
U509(2)	5C31
U509(3)	8FHA
U509(7)	8FHA
U509(10)	0143
U509(15)	H6A8

Table 7-15 A20 Processor Interface Signatures (Cont'd)

Signal Analyzer Setup:		
Signal	**Polarity**	**Connection**
Clock	⌐¯	A20J200(3) "$\overline{\text{RIOS}}$"
Start	⌐¯	A40J100(5)
Stop	¯⌐	A40J100(4)
+5 V Signature - H253		

Digital Filter Data Bus Latch			
U400(2)	0PFP	U402(2)	U78H
U400(3)	0P41	U402(3)	853F
U400(4)	4242	U402(4)	FHU5
U400(5)	8U1F	U402(5)	U91F
U400(6)	3A27	U402(6)	4UPA
U400(7)	UH59	U402(7)	64A5
U400(8)	PU57	U402(8)	H111
U400(9)	71AF	U402(9)	P6CA

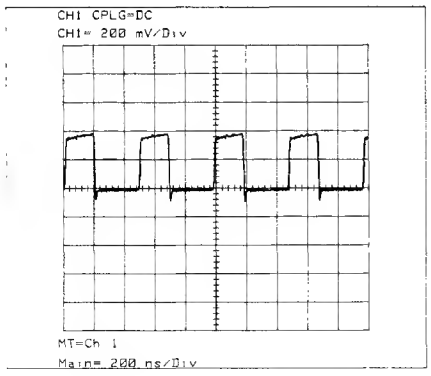
[V] TRIGGER TIMING, [X] COUNTER CLOCK SELECT, [AA] PRN CAL SIGNAL GENERATOR

1. Set the -hp-3561A controls as follows:

   PRESET
   TRIGger SELect . . . TRIGGER
   INTERNAL TRIGGER
   INPUT . . . . . CAL SIG ON

2. Check the waveforms as shown in Figure 7-13.

Figure 7-13 A20 Counter Clock Waveforms

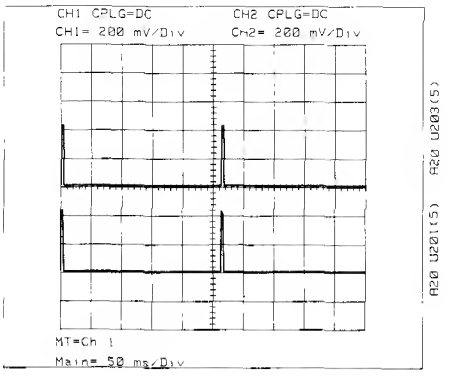


Probe: 10:1

Ch1: Connection- A20 U505(9) "U202 Clock"
A20 U300(3)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

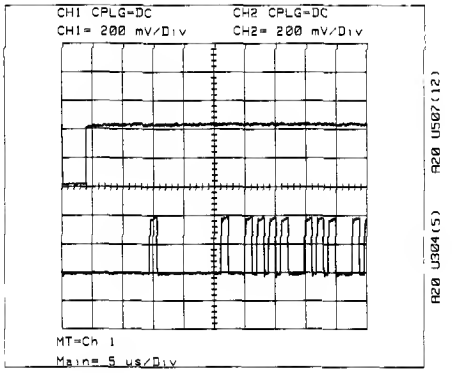
Ch1: Connection- A20 U203(S) "ITRIG"
Coupling- dc
Ground- Center Graticule

Ch1: Connection- A20 U201(5) "ITRIG"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

Note: the period of these signals alternates between 280 mSec, and 460 mSec.



Probe: 10:1

Ch1: Connection- A20 U507(12) "CAL
TRIG"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20U304(5) "PRN CAL"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: ON

[W] PHASE COUNTER CLOCK, [Y] TIMING AND CONTROL COUNTER, [Z] COUNTER DATA BUS LATCH, [DD] CAL SIGNAL SELECT, [EE] TRIGGER SELECT

1. Set the -hp-3561A Controls as follows:

   PRESET
   MODE ..... TEST SELECT.....DEFINE TEST NUM.....121 ENTER
   START CONT TST

2. Check the waveforms as shown in Figure 7-14.

3. If all of the waveforms given in Figure 7-14 are correct, set the -hp-3561A controls as shown below to run Test 13. If Test 13 fails with one or more return codes, the failure is most likely in U202, U300, or U600.

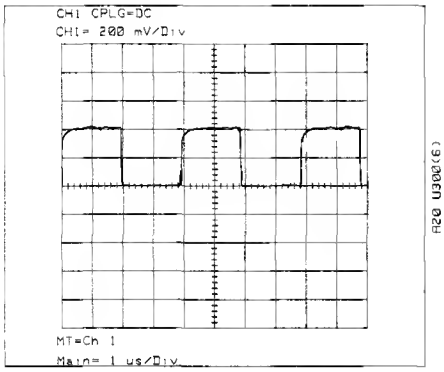
   PRESET
   MODE ..... TEST SELECT.....DEFINE TEST NUM.....13 ENTER
   START SNGL TST

4. If Test 13 passes with no return codes, set the -hp-3561A controls as follows:

   PRESET
   TRIGger SELect . . . TRIGGER
   INTERNAL TRIGGER
   INPUT . . . . . CAL SIG ON

5. Check the waveforms given in Figure 7-15.

Figure 7-14 Test 121 Counter Input Waveforms

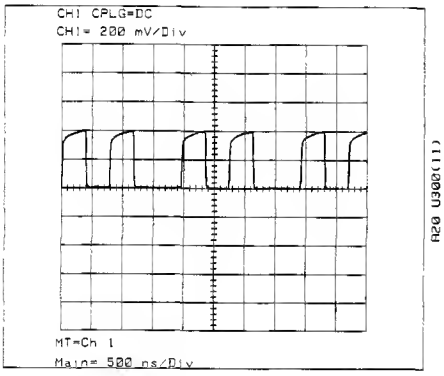


Probe: 10:1

Ch1: Connection- A20 U300(6) "PHASE CLK"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

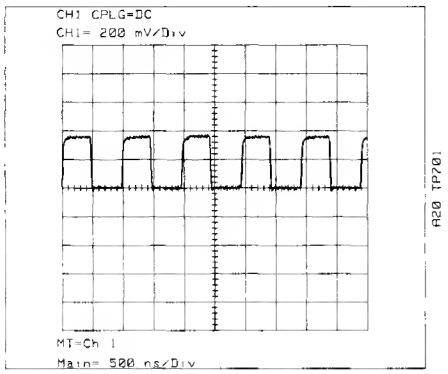
Ch1: Connection- A20 U300(11) "PHASE CLK"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Note: The waveform at U202(31) will be the "or" of these two signals gated on and off by the ITRIG signal. The signal at U202(31) can be checked by triggering on either U300(6) or U300(11).

Figure 7-15 A20 Counter Output Waveforms

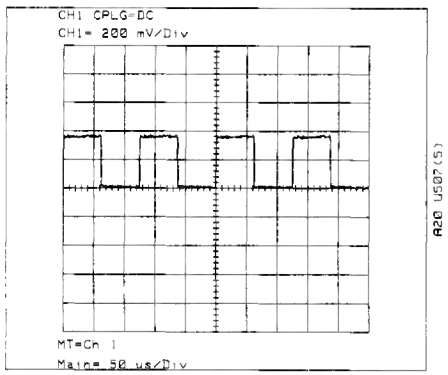


Probe: 10:1

Ch1: Connection- A20 TP701 "ESR*4"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A20 U507(5) "CAL GEN"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

[B] CHANNEL R DMA COUNTER, [D] CHANNEL R ADDRESS BUS LATCH [I] RAM BUS INTERFACE, [K] DMA CHANNEL SELECT, [M] DIGITAL FILTER

1. Set the -hp-3561A controls as follows:

   PRESET
   MODE ..... TEST SELECT.....DEFINE TEST NUM.....123 ENTER
   START CONT TST

2. Check the waveforms given in Figure 7-16. These waveforms depend on the proper operation of the RAM bus interface, the DMA channel select, and the digital filter control IC (U4).

3. When the waveforms given in Figure 7-16 are correct, check the waveforms given in Figure 7-17 and the signatures given Table 7-16 to troubleshoot the channel R DMA counters.

4. When the channel R DMA counter is operating correctly, Diagnostic Self Test #14 can be used to troubleshoot the real and imaginary digital filters. Set the -hp-3561A controls as follows:

   PRESET
   MODE ..... TEST SELECT.....DEFINE TEST NUM.....14 ENTER
   START CONT TST

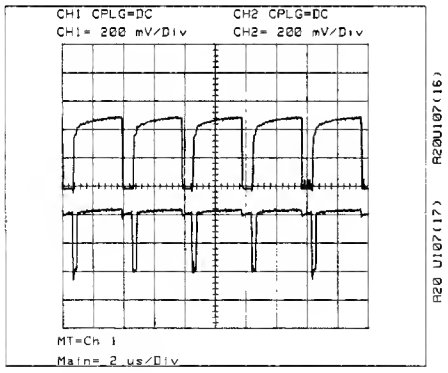
   If no return codes are displayed, the digital filters are operational. If only even numbered return codes are displayed, the failure is in U4 or U401. If only odd numbered return codes are displayed the failure is in U4 or U1. If both odd and even numbered return codes are displayed, the failure could be in any one of the three digital filter ICs. To isolate the failure, either U1 or U401 can be removed. When U401 is removed, only even numbered errors should occur, and when U1 is removed, only odd errors should occur. U1 and U401 are completely interchangeable and can be swapped to see if the failure follows the digital filter. If the error does not follow the digital filter, the failure is in U4.

5. To check the digital filter control IC (U4), set the -hp-3561A controls as follows:

   PRESET
   MODE ..... TEST SELECT.....DEFINE TEST NUM.....120 ENTER
   START CONT TST

6. Check the signatures given in Table 7-17.

Figure 7-16 Test 123 RAM Bus Interface Waveforms



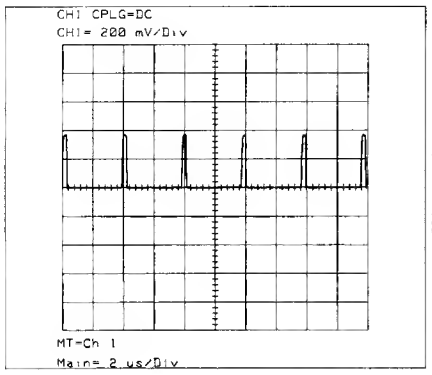
Probe: 10:1

Ch1: Connection- A20 U107(16) "DF2BR"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 U107(17) "DF2BG"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: ON



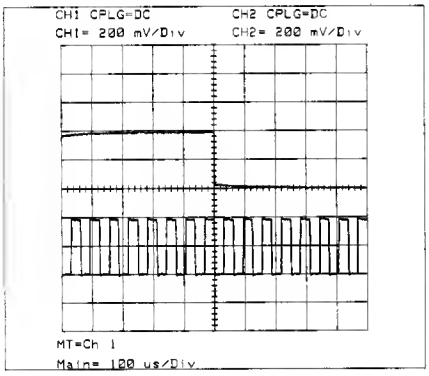
Probe: 10:1

Ch1: Connection- A20 U111(7) "BGR"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Figure 7-17 Test 123 Channel R DMA Counter Waveforms



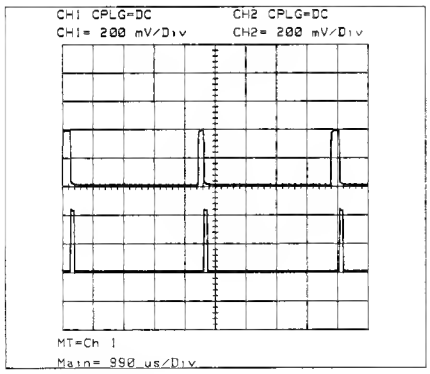
Probe: 10:1

Ch1: Connection- A20 U700(6)
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 U705(6)
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A20 U706(9) "DONER"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 U706(12) "ER"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Table 7-16 Test 123 Channel R Address Bus Latch Signatures

Signature Analyzer Setup

Signal	Polarity	Connection
Clock		A20U703(12) "$\overline{BGR}$"
Start		A20U706(9) "DONER"
Stop		A20U706(9) "DONER"

+5 V Signature - 472A

Channel R Address Bus Latch

U603(2)	3H19
U603(5)	14U7
U603(6)	0431
U603(9)	PPA9
U603(12)	P30H
U603(15)	8084
U603(16)	1H4H
U603(19)	6886
U607(2)	94A3
U607(5)	22FC

Table 7-17 Test 120 Digital Filter Signatures

Signature Analyzer Setup

Signal	Polarity	Connection
Clock	⌐	A20J100(3) "DFCLKϕ1"
Start	⌐	A20J100(4) "CLR"
Stop	⌙	A20J100(5) "DSASTOP"

Note: The stop and start connections are reversed from the labels printed on the PC board.

+5 V Signature - 695A

Digital Filter Interface Signals	
U4(3)	03U9
U4(19)	38HU
U4(20)	H914
U4(21)	54P2
U4(36)	0 volts
U4(49)	2208
U4(50)	8UP9
U4(51)	8UP9
U4(52)	2208
U4(59)	25P6
U4(60)	U614
U4(61)	F545
U4(62)	U9AA
U4(63)	H330

[C] CHANNEL G DMA COUNTER, [E] CHANNEL G ADDRESS BUS LATCH, [L] CHANNEL G COUNTER PRESET

1. Set the -hp-3561A controls as follows:

   PRESET
   MODE ..... TEST SELECT.....DEFINE TEST NUM.....122 ENTER
   START CONT TST

2. Check the waveforms given in Figure 7-18.

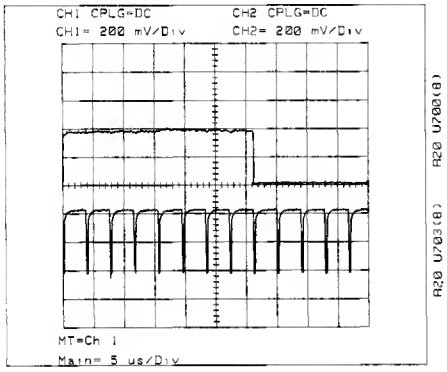
3. If all of the waveforms in Figure 7-18 are correct, check all of the signatures in Table 7-18.

4. Set the -hp-3561A controls as follows:

   PRESET
   TRIGger SELect . . . TRIGGER
   INTERNAL TRIGGER

5. Check the waveform given in Figure 7-19.

Figure 7-18 Test 122 Channel G DMA Counter Waveforms



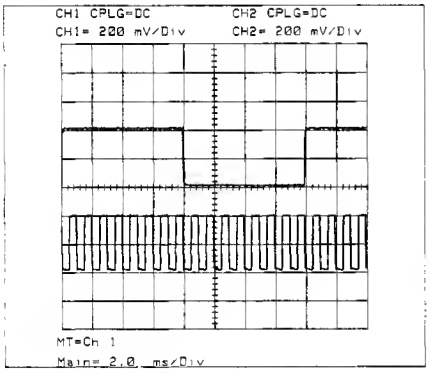
Probe: 10:1

Ch1: Connection- A20 U700(8) "G3"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 U703(8) "$\overline{BGG}$"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



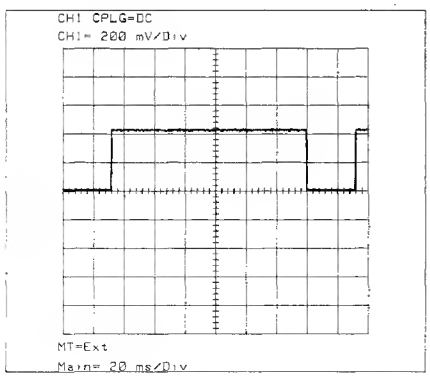
Probe: 10:1

Ch1: Connection- A20 U706(6) "GB"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 U705(8) "G7"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



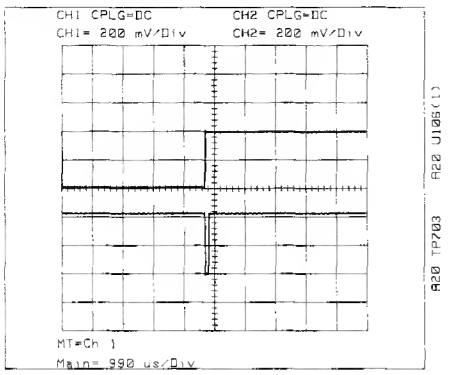
Probe: 10:1

Ch1: Connection- A20 U508(11) "GCNTF"
Coupling- dc
Ground- Center Graticule

Trigger: External- U700(12) "EG"
Slope- Positive

Bandwidth Limit: OFF

Figure 7-19 "DONEG" Waveforms



Probe: 10:1

Ch1: Connection- A20 U106(1)
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 TP703 "DONEG"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: ON

Table 7-18 Test 122 Channel G Address Bus Latch Signatures

Signature Analyzer Setup			
Signal	**Polarity**	**Connection**	
Clock	⌐¯\	A20U703(8) "$\overline{BGG}$"	
Start	⌐¯\	A20U508(11) "GCNTF"	
Stop	¯_	A20U508(11) "GCNTF"	
+5 V Signature - 755U			
Channel G Address Bus Latch			
U602(2)	H335	U606(2)	7707
U602(5)	C113	U606(5)	577A
U602(6)	7050	U606(6)	HH86
U602(9)	0772	U606(9)	89F1
U602(12)	A3C1	U606(12)	755U
U602(15)	7211	U606(15)	1180
U602(16)	AA08	U606(16)	PCF3
U602(19)	C4C3	U606(19)	AC99

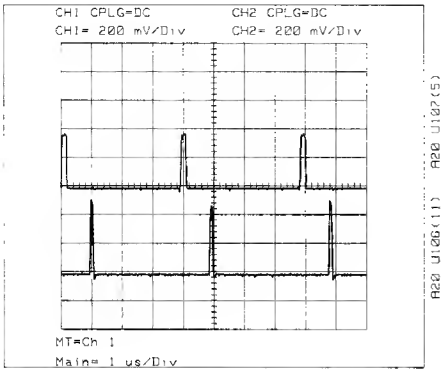
[Q] DATA REQ/SYNC2 GENERATOR, [T] CONVERT SIGNAL SELECT [P] CONVERT SIGNAL TIMING

1. Set the -hp-3561A controls as follows:

   PRESET
   MODE ..... TEST SELECT.....DEFINE TEST NUM.....122 ENTER
   START CONT TST

2. Check the waveforms given in Figure 7-20.

Figure 7-20 Convert/Sync2 Waveforms In Test 122



Probe: 10:1

Ch1: Connection- A20 U107(5) "CONVERT"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A20 U106(11) "SYNC2"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Table 7-19 A20 Assembly Signal Connections

INPUTS

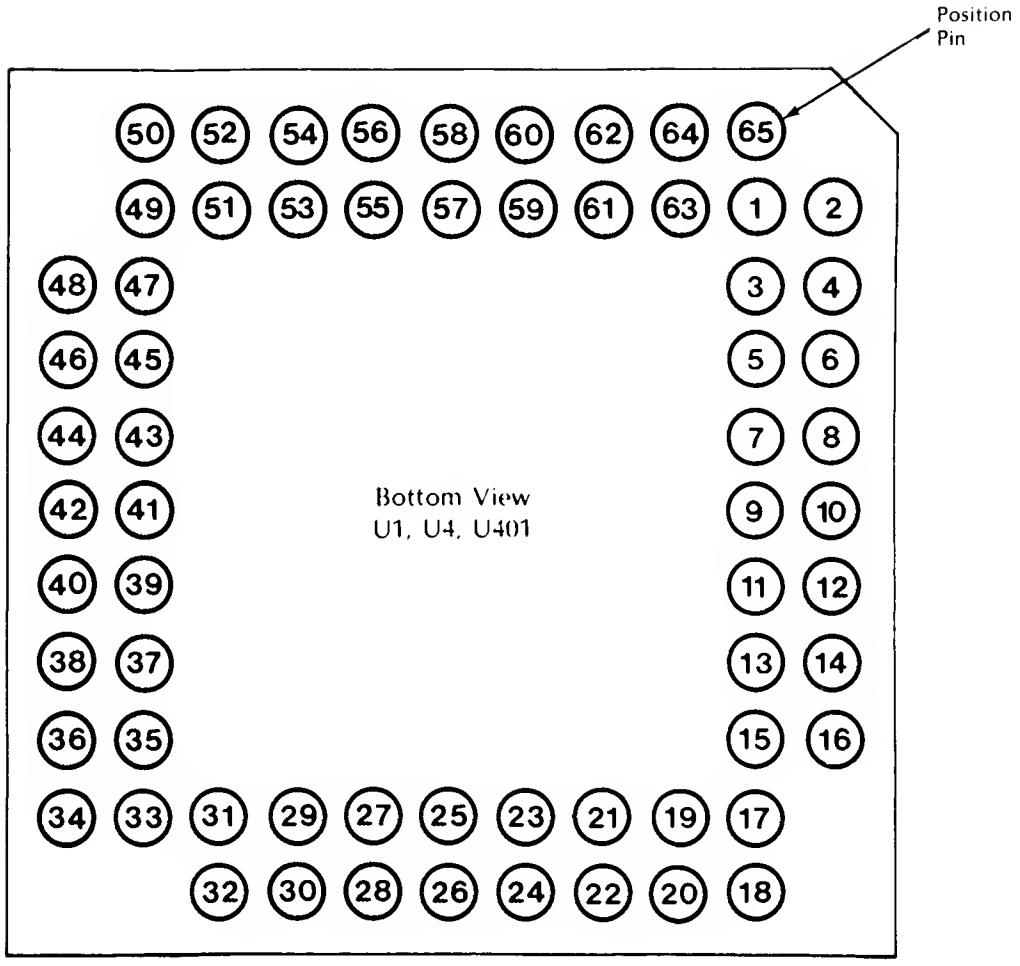
Signal Name	Functional Block	Connector Origin Number	Assembly
A/D DATA	U	P22(A2)	A15
COSINE	U	P21(A19)	A50
$\overline{\text{DF1BC}}$	I	P22(A11)	A30
$\overline{\text{DF2BC}}$	I	P22(A10)	A30
$\overline{\text{DF3BC}}$	I	P22(A9)	A30
EXT SAMP	T	P22(A7)	A82
$\overline{\text{FEISO}}$	BB	P21(A23)	S2 (front panel)
FETRIG	EE	P22(B5)	A15
RBR/$\overline{\text{W}}$	F	P21(A10)	A30
$\overline{\text{RESET}}$	H	P21(A21)	A40
$\overline{\text{RIOS}}$	F	P21(B10)	A30
-SINE	U	P21(B19)	A50
SSTAT	O	P22(B4)	A15
1/3TRIG	EE	P22(B7)	A50
20.48 MHz	FF	P21(B24)	A40

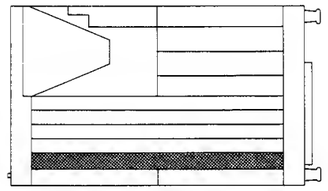
OUTPUTS

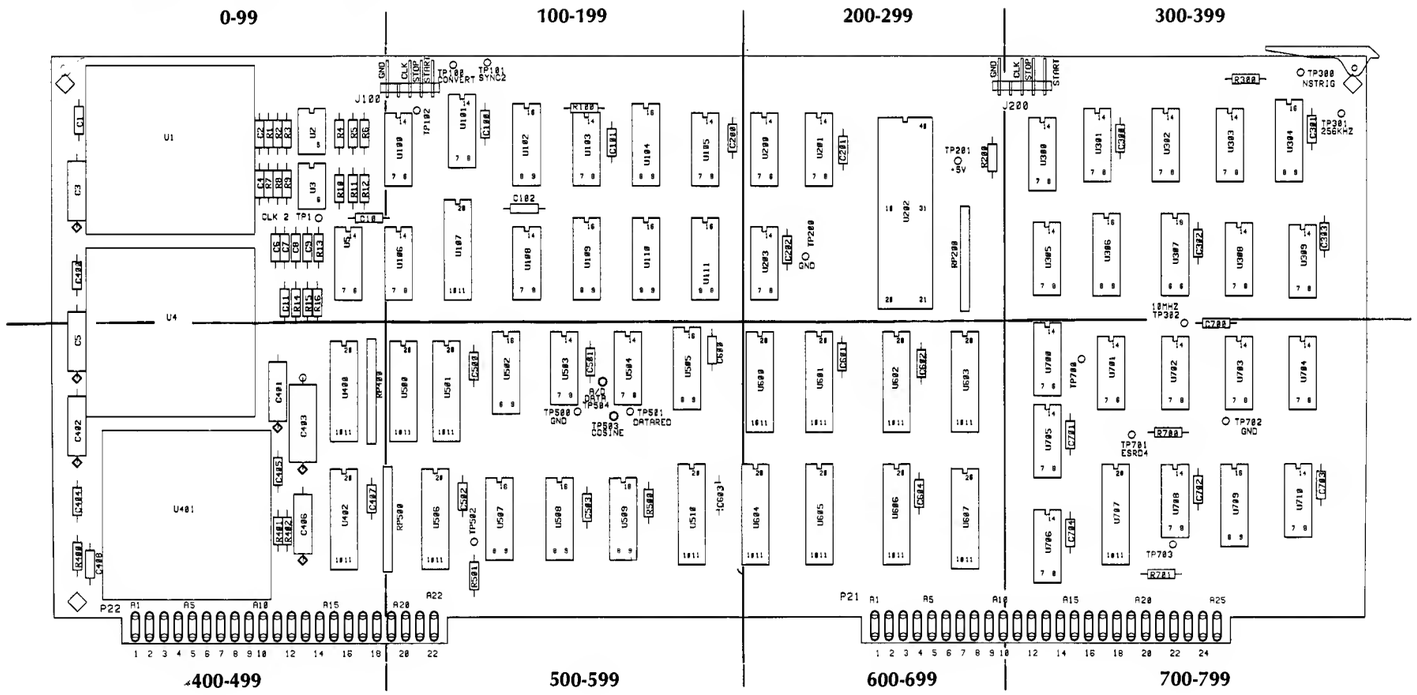
Signal Name	Functional Block	Connector Number	Destination Assemblies
CONVERT	P	P22(B2)	A15
DATA REQ	Q	P22(B3)	A15
DMAI	Y	P21(B16)	A40
DF1BR	I	P22(B11)	A30
DF2BR	I	P22(B10)	A30
DF3BR	I	P22(B9)	A30
ESR*4	Y	P21(A23)	A50
FE CAL	DD	P21(B12)	A10
FECLK	S	P21(B11)	A10
FEDATA	S	P21(A11)	A10
FELATCH	S	P21(A12)	A10
SYNC2	Q	P21(B18)	A50
ZPHTRIG	V	P21(A17)	A50
256 KHz	GG	P21(B23)	A70
10.24 MHz	FF	P21(A24)	A15, A50

I/O SIGNALS

Signal Name	Functional Block	Connector Number	Destination Assemblies
RAM Address Bus RAB0 - RABF	A	P21(A2 - A9) P21(B2 - B9)	A30, A40
RAM Data Bus RDB0 - RDBF	R	P22(A12 - A19) P22(B12 - B19)	A30

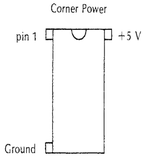

Position Pin
50 52 54 56 58 60 62 64 65
49 51 53 55 57 59 61 63 1 2
48 47 3 4
46 45 5 6
44 43 7 8
42 41 9 10
40 39 11 12
38 37 13 14
36 35 15 16
34 33 31 29 27 25 23 21 19 17
32 30 28 26 24 22 20 18
Bottom View
U1, U4, U401



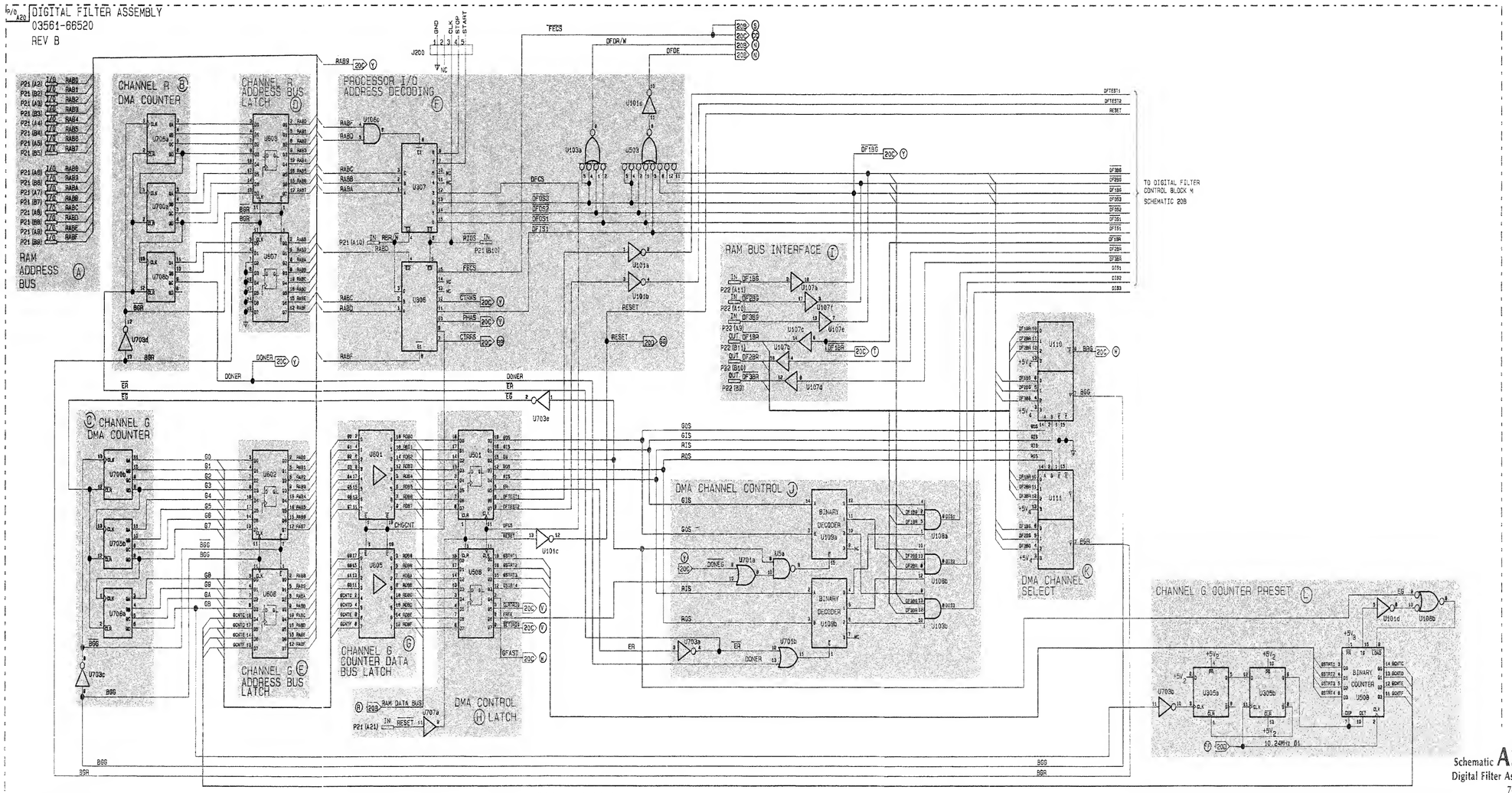

0-99
100-199
200-299
300-399
400-499
500-599
600-699
700-799
J100
J200
P22
P21
U1
U4
U481
C102
TP102
TP281
TP288
TP382
TP581
TP582
TP584
TP588
TP703
TP781
TP782
TP783
R288
R382
R788
R783
C382
C383
C782
C783
C788
C882
C883
C888
C982
C983
C988
C1082
C1083
C1088
C1182
C1183
C1188
C1282
C1283
C1288
C1382
C1383
C1388
C1482
C1483
C1488
C1582
C1583
C1588
C1682
C1683
C1688
C1782
C1783
C1788
C1882
C1883
C1888
C1982
C1983
C1988
C2082
C2083
C2088
C2182
C2183
C2188
C2282
C2283
C2288
C2382
C2383
C2388
C2482
C2483
C2488
C2582
C2583
C2588
C2682
C2683
C2688
C2782
C2783
C2788
C2882
C2883
C2888
C2982
C2983
C2988
C3082
C3083
C3088
C3182
C3183
C3188
C3282
C3283
C3288
C3382
C3383
C3388
C3482
C3483
C3488
C3582
C3583
C3588
C3682
C3683
C3688
C3782
C3783
C3788
C3882
C3883
C3888
C3982
C3983
C3988
C4082
C4083
C4088
C4182
C4183
C4188
C4282
C4283
C4288
C4382
C4383
C4388
C4482
C4483
C4488
C4582
C4583
C4588
C4682
C4683
C4688
C4782
C4783
C4788
C4882
C4883
C4888
C4982
C4983
C4988
C5082
C5083
C5088
C5182
C5183
C5188
C5282
C5283
C5288
C5382
C5383
C5388
C5482
C5483
C5488
C5582
C5583
C5588
C5682
C5683
C5688
C5782
C5783
C5788
C5882
C5883
C5888
C5982
C5983
C5988
C6082
C6083
C6088
C6182
C6183
C6188
C6282
C6283
C6288
C6382
C6383
C6388
C6482
C6483
C6488
C6582
C6583
C6588
C6682
C6683
C6688
C6782
C6783
C6788
C6882
C6883
C6888
C6982
C6983
C6988
C7082
C7083
C7088
C7182
C7183
C7188
C7282
C7283
C7288
C7382
C7383
C7388
C7482
C7483
C7488
C7582
C7583
C7588
C7682
C7683
C7688
C7782
C7783
C7788
C7882
C7883
C7888
C7982
C7983
C7988
C8082
C8083
C8088
C8182
C8183
C8188
C8282
C8283
C8288
C8382
C8383
C8388
C8482
C8483
C8488
C8582
C8583
C8588
C8682
C8683
C8688
C8782
C8783
C8788
C8882
C8883
C8888
C8982
C8983
C8988
C9082
C9083
C9088
C9182
C9183
C9188
C9282
C9283
C9288
C9382
C9383
C9388
C9482
C9483
C9488
C9582
C9583
C9588
C9682
C9683
C9688
C9782
C9783
C9788
C9882
C9883
C9888
C9982
C9983
C9988

A20 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)



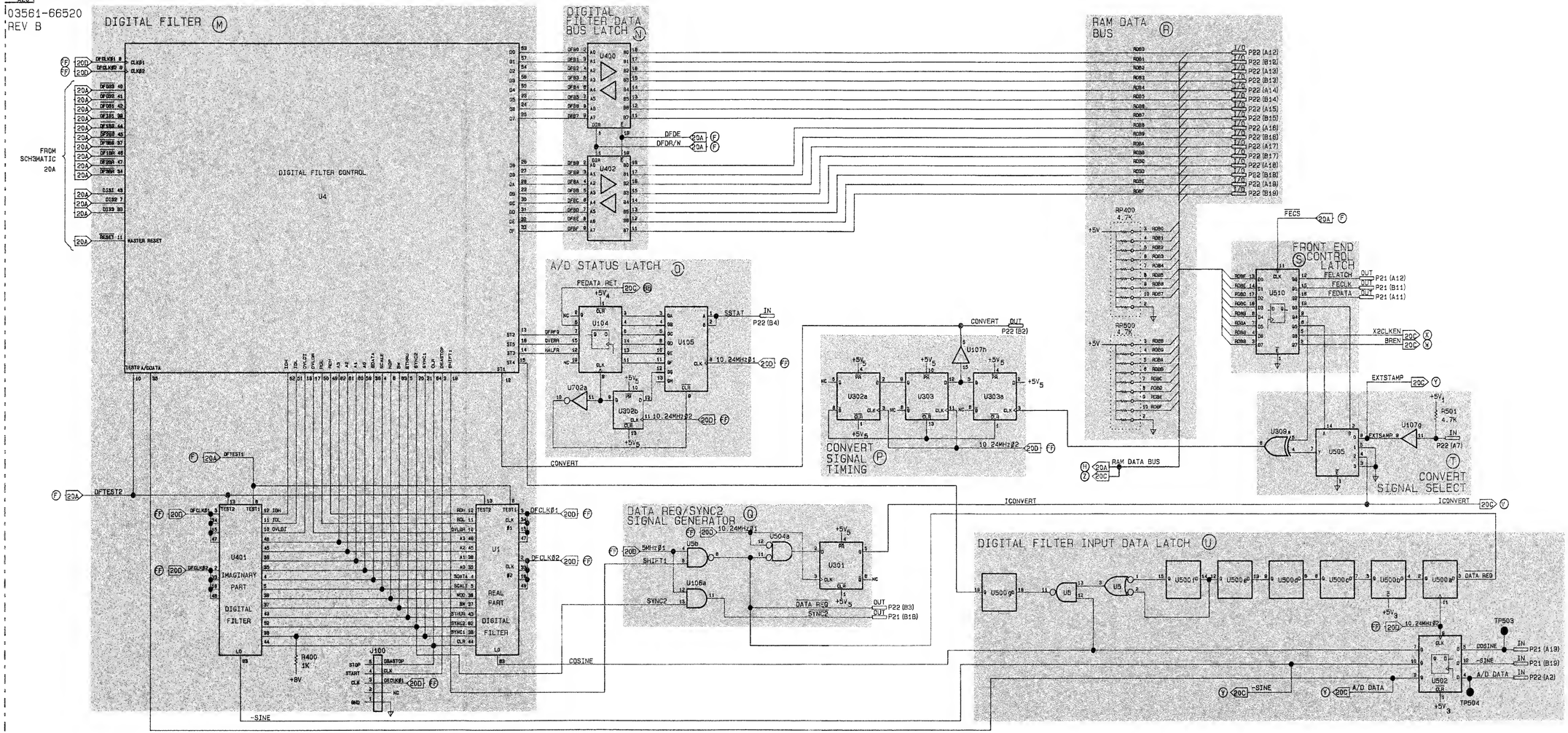
	+8V	+5V	-2V	GND
U1	7,9, 40,42	8,41	1	17,32, 49,64
U2	7			3
U3	7			3
U4	2,48	22	1	58
U202		1		21
U401	7,9, 40,42	8,41	1	17,32, 49,64



Schematic **A20A**
Digital Filter Assembly
7-63/7-64

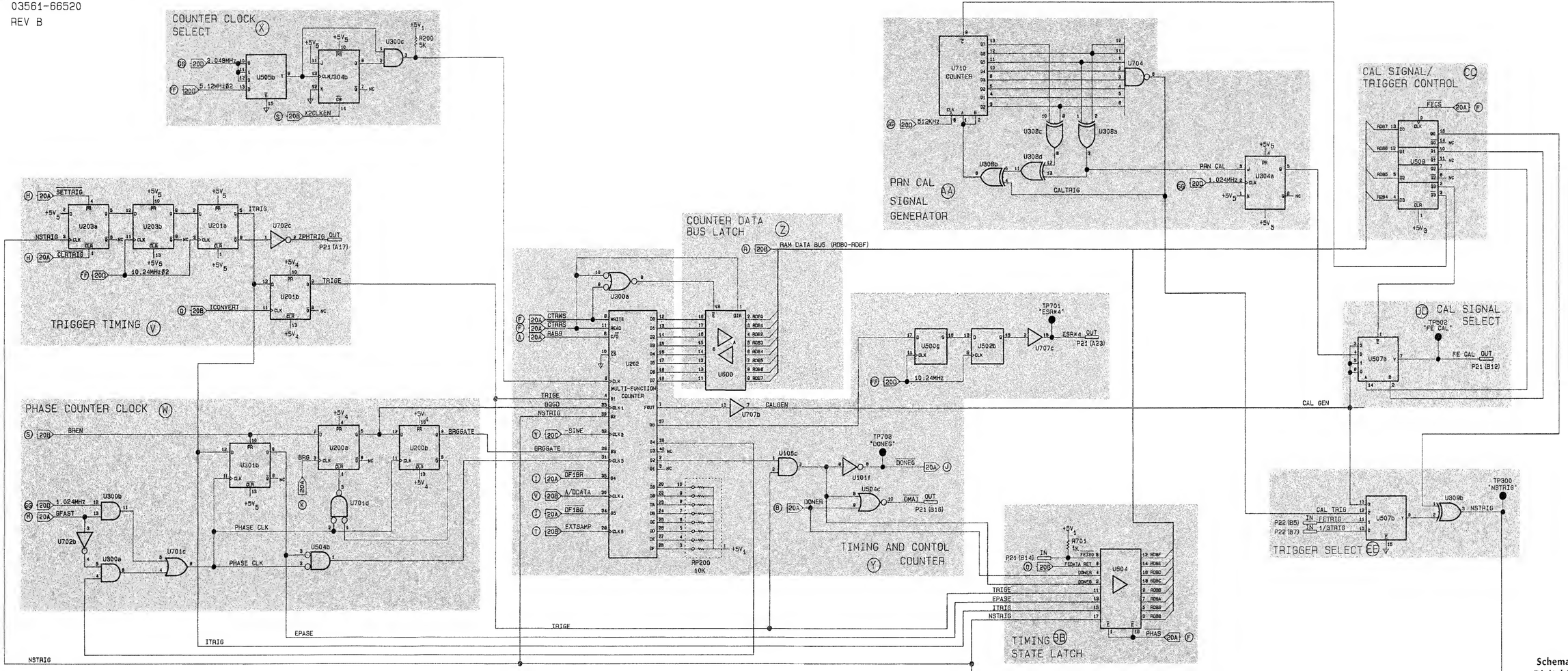
P/O A20 DIGITAL FILTER ASSEMBLY

03561-66520
REV B

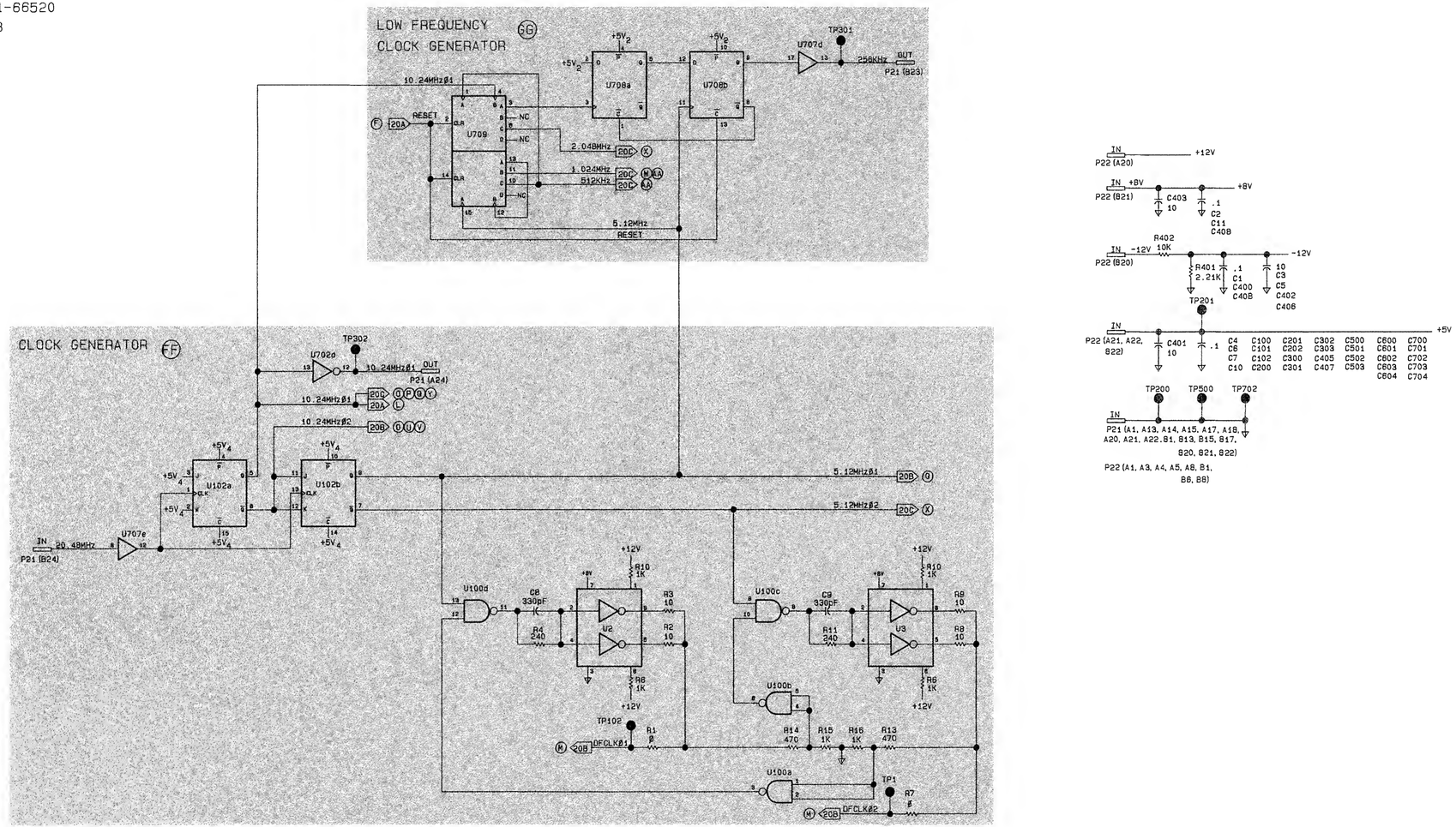


Schematic **A20B**
Digital Filter Assembly
7-65/7-66

P/O A20 DIGITAL FILTER ASSEMBLY
03561-66520
REV B



P/O A20 DIGITAL FILTER ASSEMBLY
03561-66520
REV B



7-13 A30 FFT/RAM ASSEMBLY

7-14 FFT/RAM Circuit Description

GENERAL

The A30 Assembly contains the instrument RAM and the FFT processor. The instrument RAM is accessed for data storage by three circuits: the central processor, the FFT processor, and the digital filter. Access to the RAM bus is regulated by the RAM bus arbitrator, which prevent these three circuits from interfering with one another.

The FFT processor is an asynchronous microprccessor dedicated to performing the Fast Fourier Transform. An FFT is initialized by the main processor through the $\overline{\text{FFT RESET}}$ signal.

RAM BUS STRUCTURE

The -hp-3561A has a two bus structure for transferring data between circuits. The processor bus is controlled by the central microprocessor on the A40 Assembly and the RAM bus is controlled by the RAM bus arbitrator on the A30 Assembly. The RAM bus consists of a 16 bit data bus and a 16 bit address bus. To access the RAM bus, a circuit must issue a bus request signal to the RAM bus arbitrator. The RAM bus arbitrator then issues a bus grant to the highest priority bus request. In addition to direct RAM access, the RAM bus is used by the central processor to transfer I/O data to the A20 and A30 Assemblies.

[D] MAIN RAM

The A30 Assembly contains sixteen 64k by 1 bit RAMs. The RAM is addressed in a two step process. First, an 8 bit row address is placed on the memory address bus, which is latched by the RAM on the rising edge of $\overline{\text{RAS}}$. Second, an 8 bit column address is placed on the memory address bus, which is latched by the RAM on the rising edge of $\overline{\text{CAS}}$. The RAM either reads data from, or writes data to the the memory data bus on the rising edge of $\overline{\text{CAS}}$.

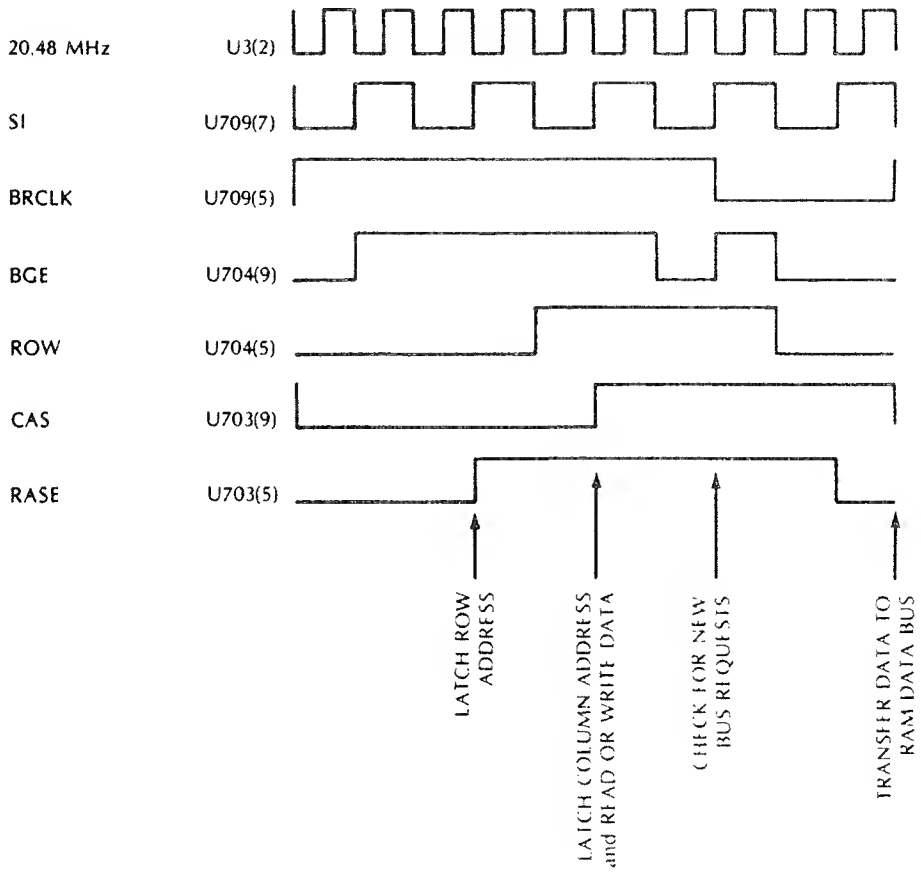
[B] RAM ADDRESS SELECTOR, [F] RAM COLUMN ADDRESS STROBE

When the ROW signal is low, the RAM address selector reads the row address from the lower 8 bits of the RAM address bus and when the ROW signal is high, the RAM address selector reads the column address from the upper 8 bits of the RAM address bus. The RAM column address strobe allows the processor to perform 8 bit or 16 bit operations by allowing access to just the lower 8 bits of RAM, just the upper 8 bits of RAM, or both.

[E] RAM ACCESS STATE MACHINE

This state machine generates all of the timing signals which control the RAM bus cycle. Figure 7-21 gives a timing diagram of the state machine outputs.

Figure 7-21 RAM Access State Machine Timing



[I] RAM BUS ARBITRATOR

The RAM bus arbitrator is a priority decoder which controls access to the RAM bus. When the RAM bus arbitrator receives a bus request signal, it compares the request against any other bus requests it has received. A bus grant signal is then issued to highest priority requester. The RAM bus arbitrator checks for new bus request signals once per RAM bus cycle on the rising edge of the BGE signal.

[G] 100 kHz REFRESH CLOCK, [J] RAM REFRESH COUNTER

The refresh clock issues a RAM bus request every ten micro seconds. If a bus grant is not received before the next ten micro second period, a higher priority bus request is issued. When a bus grant is received from the RAM bus arbitrator, the refresh counter addresses the memory location to be refreshed on the next RAM bus cycle.

[K] RAM READ/WRITE GENERATOR

This circuit determines what type of operation will occur on the next RAM bus cycle. When the $\overline{\text{PRIOS}}$ signal is high, a read from or write to RAM operation occurs and when the $\overline{\text{PRIOS}}$ signal is low, a processor I/O operation occurs.

[O] FFT PROCESSOR

When the FFT processor receives an $\overline{\text{FFT RESET}}$ signal from the main processor, it begins to execute the instructions stored in the FFT ROM. The FFT processor reads 1024 time data points from the RAM, performs an FFT on the data, and then writes the results back into RAM. When the complete 1024 point FFT is complete, the FFT processor issues an interrupt ($\overline{\text{FFTI}}$), which indicates to the central processor that the FFT is complete, and the results can be displayed on the CRT. The FFT processor runs on its own 20.00 MHz crystal oscillator.

[U] FFT/RAM INTERFACE

When the FFT processor wishes to access RAM, it issues a RAM bus request ($\overline{\text{FFTBR}}$) through the FFT/RAM interface. On receipt of a RAM bus grant, the FFT/RAM interface clears the bus request and latches the RAM address onto the RAM address bus. The FFT processor then uses the FFT/RAM interface to transfer data to or from the RAM.

Table 7-20 A30 Assembly Signal Descriptions

Signal	Description
BRCLK	Bus Request CLocK: Clocks the RAM bus request signals into the RAM bus arbitrator once per RAM bus cycle.
$\overline{\text{CASL}}$	Column Address Strobe Lower 8 bits (bits 0-7): On the rising edge of this signal, the lower 8 bit RAMs latch the column address from the address bus and data from the memory data bus.
$\overline{\text{CASU}}$	Column Address Strobe Upper 8 bits (bits 8-F): On the rising edge of this signal, the upper 8 bit RAMs latch the column address from the address bus and data from the memory data bus.
$\overline{\text{DBE}}$	Data Bus Enable: Enables data transfer between the RAM and the RAM data bus through the RAM data bus buffers.
$\overline{\text{DEN}}$	Data input ENable: Enables Data to be input to the FFT processor from the RAM data bus.
$\overline{\text{DF1BG}}$ $\overline{\text{DF2BG}}$ $\overline{\text{DF3BG}}$	Digital Filter Channel (1,2,3) Bus Grant: These signals go low give the digital filter access to the RAM bus for storing type one, two or three data.
$\overline{\text{DF1BR}}$ $\overline{\text{DF2BR}}$ $\overline{\text{DF3BR}}$	Digital Filter Channel (1,2,3) Bus Request: Issued by the digital filter to request access to the RAM bus.
FAB0-FABB	FFT Address Bus (12 bit): Used by the FFT processor to address the FFT instruction ROM.
FDB0-FDBF	FFT Data Bus (16 bit): Transfers data from ROM to the FFT processor and transfers data between the FFT processor and RAM.
$\overline{\text{FFTBG}}$	FFT Bus Grant: Grants the FFT processor access to the RAM bus.
$\overline{\text{FFTBR}}$	FFT Bus Request: Issued by the FFT processor to request access to the RAM bus. Highest priority request.
$\overline{\text{FFTCONS}}$	FFT CONtrol Select: Clocks FFT control data into the FFT/Processor Interface Register.
$\overline{\text{FFTI}}$	FFT Interrupt: Signals the central processor that the FFT processor has completed an FFT on a time record.
$\overline{\text{FFTINTCLR}}$	FFT INTerrupt CLeaR: Issued by the processor to clear the FFT interrupt.
$\overline{\text{FFT RESET}}$	FFT RESET: Issued by the central processor to reset the FFT processor and initialize an FFT on a new time record.
$\overline{\text{MEN}}$	Memory ENable: Issued by the FFT processor to address the FFT ROM.
NODBE	NO Data Bus Enable: Inhibits a data bus enable when the processor is tranferring I/O data over the RAM bus rather than directly accessing the RAM.
NOCAS	NO Column Address Strobe: Inhibits a column address strobe during RAM refresh.

Table 7-20 A30 Assembly Signal Descriptions (Cont'd)

Signal	Description
$\overline{\text{PBG}}$	Processor Bus Grant: This signal goes low to give the processor access to the RAM bus on the next RAM bus cycle.
$\overline{\text{PBLDS}}$	Processor Bus Lower Data Strobe: Low when the processor is addressing the the lower 8 bits of RAM.
$\overline{\text{PBR}}$	Processor Bus Request: Issued by the processor to request access to the RAM bus.
$\overline{\text{PRAMRE}}$	Processor RAM REad: Low to enable data from the RAM data bus onto the processor data bus in a RAM read or I/O port read operation.
$\overline{\text{PRIOS}}$	Processor Ram I/O Select: High when the processor is accessing RAM, low when the processor is accessing an I/O port through the RAM bus.
$\overline{\text{PBUDS}}$	Processor Bus Upper Data Strobe: Low when the processor is addressing the upper 8 bits of RAM.
$\overline{\text{RAS}}$	Row Address Strobe: On the rising edge of $\overline{\text{RAS}}$ the RAM latches the row address.
$\overline{\text{REFEN}}$	REFresh ENable: Gives the refresh counter access to the RAM bus. The refresh counter address increments by one each time a $\overline{\text{REFEN}}$ is received.
REFSEL	REFresh SELect: Low to disable the refresh request issued by the 100 kHz refresh clock.
ROW	ROW: High to indicate that the column address is on the memory address bus and low to indicate that the row address is on the memory address bus.
$\overline{\text{WE}}$	Write Enable: Issued by the FFT processor when it writes to RAM.

6-15 Troubleshooting the A30 Assembly

GENERAL

Failures in the RAM will generally be flagged by the power on test. Failures in the FFT will generally result in no data or bad data being displayed on the CRT also causing the power on test to fail. Because the FFT processor has the highest priority access to the RAM, some FFT failures will prevent the central processor from accessing RAM, and thus appear as a RAM failure.

Troubleshoot the circuits on the A30 Assembly in the order given in Table 7-21. In this table, level one circuits must be operational before level two circuits can be tested, which must be operational before level three circuits can be tested and so on.

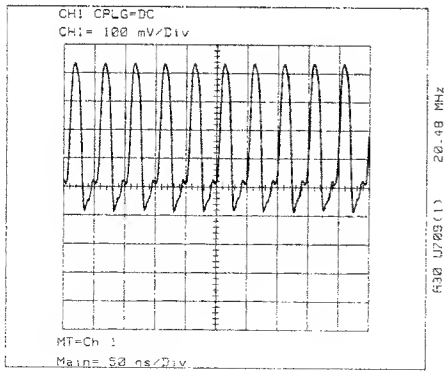
Table 7-21 A30 Circuit Troubleshooting Order

Level	Functional Blocks
1	Ram Access State Machine: E, C 100 kHz Refresh Clock: G
2	RAM Column Address Strobe: F RAM Bus Arbitrator: H, I, K
3	RAM Refresh Counter: J
4	Processor Interface: L, R, U
5	RAM: D RAM Address Bus: B RAM Data Bus: A
6	FFT Processor: M, N, O, P, S, T, V

[E] RAM ACCESS STATE MACHINE

Due to the feedback in the RAM access state machine, a failure on one signal will cause all of the signals to be incorrect. The correct output waveforms are given in Figure 7-22. Check the 20.48 MHz clock and the $\overline{SI}$ signal first. $\overline{SI}$ depends only on the clock. If these signals are correct, check the remaining signals. If these remaining signals are incorrect, replace U709, U704, U703, U702, U311, and U305 one at a time until the waveforms are correct. Recheck the waveforms after each IC is replaced.

Figure 7-22 RAM State Machine Waveforms

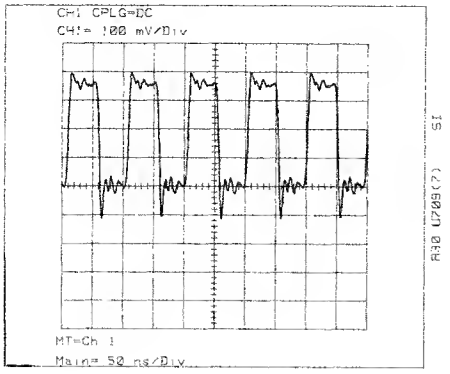


Probe: 10:1

Ch1: Connection- A30U709(1) "20.48 MHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

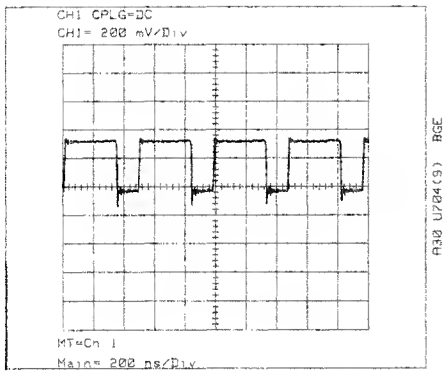


Probe: 10:1

Ch1: Connection- A30U709(7) "$\overline{SI}$"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

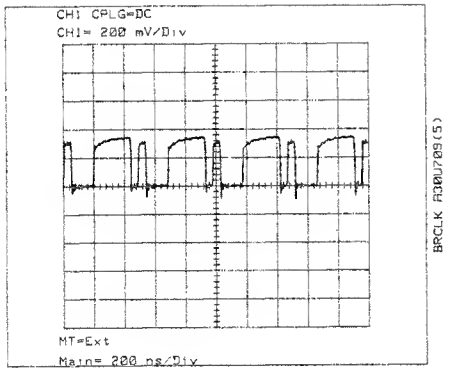


Probe: 10:1

Ch1: Connection- A30U704(9) "BGE"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

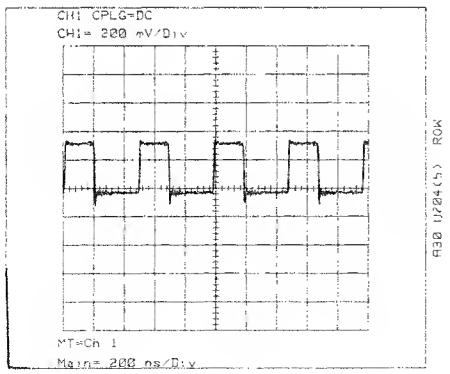


Probe: 10:1 and Trigger

Ch1: Connection- A30U709(5) "BRCLK"
Coupling- dc
Ground- Center Graticule

Trigger- External: A30U704(9) "BGE"
Slope- Negative

Bandwidth Limit: OFF

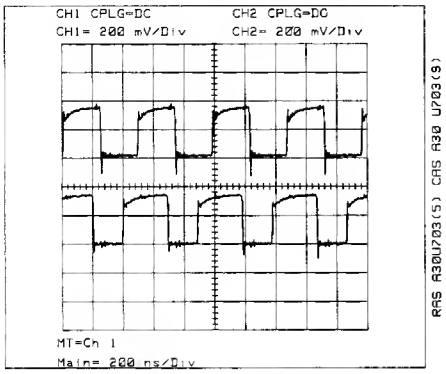


Probe: 10:1

Ch1: Connection- A30U704(5) "ROW"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A30U703(9) "$\overline{\text{CAS}}$"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A30U703(5) "$\overline{\text{RAS}}$"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

[H] RAM BUS ARBITRATOR, [I] BUS GRANT TIMING, [G] 100 kHz REFRESH CLOCK

1. Turn the -hp-3561A LINE power switch OFF.
2. Remove the A20 Assembly and use a clip lead to short the the two pins of A30W100 together.
3. Move test jumper A40W1 to the test position.
4. Turn the -hp-3561A LINE power switch ON.
5. When the "BLT TEST ROUTINE" message is displayed, verify that U707(3, 4, 7, 8, 13) are all at a TTL high state. If these signals are all correct, check the waveforms given in Figure 7-23. These waveforms trace the Processor bus request signal and the refresh enable signal through the RAM bus arbitrator.

NOTE

The A60 Assembly may be removed during this test to disable the beeper. However, this also disables the display so the "BLT TEST ROUTINE" will not be displayed. The waveforms and signatures will be valid when the front panel LEDs begin to blink.

6. Use a clip lead to short A30TP704 ($\overline{\text{DG3BR}}$) to ground, simulating a constant digital filter bus request.

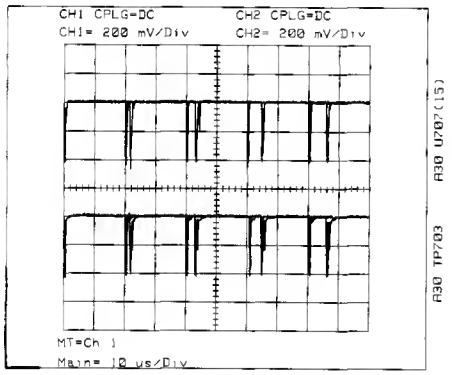
7. Check the signals listed in Table 7-22 and the waveforms given in Figure 7-24. While $\overline{\text{DF3BR}}$ is shorted to ground it is the highest priority bus request. The refresh enable signal and all bus grant signals except $\overline{\text{DF3BG}}$ should be inactive. This test may be repeated for $\overline{\text{DF2BG}}$ and $\overline{\text{DF1BG}}$.

8. When all of the waveforms and signatures have been checked, move jumper A40W1 back to the run position, re-insert the A20 Assembly, and remove the short from A30W100.

Table 7-22 RAM Bus Arbitrator Signals With DF3BR Grounded

Signal	State
U707(2)	TTL High
U708(6)	Low
U708(7)	Low
U708(9)	TTL High
U706(4)	Low
U706(5)	TTL High
U706(6)	Low
U701(2)	Low
U701(5)	TTL High
U701(6)	Low

Figure 7-23 RAM Bus Arbitrator Waveforms



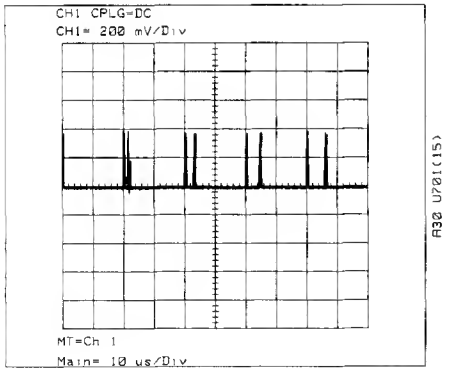
Probe: 10:1

Ch1: Connection- A30U707(14) "$\overline{PBR}$"
Coupling- dc
Ground- Fourth Graticule From Top

Ch2: Connection- A30TP703 "$\overline{PBG}$"
Coupling- dc
Ground- Second Graticule From Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: OFF

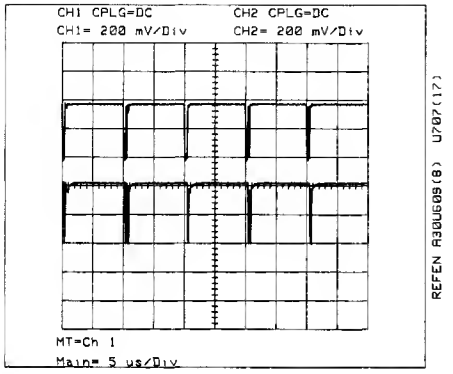


Probe: 10:1

Ch1: Connection- A30U701(15)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

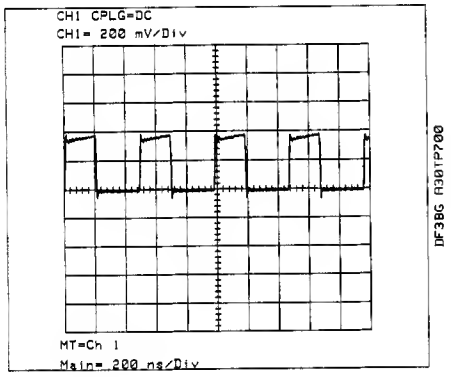
Ch1: Connection- A30U707(17)
Coupling- dc
Ground- Fourth Graticule From Top

Ch2: Connection- A30U609(8) "$\overline{\text{REFEN}}$"
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: OFF

Figure 7-24 $\overline{\text{DF3BG}}$ With $\overline{\text{DF3BR}}$ Grounded



Probe: 10:1

Ch1: Connection- A30TP700 "$\overline{\text{DF3BG}}$"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

[A] RAM DATA BUS BUFFERS, [B] RAM ADDRESS SELECTOR, [D] MAIN RAM [J] RAM REFRESH COUNTER, [L] PROCESSOR/RAM DATA BUS INTERFACE [R] FFT/PROCESSOR INTERFACE, [U] RAM TEST PORT

1. Turn the -hp-3561A LINE power switch OFF.

2. Remove the A20 Assembly and use a clip lead to short the two pins of A30W100 together.

3. Move test jumper A40W1 to the TEST position.

4. Turn the -hp-3561A LINE power switch ON.

5. When the "BLT TEST ROUTINE" message is displayed on the CRT, check the refresh counter waveforms given in Figure 7-25.

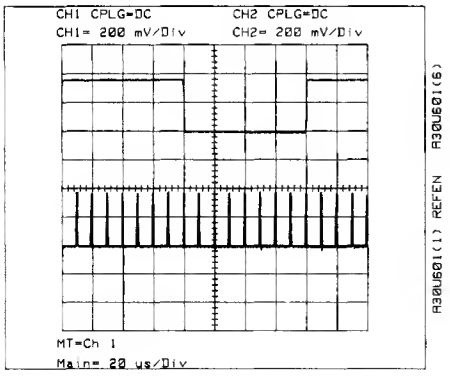
NOTE

The A60 Assembly may be removed during this test to disable the beeper. However, this also disables the display so the "BLT TEST ROUTINE" message will not appear. The wave forms and signatures will be valid when the front panel LEDs begin to blink.

6. Check the signatures given in Table 7-23 and 7-24 to troubleshoot the remaining RAM circuits and processor interface circuits.

7. When all of the waveforms and signatures have been checked, move jumper A40W1 back to the RUN position, re-insert the A20 Assembly, and remove the short from A30W100.

Figure 7-25 RAM Refresh Counter Waveforms



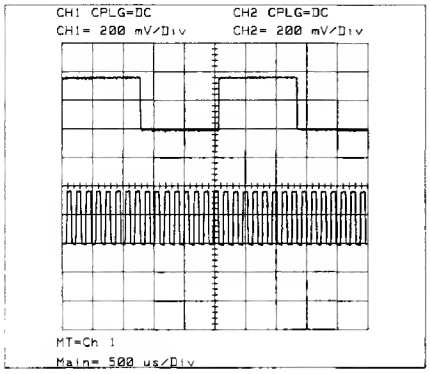
Probe: 10:1

Ch1: Connection- A30U601(6)
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A30U601(1) "$\overline{\text{REFEN}}$"
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A30TP600 "REFA7"
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A30U601(6)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

Table 7-23 RAM Address and Data Bus Signatures

Signature Analyzer Setup

Signal	Polarity	Connection
Clock	⌐¬	A30TP703 "$\overline{PBG}$"
Start	⌐¬	A40J100(5)
Stop	¬⌐	A40J100(4)

+5 V Signature - 5UAH

Processor/RAM Data Bus Interface (write to RAM)	
U502(3)	70H0
U502(5)	0C43
U502(7)	00A2
U502(9)	515U
U502(12)	C8H3
U502(14)	F61C
U502(16)	929C
U502(18)	AFU0
U506(3)	AP35
U506(5)	F680
U506(7)	HAU4
U506(9)	F15A
U506(12)	118F
U506(14)	276U
U506(16)	5165
U506(18)	354A

RAM Data Bus Buffers (write to RAM)	
U604(2)	H058
U604(3)	2133
U604(4)	UU2A
U604(5)	9C1H
U604(6)	A4UA
U604(7)	0U28
U604(8)	49UH
U604(9)	PPHF
U700(2)	U68P
U700(3)	P0P2
U700(4)	9621
U700(5)	H2HP
U700(6)	518H
U700(7)	F80A
U700(8)	2HAH
U700(9)	24F4

RAM Address Selector	
U200(4)	2525
U200(7)	0476
U200(9)	UACC
U200(12)	P76P
U205(4)	265H
U205(7)	5U5P
U205(9)	2134
U205(12)	CC17

Table 7-23 RAM Address and Data Bus Signatures (Cont'd)

Signal	Polarity	Connection
Clock	⌐¯	A30TP703 "$\overline{\text{PBG}}$"
Start	¯_	A40J100(5)
Stop	_⌐¯	A40J100(4)

+5 V Signature - 5UAH

Main RAM		Processor/Ram Bus Interface (Read from RAM)	
U201(2)	6CAC	U501(2)	35H5
U202(2)	6890	U501(5)	F433
U203(2)	4168	U501(6)	A0C4
U204(2)	899A	U501(9)	C4C6
U207(2)	AAF8	U501(12)	F925
U208(2)	U6U6	U501(15)	225P
U209(2)	5216	U501(16)	H48P
U210(2)	17CF	U501(19)	027H
U300(2)	924A	U505(2)	H564
U301(2)	A44A	U505(5)	7C7C
U302(2)	49PA	U505(6)	A90C
U303(2)	04UA	U505(9)	0CHP
U306(2)	H0A2	U505(12)	182A
U307(2)	6U6U	U505(15)	47FF
U308(2)	91HU	U505(16)	C894
U309(2)	FF67	U505(19)	6633

Table 7-24 FFT/Processor Interface Signatures

Signal	Polarity	Connection
Clock	⌐¯	A30TP601 "$\overline{\text{RIOS}}$"
Start	¯_	A40J100(5)
Stop	_⌐¯	A40J100(4)

+5 V Signature - H7PC

FFT/Processor Interface	
U600(2)	F6F0
U600(3)	112C
U600(7)	HPH1
U600(10)	P376
U600(14)	F6F0
U606(15)	7F2P

[D] MAIN RAM

If the signatures given in Table 7-23 are correct, the power on test can be used to isolate RAM failures to the component. When the power on test encounters a RAM failure, it lists return code 0 7 26 and a chip code. Table 7-25 lists the chip codes and the corresponding failed RAM.

Table 7-25 Power on Test RAM failures

Return code - 0 7 26	
Chip code	**Failed RAM**
0	U201
1	U202
2	U203
3	U204
4	U205
5	U300
6	U301
7	U302
8	U303
9	U207
A	U208
B	U209
C	U210
D	U307
E	U308
F	U309

[O] FFT PROCESSOR, [Q] FFT INSTRUCTION ROM

1. Turn the -hp-3561A LINE power switch OFF.

2. Move test jumpers A30W101 and A30W102 to the test position. Use a clip lead to short the two pins of A30W100 together.

3. Turn the -hp-3561A LINE power switch ON and check the signatures given in Table 7-26.

4. When all of the signatures have been checked, move jumpers A30W101 and A30W102 back to the NORM position and remove the short from A30W100.

Table 7-26 FFT Processor and ROM Signatures

Signal	Polarity	Connection
Clock		A30J1(3)
Start		A30J1(5)
Stop		A30J1(4)

+5 V Signature - 7A70

FFT Processor Address Bus

U100(1)	C21A
U100(2)	H62U
U100(27)	0000
U100(28)	8P54
U100(29)	1734
U100(34)	9635
U100(35)	0772
U100(36)	4U2A
U100(37)	4442
U100(38)	P030
U100(39)	H0AA
U100(40)	HA07

FFT Instruction ROM

U400(9)	HP00
U400(10)	HP01
U400(11)	HP02
U400(13)	HP03
U400(14)	HP04
U400(15)	HP05
U400(16)	HP06
U400(17)	HP07
U402(9)	HP08
U402(10)	HP09
U402(11)	HP10
U402(13)	HP11
U402(14)	HP12
U402(15)	HP13
U402(16)	HP14
U402(17)	HP15

FFT Address Bus Buffers

U4(3)	H62U
U4(5)	C21A
U4(7)	HA07
U4(9)	H0AA
U4(12)	P030
U4(14)	4442
U4(16)	4U2A
U4(18)	0772
U7(3)	9635
U7(5)	1734
U7(7)	8P54
U7(9)	0000

Table 7-27 A30 Assembly Signal Connections

INPUTS

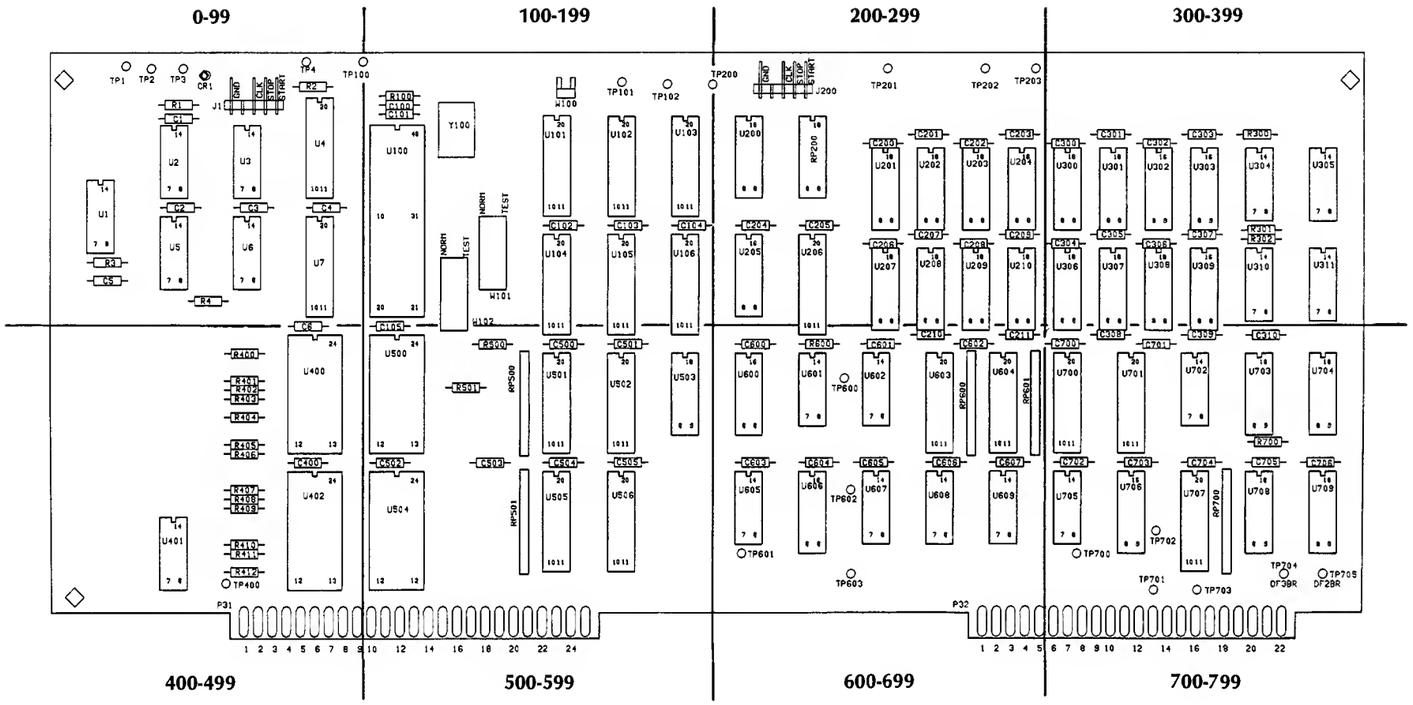
Signal Name	Functional Block	Connector Number	Origin Assembly
$\overline{\text{DF1BR}}$	H	P32(A12)	A20
$\overline{\text{DF2BR}}$	H	P32(A13)	A20
$\overline{\text{DF3BR}}$	H	P32(A14)	A20
$\overline{\text{PBLDS}}$	F	P31(A6)	A40
$\overline{\text{PBR}}$	H	P32(A16)	A40
PBR/$\overline{\text{W}}$	K	P32(B7)	A40
$\overline{\text{PBUDS}}$	F	P31(B6)	A40
$\overline{\text{PRAMRE}}$	L	P31(A7)	A40
$\overline{\text{PRIOS}}$	I	P32(B17)	A40
$\overline{\text{RESET}}$	R	P31(B3)	A40
100 kHz	G	P31(B2)	A40
20.48 MHz	C	P31(A2)	A40

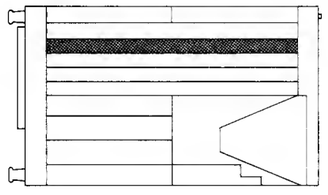
OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assembly
$\overline{\text{DF1BG}}$	I	P32(B12)	A20
$\overline{\text{DF2BG}}$	I	P32(B13)	A20
$\overline{\text{DF3BG}}$	I	P32(B14)	A20
$\overline{\text{FFTI}}$	S	P31(B4)	A40
$\overline{\text{PBG}}$	I	P32(B16)	A40
RBR/$\overline{\text{W}}$	K	P31(B16)	A20
$\overline{\text{RIOS}}$	K	P31(A16)	A20

I/O SIGNALS

Signal Name	Functional Block	Connector Number	Destination Assembly
RAM Address Bus RAB0 - RABF	B	P31(A17 - A24) P31(B17 - B24)	A20, A40
RAM Data Bus RDB0 - RDBF	L	P32(A4 - A11) P32(B4 - B11)	A20
Processor Data Bus PDB0 - PDBF	L	P31(A8 - A15) P31(B8 - B15)	A40, A50, A60, A65/66

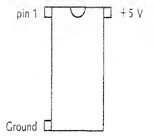

0-99
100-199
200-299
300-399
400-499
500-599
600-699
700-799
P31
P32



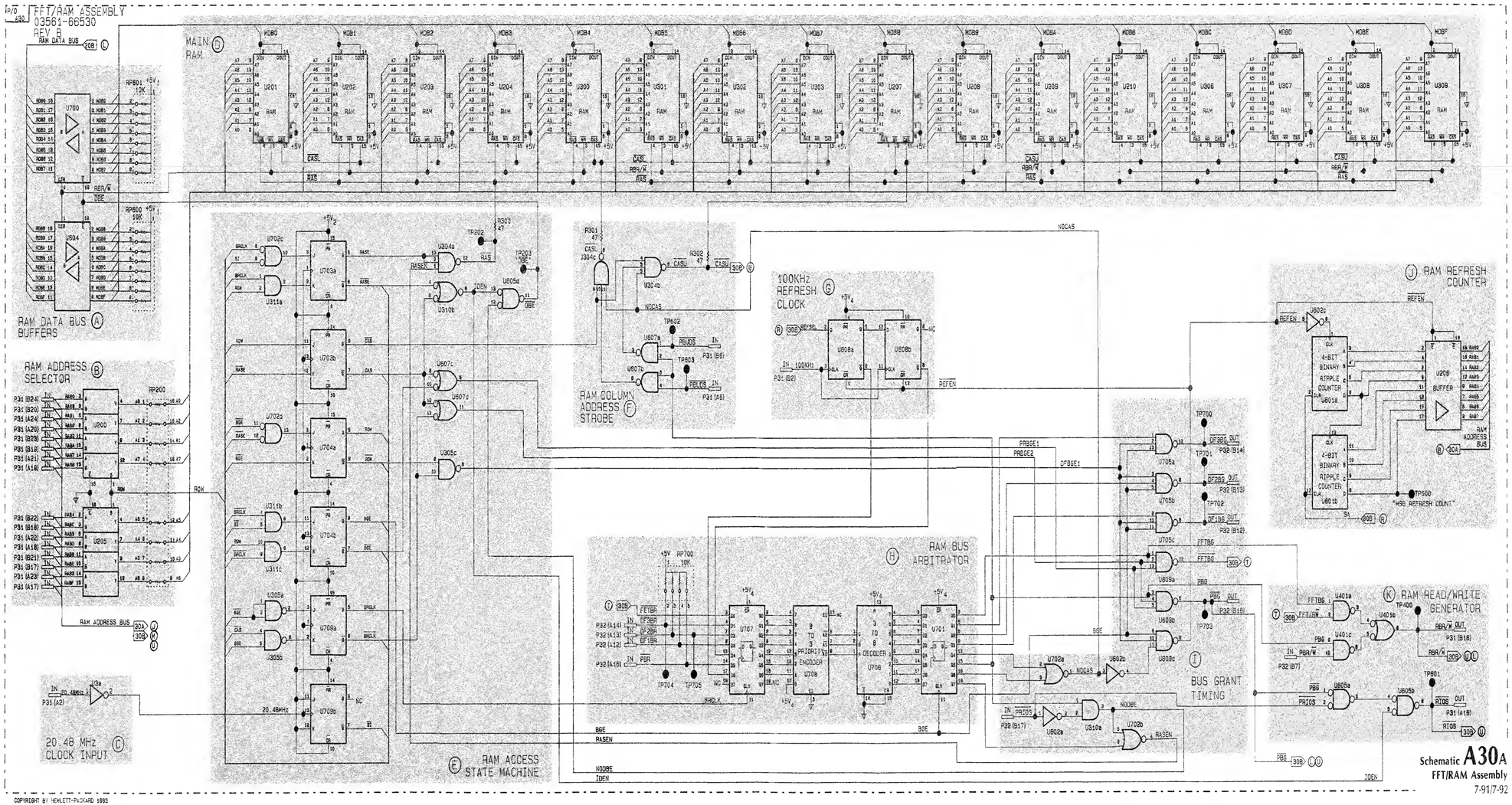
A30 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)

Corner Power

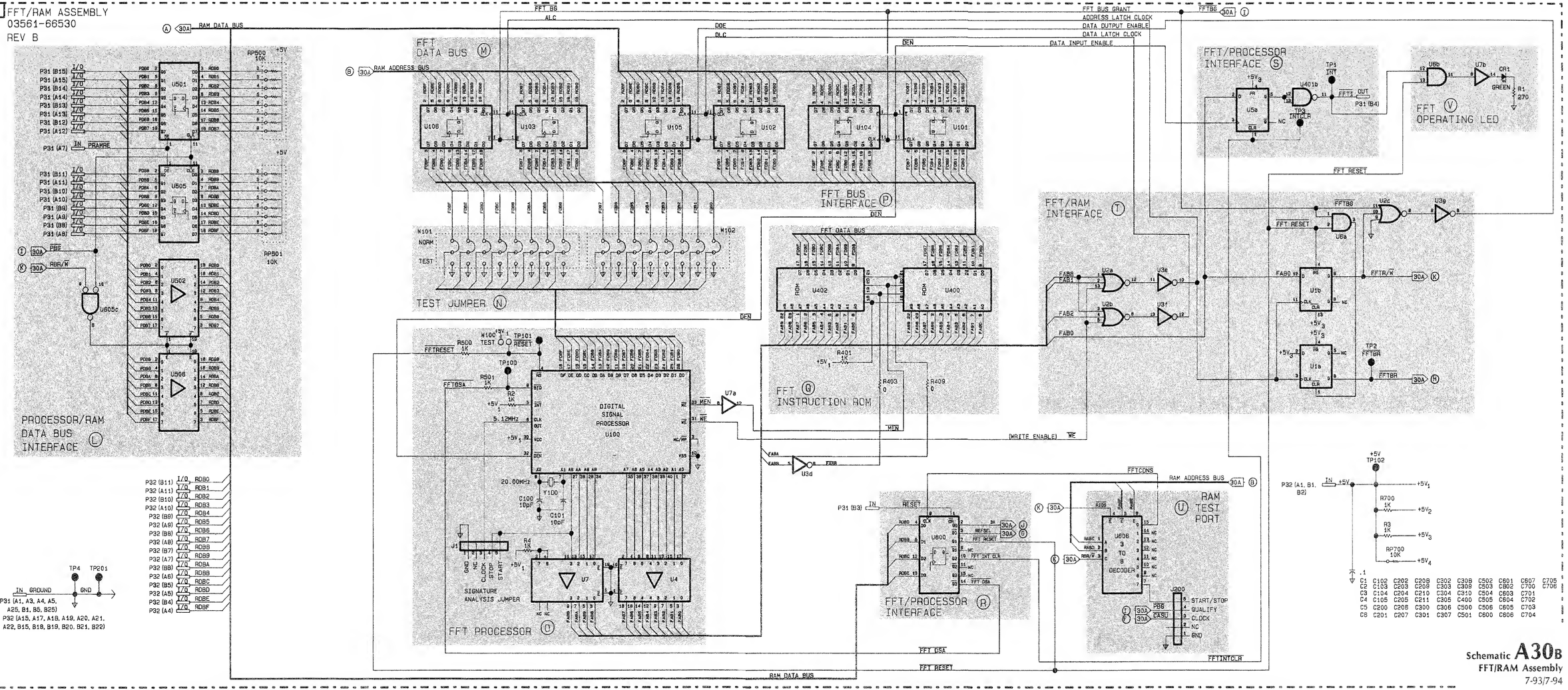


	+5V	GND
U100	30	10
U201	8	16
U202	8	16
U203	8	16
U204	8	16
U207	8	16
U208	8	16
U209	8	16
U210	8	16
U300	8	16
U301	8	16
U302	8	16
U303	8	16
U304	8	16
U305	8	16
U306	8	16
U307	8	16
U308	8	16
U309	8	16



P/O A30

FFT/RAM ASSEMBLY
03561-66530
REV B



Schematic **A30B**
FFT/RAM Assembly
7-93/7-94

7-16 A40 PROCESSOR/ROM ASSEMBLY

7-17 Processor/ROM Circuit Description

GENERAL

The main function of the microprocessor assembly is instrument control. Through the processor data bus, address bus, and I/O select lines, the microprocessor sets up and controls most circuits in the -hp-3561A and through the processor interrupt lines, these circuits can access the microprocessor. Together all of these signals allow the processor to direct the activity required for the -hp-3561A to take, process, and display measurement data. In addition to the microprocessor, ROM, and I/O control circuitry, the A40 Assembly contains the master 20.48 MHz clock, which determines the frequency accuracy of the instrument.

[A] INTERRUPT PRIORITY ENCODER, [K] INTERRUPT VECTOR GENERATOR

When an interrupt is received by the priority interrupt encoder, it compares the priority of the interrupt with the priority of any other active interrupts (level 7 in U408 being the highest level and level 0 the lowest). It then issues the highest priority interrupt to the processor where an interrupt acknowledge cycle is initiated. In this cycle the processor outputs the binary interrupt level on the first three address lines PA0, PA1, and PA2, and issues an interrupt acknowledge signal, $\overline{\text{PINTA}}$. $\overline{\text{PINTA}}$ latches the first three address lines in the interrupt vector generator. The processor next reads the vector generator to determine the location in memory of the interrupt service routine.

[I] RAM BUS INTERFACE HANDSHAKE, [B] RAM BUS INTERFACE BUFFER

To access the instrument RAM, the processor must issue a bus request ($\overline{\text{PBR}}$) to the RAM bus arbitrator. If the processor bus request is the highest priority request, the RAM bus arbitrator will issue a bus grant to the processor. On receipt of a bus grant, the processor places an address and data onto the RAM address and data bus respectively. The RAM bus interface then clears the bus request, and issues a $\overline{\text{RAMH}}$ signal to complete the RAM bus cycle.

[D] MICROPROCESSOR

The central microprocessor is a 68000, 16 bit processor. It communicates with peripheral circuits through the processor address bus and processor data bus, using the address strobe, data strobe, and the data acknowledge signals to coordinate the data transfer. Address strobe, $\overline{AS}$, goes low to indicate that the address is valid on the processor address bus. Upper data strobe, $\overline{PUDS}$, and lower data strobe, $\overline{PLDS}$, go low to indicate that data is valid on the upper 8 bits and lower 8 bits of the data bus respectively. A processor bus cycle is terminated by the data acknowledge signal, $\overline{DTACK}$.

[H] ADDRESS STROBE TIMING DELAY, [J] DATA ACKNOWLEDGE GENERATOR

The address strobe timing delay circuit delays the address strobe signal to account for address delays through the bus buffers. Delayed address strobe, $\overline{DAS}$ is delayed by one clock cycle, and is used for addressing circuits on the A40 Assembly. The address strobe signal is further delayed to account for the communication time to the ROM, noise source, and front panel.

The delayed address strobe signals are used by the data acknowledge generator to determine the length of a bus cycle to any particular peripheral. The data acknowledge generator reads the address bus to determine which peripheral the processor is talking to. This address is then used to select the appropriate delayed address strobe to generate the $\overline{DTACK}$ signal. All bus cycle times are fixed by the delayed address strobe signals except RAM access and display access. The data acknowledge generator depends on a response from these two circuits to generate a $\overline{DTACK}$. $\overline{RAMH}$ indicates that the RAM bus cycle is complete and $\overline{DSPH}$ indicates that a display bus cycle is complete.

[M] I/O ADDRESS DECODING, [L] CONTROL AND ADDRESS BUS BUFFER

The processor address bus is partially decoded on the A40 Assembly by the I/O address decoder. This circuit generates a select signal for each major circuit in the instrument. The processor address bus and the data bus strobe are buffered through the control and address bus buffer and sent to the peripheral circuits where the address is further decoded to a particular device within the selected circuit.

[Q] POWER-ON RESET

The LOW+5 signal from the power supply holds the processor in reset until the +5 volt supply is fully operational at power on. The RESET and HALT signals are bidirectional and can be driven by either the processor or the power on reset circuit to reset the -hp-3561A. The two pins of the RESET test point (TP2) may be shorted together to manually reset the processor.

[T] WATCH DOG TIMER

This circuit will reset the processor if the processor does not access the front panel every ten micro seconds. This should only occur in the case of a failure. The watch dog timer may be disabled by jumper A40W3.

[P] ROM, [O] ROM ADDRESS DECODING

The processor executes the instructions stored in the ROM. The ROM address consists of two parts, the ROM chip select signals address a ROM chip while the address bus addresses the location within the selected ROM. The power on self test is stored in ROMS #1 and #2 (U502, U106) If these ROMs have failed, the power on test will not run. Using the power up test program stored in ROM #1, the processor can check the integrity of the other ROMs.

[R] CLOCK GENERATOR, [S] CLOCK DIVIDE ÷10 ÷100

In addition to the microprocessor circuits, this oscillator provides a clock signal to the following circuits: Noise Source (A50), CMOS and Bubble Memory (A66/65).

[U] 20.48 MHz CRYSTAL OSCILLATOR, [V] CLOCK OUTPUT BUFFER

This oscillator provides a clock signal for the following circuits: RAM (A30), Digital Filter (A20), Power Supply (A70), A/D Converter (A15). The accuracy of this oscillator determines the overall frequency accuracy of the instrument.

Table 7-28 A40 Assembly Signal Descriptions

Signal	Description
$\overline{AS}$	Address Strobe: This signal goes low once per processor bus cycle to indicate that data is valid on the processor address bus.
$\overline{BERR}$	Bus ERRor: This signal goes low to abort the current bus cycle. The $\overline{BERR}$ signal is activated if the bus cycle takes longer than expected.
$\overline{BUBI}$	BUBble memory Interrupt: The bubble memory uses this signal to request service from the processor.
$\overline{CMOSS}$	CMOS memory Select: Addresses the CMOS memory on the A65/66 Assembly for processor access.
$\overline{DAS}$	Delayed Address Strobe: Address strobe delayed by one 8 MHz clock cycle.
$\overline{DINT}$	Data acknowledge INTerrupt: Forces a $\overline{DTACK}$ to indicate to the processor that the interrupt vector has been latched.
$\overline{DMAI}$	Direct Memory Access Interrupt: Tells the processor that the digital filter has processed a complete time record and stored the result in RAM.
$\overline{DSPH}$	DiSPlay Holdoff: This signal holds off the $\overline{DTACK}$ signal until the display access is complete.
$\overline{DSPS}$	DiSPlay Select: Addresses the display for processor access.
$\overline{DTACK}$	DaTa ACKnowledge: This signal goes low to indicate to the processor that the current bus cycle is complete.
$\overline{FFTI}$	FFT Interrupt: The FFT uses this signal to indicate that the FFT is complete, and the results are available for further processing or display.
$\overline{FIOH}$	Fast I/O Holdoff: This signal holds off the $\overline{DTACK}$ signs by four 8 MHz clock cycles for all fast I/O port bus cycles.
$\overline{FPS}$	Front Panel Select: Addresses the front panel for processor access.
$\overline{HALT}$	Processor HALT: This signal goes low to indicate that the processor is not executing instructions. The red LED, CR2, illuminates when $\overline{HALT}$ is low. This signal may be driven low by either the processor or the reset circuit.
$\overline{HPCI}$	HP-IB Control Interrupt: Used for all HP-IB activity except binary data transfer.
$\overline{HPDI}$	HP-IB Data Interrupt: A faster interrupt used for binary data transfer only.
$\overline{HPIBS}$	HP-IB Select: Addresses the HP-IB circuit on the A50 Assembly for processor access.

Table 7-28 A40 Assembly Signal Descriptions (Cont'd)

Signal	Description
$\overline{\text{IOPORT\#7}}$	I/O PORT Number 7: The processor addresses this port to clear the interrupt vector generator.
$\overline{\text{LOS}}$	Local Oscillator Select: Addresses the local oscillator on the A50 Assembly for processor access.
LOW+5	LOW +5 Volt Supply: At power on this signal is held low until the +5 V signal is fully operational.
PA0 - PAF	Processor Address bus 0-F (16 bit hex): Buffered processor address bus.
PA17 PA18 PA19	Processor Address Bus: Address lines used only for circuits on the A40 Assembly.
PD0 - PDF	Processor Data Bus 0-F (16 bit hex): Buffered processor data bus.
$\overline{\text{PINTA}}$	Processor INTerrupt Acknowledge: This signal goes low at the start of an interrupt acknowledge bus cycle to latch the interrupt vector.
$\overline{\text{PLDS}}$	Processor Lower 8 bit Data Strobe: Indicates that the lower 8 bits (PD0 - PD7) of the processor data bus are valid.
$\overline{\text{PRAMRE}}$	Processor RAM REad: Goes low to tell the RAM that the current bus cycle is a read operation.
$\overline{\text{PRIOS}}$	Processor Ram I/O Select: High when the processor is accessing the RAM and low when the processor is accessing an I/O port through the RAM bus.
$\overline{\text{PUDS}}$	Processor Upper 8 bit Data Strobe: Indicates that the upper 8 bits (PD8 - PDF) of the processor data bus are valid.
$\overline{\text{PWRFAIL}}$	PoWeR FAIL Interrupt: Indicates a power fail condition to the processor.
$\overline{\text{RESET}}$	$\overline{\text{RESET}}$: This signal is goes low to reset the processor and the entire instrument. $\overline{\text{RESET}}$ can be controlled by either the processor or the reset circuit.
RAB0 - RABF	RAM Address Bus 0 - F (16 bit hex): Addresses the RAM and I/O ports tied to the RAM bus when a $\overline{\text{PBG}}$ is issued from the RAM bus arbitrator.
RCS0 - RCS11	ROM Chip Select 0 through 11: These signals select the ROM Chip to be addressed by the address bus.
$\overline{\text{SINT}}$	Noise Source INTerrupt: This signal goes low when the noise source needs to be re-armed.
$\overline{\text{TINT}}$	Timer INTerrupt: Indicates to the processor that the watch dog timer is about to issue a RESET.

7-18 Troubleshooting the Processor/ROM

GENERAL

Failures on the A40 Assembly will generally cause the instrument to fail the power up test in some way. It is useful to separate these failures into the two categories listed below.

1) Instrument "hangs up" and does not complete the power up test.
2) Instrument completes the power up test with a return code.

Troubleshoot the circuits on the A40 Assembly in the order given in Table 7-29. In this table, level one circuits must be operational before level two circuits can be tested and so on. Instrument "hang up" failures usually indicate level one through four circuits, while return code failures usually indicate level five or six failures.

NOTE

To disable the beeper, the A60 Assembly can be removed while troubleshooting the A40 Assembly. Removing the A60 Assembly also disables the display.

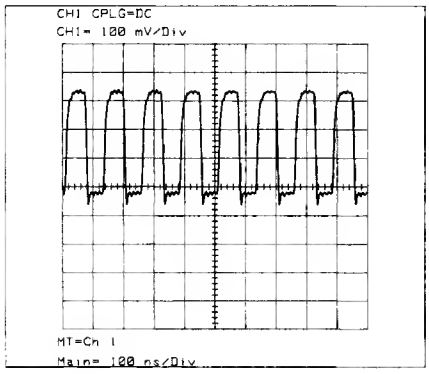
Table 7-29 A40 Circuit Troubleshooting Order

LEVEL	Functional Blocks
1	Clock: R
	Power on Reset: Q
2	Clock Divider: S
3	Interrupt Priority Encoder: A
4	Microprocessor: D
	Address Strobe Delay: H
	Data Acknowledge Generator: J
	Processor Data Bus: G
	Bus Error Detector: E
5	Processor Address Bus: C, B
	Power Up Test ROMs: P
6	All other circuits on the A40 Assembly

[R] CLOCK

Check the clock waveforms at test point A40TP401 and test point A40TP402 given in Figure 7-26.

Figure 7-26 A40 Clock Waveforms

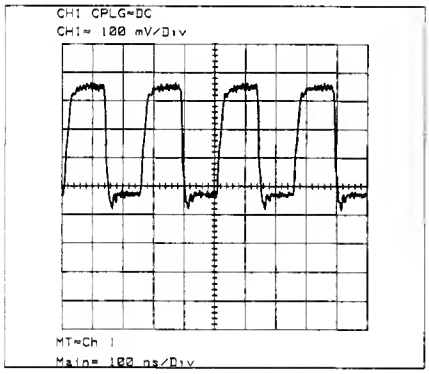


Probe: 10:1

Ch1: Connection- A40TP401 "8 MHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A40TP402 "4 MHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

[Q] POWER ON RESET

1. Move test jumper A40W3 to the test position.
2. Short the two pins of the reset test point (TP2) together.
3. Check the $\overline{\text{RESET}}$ signal and the $\overline{\text{HALT}}$ signal at U6(18) and U6(17). Both of these should be TTL low.
4. Remove the short from the reset test point (TP2) and re-check $\overline{\text{RESET}}$ and $\overline{\text{HALT}}$ signals. These signals should now be TTL high.
5. Move test jumper A40W3 to the normal position.

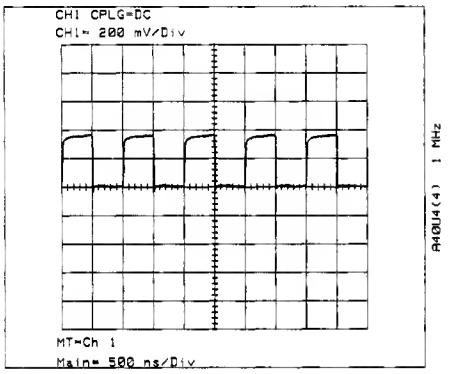
[S] CLOCK DIVIDER, [A] INTERRUPT PRIORITY ENCODER

1. Turn the -hp-3561A LINE power switch OFF and move test jumper A40W2 to the test position.

2. Turn the -hp-3561A LINE power switch ON and check the waveforms given in Figure 7-27.

3. Move test jumper A40W2 to the normal position.

Figure 7-27 Clock Divider and Interrupt Waveforms

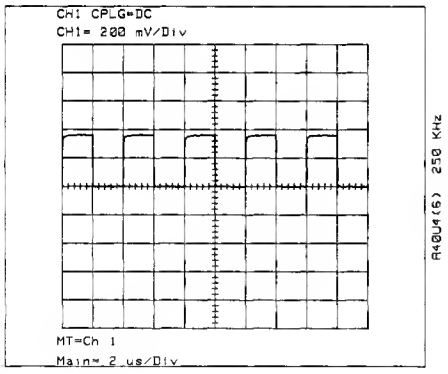


Probe: 10:1

Ch1: Connection- A40U4(4) "1 MHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

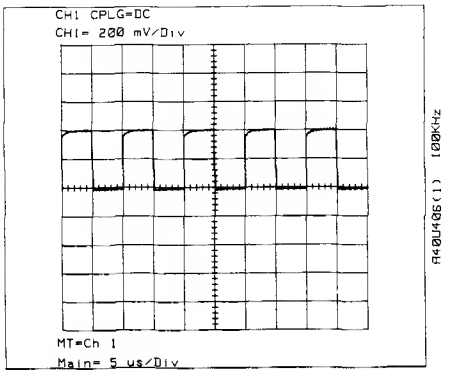


Probe: 10:1

Ch1: Connection- A40U4(6) "250 kHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

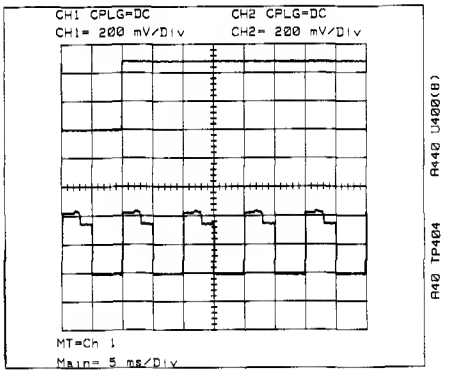


Probe: 10:1

Ch1: Connection- A40U406(1) "100 kHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



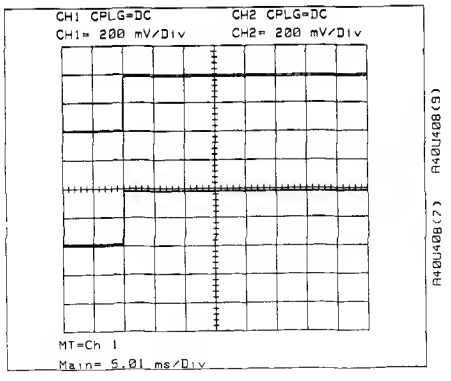
Probe: 10:1

Ch1: Connection- A40U400(8) "TINT"
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A40TP404 "100 Hz"
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A40U408(9)
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A40U408(7)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: ON

[D] MICROPROCESSOR, [H] ADDRESS STROBE TIMING DELAY, [J] DATA ACKNOWLEDGE GENERATOR, [E] BUS ERROR DETECTOR

These circuits form the basic processor bus cycle loop. A failure in any one of these circuits will cause the the processor to lock up and all of the signals will go to a static state. The basic processor loop consists of U3, U4, U8, U9, U405, U409 and the microprocessor itself U6.

1. Turn the -hp-3561A LINE power switch OFF and move test jumpers A40W2 and A40W3 to the test position.

2. Turn the -hp-3561A LINE power switch ON and check the processor input signals listed in Table 7-30. All of these signals must be correct before proceeding with the next step.

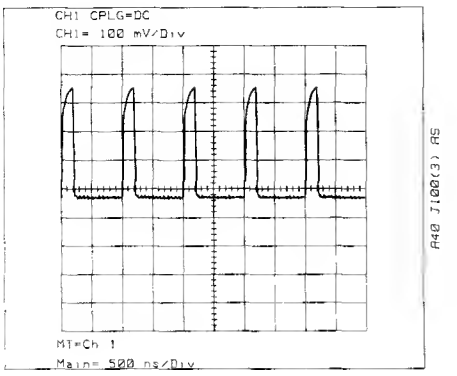
3. Check the waveforms given in Figure 7-28.

4. If all of these signals are stuck in a static state, replace U3 and re-check the waveforms given in Figure 7-28. Repeat this process for U4, U8, U9, U405, and U409. If the processor loop test is still failing, the failure is most likely in the processor itself, replace U6.

Table 7-30 Processor Loop Test Input Signals

Signal Name	Signal Position	Signal State (TTL Level)
	U402(8)	high
	U401(11)	low
	U403(11)	high
$\overline{\text{BERR}}$	U6(22)	high
$\overline{\text{HALT}}$	U6(17)	high
$\overline{\text{RESET}}$	U6(18)	high
D0	U6(5)	low
D1	U6(4)	high
D2	U6(3)	high
D3	U6(2)	high
D4	U6(1)	high
D5	U6(64)	high
D6	U6(63)	high
D7	U6(62)	high
D8	U6(61)	low
D9	U6(60)	high
D10	U6(59)	high
D11	U6(58)	high
D12	U6(57)	high
D13	U6(56)	high
D14	U6(55)	high
D15	U6(54)	low

Figure 7-28 Processor Loop Test Waveforms

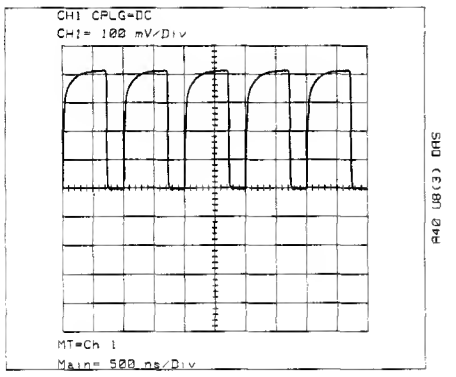


Probe: 10:1

Ch1: Connection- A40J100(3) "$\overline{AS}$"
A40U6(8) "$\overline{PLDS}$"
A40U6(7) "$\overline{PUDS}$"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

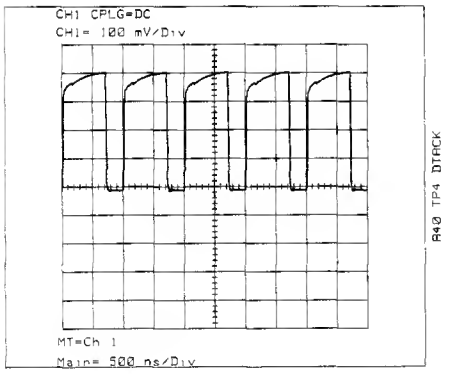


Probe: 10:1

Ch1: Connection- A40U8(3) "DAS"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

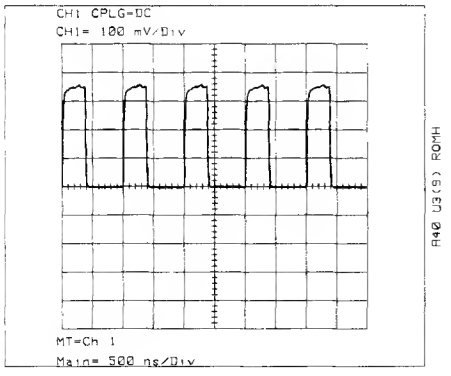


Probe: 10:1

Ch1: Connection- A40TP4 "$\overline{DTACK}$"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

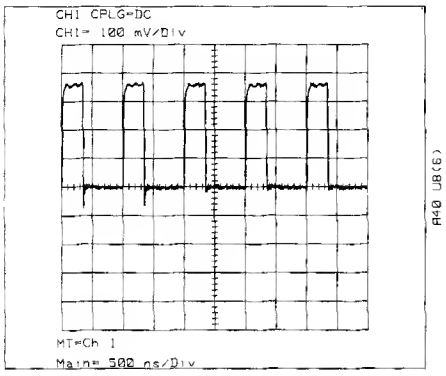


Probe: 10:1

Ch1: Connection- A40U3(9) "$\overline{ROMH}$"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A40U8(6) "$\overline{\text{FIOH}}$"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

[C] PROCESSOR ADDRESS BUS, [O] ROM ADDRESS DECODERS, [P] POWER UP TEST ROM, [G] PROCESSOR DATA BUS

The power up test software is stored in the first two ROMs, U106 and U502. These ROMs must be operational before the power up test can be run. This test checks all of the circuits used to address and read data from the first two ROMs. All other ROM failures are detected through return codes in the power up test.

1. Turn the -hp-3561A LINE power switch OFF and move test jumpers A40W2 and A40W3 to the test position.

2. Turn the -hp-3561A LINE power switch ON and check the signatures given in Table 7-31.

Table 7-31 A40W2 Test Signatures

Signature Analyzer Setup

Signal	Polarity	Connection
CLOCK		J100(3) "$\overline{AS}$"
START		J100(5)
STOP		J100(4)

+5 V Signature - 00UP

Processor Address Bus	
U6(29)	0055
U6(30)	0033
U6(31)	000U
U6(32)	UUUU
U6(33)	H42C
U6(34)	4074
U6(35)	PPP1
U6(36)	89F1
U6(37)	31PC
U6(38)	34C1
U6(39)	15HU
U6(40)	7U42
U6(41)	PC1A
U6(42)	9C51
U6(43)	U540
U6(44)	P625
U6(45)	0055
U6(46)	0033
U6(47)	000U

ROM Address Decoding	
U605(7)	60FF
U605(9)	3700
U605(10)	6935
U605(11)	3PC9
U605(12)	FO9A
U605(13)	6U02
U605(14)	H369
U605(15)	7F70
U606(7)	18U2
U606(9)	4H01
U606(10)	9A8F
U606(11)	FU6U
U606(12)	30P7
U606(13)	9C01
U606(14)	341C
U606(15)	9UHH

Processor Address Bus Buffers	
U500(3)	PPP1
U500(5)	H42C
U500(7)	000U
U500(9)	0055
U500(12)	0033
U500(14)	UUUU
U500(16)	4074
U500(18)	89F1
U503(3)	P625
U503(5)	U540
U503(7)	9C51
U503(9)	PC1A
U503(12)	7U42
U503(14)	15HU
U503(16)	31PC
U503(18)	34C1

Table 7-31 A40W2 Test Signatures (Cont'd)

Power on Test ROMs (U106, U502) and Processor Data Bus

Signature Analyzer Setup

Signal	Polarity	Connection
CLOCK		TP501 "$\overline{\text{RCS0}}$"
START		J100(5)
STOP		J100(4)

+5 V Signature - 1180

U106(11)	1H75	U502(11)	1PU7
U106(12)	4PP8	U502(12)	A506
U106(13)	1180	U502(13)	47CF
U106(15)	AC06	U502(15)	01P8
U106(16)	H161	U502(16)	3C9C
U106(17)	AP7C	U502(17)	9C3A
U106(18)	A6CP	U502(18)	771A
U106(19)	19AS	U502(19)	A33F

[P] ROM

If all tests to this point have passed, the -hp-3561A power up test will be operational. To check the remaining ROMs run the power up test. The return codes and corresponding failed ROMs are listed in Table 7-32.

Table 7-32 Power-on Test ROM Return Codes

Return Code	Failed ROM
0 1 01	U502
0 1 02	U106
0 1 03	U600
0 1 04	U200
0 1 05	U601
0 1 06	U201
0 1 07	U602
0 1 08	U202
0 1 09	U603
0 1 10	U203
0 1 11	U700
0 1 12	U302
0 1 13	U701
0 1 14	U303
0 1 15	U702
0 1 16	U304
0 1 17	U703
0 1 18	U305
0 1 19	U704
0 1 20	U306
0 1 21	U301
0 1 22	U300
0 1 23	U708
0 1 24	U707

[B] RAM ADDRESS BUS INTERFACE BUFFER, [G] DATA BUS BUFFERS, [L] CONTROL AND ADDRESS BUS BUFFER, [I/O ADDRESS DECODING

This test uses signature analysis to check most of the A40 Assembly I/O signals. Because this test depends only on the power supply and the processor assembly itself, any of the other assemblies can be removed without affecting the test results. If the test fails, assemblies A20, A30, A50, A60, and A65 can be removed and the test re-run to determine if one of these assemblies is loading down the A40 I/O signals.

1. Turn the -hp-3561A LINE power switch OFF and move test jumpers A40W2 and A40W3 to the test position.

2. Turn the -hp-3561A LINE power switch ON and check the signatures given in Table 7-33.

3. Turn the -hp-3561A LINE power switch OFF. Move test jumpers A40W2 and A40W3 back to the run position, and move test jumper A40W1 to the test position.

4. Turn the -hp-3561A LINE power switch ON. When the front panel LEDs begin to blink (≈10 seconds after power-on), check the signatures given in Table 7-34.

Table 7-33 Processor I/O and Address Bus Signatures

Signature Analyzer Setup

Signal	Polarity	Connection
CLOCK		J100(3) "$\overline{AS}$"
START		J100(5)
STOP		J100(4)

+5 V Signature - 00UP

I/O Decoding		Processor Address Bus	
U504(7)	9COH	U501(3)	0000
U504(9)	5108	U501(5)	H42C
U504(10)	6A18	U501(7)	000U
U504(11)	HU98	U501(9)	0055
U504(12)	1U5P	U501(12)	0033
U504(13)	U4UC	U501(14)	UUUU
U504(14)	HFA1	U501(16)	4074
U504(15)	488H	U501(18)	0000

Table 7-34 Processor Data Bus and RAM Address Bus Signatures

Signature Analyzer Setup

Signal	Polarity	Connection
CLOCK		TP500 "$\overline{\text{FPS}}$"
START		U10 (12) or CR1 (Cathode of Green LED)
STOP		U10 (12) or CR1 (Cathode of Green LED)

+5 V Signature - 5UAH

Processor Data Bus

U105(2)	AHC7	U102(2)	U549
U105(3)	UPA8	U102(3)	7P9A
U105(4)	U81U	U102(4)	750U
U104(5)	6F50	U102(5)	C11U
U105(6)	33PP	U102(6)	9FH6
U105(7)	2887	U102(7)	F8AP
U105(8)	4949	U102(8)	H51A
U105(9)	P6F9	U102(9)	5PU4

Signature Analyzer Setup

Signal	Polarity	Connection
CLOCK		A40TP406 "$\overline{\text{PBG}}$"
START		J100(5)
STOP		J100(4)

NOTE

These signatures require an A30 Assembly with a properly operating RAM bus arbitrator installed in the -hp-3561A.

+5 V Signature - 5UAH

RAM Address Bus

U705(3)	U92U	U706(3)	C8F3
U705(5)	H5CC	U706(5)	7P99
U705(7)	C78P	U706(7)	00U3
U705(9)	H18F	U706(9)	79U0
U705(12)	34H8	U706(12)	P4CA
U705(14)	P931	U706(14)	A516
U705(16)	79H7	U706(16)	5CH6
U705(18)	5U94	U706(18)	7A88

Table 7-35 A40 Assembly Signal Connections

INPUTS

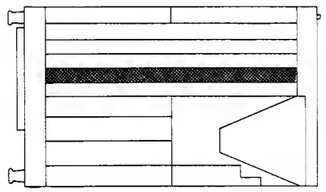
Signal Name	Functional Block	Connector Number	Origin Assembly
$\overline{\text{BUBI}}$	A	P41(A5)	A65
$\overline{\text{DMAI}}$	A	P41(A7)	A20
$\overline{\text{DSPH}}$	J	P41(B5)	A60
$\overline{\text{FFTI}}$	A	P41(A8)	A30
$\overline{\text{HPCI}}$	A	P41(B7)	A50
$\overline{\text{HPDI}}$	A	P41(B6)	A50
$\overline{\text{LOW+5}}$	Q	P42(B13)	A70
$\overline{\text{PBG}}$	I	P42(B16)	A30
$\overline{\text{PWR FAIL}}$	A	P41(B4)	A71
$\overline{\text{SINT}}$	A	P41(B12)	A50

OUTPUTS

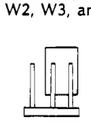
Signal Name	Functional Block	Connector Number	Destination Assembly
$\overline{\text{BUBS}}$	M	P41(A10)	A65
$\overline{\text{CMOSS}}$	M	P41(B10)	A65
$\overline{\text{DSPS}}$	M	P41(A9)	A60
$\overline{\text{FPS}}$	M	P41(B8)	A81
$\overline{\text{HPIBS}}$	M	P41(B11)	A50
$\overline{\text{LOS}}$	M	P41(A11)	A50
$\overline{\text{PBLDS}}$	L	P41(A12)	A30
$\overline{\text{PBR}}$	I	P42(A16)	A30
$\overline{\text{PBUDS}}$	L	P41(A13)	A30, A50
$\overline{\text{PRAMRE}}$	I	P41(A4)	A30
$\overline{\text{PRIOS}}$	I	P42(B17)	A30
$\overline{\text{RESET}}$	Q	P41(B3)	A20, A30, A50, A60, A66/65, A81
100 kHz	S	P41(A3)	A30
4 MHz	R	P41(B2)	A50, A66/65
20.48 MHz	V	P41(A2)	A15, A20, A30

I/O SIGNALS

Signal Name	Functional Block	Connector Number	Destination Assembly
Processor Address Bus PAB0 - PAB5	L	P41(A14 - A16) P41(B14 - B16)	A50, A60, A66/65
Processor Data Bus PDB0 - PDBF	G	P41(A17 - A24) P41(B17 - B24)	A30, A50, A60, A65/66
RAM Address Bus RAB0 - RABF	B	P42(A4 - A11) P42(B4 - B11)	A20, A30

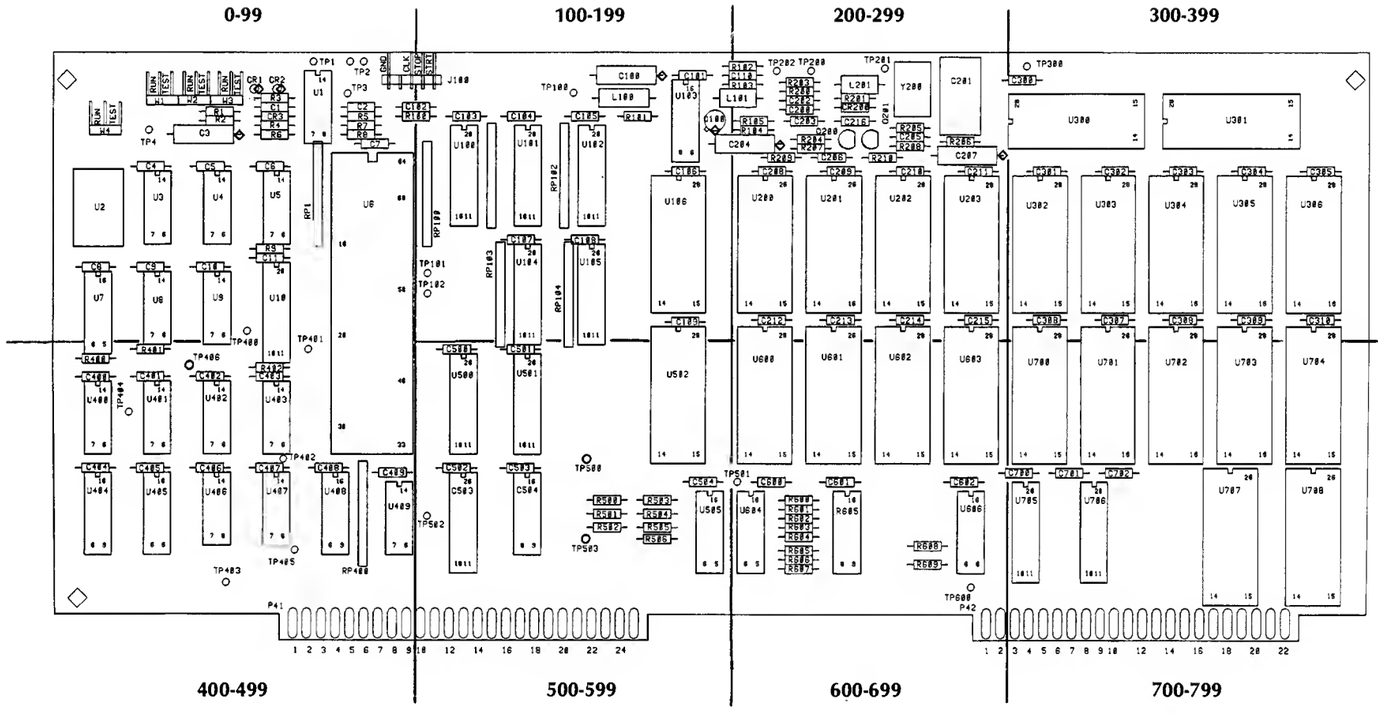


A40 Assembly
Test Jumpers
W1, W2, W3, and W4



Test Position

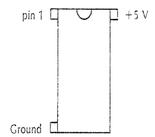
Run Position



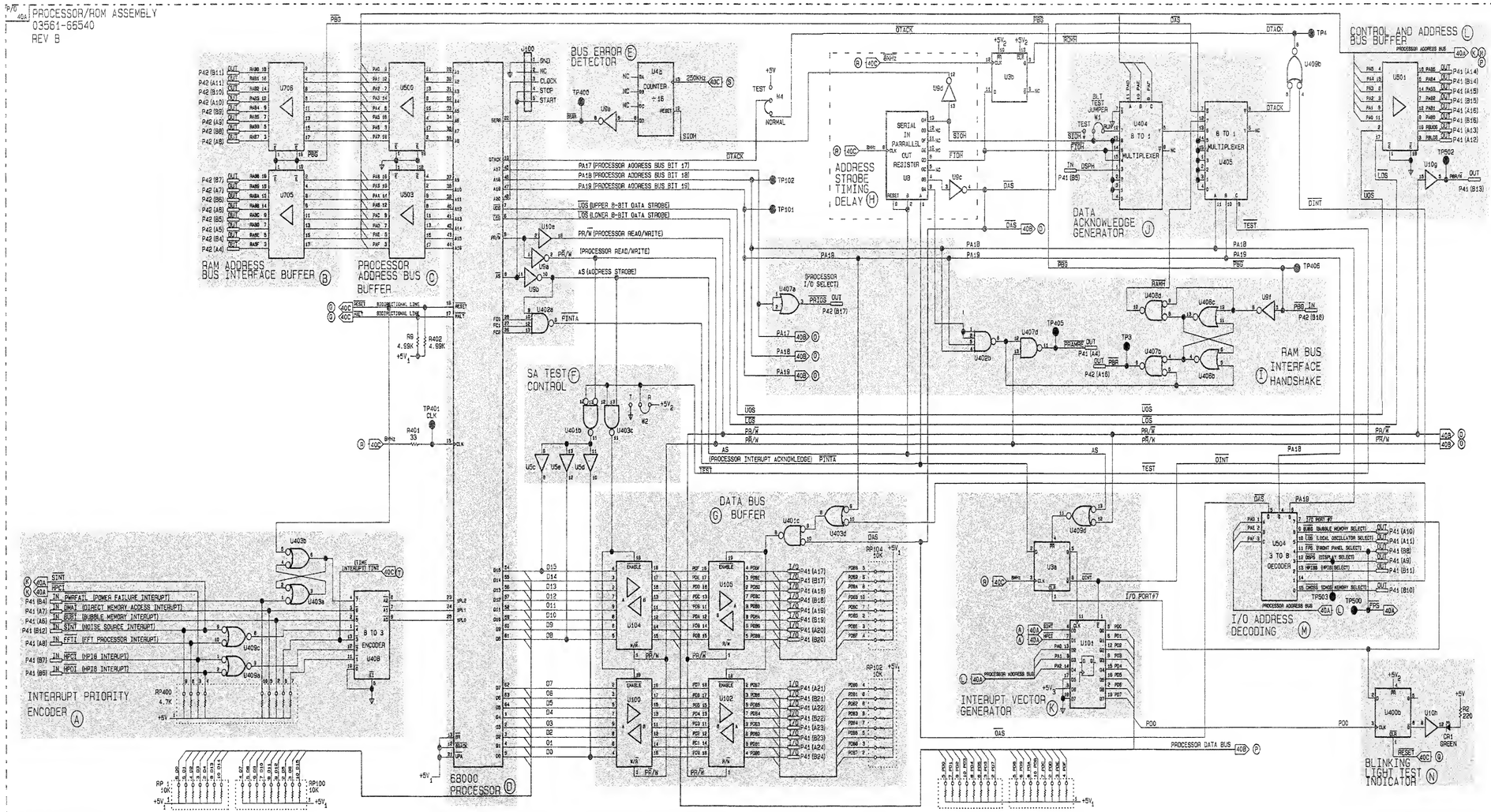
A40 Assembly

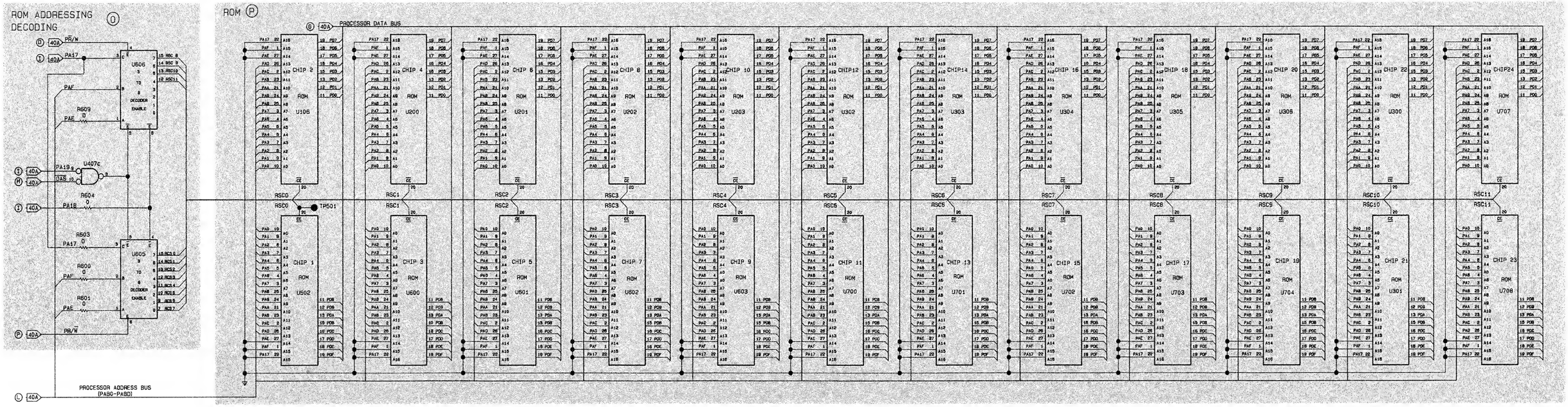
All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)

Corner Power

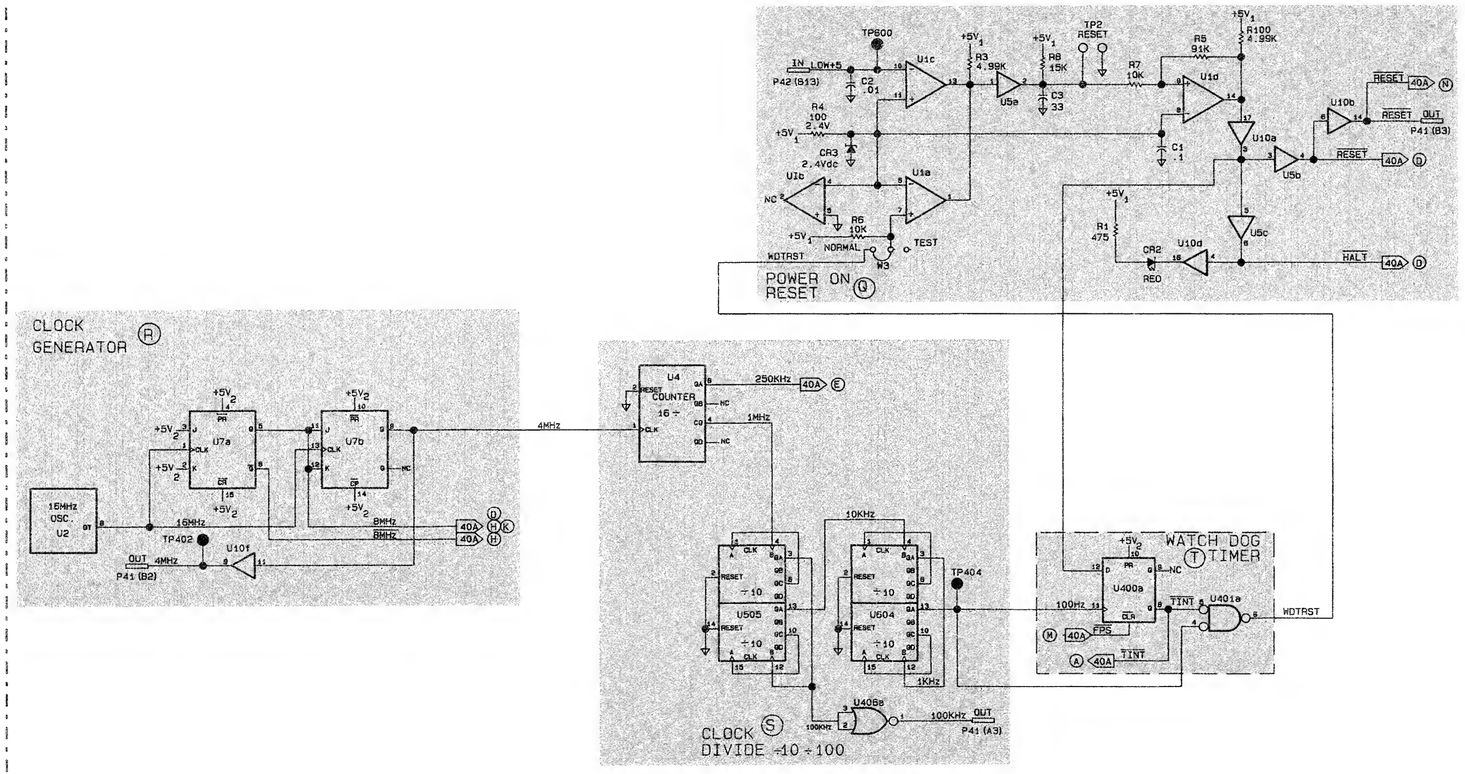


	+5V1	+5V4	GND
U1		5	12
U6	14,49	16,53	
U103		16	7

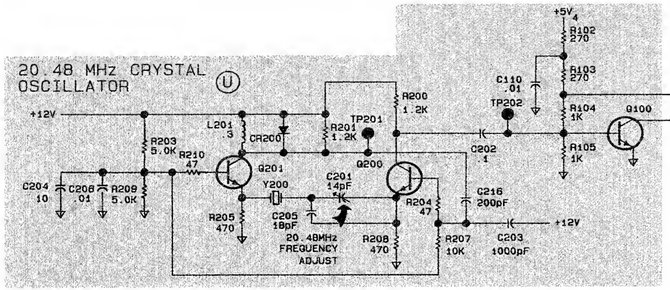


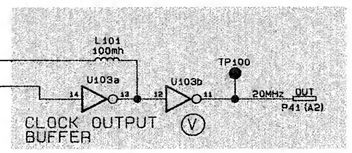


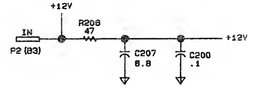
P/O A40 PROCESSOR/ROM ASSEMBLY
03561-66540
REV B

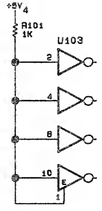


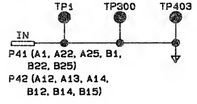
P/O A40 PROCESSOR/ROM ASSEMBLY
03561-66540
REV B

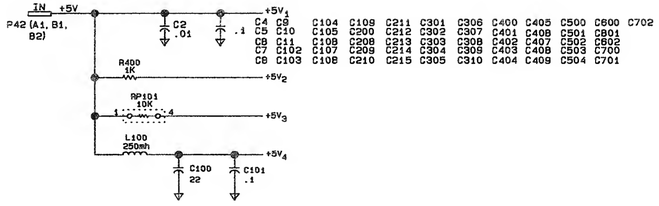












7-19 A50 LOCAL OSCILLATOR/NOISE SOURCE ASSEMBLY

7-20 Local Oscillator/Noise Source Circuit Description

GENERAL

The A50 Assembly contains three separate operational circuits. They are:Local Oscillator, Noise Source and HP-IB. These circuits are described in general in the following three paragraphs and in detail after that.

The Local Oscillator is used when measuring in the zoom mode. It is set to the center frequency value of the zoom measurement and mixed with the incoming signal. The generated result is then FFTed and displayed. It is also used to shift the frequency band of the noise source so the resulting frequency content of the noise will track that of the measurement span.

The Noise Source generates random, periodic random and impulse signals which are band limited as determined by the frequency span of the measurement. The output is connected to the rear panel SOURCE BNC.

The HP-IB circuitry uses an Integrated Circuit to interface the -hp-3561A with the IEEE-488-1978 interface bus.

The theory that follows describes the functional blocks of each of the three previously mentioned operational circuits. Table 7-36 identifies and describes the signals used on this assembly.

[A] PHASE LATCH

The Phase Latch loads and stores the desired Local Oscillator frequency from the processor data bus. The data is actually a phase increment where 360 degrees equals 256kHz.

[B] PHASE CORRECTION

The Phase Correction contains the phase information of the local oscillator signal. This information is read by the processor so it can determine the phase of the input signal being measured.

[C] PHASE INCREMENT ADDER

This circuit adds the phase increment with the prior phase to calculate the new current phase with the increment ROM. The increment ROM performs a modulus 125 conversion of the lower 7 bits of the phase.

[D] ANGLE ACCUMULATOR

The Angle Accumulator latches the current phase angle which is fed back to the input of the Phase Increment Adder [C], to the Interpolator [J] and to the Sine Table [G].

[E] TIMING STATE MACHINE

The Timing State Machine generates the clock signals which control the timing of the A50 Assembly.

[F] QUADRANT SHIFTER

The Quadrant Shifter keeps track of which of the four quadrants (90 degrees each) the Local Oscillator is in. The states of AP18 and AP19 determine which quadrant and LOSM1 determines Sine or Cosine.

[G] SINE TABLE

These two ROMs contain both the 15 bit Sine/Cosine values for angles at increments of about 0.09 degrees, and the 8 bit slope numbers which allow the Local Oscillator to compute values for in-between angles. U507 contains the LSB bits for the sine values and U506 contains the MSB bits for the sine values along with the 8 bit slope numbers.

[H] SLOPE DATA REGISTER

This circuit is a parallel-in serial-out register which loads the Slope information from the Sine Table circuit and shifts it out serially to the Interpolator [J].

[I] SINE DATA REGISTER

This is a parallel-in serial-out circuit which loads in the sine data from the sine table and shifts it out to the Interpolator [J].

[J] INTERPOLATOR

The Interpolator circuit takes the slope information and the quadrant information and calculates the sine values for the 250 points between the sine points stored in the sine table ROMs. The interpolated result is output to the Local Oscillator Output [L].

[K] GCLOCK GENERATOR

The GCLOCK signal is the main A50 Assembly clock. In normal operation, it runs at 10.24 MHz. When the -hp-3561A operates in External Sample Rate, GCLOCK becomes a pulse train of 40 pulses, each train comprising one complete Local Oscillator cycle. Each train is started by a rising edge of SYNC2. SYNC2 may not exceed 256kHz.

[L] LOCAL OSCILLATOR OUTPUT

The Local Oscillator Output circuit has three data outputs: +COSINE, -SINE and Local Oscillator Output. The +COSINE and -SINE are used to set the center frequency of a zoom measurement. The Local Oscillator Output is used to shift the frequency band of the Noise Source such that the noise source frequency content falls within the bandwidth of the zoom measurement.

[M] I/O CONTROL PORT

This circuit latches processor data bits 0 through 7 which are then used by the A50 Assembly as control signals.

[N] CLOCK
[O] SERIAL FEEDBACK REGISTERS
[P] NOISE SOURCE ROM ADDRESS REGISTERS

In random mode, the Serial Feedback Registers and the Noise Source Address Registers form a 36 bit shift register. Input bits are generated by Exclusive ORing bits 13 and 33 and inverting the result. In effect, the circuit is a digital tapped delay line.

In Pseudo-random and Impulse modes, the Noise Source ROM Address Registers form a 12 bit counter which steps through the 4096 baseband or 2048 zoom points.

[Q] RANDOM NOISE ROM
[R] PERIODIC NOISE ROM

ROM U700 takes the fourteen address bits and filters them by doing a weighted sum. Bits 6 and 7 weigh most heavily, bits 0 and 13 are weighted the least. U700 contains the sequences for a random signal. U701 contains the sequences for periodic random and impulse signals but does not act as a filter.

[T] CLOCK SYNCHRONIZING LATCH

This circuit latches the data from the noise ROMs and at the correct time, shifts the data out to the mixer circuitry.

[W] LOCAL OSCILLATOR/NOISE SOURCE MIXER
[X] LOCAL OSCILLATOR INTERFACE

U201 takes the parallel Local Oscillator data and shifts it out serially to U704 where it is multiplied by the noise data. In Zoom, the Local Oscillator data shifts the frequency spectrum of the noise data so it is centered around the measurement's center frequency.

[AA] SERIAL TO PARALLEL CONVERTER
[CC] D TO A CONVERTER
[FF] PROGRAMMABLE LOG ATTENUATOR

The noise data is converted from serial to parallel by U306 and latched by U307. The digital parallel output is then converted to an analog signal by U402 and buffered by U403. The analog output is then fed to a log programmable attenuator U400.

Table 7-36 A50 Assembly Signal Descriptions

Signal	Description
BBS	BaseBand Sync: Indicates the end of a baseband record.
$\overline{\text{BB}}$/ZOOM	$\overline{\text{BaseBand}}$/ZOOM: Signal from the processor used to setup the A50 Assembly for Baseband or Zoom measurements.
CSR1 THROUGH CSR4	Chip Select Read 1 through 4: Processor Address signals used to enable various ports to output their data.
CSW1 THROUGH CSW4	Chip Select Write 1 through 4: Processor Address signals used to enable various ports to input data.
ESR*4	Effective Sample Rate multiplied by 4: Used by the A50 Assembly as a clock. The effective sample rate is the ADC sample rate clock.
GCLOCK	Gated CLOCK: This is the main processing clock for the A50 Assembly. It is a 40 pulse clock train running at 256kHz.
$\overline{\text{LOS}}$	Local Oscillator Select: Processor Address signal used to access the A50 Assembly input and output ports.
LOSM1 THROUGH LSOMB	Local Oscillator State Machine 1 through 8: 8 Clocks generated by the A50 State Machine which provide the timing for the A50 Assembly.
NB0 THROUGH NB7	Noise Bit 0 through 7: 8 Data bits output by the two noise ROMs.
$\overline{\text{PER}}$/IMP	$\overline{\text{PERiodic}}$/IMPulse: Processor setup signal used in conjunction with the RANDOM signal to enable either the periodic or the impulse noise output.
RANDOM	RANDOM: Processor setup signal used to enable the A50 Assembly to be in the random or periodic/impulse mode of operation.
SB0 THROUGH SBD	Source Bits 0 through D: 14 Address bits which are generated by the ROM Address Counter circuit and are used to address the data locations within the Noise ROMs U700 and U701.
SYNC2	SYNC2: Sample rate clock from the A20 Assembly. A rising edge triggers one cycle of the Local Oscillator. When cycled, the A50 Assembly outputs one complex value to the Digital Filters and one real value to the source.
TRIG0 TRIG1	TRIGger0 and TRIGger2: Processor signals which determine which trigger source the -hp-3561A will use. This circuit function runs independently of the rest of the A50 Assembly.
ZPH TRIGGER	Zoom PHase TRIGGER: Processor signal used to latch information into the phase correction latches.
ZS	Zoom Sync: Used in the Zoom mode to indicate the end of a record. This signal has the same function the BBS signal has in Baseband measurements.

7-21 Troubleshooting The Local Oscillator/Noise Source

GENERAL

Although there are only three major operational circuits, there are eight separate subcircuits. The troubleshooting procedure will be to verify proper operation of particular subcircuits, one at a time, in order of dependency. Table 7-37 lists the order of dependency. In this table, level one circuits must be operational before level two circuits can be checked, etcetera. Test Routines 150, 151, 152, 153 and 154 will be used to troubleshoot this assembly. Troubleshooting consists of verifying waveforms with an oscilloscope and Digital Signature Analysis. Also, some user-programmable parameters entered via the front panel keys are used to preset circuit conditions.

Table 7-37 A50 Circuit Troubleshooting Order

Level	Functional Blocks
1	Processor Address Decoding: S
2	I/O Control Port: M
3	GCLOCK Generator: K
4	Timing State Machine: E
5	Local Oscillator Circuitry: A, B, C, D, E, F, G, H, I, J, K, L
6	Local Oscillator Interface: X
7	Noise Source Circuitry: N, O, P, Q, R, T, U, V, W, Y, Z, AA, BB, CC, EE, FF, HH, II
8	HP-IB I/O Circuitry: DD, GG

[S] PROCESSOR ADDRESS DECODING

Troubleshoot this circuit using the Signature Analyzer as a logic probe. The procedure will be to monitor the pins of U501 while running or starting and stopping the diagnostic test.

1. Program the -hp-3561A in Test Routine 150 by pressing the following front panel keys:

   MODE ..... TEST SELECT..... .....150 ENTER

2. Initiate continuous testing by pressing the START CONT TST softkey.

3. Use the logic probe and verify that U501(12,13,14,15) are toggling. If they are not, replace U501.

4. Stop the test by pressing the softkey STOP TEST.

5. Place the logic probe on U501(10, 11) one at a time and press the soft key START SNGL TST. These pins should pulse low when the test routine is initiated. If they do not, replace U501.

[M] I/O CONTROL PORT

Troubleshoot this circuit using the Signature Analyzer as a logic probe. The procedure will be to monitor U602(6,9,12,16) while initiating particular measurement parameters.

1. Press the front panel PRESET key.

2. Press the front panel TRIG SEL key to display the trigger selection menu on the CRT.

3. Use the logic probe to verify that U602(6,9) are low.

4. Press the softkey FREE RUN/TRIGGER so TRIGGER is highlighted.

5. Probe U602(6,9) and press the softkey EXTERNAL TRIGGER and verify that they go high. Press the softkey INTERNAL TRIGGER and verify that they go low. If not, replace U602.

6. Press the front panel PRESET key.

7. Press the front panel SOURCE key to display the source selection menu on the CRT.

8. Use the logic probe to verify that U602(12) is high and U602(16) is low.

9. Probe U602(12,16) and press the softkey IMPULSE and verify that they change state. Pin 12 should go low and pin 16 should go high. If not, replace U602.

[K] GCLOCK GENERATOR

Troubleshoot this circuit by using the Signature Analyzer as a logic probe. The procedure will be to monitor the pins of U500 and U505 for a toggling condition with the -hp-3561A running in the PRESET state.

1. Press the front panel PRESET key.

2. Use the logic probe and verify that U500(1,3,6) and U505(1,6,9,11) are toggling.

3. If U500(1) is not toggling, check U807(1) for a toggling condition. If it is not toggling, there may be a failure in the Timing State Machine. Troubleshoot that circuit.

4. If any of the pins are not toggling, replace the suspected IC.

[E] TIMING STATE MACHINE

Troubleshoot this circuit by using the Signature Analyzer as a logic probe. The procedure will be to monitor the pins of U606 for a toggling condition while the -hp-3561A is operating in the PRESET state.

1. Press the front panel PRESET key.

2. Use the logic probe and verify that U606(6,7,8,9 and 12 through 19) are toggling.

3. If any are not, replace the suspected IC. Also note that the outputs of U606 (LOSM1 through LOSM8) clock other functional circuits which may be holding these output lines low or high.

LOCAL OSCILLATOR CIRCUITRY

Troubleshooting this circuitry consists of verifying signatures with a Signature Analyzer while running a diagnostic test routine. The Local Oscillator Functional Circuits are listed below along with the table which contains their correct signatures.

[A] Phase Latch	Table 7-38
[B] Phase Correction	Table 7-38
[C] Phase Increment Adder	Table 7-38
[D] Angle Accumulator	Table 7-38
[F] Quadrant Shifter	Table 7-38
[G] Sine Table	Table 7-39
[H] Slope Data Register	Table 7-40
[I] Sine Data Register	Table 7-40
[J] Interpolator	Table 7-40
[L] Local Oscillator Output	Table 7-40

1. Program the -hp-3561A into Test Routine 150 by pressing the following front panel keys:

   MODE ..... TEST SELECT..... .....150 ENTER

2. Initiate continuous testing by pressing the START CONT TST softkey.

3. Check the signatures given in Table 7-38 to troubleshoot those functional circuits listed.

4. Check the signatures given in Table 7-39 to troubleshoot the Sine Table ROMs. Note that there are two setups for the Signature Analyzer Clock. Both setups must be checked.

5. Check the signatures given in Table 7-40 to troubleshoot those functional circuits listed.

Table 7-38 Local Oscillator Signatures For Functional Circuits [A], [C], [D] And [F]

Signature Analyzer Setup

Signal	Polarity	Connection
Clock	⌐‾	A50 J1 "LOSM1"
Start	⌐‾	A50 J100 "STRT"
Stop	‾⌐	A50 J100 "STOP"

+5 V Signature - 5C1C

[A] Phase Latch Circuit

U504(2)	8UA8
U504(5)	6P45
U504(6)	9231
U504(9)	F7H4
U504(12)	41C4
U504(15)	CU8P
U504(16)	157F
U504(19)	564F
U600(2)	46U9
U600(5)	5H83
U600(6)	CF6P
U600(9)	U0AC
U600(12)	A54P
U600(15)	232P
U600(16)	HH14
U600(19)	77P6
U601(2)	2951
U601(5)	8ACP
U601(6)	2C26
U601(9)	5C1C
U601(12)	5C1C (HIGH)

[C] Phase Increment Adder Circuit

U6(1)	15F1
U6(4)	H2A1
U6(10)	HFUC
U6(13)	1FP8
U8(1)	486U
U8(4)	U914
U8(10)	4949
U8(13)	7098
U9(1)	40AP
U9(4)	5A19
U9(10)	4894
U9(13)	7177
U106(1)	FFU2
U106(4)	84AP
U106(10)	HOFP
U106(13)	C804
U107(1)	UC4H
U107(4)	3PHC
U107(10)	00F9
U107(13)	199C

Table 7-38 Local Oscillator Signatures for Functional Circuits [A], [C], [D] and [F] (Cont'd)

[D] Angle Accumulator Circuit		[F] Quadrant Shifter Circuit	
U1(2)	384F	U5(1)	3C12
U1(5)	24A4	U5(4)	H56U
U1(7)	6950	U5(10)	5C1C
U1(10)	8AP0	U5(13)	7F80
U1(12)	8P74		
U1(15)	PP7H		
U102(2)	F257		
U102(5)	5A27		
U102(6)	F0UA		
U102(9)	U125		
U102(12)	C715		
U102(15)	F785		
U102(16)	HAA1		
U102(19)	AU52		
U105(2)	AH0F		
U105(5)	2057		
U105(7)	38CC		
U105(10)	A44A		
U105(12)	UF8A		
U105(15)	A437		

Table 7-39 Local Oscillator Signatures For Functional Circuit [G]

There are two Signature Analyzer setups necessary to check the ROMs. Both setups are given along with the signatures. If there is a signature mismatch in either setup, replace the defective ROM.

Signature Analyzer Setup #1

Signal	Polarity	Connection
Clock		A50 J1 "LOSM6"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"

+5 V Signature - 7576

U506(9)	4209	U507(9)	UPPC
U506(10)	111H	U507(10)	330P
U506(11)	2C70	U507(11)	34FA
U506(13)	C1AP	U507(13)	9CP5
U506(14)	45FH	U507(14)	UP0F
U506(15)	HC46	U507(15)	C525
U506(16)	H148	U507(16)	06U3
U506(17)	0000	U507(17)	3AU3

Signature Analyzer Setup #2

Signal	Polarity	Connection
Clock		A50 J1 "LOSM6"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"

+5 V Signature - 7576

U506(9)	C941	U507(9)	UPPC
U506(10)	3H95	U507(10)	330P
U506(11)	41HP	U507(11)	34FA
U506(13)	11U5	U507(13)	9CP5
U506(14)	H401	U507(14)	UP0F
U506(15)	05F7	U507(15)	C525
U506(16)	49P9	U507(16)	06U3
U506(17)	UH5A	U507(17)	3AU3

Table 7-40 Local Oscillator Signatures For Functional Circuits [H], [I], [J] And [L]

There are two Signature Analyzer setups necessary to fully check functional circuit [J] Interpolator. The first setup is used to check all four functional circuits while the second setup is only used as a second check for functional circuit [J].

Signature Analyzer Setup #1

Signal	Polarity	Connection
Clock		A50 J100 "CLK"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"

+5 V Signature - C21U

[H] Slope Data Register		[L] Local Oscillator Output	
U7(2)	UFAA	U200(3)	C97H
U7(12)	CUPA	U200(7)	5220
		U200(8)	1HAH
[I] Sine Data Register			
		U200(9)	PO96
U502(13)	C3F0	U200(10)	6P07
U502(15)	AUC8	U200(11)	5P3U
		U200(13)	717C
[J] Interpolator			
		U200(14)	A75H
U101(6)	3UAU	U200(15)	U8C3
U4(3)	0460		
U4(10)	0813		

The following Signature Analyzer setup is for functional circuit [J] Interpolator only.

Signature Analyzer Setup #2

Signal	Polarity	Connection
Clock		A50 J100 "CLK"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"

+5 V Signature - C21U

[J] Interpolator		
U3(2)	2F80	
U3(9)	49C5	

[X] LOCAL OSCILLATOR INTERFACE

Troubleshoot this circuit by verifying the signatures with a Signature Analyzer while running Diagnostic Test Routine 150.

1. Program the -hp-3561A into Test Routine 150 by pressing the following front panel keys:

   MODE ..... TEST SELECT..... .....150 ENTER

2. Initiate the continuous testing by pressing the START CONT TST softkey.

3. Check the signatures given in Table 7-41 to troubleshoot Functional Circuit [X].

Table 7-41 Local Oscillator Interface Signatures For Functional Circuit [X]

Signature Analyzer Setup		
Signal	**Polarity**	**Connection**
Clock		A50 J100 "CLK"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"
+5 V Signature - C21U		
[X] Local Oscillator Interface		
U201(12)	6P58	
U302(8)	5220	
U302(11)	0000	

NOISE SOURCE CIRCUITRY

There are two techniques used to troubleshoot the Noise Source circuitry. The first is to use an oscilloscope to check analog waveforms while running Diagnostic Test Routine 151. This Test Routine programs the Noise Source to output a 250 Hz Sinewave and is used to troubleshoot the analog portion of the Noise Source circuitry. The second technique is to use a Signature Analyzer to verify the proper operation of the digital portion of the Noise Source. Test Routines 150, 152 and 153 are used for Signature Analysis troubleshooting.

The Noise Source Functional Circuits are listed below in the order in which they should be checked. Also listed is the table or figure which contains their correct signatures or waveforms.

Note that the troubleshooting order does not match the table order. Instead, the tables are organized as determined by the Signature Analyzer Setup.

[O] Serial Feedback Registers	Table 7-42
[P] Noise Source ROM Address Counters	Table 7-42
[Q] Random Noise ROM	Table 7-43
[R] Periodic Noise ROM	Table 7-42
[T] Clock Synchronizing Latch	Table 7-42
[W] Local Oscillator/Noise Source Mixer	Table 7-44
[AA] Serial To Parallel Data Converter	Table 7-44
[CC] D/A Converter	Figure 7-29
[FF] Programmable Log Attenuator	Figure 7-30
[HH] 100kHz Lowpass	Figure 7-31
[II] Output	Figure 7-32
[EE] Noise Source Sync Generator	Table 7-43
[Y] Trigger Select	Table 7-43

1. Program the -hp-3561A into the proper Test Routine, as determined by the table, by pressing the following front panel keys:

   MODE . . . . . TEST SELECT . . . . . xxx ENTER

   Where xxx is the Test Routine Number (150, 151, 152 or 153).

2. Before checking signatures or waveforms, initiate continuous testing mode by pressing the START CONT TST softkey.

3. Check the signatures or the waveforms given in the appropriate table to troubleshoot the functional circuits indicated by that table.

Table 7-42 Noise Source Signatures For Functional Circuits [O], [P], [R], And [T]

The following signatures are valid with the -hp-3561A running Diagnostic Test Routine 152.

Signature Analyzer Setup

Signal	Polarity	Connection
Clock		A50 J200 "CLK"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"

+5 V Signature - 5C1C

[O] Serial Feedback Register

U100(7)	36U6
U202(3)	PH8H
U202(4)	U6F6
U202(13)	4C81
U203(13)	FFFC
U300(10)	F3UU
U302(6)	2P72
U801(4)	6HPH

[P] Noise Source ROM Address Counters

U204(11)	1C7C
U204(12)	36U6
U204(13)	6HPH
U204(14)	36U6
U204(15)	0000 (LOW)
U205(11)	C1C7
U205(12)	636U
U205(13)	F6HP
U205(14)	8HCH
U205(15)	0000 (LOW)
U206(11)	HC1C
U206(12)	C636
U206(13)	6F6H
U206(14)	H8HC
U206(15)	0000 (LOW)

[R] Periodic Noise ROM

U701(11)	26FP
U701(12)	U1U8
U701(13)	HP35
U701(15)	8U6H
U701(16)	P180
U701(17)	A49P
U701(18)	4CC3
U701(19)	F270

[T] Clock Synchronizing Latch

U702(2)	97AP
U702(5)	A5H9
U702(6)	A4H9
U702(9)	U0F0
U702(12)	47C6
U702(15)	998F
U702(16)	78UF
U702(19)	65U1
U806(11)	0000 (LOW)
U807(8)	5C1C (HIGH)

Table 7-43 Noise Source Signatures For Functional Circuits [Q], [Y] And [EE]

The following signatures are valid with the -hp-3561A running in Test Routine 153.

Signature Analyzer Setup

Signal	Polarity	Connection
Clock		A50 J200 "CLK"
Start		A50 J200 "STRT"
Stop		A50 J200 "STOP"

+5 V Signature - 7A70

[Q] Random Noise ROM

U700(11)	P103
U700(12)	518P
U700(13)	A3AP
U700(15)	0402
U700(16)	H977
U700(17)	UUFP
U700(18)	7979
U700(19)	H918

[Y] Trigger Select

U808(7)	F748

[EE] Noise Source Sync Generator

U304(9)	F748
U305(8)	99H4
U500(8)	7A70 (HIGH)
U803(6)	P3A4

Table 7-44 Noise Source Signatures For Functional Circuits [W] And [AA]

The following signatures are valid with the -hp-3561A running Diagnostic Test Routine 150. Note there are two Signature Analyzer setups for checking Functional Circuit [AA].

Signature Analyzer Setup #1

Signal	Polarity	Connection
Clock		A50 J100 "CLK"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"

+5 V Signature - C21U

[W] Local Oscillator/Noise Source Mixer

U704(6)	0AFF

[AA] Serial To Parallel Data Converter

U306(3)	PP76
U306(4)	1F2C
U306(5)	P505
U306(6)	1992
U306(10)	P7H9
U306(11)	18UF
U306(12)	P76P
U306(13)	18A7
U806(6)	AH88

Signature Analyzer Setup #2

Signal	Polarity	Connection
Clock		A50 J100 "CLK"
Start		A50 J100 "STRT"
Stop		A50 J100 "STOP"

+5 V Signature - C21U

[AA] Serial To Parallel Data Converter

U307(2)	42UA	U307(12)	3PCP
U307(5)	C5P8	U307(15)	8P5P
U307(6)	FU52	U307(16)	0AA3
U307(9)	CU5A	U307(19)	4U63
U801(8)	C8H3		

NOISE SOURCE TROUBLESHOOTING WAVEFORMS FOR FUNCTIONAL CIRCUITS [CC], [FF], [HH] AND [II].

The following troubleshooting information is valid with the -hp-3561A running Diagnostic Test Routine 151.

[CC] D/A CONVERTER

Verify the waveform at TP DAC OUT with that shown in Figure 7-29. If the waveform is incorrect, use a Logic Probe to verify that U402(5,6,7,8,9,10,11,12) are toggling. If they are, replace U402 and U403 or the analog elements around them. If they are not, troubleshoot Functional Circuit [AA].

[FF] PROGRAMMABLE LOG ATTENUATOR

Verify the waveform at U401(6) with that shown in Figure 7-30. If the waveform is incorrect, use the logic probe to verify that U400(2,3,4,5,6,7) are all low. If they are not, replace U303. If they are, replace U400 and U401.

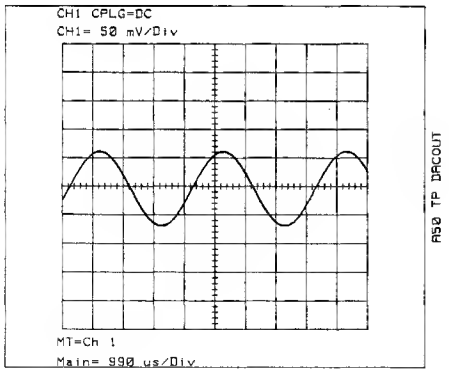
[HH] 100kHz LOWPASS

Verify the waveform at U404(6) with that shown in Figure 7-31. If the waveform is incorrect, troubleshoot this circuit.

[II] OUTPUT

Verify the waveform at U901(4) with that shown in Figure 7-32. If the waveform is incorrect, troubleshoot this circuit.

Figure 7-29 Correct Waveform At A50 TP DAC OUT.

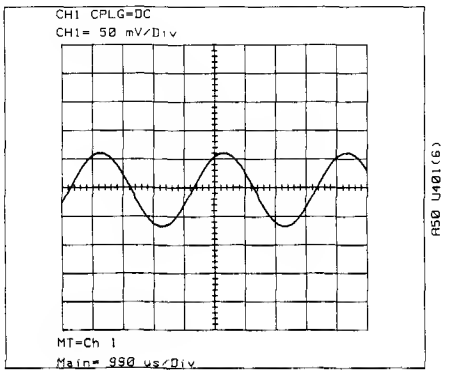


Probe: 10:1

Ch1: Connection- A50 TP DACOUT
Coupling- dc
Ground- Center Graticule

Trigger: Internal Ch1
Slope- Positive

Figure 7-30 Correct Waveform At A50U401(6).

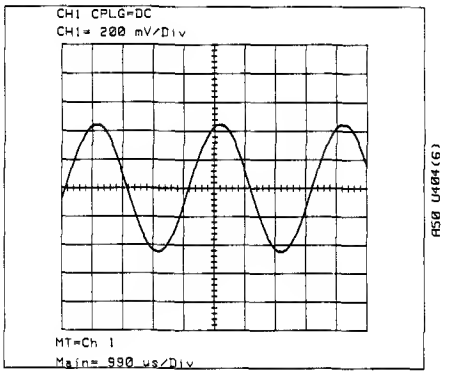


Probe: 10:1

Ch1: Connection- A50 U401(6)
Coupling- dc
Ground- Center Graticule

Trigger: Internal Ch1
Slope- Positive

Figure 7-31 Correct Waveform At A50U404(6).

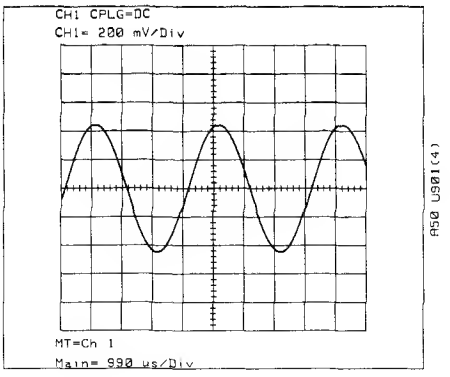


Probe: 10:1

Ch1: Connection- A50 U404(6)
Coupling- dc
Ground- Center Graticule

Trigger: Internal Ch1
Slope- Positive

Figure 7-32 Correct Waveform At A50U901(4).



Probe: 10:1

Ch1: Connection- U901(4)
Coupling- dc
Ground- Center Graticule

Trigger: Internal Ch1
Slope- Positive

HP-IB I/O CIRCUITRY

Test Routine 154 is used to troubleshoot the HP-IB circuitry. This test routine allows the processor to monitor the I/O pins of the HP-IB connector and display their status on the -hp-3561A CRT. While the test is running, the HP-IB connector pins must be shorted to ground one at a time. When this is done, the CRT display will so indicate. The HP-IB connector is located on the rear panel of the instrument.

Use the following procedure to initiate and operate Test Routine 154:

1. Program the -hp-3561A to run the test by pressing the following front panel keys:

   PRESET
   MODE ..... TEST SELECT..... .....154 ENTER
   START CONT TST

   The CRT should indicate that Test 154 is in progress and to press the STOP TEST key to abort the test. The STOP TEST key must be pressed to exit this test! Failure to do this will result in -hp-3561A operating errors. The CRT should also display the HP-IB I/O connector signal names, pin numbers and pin state in six columns as shown next:

DIO1	1	0	0	13	DIO5
DIO2	2	0	0	14	DIO6
DIO3	3	0	0	15	DIO7
DIO4	4	0	0	16	DIO8
EOI	5	0	0	17	REN
DAV	6	0	0	18	GND
NRFD	7	0	0	19	GND
NDAC	8	0	0	20	GND
IFC	9	0	0	21	GND
SRQ	10	0	0	22	GND
ATN	11	0	0	23	GND
SHLD	12	0	0	24	IGND

   Columns one and six identify the signal names, columns two and five identify the connector pin numbers and columns three and four identify the state of the pins (O indicates high, # indicates low).

2. Short the I/O pins to chassis ground one at a time. The shorted pin will cause the CRT to display a # instead of an O next to the corresponding pin number.

   For example: Short connector pin number 1 to chassis ground. This will cause the CRT to display

   DIO1 1 # 0 13 DIO5

No other pins should be affected. If any other pins are affected, ground U900(19). If the CRT indicates correctly, there is a short in the I/O connector, cable or U900. If other pins are still affected, the problem may be in U805.

3. Perform step 2 for the remaining signal pins with the exception of pin 11 ATN. Proceed to step 4 for this pin.

   Note that the grounding of the IGND, GND and SHLD pins will not affect the CRT display. If there is a problem with all of the pins, U805 and/or U804 may be defective.

4. When pin 11, ATN, is grounded, the CRT will display the following:

DIO1	1	?	?	13	DIO5
DIO2	2	?	?	14	DIO6
DIO3	3	?	?	15	DIO7
DIO4	4	?	?	16	DIO8
EOI	5	?	?	17	REN
DAV	6	?	O	18	GND
NRFD	7	?	O	19	GND
NDAC	8	?	O	20	GND
IFC	9	?	O	21	GND
SRQ	10	?	O	22	GND
ATN	11	#	O	23	GND
SHLD	12	O	O	24	IGND

   If not, ground U805(28). If the CRT display is correct, replace U903. If the CRT is still incorrect, the problem may be U805 and/or U804.

Table 7-45 A50 Assembly Signal Connections

INPUTS

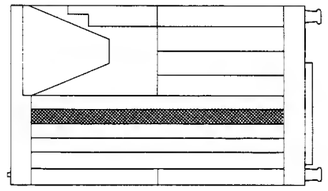
Signal Name	Functional Block	Connector Number	Origin Assembly
ESR*4	N	P51(B3)	A20
EXT TRIG	Y	P51(A8)	A82
HPIBS	GG	P51(A11)	A40
LOS_	S	P51(A10)	A40
PBR/W	GG	P51(A13)	A40
PBUDS	GG	P51(B13)	A40
RESET	GG	P51(A3)	A40
SYNC2	K	P51(A5)	A20
ZPHTRIG	B	P51(A9)	A20
4 MHz	GG	P51(A2)	A40
10.24 MHz	K	P51(B2)	A20

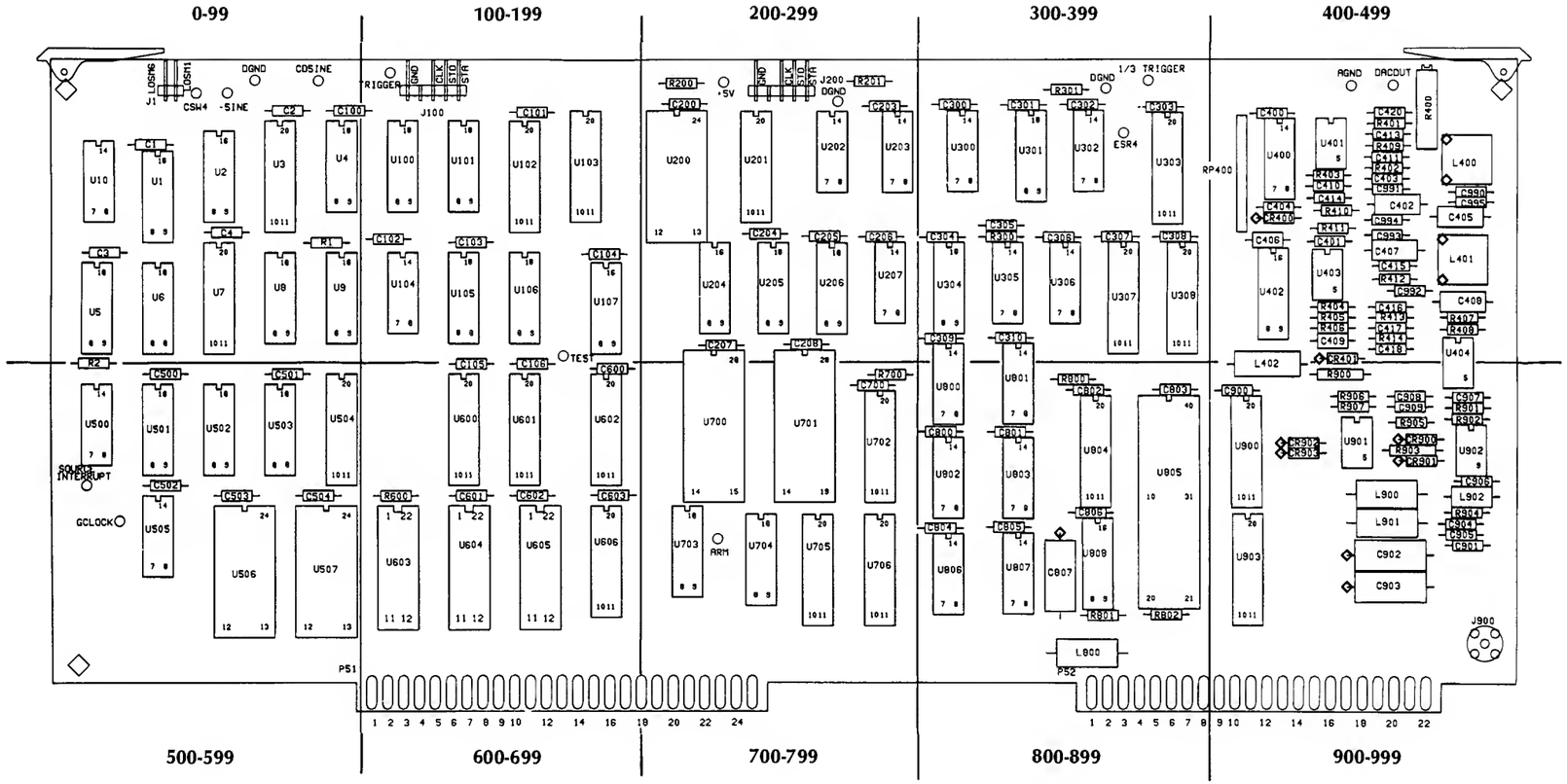
OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assemblies
COSINE	L	P51(B8)	A20
HPCI	GG	P51(A7)	A40
HPDI	DD	P51(A6)	A40
NOISE	II	P52(B21)	A82
PRN SYNC	EE	P52(A21)	A82
SINT	EE	P51(A12)	A40
-SINE	L	P51(A8)	A20

I/O SIGNALS

Signal Name	Functional Block	Connector Number	Destination Assembly
HPIB Data Bus DIO1 - DIO8	GG	P52(A11 - A14) P52(B11 - B14)	A82
HPIB I/O Control signals			
ATN	GG	P52(A18)	A82
DAV	GG	P52(B16)	A82
EOI	GG	P52(B15)	A82
IFC	GG	P52(A16)	A82
NDAC	GG	P52(B18)	A82
NRFD	GG	P52(B17)	A82
REN	GG	P52(A15)	A82
SRQ	GG	P52(A17)	A82
Processor Address Bus PAB0 - PAB2	GG	P52(A16,B15,B16)	A40, A60, A66/65
Processor Data Bus PDB0 - PDBF	A	P51(A17 - A24) P51(B17 - B24)	A30, A40, A60, A66/65

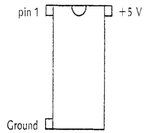



0-99
100-199
200-299
300-399
400-499
500-599
600-699
700-799
800-899
900-999
LOGSIN
QSIN1
DGND
COSINE
CSIN1
-SINE
TRIGGER
J100
GND
CLK
S10
SYR
+5V
J200
1/3 TRIGGER
ESR4
AGND
DACOUT
RP400
TEST
SOURCE INTERRUPT
GCLOCK
ARM
P51
P52
J900

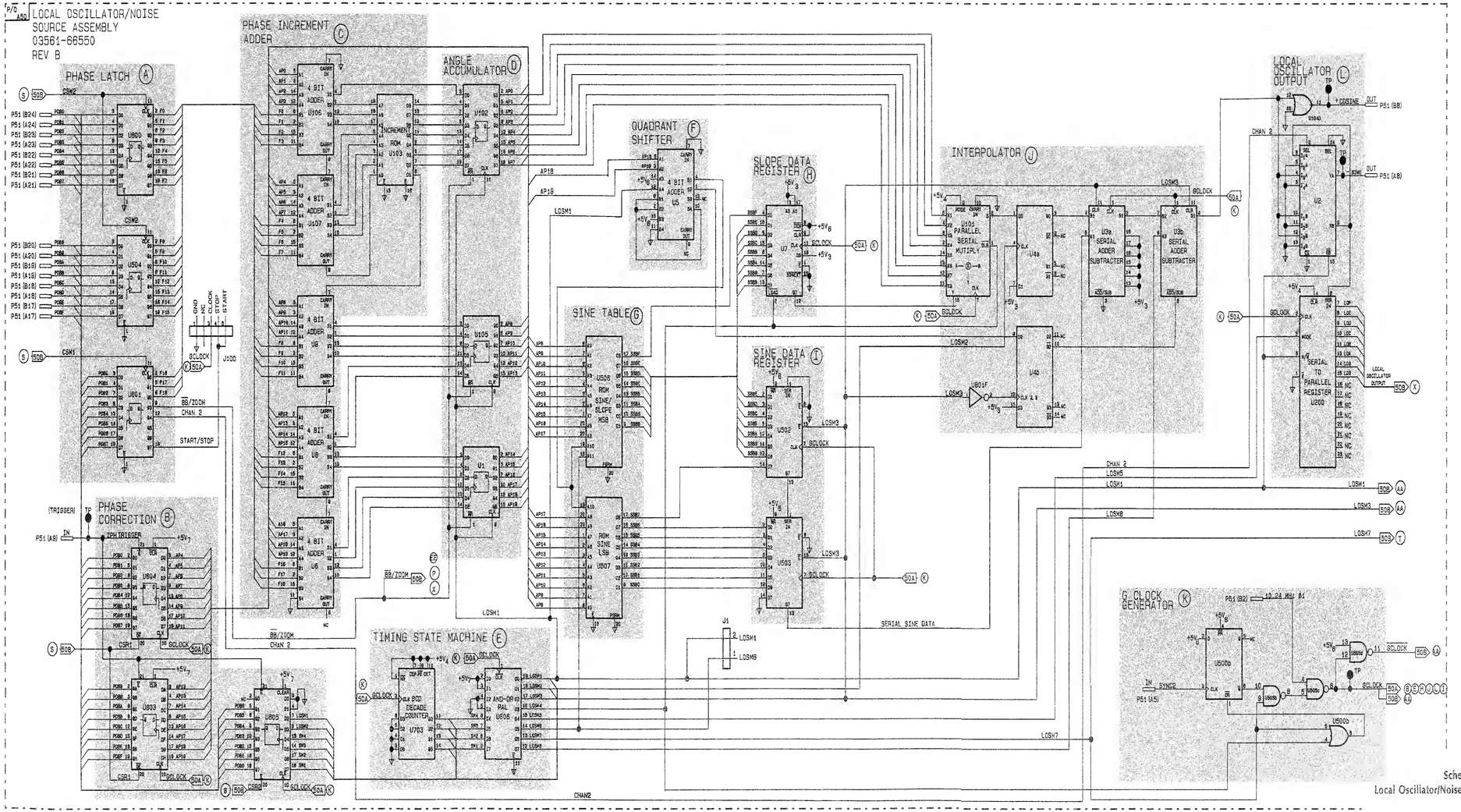
A50 Assembly

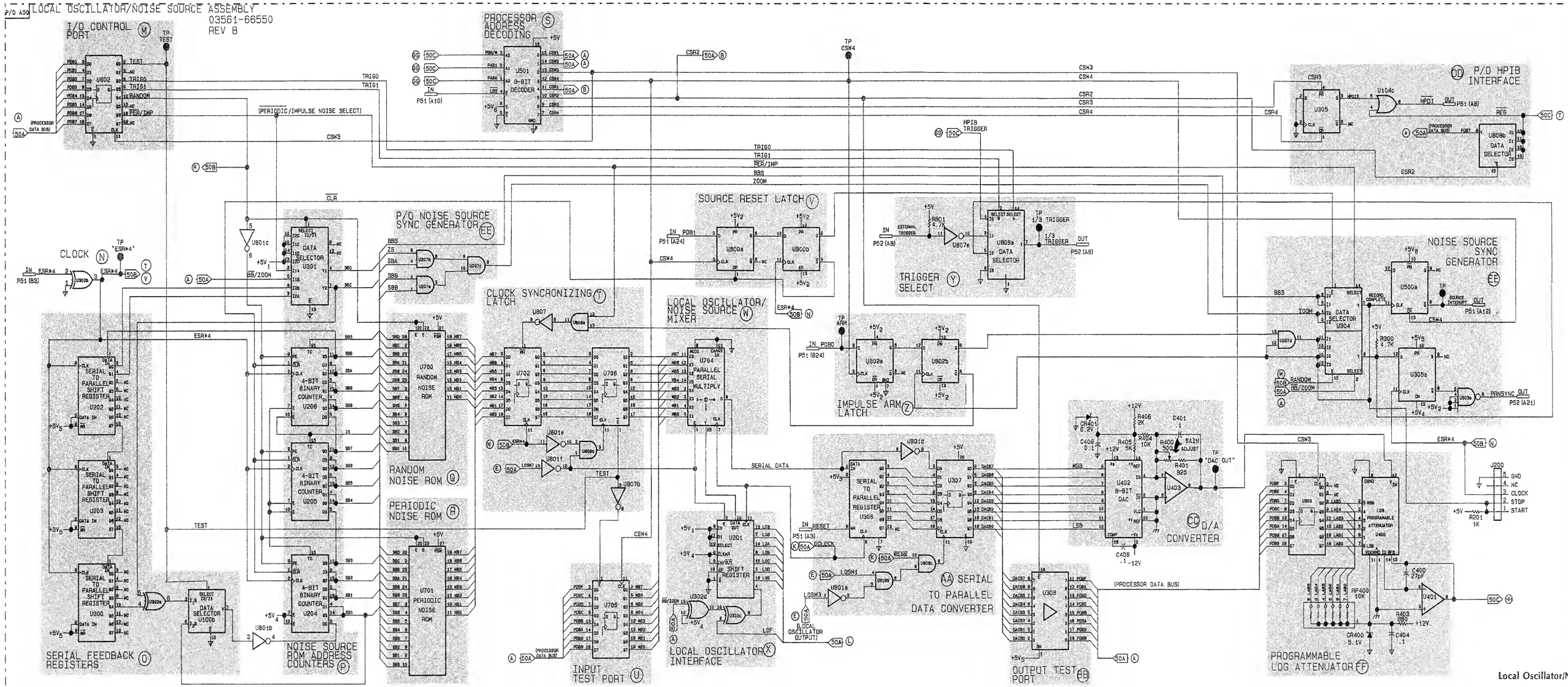
All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)

Corner Power

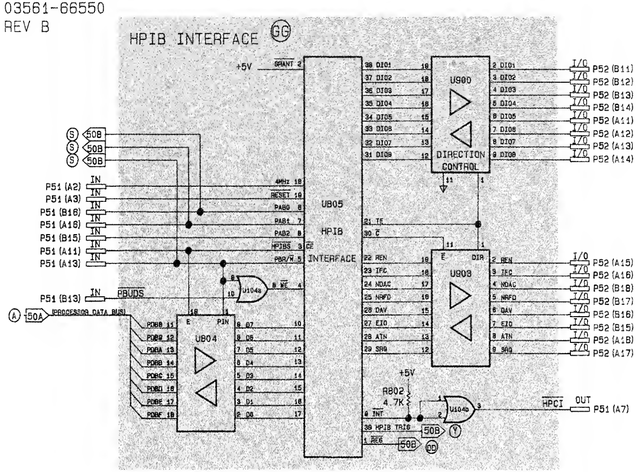


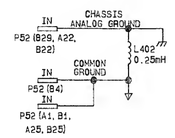
	+12V	+12V$_1$	+12V$_2$	+12V$_3$	+12V$_4$	-12V	-12V$_1$	-12V$_2$	-12V$_3$	-12V$_4$	+5V	GND
U401				7					4			
U402	13					3						
U403					7					4		
U404			7					4				
U506											24,21	12
U507											24,21	12
U805											40	1
U901	1					7						
U902		7					4					

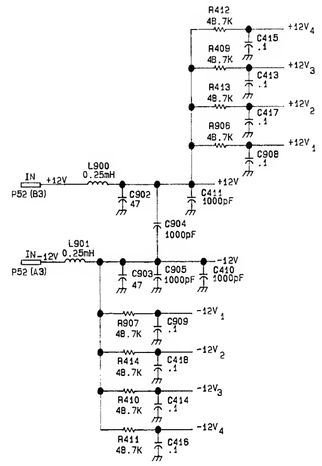


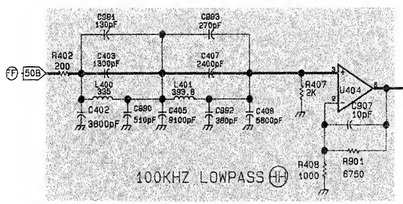


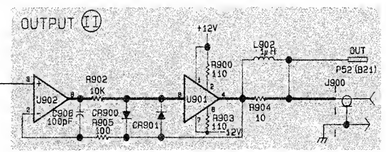
P/O A50 LOCAL OSCILLATOR/NOISE SOURCE ASSEMBLY
03561-66550
REV B

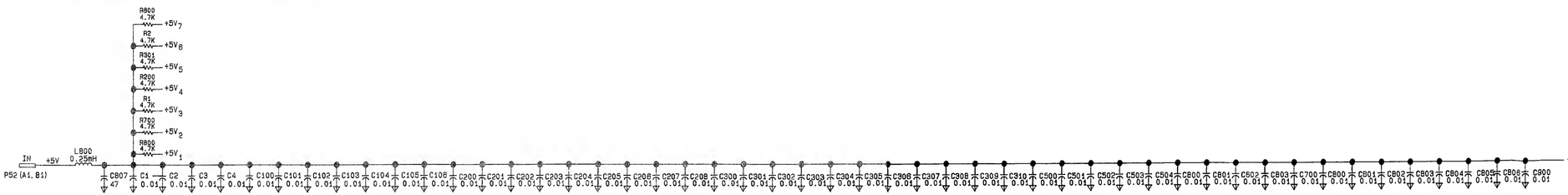












7-22 A60 DIGITAL DISPLAY DRIVER ASSEMBLY

7-23 Digital Display Driver Circuit Description

GENERAL

The -hp-3561A uses a raster scan CRT with a 512 horizontal (X), by 256 vertical (Y) grid screen. (128K total positions). Each grid position is called a pixel, and can be turned on or off by the display driver circuits. The digital display driver contains two 128k bit arrays of RAM; one array for the full bright display and one for the half bright display. Both the full bright display RAM and the half bright display RAM contain one memory location for each pixel on the CRT screen. A "1" stored in the memory location turns the pixel on and a "0" turns the pixel off. Graphics data is written into the display RAM as a series of lines. For each line the processor loads an X and Y axis start address, an X and Y axis increment value and a line length into the A60 Assembly. The A60 Assembly then uses these three values to generate all points of the line, and the addresses needed to store the line in RAM. Alpha-numeric data is directly stored into the RAM through the character writer circuit. Once data has been written into the display it remains there until the processor erases the display or writes new data over it. Display RAM bus cycles alternate between reading data out of RAM to update the CRT screen and writing new data from the processor into RAM. In this way the CRT screen is continuously updated.

[A] INCREMENT REGISTER, [C] POSITION ADDRESS ADDER, [D] POSITION ADDRESS REGISTER

When the processor writes a line to the display RAM these circuits generate the position address for each pixel of of the line. The position address for successive points in the line is obtained by adding the X-increment and Y-increment values to the current X and Y position address.

[B] RAM BYTE ADDRESS REGISTER, [F] RAM BIT ADDRESS REGISTER

These circuits convert the position address register output into a RAM byte address and a RAM bit address. The bit address bus selects one of the eight RAMs in the selected RAM plane and the byte address bus addresses the specific location within the RAM. The byte address consists of two parts: a row address and a column address. The column address is taken from the upper seven bits of the position address register; the row address is taken from the next seven bits. The bottom three bits of the position address register are decoded to form the bit address bus.

[G] MODE CONTROL LATCH, [I] RAM DATA WRITER, [J] CHARACTER WRITER

These circuits generate the data which is stored into the memory location selected by the position address register. Data can be stored into RAM from five different sources. The data source is selected by the processor through the mode control signals M0, M1, and M2. The character writer is selected only when the processor is writing alphanumeric data directly into the display RAM.

Mode Control Signals			Data Source Selected U804	
M0	**M1**	**M2**	**Pin#**	**Description**
0	0	0	4	Write a "0" into RAM; erases the CRT screen at the selected address.
0	0	1	3	Copy the current RAM data at the selected address.
0	1	0	2	Invert the current RAM data at the selected address.
0	1	1	1	Write a "1" into RAM; turns the CRT screen on at the selected address.
1	X	X	12 13 14 15	Write data from the character register into the selected address.

[K] FREE RUN/LINE SYNC TIMING, [L] COLUMN ADDRESS COUNTER, [M] ROW ADDRESS COUNTER

These circuits access the display RAM on every other bus cycle to continuously refresh and update the pattern on the CRT screen. The rate at which the CRT screen is updated is determined by the free run/line sync circuit. When A60J200 is in the sync position the refresh rate is determined by the LSYNC signal, which is locked to the power line frequency. When A60J200 is in the free run position, the refresh rate is fixed at 62.8 Hz. The row address counter and the column address counter cycle through all memory locations for each pattern refresh.

[N] RAM PLANE 1, [O] RAM PLANE 2

Each RAM is a 16k by 1 bit dynamic RAM. The RAM is addressed in a two step process. In the first step, a seven bit row address is latched into the RAM, and in the second step, a seven bit column address is latched into the RAM. The RAM then internally combines these addresses to obtain the location address.

[S] RAM DATA READER

To refresh the CRT screen, the RAM data reader transfers data from the display RAM to the CRT cathode drive circuit. The data is read from the RAM address generated by the row and column address counters. At each address, the BYTE WRITE signal is used to read one bit of data from each of the eight RAMs in plane 1 to generate the VIDF signal, and one bit of data from each of the RAMs in plane 2 to generate the VIDH signal.

[R] FSYNC/SSYNC TIMING

This circuit uses the address counter outputs to generate the CRT vertical and horizontal sweep signals. The slow sync signal (SSYNC) triggers a horizontal sweep and the fast sync signal (FSYNC) triggers a vertical sweep. A new vertical sweep is generated each time the row address counter reaches a count of 38. A new horizontal sweep is generated each time the column address counter reaches its highest count.

[P] COPY/COMPLIMENT DATA FEEDBACK, [Q] PROCESSOR DATA REGISTER

Through these registers, the data in RAM can be read out and transferred back to the RAM data writer. The RAM data writer can then either copy the data directly back into RAM or compliment the data before writing it back into RAM.
Through the processor data register, the processor may read the data stored in the display RAM. This is used only for the the display RAM test at power on.

[T] LINE LENGTH COUNTER

This counter determines the length of the line to be written to the CRT screen. The processor loads the counter with a value equal to the full count minus the line length. When the counter reaches full count a carry is generated ($\overline{\text{CDONE}}$). The $\overline{\text{CDONE}}$ signal clears the position address and stops the line write timing generator.

[W] TIMING GENERATOR, [U] LINE WRITE TIMING GENERATOR
[X] RAM ROW AddRESS STROBE TIMING

These circuits generate all of the timing signals used to generate a line and store it in the display RAM. The line write timing generator starts a sequence when the processor loads the Y increment register and stops when the line length counter issues a $\overline{\text{CDONE}}$ signal.

Table 7-46 A60 Assembly Signal Descriptions

Signal	Description
BIT/BYTE	Low when only one bit of data is being written to or read from the RAM. High to write identical data to all eight RAMs in a plane.
BITCLK	BIT CLocK: Clocks the RAM data into the analog display driver through the RAM data reader.
$\overline{\text{CDONE}}$	Counter DONE: Issued by the line length counter to indicate that the line is complete.
$\overline{\text{CAS}}$	Column Address Strobe: Clocks the column address into the RAM.
$\overline{\text{CLK}}$	Character CLocK: High to enable a read from RAM and low to enable a write to RAM.
$\overline{\text{CRTON}}$	Low to turn the CRT on.
$\overline{\text{CTSEL}}$	CounTer SEL: Loads the line length data into the line length counter.
$\overline{\text{DDBCLK}}$	Display Data FeedBack CLocK: Latches the RAM output data into the feedback register.
$\overline{\text{DNCLK}}$	DowN CLocK: Increments the line length counter and the position address counter by one.
$\overline{\text{DSPH}}$	DiSPlay Holdoff: Indicates to the processor that the current data transfer is complete. This signal also starts the line length timing generator.
$\overline{\text{DSPS}}$	DiSPlay Select: Used by the processor to address the A60 Assembly.
FSYNC	Fast Sweep SYNCronizer: Syncronizes the CRT vertical sweep with the horizontal sweep and the CRT video data.
LSYNC	Line SYNCronizer: Syncronizes the CRT refresh rate to the power line frequency.
PW1, PW2	Plane 1 Write, Plane 2 Write: Programmed by the processor to indicate which RAM plane the data should be written to. Only one of these lines is active at a time.
R/C	Row/Column Address: Low to select the RAM row address on the byte address bus.
R/C	Row/Column Address: Low to select the RAM column address on the byte address bus.
RAS1 RAS2	Ram Address Strobe PLANE1: Clocks the row address into RAM (PLANE1 or PLANE2).
SSYNC	Slow SYNCronizer: Syncronizes the CRT horizontal sweep to the vertical sweep and to the video data.
SSYNCE	Slow SYNCronizer Enable: Enables a SSYNC signal when the column address counter reaches its highest count.

Table 7-46 A60 Assembly Signal Descriptions (Cont'd)

VIDF	VIDeo Full Bright Data: Full bright (PLANE1) RAM data to drive the CRT cathode.
VIDH	VIDeo Half Bright Data: Half bright (PLANE2) RAM data to drive the CRT cathode.
XINC	X-axis INCrement: Loads data into the X-axis increment register.
XSEL	X-axis SELect: Enables data to be clocked into the X-axis increment register.
YINC	Y-axis INCrement: Loads data into the Y-axis increment register, and triggers the line write timing generator to start writing a line to RAM.
YSEL	Y-axis SELect: Enables data to be clocked into the X-axis increment register.

7-24 Troubleshooting the Digital Display Driver

GENERAL

All of the circuits on the A60 Assembly, except the processor interface circuits and the RAM, can be tested with the A60J100 jumper test. The A60J100 jumper test can be run with only the power supply and the A60 Assemblies installed in the the -hp-3561A. The A40W1 jumper test is used to troubleshoot the processor interface circuits, and the power-on test is used to troubleshoot the RAM. These two tests require an operational A40 Assembly to be installed in the -hp-3561A. Failures occurring on the alpha-numerics only are most likely the character writer.

Troubleshoot the circuits on the A60 Assembly in the order given in Table 7-47. In this table, level one circuits must be operational before level two circuits can be tested, etcetera.

Table 7-47 A60 Circuit Troubleshooting Order

Level	Functional Blocks
1	Test Control Circuit: H Timing Circuits: U, V, W, X
2	RAM Address Generation Circuits: C, D, E, F CRT Refresh Timing Circuits: K, L, M, R
3	RAM: N, O
4	RAM Data Reader: S
5	Processor Interface Circuits: A, B, G, J, T, Y

[H] Test Control

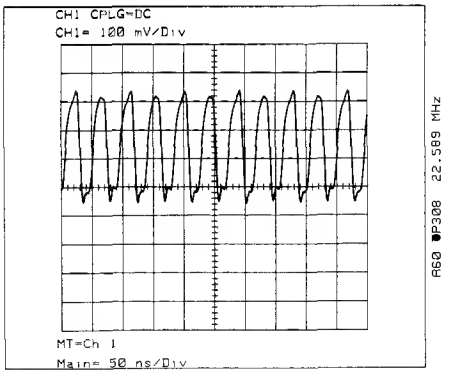
1. Turn the -hp-3561A LINE power switch OFF.
2. Move the A60J100 test jumper to the PLANE1 test position and place the A60 Assembly on an extender board.
3. Turn the -hp-3561A LINE power switch ON.
4. Check the following signals.

U1(8)	TTL high
U205(10)	0 V
U304(3,6,8)	TTL high
U305(5)	TTL high
U401(6)	0 V
U304(3)	TTL high
U805(3)	TTL high
U900(5,9)	TTL high

[U] LINE WRITE TIMING GENERATOR, [V] DISPLAY CLOCK, [W] TIMING GENERATOR, [X] RAM ROW ADDRESS STROBE TIMING

To troubleshoot these circuits move the A60J100 test jumper to the PLANE1 test position and check the waveforms given in Figure 7-33.

Figure 7-33 Clock and Timing Waveforms

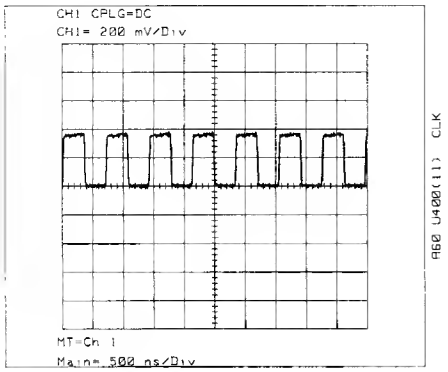


Probe: 10:1

Ch1: Connection- A60 TP308 "22.589 MHz"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

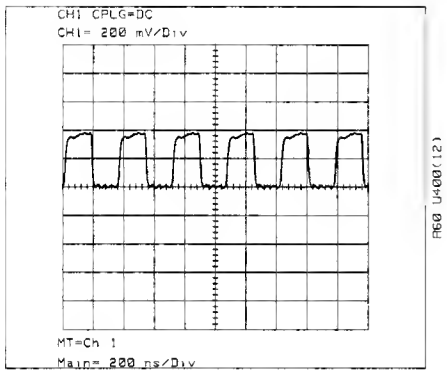


Probe: 10:1

Ch1: Connection- A60 U400(11) "CLK"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

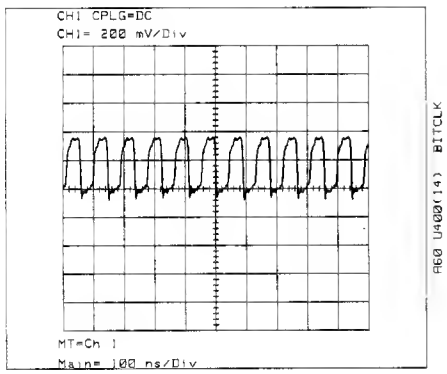


Probe: 10:1

Ch1: Connection- A60 U400(12)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

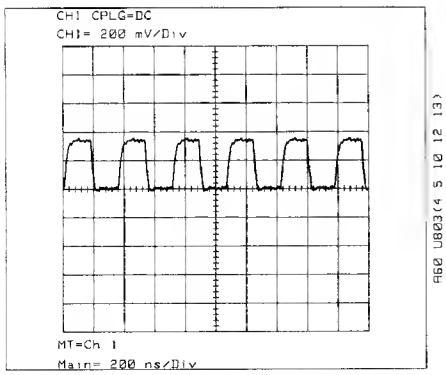


Probe: 10:1

Ch1: Connection- A60 U400(14) "BITCLK"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

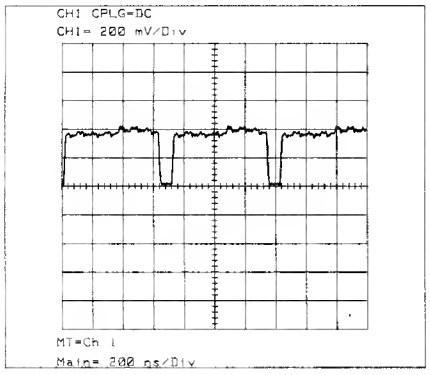


Probe: 10:1

Ch1: Connection- A60 U803(4)
A60 U803(5) "R/C"
A60 U803(10)
A60 U803(12) "R/C"
A60 U803(13) "CAS"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

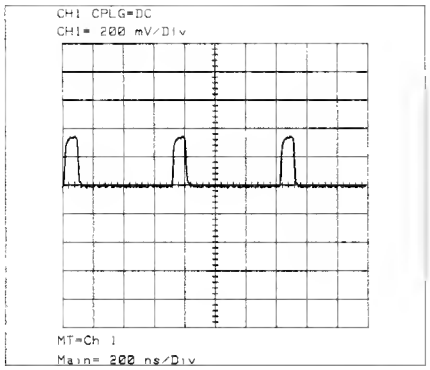


Probe: 10:1

Ch1: Connection- A60 U305(8) "S/L"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

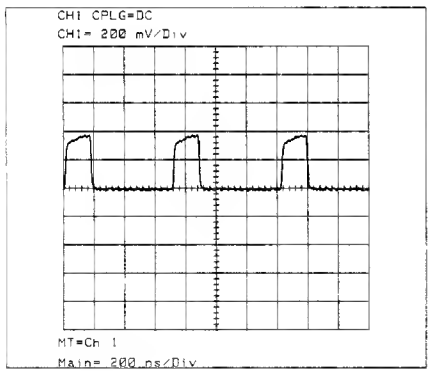


Probe: 10:1

Ch1: Connection- A60 U901(6) "DNCLK"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

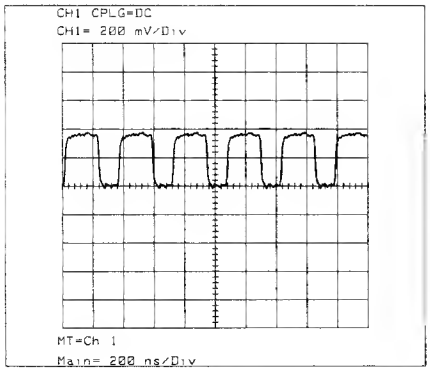


Probe: 10:1

Ch1: Connection- A60 U901(12) "PIXEN"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

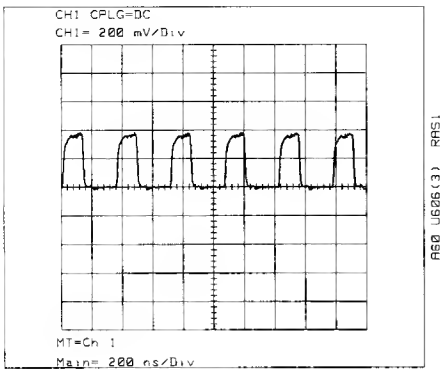


Probe: 10:1

Ch1: Connection- A60U805(8) "RAS"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

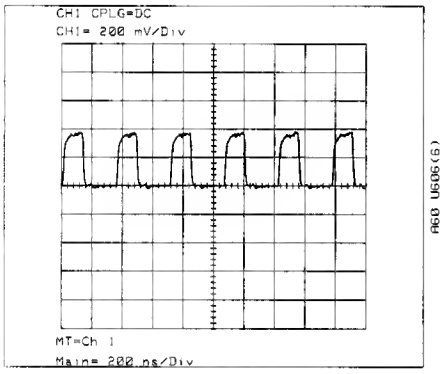


Probe: 10:1

Ch1: Connection- A60U606(3) "RAS1"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A60U606(6) "RAS2"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

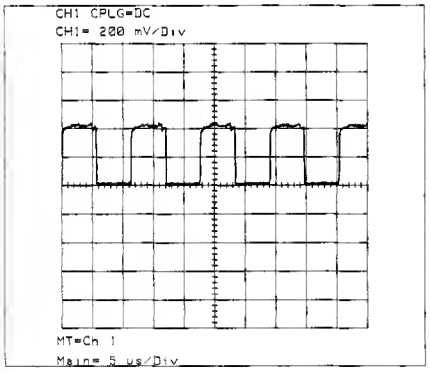
Bandwidth Limit: ON

[C] POSITION ADDRESS ADDER, [D] POSITION ADDRESS REGISTER, [E] RAM BYTE ADDRESS REGISTER, [F] RAM BIT ADDRESS REGISTER

Move the A60J100 test jumper to the PLANE1 test position and check the waveforms given in Figure 7-34. These waveforms should be checked starting with the least significant bit (PXB0) and proceeding to the most significant bit (PXB16).

If these waveforms are correct, check the signatures given in Table 7-48.

Figure 7-34 Position Address Waveforms

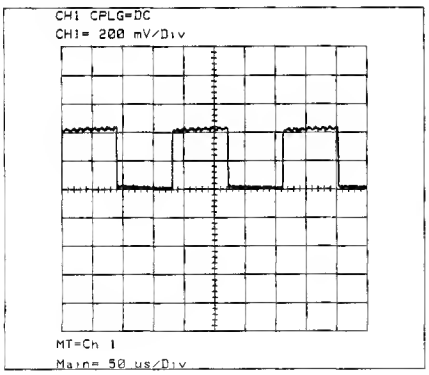


Probe: 10:1

Ch1: Connection- A60 TP102 "PXB3"
A60 U700(10)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

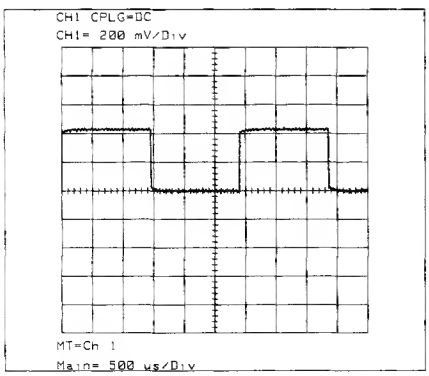


Probe: 10:1

Ch1: Connection- A60 TP200 "PXB7"
A60 U208(10)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

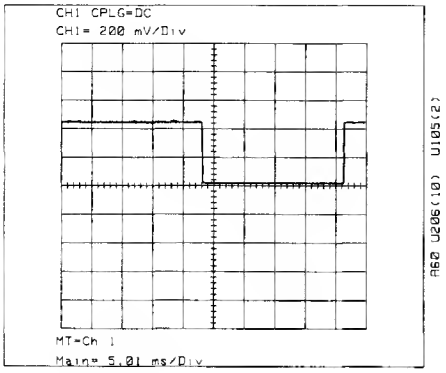


Probe: 10:1

Ch1: Connection- A60 TP300 "PBX11"
A60 U207(10)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

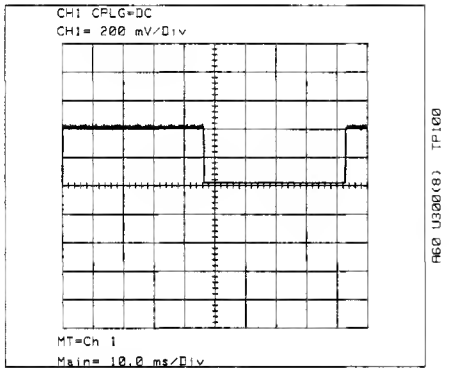


Probe: 10:1

Ch1: Connection- A60 U105(2) "PXB15"
A60 U206(10)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

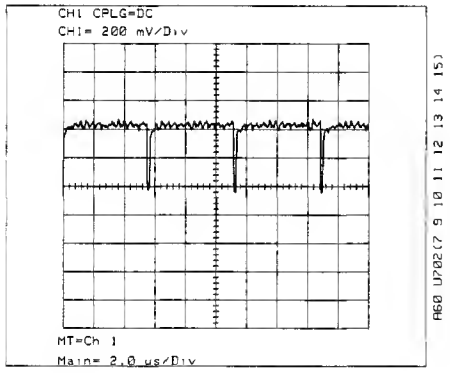


Probe: 10:1

Ch1: Connection- A60 TP100 "PXB16"
A60 U300(8)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A60 U702(7, 9, 10, 11, 12, 13, 14 ,15)
A60 U600(3, 6, 8, 11)
A60 U601(3, 6, 8, 11)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Table 7-48 RAM Byte Address and Bit Address Signatures

Signal	Polarity	Connection
Clock		A60 U106(1) "CLK"
Start		A60 TP100 "PXB16"
Stop		A60 TP100 "PXB16"
+5 V Signature - 0003		
RAM Byte Address Register		
U104(3)	7791	
U104(5)	0356	
U104(7)	U759	
U104(9)	6F9A	
U104(13)	P763	
U104(15)	1UP5	
U104(17)	8484	

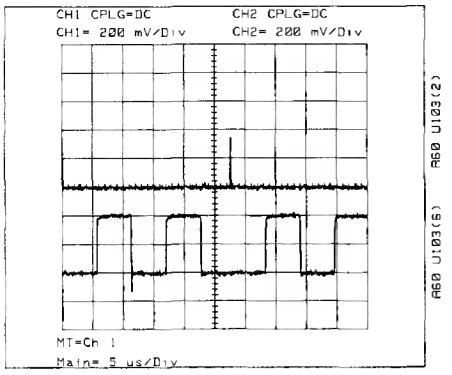
[K] FREE RUN/LINE SYNC TIMING, [L] COLUMN ADDRESS COUNTER, [M] ROW ADDRESS COUNTER, [R] FSYNC/SSYNC TIMING

Move the A60J100 test jumper to the PLANE1 test position and the A60J200 test jumper to the 60 Hz position. Check the waveforms given in Figure 7-35. These waveforms should be checked starting with the least significant bit of the row address counter (U103(3)) and proceeding to the most significant bit of the column address counter (U200(10)).

Move the A60J200 test jumper back to the SYNC position.

If all of the waveforms given in Figure 7-35 are correct, check the signatures given in Table 7-49.

Figure 7-35 Row and Column Address Counter Waveforms



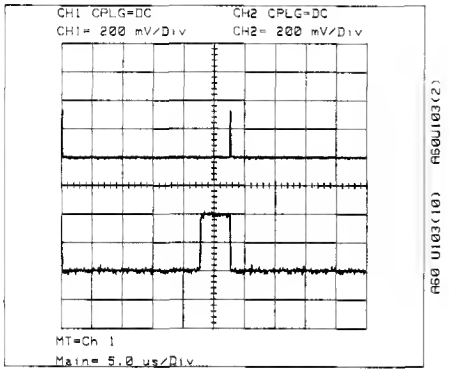
Probe: 10:1

Ch1: Connection- A60 U103(2)
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A60 U103(6)
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



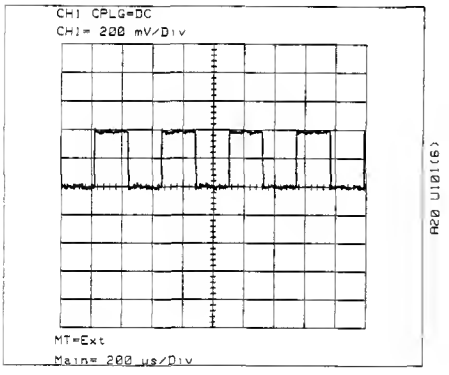
Probe: 10:1

Ch1: Connection- A60 U103(2)
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A60 U103(10)
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

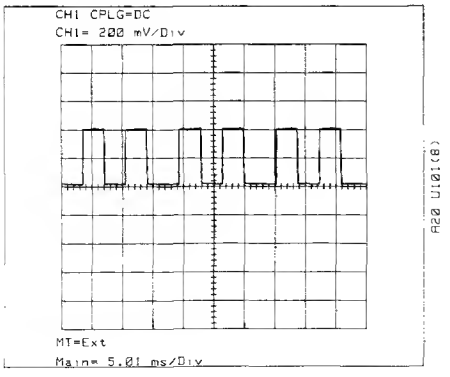


Probe: 10:1

Ch1: Connection- A60 U101(6)
Coupling- dc
Ground- Center Graticule

Trigger: External- A60 U101(2)
Slope- Positive

Bandwidth Limit: OFF

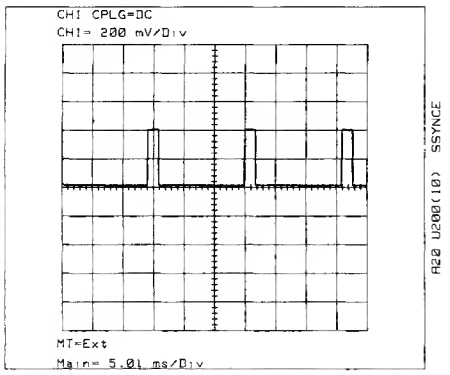


Probe: 10:1

Ch1: Connection- A60 U101(8)
Coupling- dc
Ground- Center Graticule

Trigger: External- A60 U101(2)
Slope- Positive

Bandwidth Limit: OFF

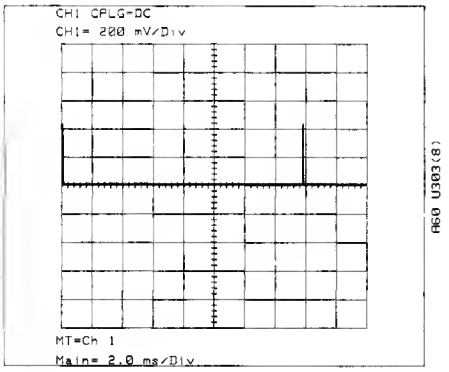


Probe: 10:1

Ch1: Connection- A60 U200(10) "SSYNCE"
Coupling- dc
Ground- Center Graticule

Trigger: External- A60 U101(2)
Slope- Positive

Bandwidth Limit: OFF

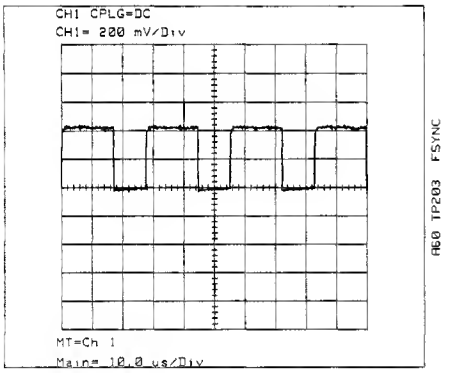


Probe: 10:1

Ch1: Connection- A60 U303(8)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

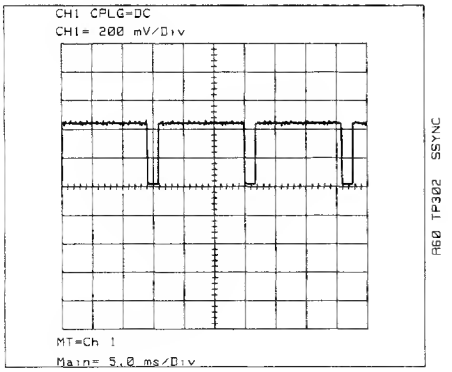


Probe: 10:1

Ch1: Connection- A60 TP203 "FSYNC"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A60 TP302 "SSYNC"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Table 7-49 RAM Address Signatures

Signal	Polarity	Connection
Clock		A60 U100(19) "CLK"
Start		A60 U200(10) "SSYNCE"
Stop		A60 U200(10) "SSYNCE"
+5 V Signature - 5F52		
U100(3)	AF98	
U100(5)	C74H	
U100(7)	AF1C	
U100(9)	8641	
U100(13)	CH3C	
U100(15)	77H9	
U100(17)	4H8U	

[N] RAM PLANE1 (FULL BRIGHT), [O] RAM PLANE2 (HALF BRIGHT)

Troubleshoot the RAM circuits using the -hp-3561A power-on test. The A60J100 test jumper should be in the run position for this test. Table 7-50 lists the power-on test return codes and the corresponding failed RAM. If the power-on test indicates a failure in several RAMs, the most likely cause of the failure is the copy compliment data feedback registers or the processor data register.

Table 7-50 Power Or Test Return Codes for the Display RAM

Return Code	Chip Code	Failed RAM
0 7 28	G	U507
0 7 28	H	U505
0 7 28	J	U503
0 7 28	K	U501
0 7 28	L	U9
0 7 28	M	U7
0 7 28	N	U5
0 7 28	P	U3
0 7 28	R	U506
0 7 28	T	U504
0 7 28	U	U502
0 7 28	V	U500
0 7 28	W	U8
0 7 28	X	U6
0 7 28	Y	U4
0 7 28	Z	U2

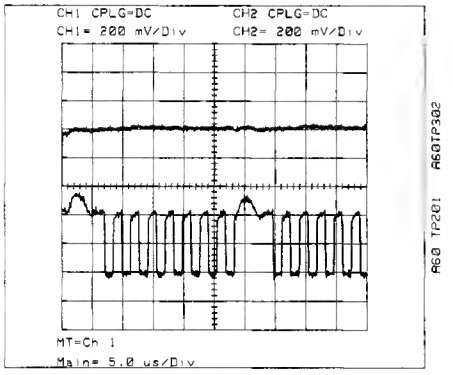
[S] RAM DATA READER

1. Move the A60J100 test jumper to the PLANE1 test position and the A60J200 test jumper to the 60 Hz position. Check the waveform at A60TP201 as shown in Figure 7-36.

2. Move the A60J100 test jumper to the PLANE2 test position and check the waveform at A60TP202 as shown in Figure 7-36.

3. Move the A60J200 test jumper back to the SYNC position.

Figure 7-36 RAM Data Reader Waveforms



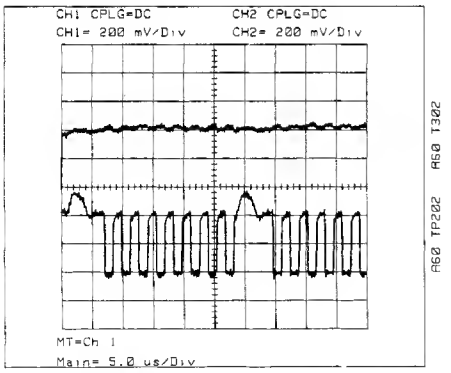
Probe: 10:1

Ch1: Connection- A60 TP302 "SSYNC"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A60 TP201 "VIDF"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A60 TP302 "SSYNC"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A60 TP202 "VIDH"
Coupling- dc
Ground- Center Graticule

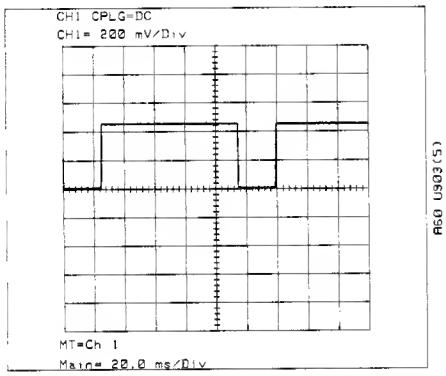
Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

[A] INCREMENT REGISTER, [B] ADDRESS DECODER, [G] MODE CONTROL LATCH [J] CHARACTER WRITER, [T] LINE LENGTH COUNTER, [Y] BEEPER TIMING

1. Turn the -hp-3561A LINE power switch OFF.
2. Move test jumper A40W1 on the A40 Assembly to the test position.
3. Move test jumper A60J100 on the A60 Assembly to the run position.
4. Turn the -hp-3561A LINE power switch ON. When the front panel LEDs begin to blink (approximately seconds after power-on), check the signatures given in Table 7-51 and the waveforms given in Figure 7-37.

Figure 7-37 Beeper Timing Waveforms

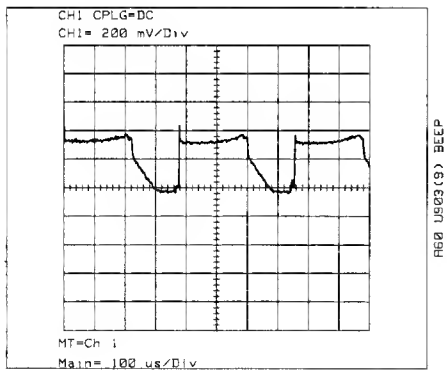


Probe: 10:1

Ch1: Connection- A60 U903(5)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A60 U903(9) "BEEP"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON
Note: This waveform will appear to jitter.

Table 7-51 A60 Processor Interface Signatures

Signature Analyzer Setup Signal	Polarity	Connection
Clock		A60 U806(4) "$\overline{\text{DSPS}}$"
Start		A40CR1 (Cathode of Green LED)
Stop		A40CR1 (Cathode of Green LED)
+5 V Signature - AU96		

Address Decoder		Increment Register	
U303(3)	AP3H	U209(2)	9747
U303(6)	C232	U209(5)	59F5
U806(7)	4304	U209(6)	A8A2
U806(9)	9FU5	U209(9)	3052
U806(10)	A205	U209(12)	UPUP
U806(11)	PA07	U209(15)	H938
U806(12)	C23H	U209(16)	456H
U806(13)	FP6H	U209(19)	9H2P
U806(14)	U7A3		
U806(15)	C396	U302(5)	A36U
Mode Control Latch		U304(3)	A171
U800(2)	P852	U701(2)	4HUP
U800(5)	H766	U701(5)	F5U2
U800(6)	5967	U701(6)	6504
U800(9)	A1AA	U701(9)	A171
U800(12)	9P18	U701(12)	CF35
U800(15)	06P3	U701(15)	0A70
U800(16)	6520	U701(16)	P800
U800(19)		U701(19)	2142
U304(6)	H766		
U304(8)	5967		

Table 7-52 A60 Assembly Signal Connections

INPUTS

Signal Name	Functional Block	Connector Number	Origin Assembly
$\overline{\text{DSPS}}$	B	P61(A8)	A40
LSYNC	K	P62(B9)	A71
PBR/$\overline{\text{W}}$	Q	P61(A13)	A40
$\overline{\text{RESET}}$	H	P61(A3)	A40

OUTPUTS

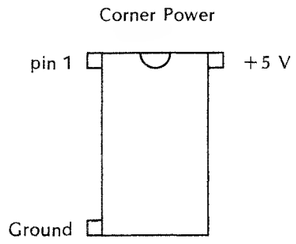
Signal Name	Functional Block	Connector Number	Destination Assembly
BEEP	Y	P62(B8)	A72
DSPH	U	P61(A7)	A40
FSYNC	R	P61(B4)	A90
SSYNC	R	P61(B5)	A90
VIDF	S	P61(B3)	A90
VIDH	S	P61(B2)	A90

I/O SIGNALS

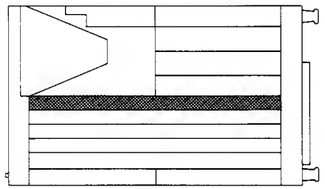
Signal Name	Functional Block	Connector Number	Destination Assemblies
Processor Address Bus	B	P61(A16,B15,B16)	A40, A50, A66/65
PAB0 - PAB2			A81
Processor Data Bus	A,Q	P61(A17 - A24)	A30, A40, A50
PDB0 - PDBF		P61(B17 - B24)	A66/65, A80

A60 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)



	+5V	GND
U2	8	16
U3	8	16
U4	8	16
U5	8	16
U6	8	16
U7	8	16
U500	8	16
U501	8	16
U502	8	16
U503	8	16
U504	8	16
U505	8	16
U506	8	16
U507	8	16



A60 J100

PLANE1 POSITION
(Full Bright)

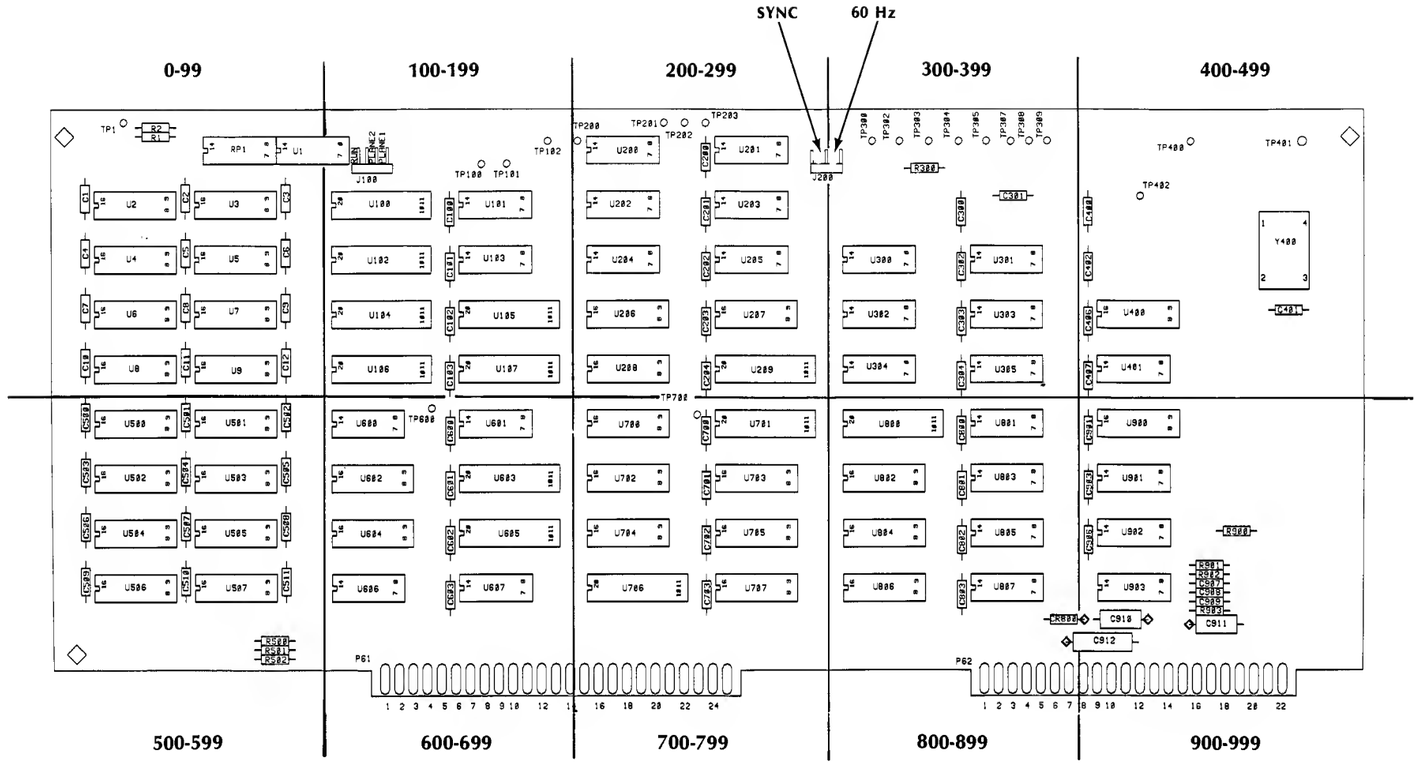
PLANE2 POSITION
(Half Bright)

RUN POSITION

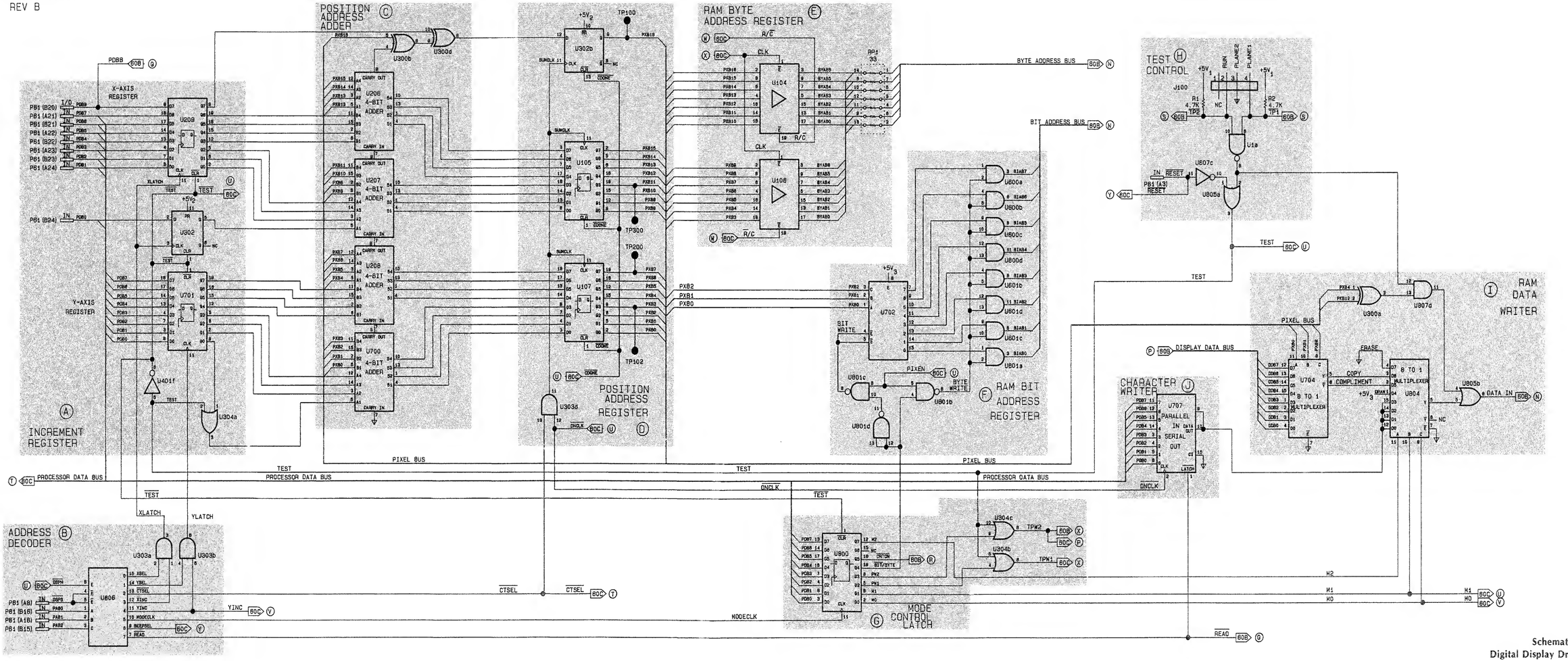
A60 J200

60 Hz Position

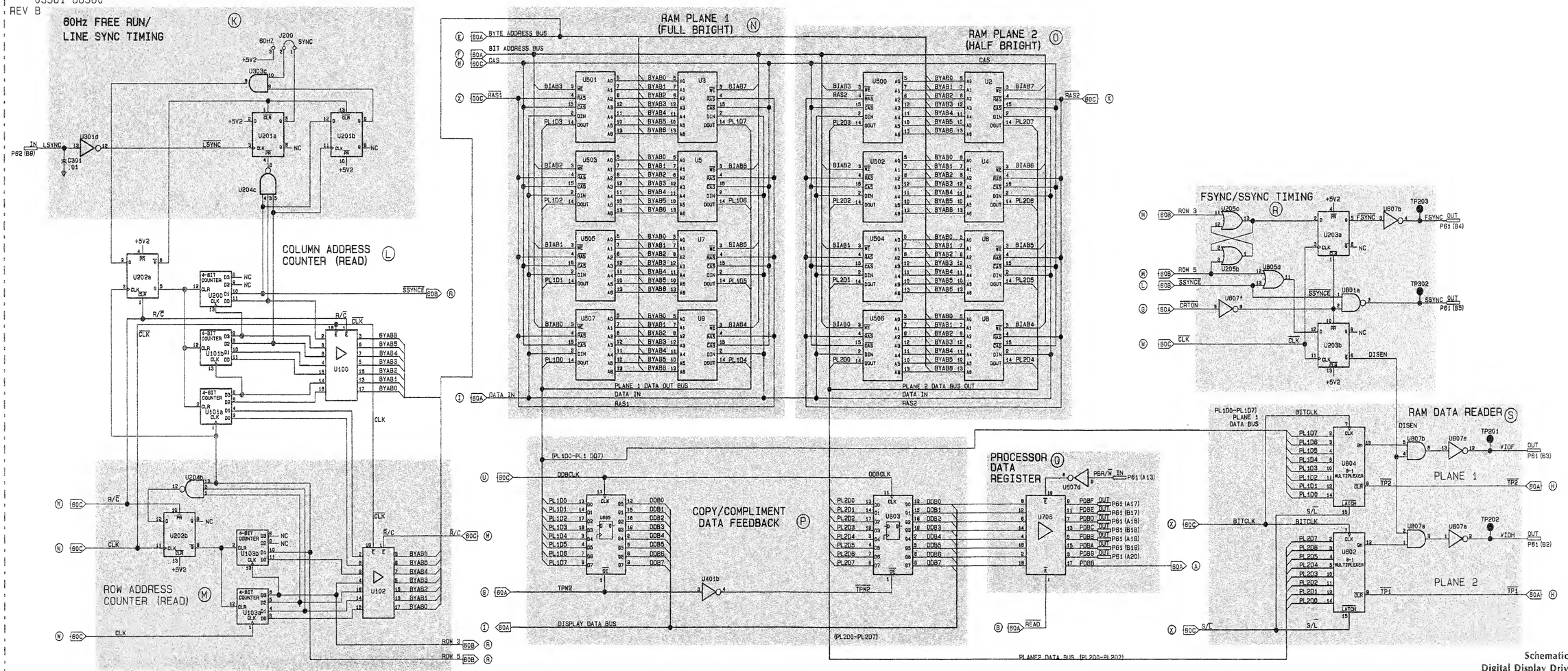
SYNC Position



P/O A60 DIGITAL DISPLAY DRIVER ASSEMBLY
03561-66560
REV B

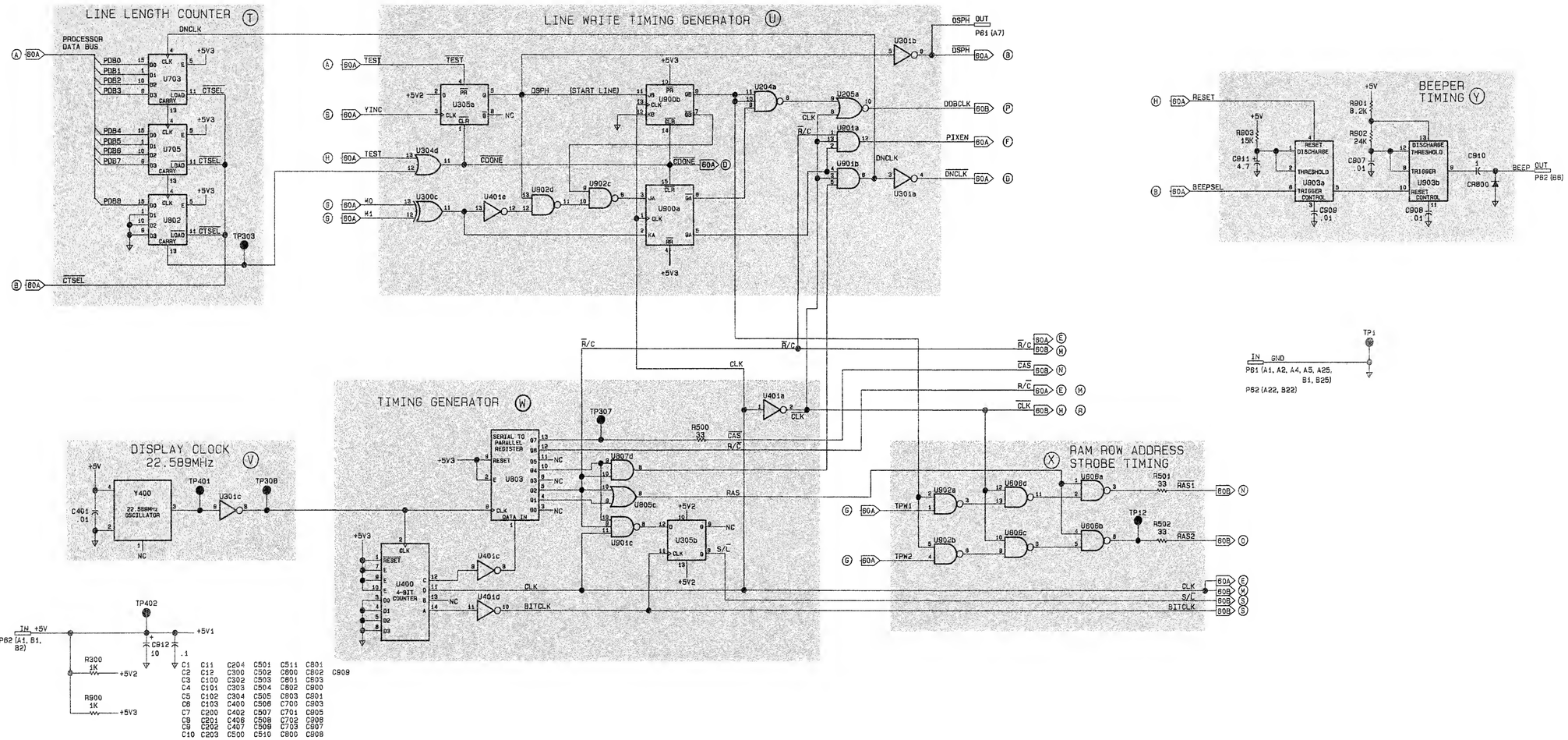


P/O A60 DIGITAL DISPLAY DRIVER ASSEMBLY
03561-66560
REV B



Schematic **A60B**
Digital Display Driver Assembly
7-177/7-178

P/O A60 DIGITAL DISPLAY DRIVER ASSEMBLY
03561-66560
REV B



3561A-A60/3

7-25 A65/A66 CMOS BUBBLE MEMORY ASSEMBLY

7-26 Circuit Description: CMOS Bubble Memory

GENERAL

The purpose of these assemblies is to store data in non-volatile memory. The A66 Assembly is standard and contains an 8k-byte CMOS RAM with battery backup. The optional A65 Assembly contains the same CMOS RAM with an additional 128k-byte Bubble memory module. The following information will concentrate on the optional A65 CMOS/Bubble Memory Assembly since it also contains the standard CMOS memory circuitry. The following theory will be to the circuit function level. Those circuits which are located on both the A65 and the A66 assemblies will be in (parenthesis). Table 7-53 identifies and describes the signals used on these assemblies.

[A] BUBBLE ON/OFF

When the Bubble Memory is addressed to read or write and the reset is not active, the Bubble On/Off circuit controls the Bubble Power Down circuit [H].

[B] CONTROL SIGNAL BUFFER

The Control Signal Buffer isolates the control signals which determine the read and write operation and whether the data is for the CMOS or the Bubble Memory.

[C] (BUS DRIVERS)

The Bus Drivers control the flow of data and address lines to and from the A65/66 Assemblies.

[D] (CMOS MEMORY)

This is the 8k-byte CMOS Memory and Page Select ICs. U203 selects which 256-bit page will be addressed.

[E] BUBBLE INTERRUPT

This circuit controls the interrupt from the Bubble Memory Controller circuit [I].

[F] BUBBLE READ/WRITE

This circuit controls the read and write operations of the Bubble Memory circuit by decoding the processor signals.

[G] (BATTERY AND CMOS POWER DOWN)

This circuit supplies either +5V or the battery to the CMOS IC to prevent data loss or corruption in the case of a power failure. When the instrument is turned on, +5V is supplied. When the instrument is turned off, the battery is smoothly switched in to prevent data loss.

[H] BUBBLE POWER DOWN

The Bubble Power Down holds the Bubble circuits in the power down state during the time that data transfer is not occuring. This method is used to prevent data loss or corruption in the case of a power failure.

[I] BUBBLE CONTROLLER

The Bubble Controller interfaces the Bubble circuits with the processor. It provides all the control and timing functions needed to operate the Bubble Circuitry.

[J] BUBBLE COIL DRIVERS

This circuit transforms the TTL inputs from the Bubble Controller [I] to high voltage drive signals. These drive signals then drive the coils internal to the Bubble Memory module U4. These coils generate the magnetic fields which move the bubbles within the module.

[K] BUBBLE MEMORY

There are three LSI devices in this circuit. They are as follows:

A Current Pulse Generator which contains individual current sinks that supply the proper currents when enabled by the respective TTL inputs.

A Sense Amplifier which reads and latches the bootloop from the Bubble Memory module. It then controls the address where data is to be read from or written to. This IC also contains an Error Correction circuit which detects and corrects data errors during both read and write operations.

The Magnetic Bubble Memory Module is a 128k-byte non-volatile solid state memory.

[L] (CMOS CONTROL)

This circuit controls the Battery and CMOS Power Down circuit [G] enabling it during a read or write operation and disabling it all other times.

Table 7-53 Signal Descriptions

Signal	Description
$\overline{\text{BUBS}}$	Bubble Select: Signal from the A40 Processor Assembly used enable the Bubble memory circuits to perform a read or write operation.
$\overline{\text{CMOSS}}$	CMOS Select: Signal from the A40 Processor Assembly used to clock data into the CMOS memory.
MAB0 through MABC	Memory Address Bus: These are the 12 Memory Address lines derived from the processor data bus lines 0-7 and processor address bus lines 0-4. They are used on this assembly only.
MDB0 through MDB7	Memory Data Bus: These are the 8 Memory Data Bus lines derived from the processor data bus. They are used on this assembly only.
PAB0 through PAB4	Processor Address Bus: These are five lines of the Processor Address Bus.
PAB5	Processor Address Bus: Bit 5 is used on this assembly to enable the CMOS Control circuit and Bubble Controller.
PBR/$\overline{\text{W}}$	Processor Bus Read/Write: This is the buffered processor R/W signal which programs the memory circuits to perform a read or write operation.
PDB0 through PDBF	Processor Data Bus: These are the 16 Processor Data bus lines.
4MHz	This clock is from the A40 Processor Assembly and is used by the A65/66 Assemblies as the main clock.

7-27 Troubleshooting The A65/66 Assemblies

GENERAL

Failures in the CMOS/Bubble memory may or may not be detected by the power-up test routine. If the processor is not able to talk to the assembly, the processor will display "NONVOLATILE MEMORY ERROR: FORMAT REQUIRED" on the CRT display. If, however, there are memory location errors, error messages will be displayed during a store or recall operation.

If any of the following three failures occur on the optional Bubble Memory Assembly (03561-66565), the assembly will require formatting.

1. Replacement of the battery BT1
2. Replacement of IC U4.
3. Replacement of IC U103.

Format the assembly by pressing the following front panel keys:

PRESET
MODE . . . . . TEST SELECT . . . . . 1 7 0 ENTER
START SNGL TST

The following built-in diagnostic routines can be used to determine if a failure exists in the CMOS or the Bubble portion and then to troubleshoot the defective circuit.

Test 19 CMOS Memory test which writes and reads a known pattern to the A66/A65 Assembly.

Test 20 Bubble Memory test which writes and reads a known pattern to the A65 Assembly.

Test 167 Bubble Memory Read DSA test used to troubleshoot the Bubble memory in the read mode.

Test 170 Memory Format Routine used to initilize the CMOS memory on the A65 Bubble Memory Assembly.

Two troubleshooting procedures are given. The first procedure is for the standard A66 CMOS Memory assembly. The second is for the optional A65 CMOS/Bubble Memory assembly.

A66 CMOS TROUBLESHOOTING

WARNING

Having the A66 cover removed exposes the power supply assemblies. These assemblies contain exposed ±170 primary voltage. Exercise extreme caution when troubleshooting since contact with these voltages can cause personal injury.

CAUTION

Always stop the diagnostic test routine from running before turning the instrument LINE power OFF! Otherwise, damage to the memory circuits will occur!

Troubleshoot the circuits on the A66 Assembly in the order given in Table 7-54. In this table, level one circuits must be operational before level two circuits can be checked, etcetera. Test Routine 19, CMOS Memory Test, will be used to troubleshoot the A66 Assembly. To enter into self test routine 19, press the following -hp-3561A front panel keys in the order given:

PRESET
MODE . . . . . TEST SELECT . . . . . 19 ENTER

Table 7-54 A66 Circuit Troubleshooting Order

Level	Functional Blocks
1	Bus Drivers: C
2	CMOS Control: L
3	Battery And CMOS Power Down: G
4	CMOS Memory: D

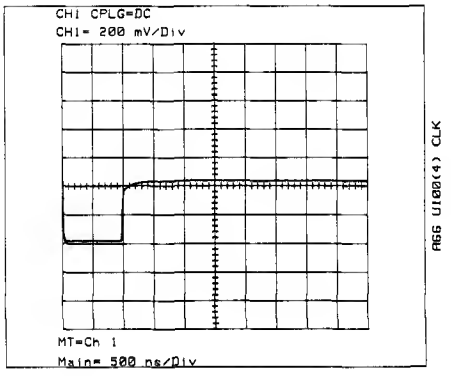
[C] BUS DRIVERS

With test routine 19 running continuously, check that the output pins of U101(3,5,7,9,12,14,16,18) are toggling. If any of the pins are not, replace U101.

[L] CMOS CONTROL

With test routine 19 running continuously, verify the signals on the output of U100 with those shown in Figure 7-38. If either do not match, replace U100.

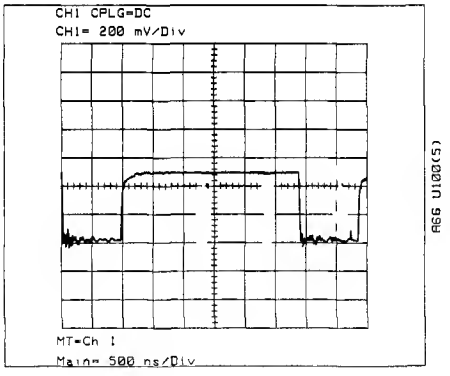
Figure 7-38 Correct Waveforms At A66U100(4,5)



Probe: 10:1

Ch1: Connection- U100(4)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative



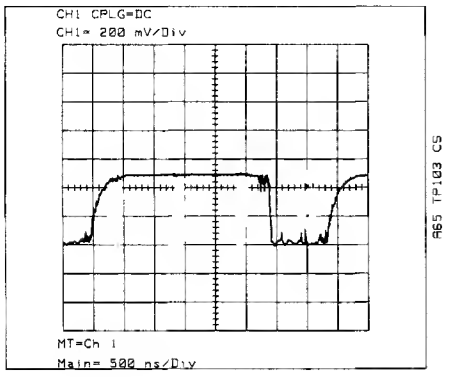
Probe: 10:1
Ch1: Connection- U100(5)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

[G] BATTERY AND CMOS POWER DOWN

With test routine 19 running continuously, verify that TP102 is +5Vdc. Verify the signal at TP103 with that shown in Figure 7-39. Also, with test routine 19 stopped, turn the instrument power off and verify that the voltage on TP102 is greater than +2Vdc. If any measurements are incorrect, troubleshoot this functional circuit.

Figure 7-39 Correct Waveform At A66 TP103



Probe: 10:1

Ch1: Connection- TP103
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

[D] CMOS MEMORY

The troubleshooting for this circuit is to first replace U203. If the the failure remains, replace U103.

A65 BUBBLE MEMORY TROUBLESHOOTING

If at power-on, the CRT displays the message "NONVOLATILE MEMORY ERROR: FORMAT REQUIRED," perform the formatting routine by running Diagnostic Test Routine 170 located in Section VI. If after running this routine, the format message is still displayed, proceed with the following troubleshooting information.

WARNING

Having the A65 cover removed exposes the power supply assemblies. These assemblies contain exposed ±170Vdc primary voltage. Exercise extreme caution when troubleshooting in this area since contact with these voltages can cause personal injury.

CAUTION

Always stop the test routine from running before turning the instrument LINE power OFF! Otherwise, damage to the memory circuits will occur!

This troubleshooting procedure is for the Bubble Memory circuitry only. Troubleshooting information for the CMOS circuitry is given in Paragraph A66 CMOS Troubleshooting.

Use the failure isolation chart in Figure 7-40 to determine if the problem is in the Bubble or CMOS portion of the assembly.

Use the following flowchart to determine if the A65 failure is in the CMOS or Bubble portion of the circuitry. This flowchart will also determine if there is a hardware or a Bubble firmware failure (lost Seed or Bootloop).

All possible errors are listed in Table 7-55. Included in the list is the error number, a description of the failure and probable defective components or functional circuits which may have caused the error.

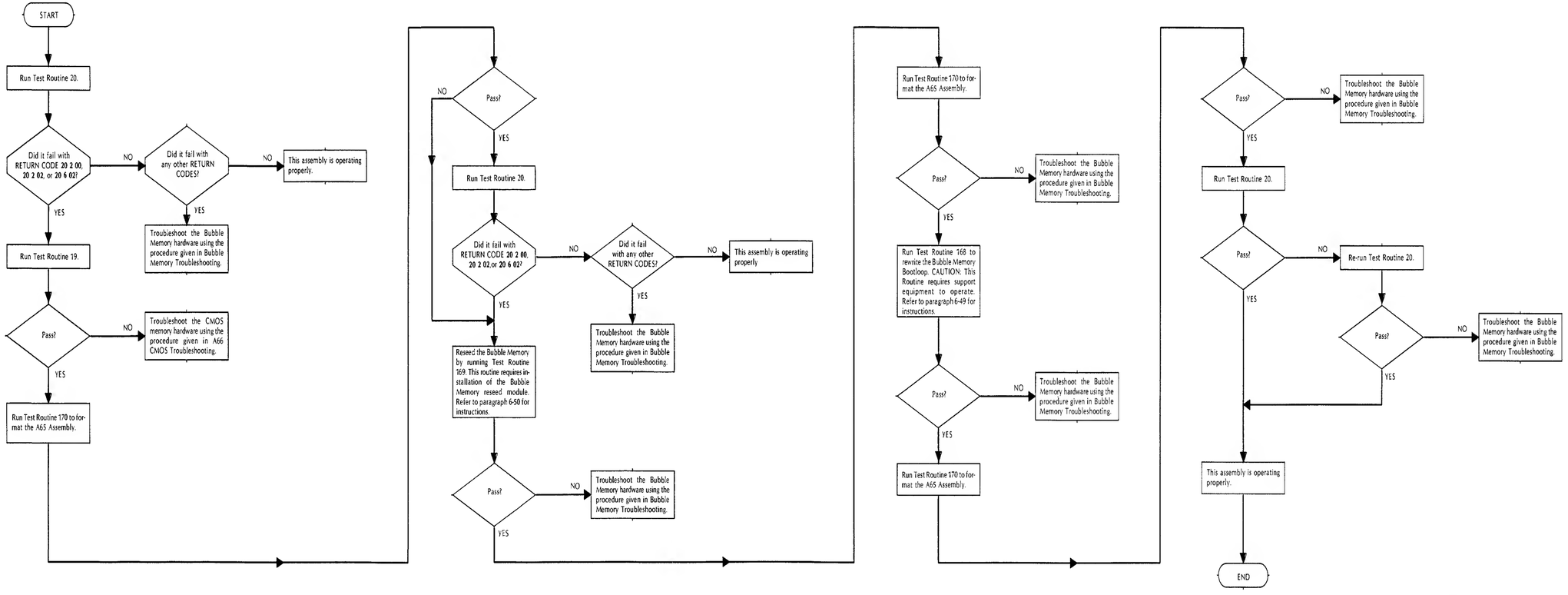


Figure 7-40 A65 Failure Isolation Chart

Table 7-55 Test 20 RETURN CODE Descriptions

Error	Description	Probable Cause
20 1 00	No Bubble is present or bad communication between the A40 Processor and A65 Bubble Memory Controller.	Usually caused by the Bus Driver U202. Verify its operation using the CMOS troubleshooting procedure.
20 2 00	The Bubble circuitry failed during a read operation.	Both errors 20 2 00 and 20 2 01 may be caused by either a defective Bubble module U4 or Current Pulse Generator U102. Verify using the K Bubble Memory troubleshooting procedure.
20 2 01	The Bubble circuitry failed during a write operation.	
20 2 02	Both errors 20 2 00 and 20 6 03 occured.	
20 2 03	Both errors 20 2 01 and 20 6 03 occured.	
20 6 00	The FIFO in the Controller U200 is failing.	Usually caused by the Bus Driver U202 and/or the Controller U200.
20 6 01	The Bootloop Register in the Sense Amplifier U3 is not communicating with the Controller U200.	Usually caused by a failure in the Sense Amplifier U3.
20 6 02	The Bubble cannot be initialized.	Usually caused by a failure in the CMOS Memory or the coil driver circuitry of the Bubble memory.
20 6 03	Data read from the Bubble Memory at initialization does not match the stored fixed pattern. The first time this test is performed, this failure will occur since the fixed pattern has not yet been written into memory. However, Test 20 writes and checks twice. If it fails the second time also, error 20 6 04 will occur.	Usually caused by a failure in the Bubble Coil Drivers J or the Bubble Memory K circuits.
20 6 04	Data pattern read from the Bubble memory does not match the stored fixed pattern. See also error 20 6 03.	
20 6 05	Both errors 20 2 00 and 20 2 01 occured.	

The Bubble troubleshooting is performed with the -hp-3561A running in Test Routine 167. Troubleshoot the functional circuits in the order given in Table 7-56. In this table, level one circuits must be operational before level two circuits can be

checked, etcetera. To enter into Test Routine 167, press the following -hp-3561A front panel keys in the order given:

PRESET
MODE ..... TEST SELECT..... .....167 ENTER

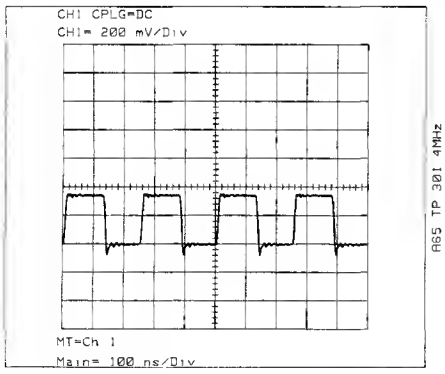
Table 7-56 A65 Circuit Troubleshooting Order

Level	Functional Blocks
1	Control Signal Buffer: B
2	Bubble On/Off: A
3	Bubble Power Down: H
4	Bubble Read/Write: F
5	Bus Drivers: C
6	Bubble Controller: I
7	Bubble Coil Drivers: J
8	Bubble Memory: K

[B] CONTROL SIGNAL BUFFER

Verify that the outputs of U306(9,11,13) are toggling. Also check the waveforms at TP301 and TP302 with those shown in Figure 7-41. If any of these signals are not present, troubleshoot this functional block.

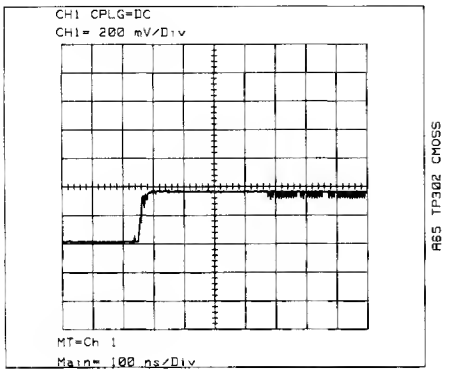
Figure 7-41 Correct Waveforms At A65 TP301 And TP302.



Probe: 10:1

Ch1: Connection- TP301
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive



Probe: 10:1

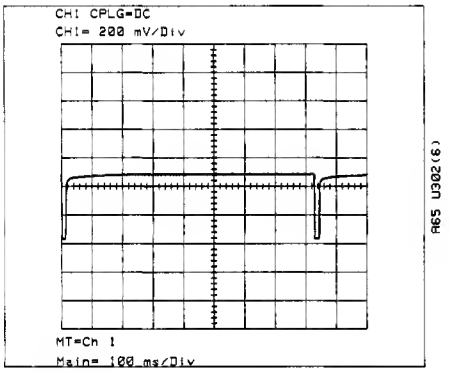
Ch1: Connection- TP302
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope-Negative

[A] BUBBLE ON/OFF

Verify the waveform at U302(6) with that shown in Figure 7-42. If it does not match, troubleshoot this functional block.

Figure 7-42 Correct Waveform At A65 U302(6).



Probe: 10:1

Ch1: Connection- U302(6)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

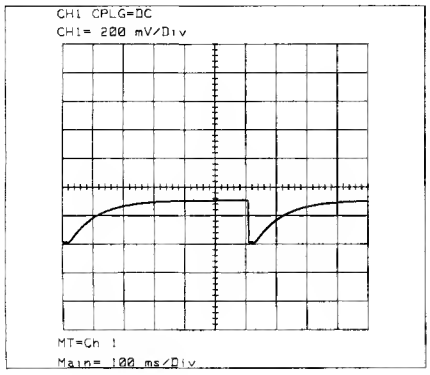
[H] BUBBLE POWER DOWN

Verify the waveform at U300(5) with that shown in Figure 7-43. If it does not match, troubleshoot this functional block.

[F] BUBBLE READ/WRITE

Verify the waveforms at U201(8,11) with those shown in Figure 7-44. If they do not match, troubleshoot this functional block.

Figure 7-43 Correct Waveform At A65 U300(5).



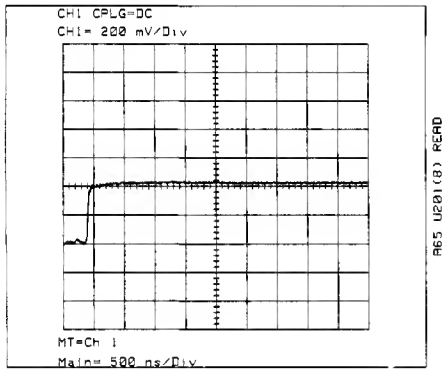
Probe: 10:1

Ch1: Connection- U300(5)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

Figure 7-44 Correct Waveforms At A65 U201(8,11).

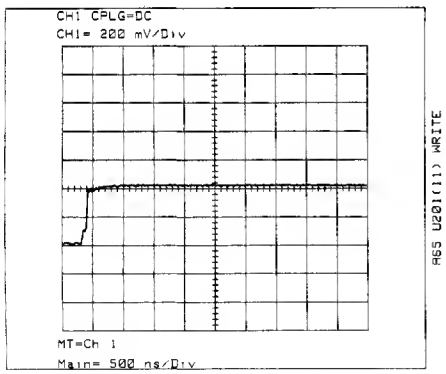


Probe: 10:1

Ch1: Connection- U201(8)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On



Probe: 10:1

Ch1: Connection- U201(11)
Coupling- dc
Ground- 3rd graticule from the bottom

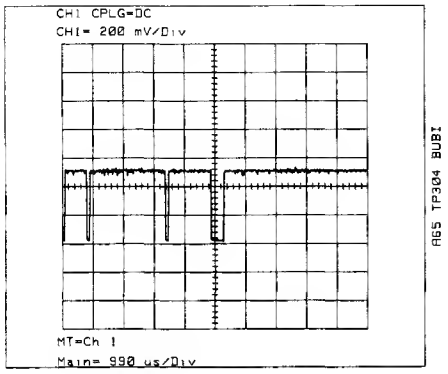
Trigger: Int- Ch1
Slope- Negative

BW Limit: On

[E] BUBBLE INTERRUPT

Verify the waveform at TP304 with that shown in Figure 7-45. If it does not match, troubleshoot this functional block.

Figure 7-45 Correct Waveform At TP304.



Probe: 10:1

Ch1: Connection- TP304
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

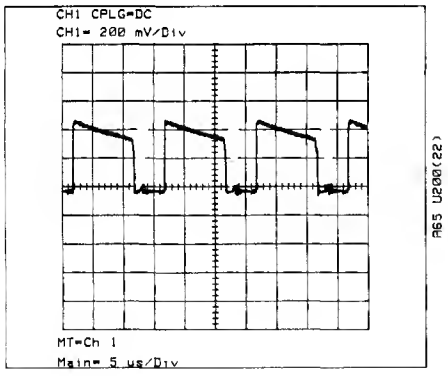
[C] BUS DRIVERS

Verify that all outputs of U202(2 through 9) are toggling. If any are not, replace U202.

[I] BUBBLE CONTROLLER

Verify the seven waveforms on the outputs of U200 with those shown in Figure 7-46. If any do not match, replace U200.

Figure 7-46 Correct Output Waveforms At A65 U200.



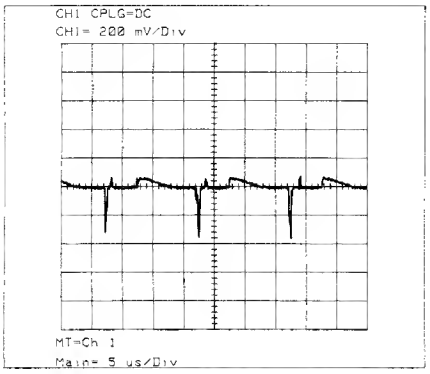
Probe: 10:1

Ch1: Connection- U200(22)
Coupling- dc
Ground- Center

Trigger: Int- Ch1
Slope- Negative

BW Limit: Off

HF REJ: On



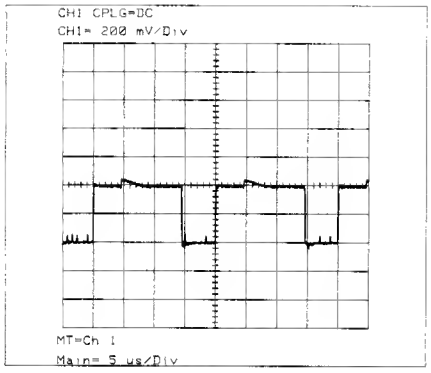
Probe: 10:1

Ch1: Connection- U200(23)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive

BW Limit: Off

HF REJ: On

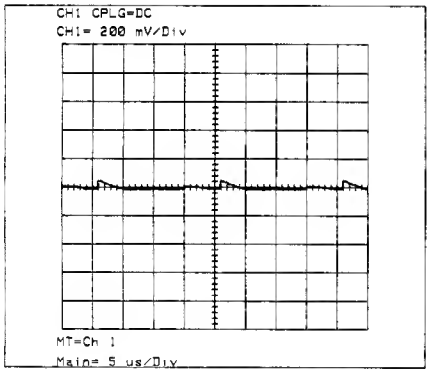


Probe: 10:1

Ch1: Connection- U200(24)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

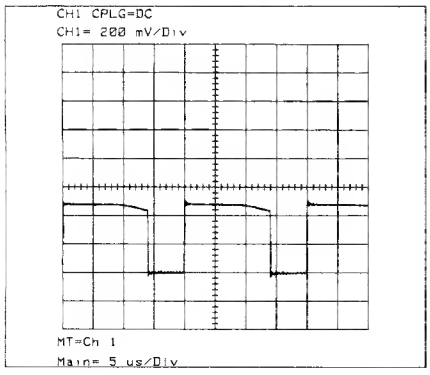


Probe: 10:1

Ch1: Connection- U200(30,31) or U102(6,9)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: Off

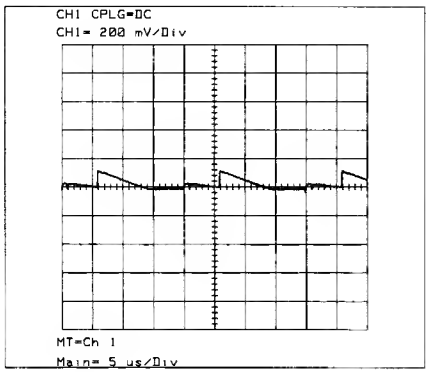


Probe: 10:1

Ch1: Connection- U200(32,34) or U102(3,10)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive

BW Limit: On

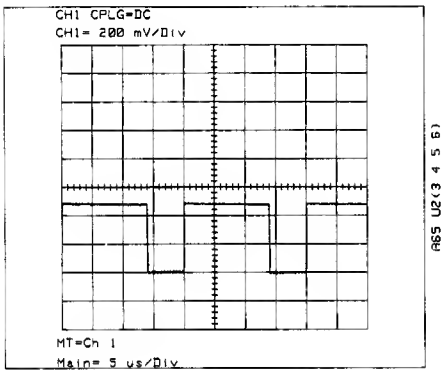


Probe: 10:1

Ch1: Connection- U200(33)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On



Probe: 10:1

Ch1: Connection- U200(36, 37, 38, 39) or
U2(3, 4, 5, 6)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive

BW Limit: On

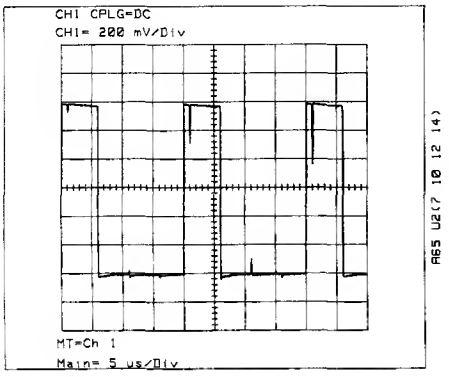
[J] BUBBLE COIL DRIVERS
[K] BUBBLE MEMORY

Verify the waveforms on the outputs of U2(7, 9 through 15) with those shown in Figure 7-47. If any do not match, replace U2.

Verify the waveform on the outputs of U1 and U100 at test points TP1, TP2, TP4 and TP104 with those shown in Figure 7-48. If any do not match, replace the appropriate IC.

If the above waveforms are correct, replace U4.

Figure 7-47 Correct Waveform At A65 U2.

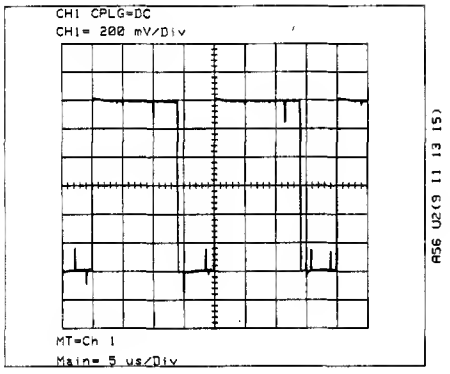


Probe: 10:1

Ch1: Connection- U2(7,10,12,14)
Coupling- dc
Ground- 2nd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive

BW Limit: On



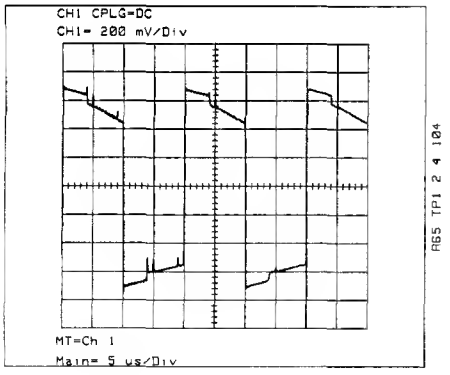
Probe: 10:1

Ch1: Connection- U2(9,11,13,15)
Coupling- dc
Ground- 2nd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

Figure 7-48 Correct Waveform At A65 U1 and U100 (TP1, 2, 4, 104).



Probe: 10:1

Ch1: Connection- TP1, TP2, TP4, TP104
Coupling- dc
Ground- 2nd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive

BW Limit: On

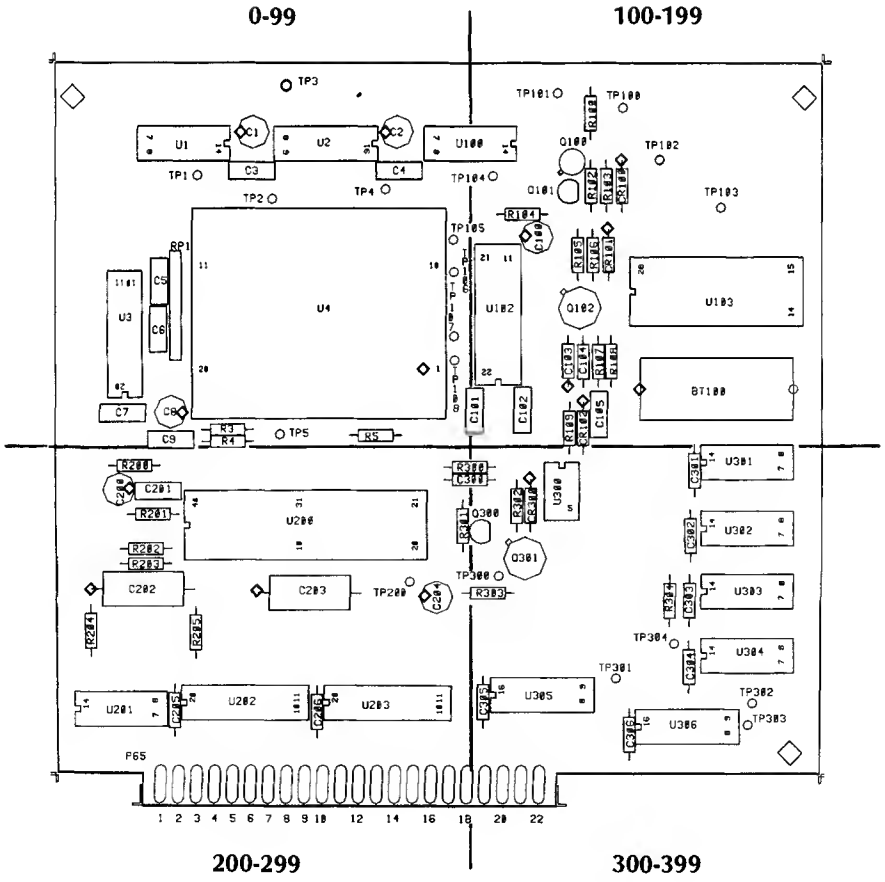
Table 7-57 A66/65 Assembly Signal Connections

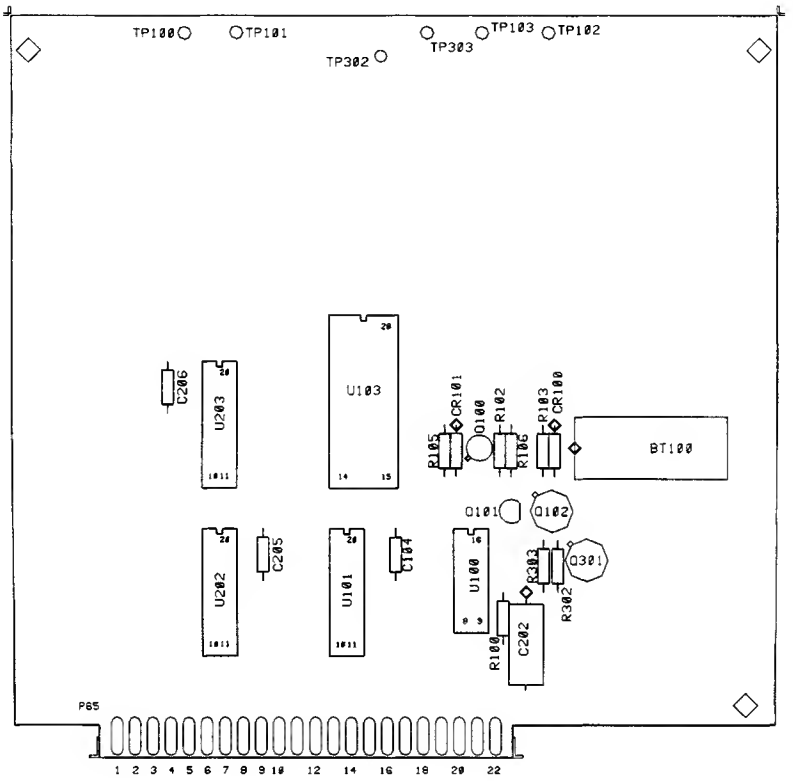
INPUTS

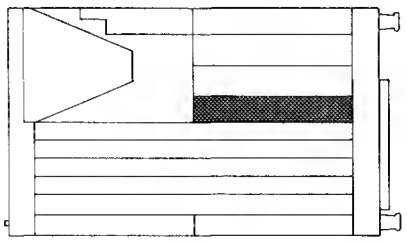
Signal Name	Functional Block	Connector Number	Origin Assembly
$\overline{\text{BUBS}}$	B	P65(B16)	A40
$\overline{\text{CMOSS}}$	B	P65(B18)	A40
PBR/$\overline{\text{W}}$	B	P65(B15)	A40
$\overline{\text{RESET}}$	A	P65(B17)	A40
Processor Address Bus	C	P65(A12 - A14)	A40
PAB0 - PAB5	C	P65(B12 - B14)	A40
PDB8	E	P65(A8)	A40
PDBF	A	P65(B11)	A40

I/O SIGNALS

Signal Name	Functional Block	Connector Number	Destination Assemblies
Processor Data Bus PDB0 - PDB7	C	P65(A4 - A7) P65(B4 - B7)	A30, A40, A50, A60, A80



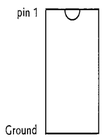

TP100
TP101
TP302
TP303
TP103
TP102
C206
U203
U103
CR101
Q100
R102
R103
CR100
R105
R106
BT100
Q101
Q102
Q301
U202
C205
U101
C104
U100
R303
R302
R100
C202
P65
1 2 3 4 5 6 7 8 9 10 12 14 16 18 20 22



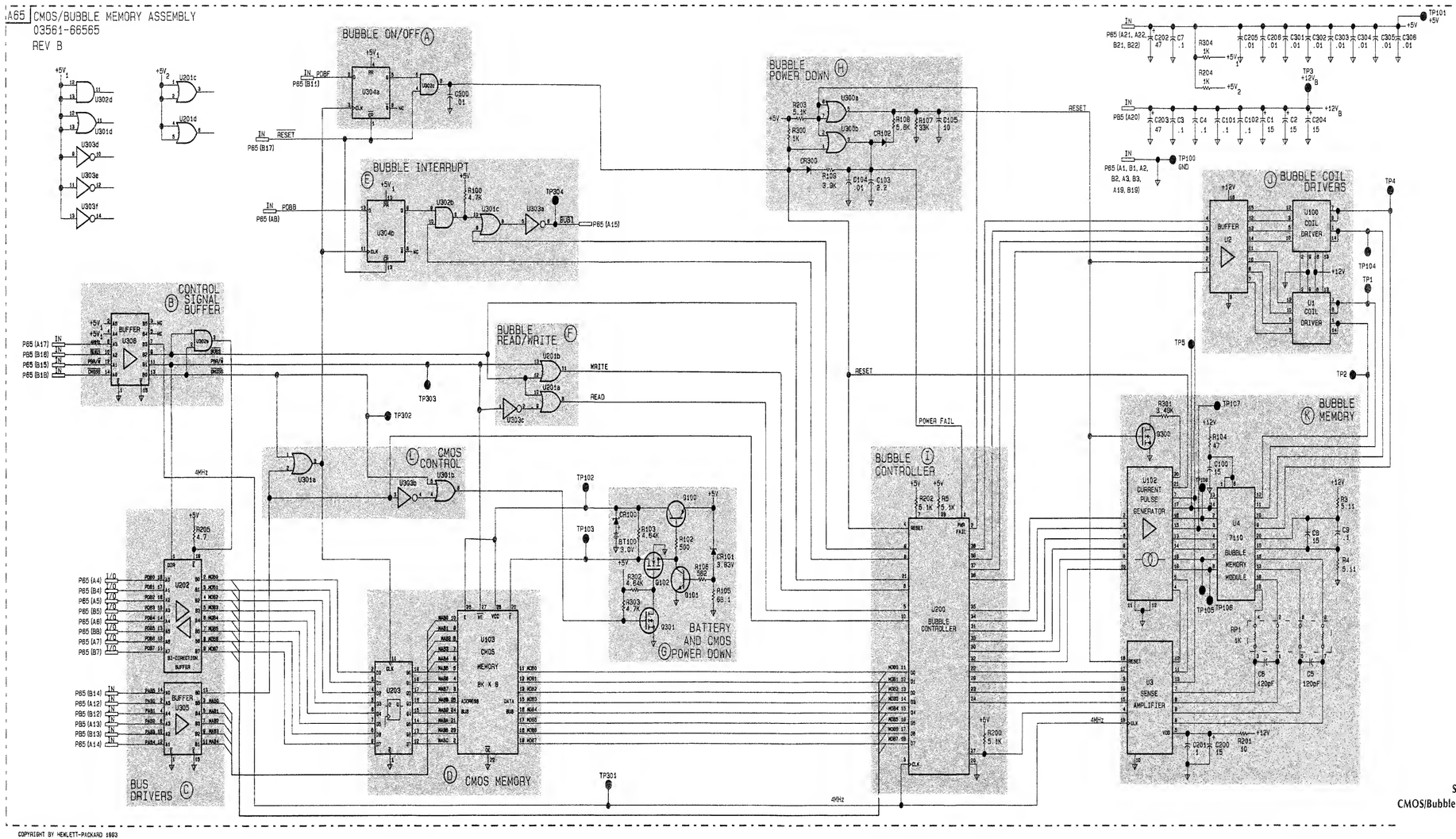
A65 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)

Corner Power



	+12V	+5V	GND
U1	6,13		2,9
U2	16		8
U4	1,6		15
U100	6,13		2,9
U102	1	22	11,12
U103		28	22
U200		40	20

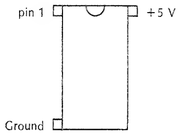


Schematic **A65**
CMOS/Bubble Memory Assembly
7-199/7-200

A66 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)

Corner Power

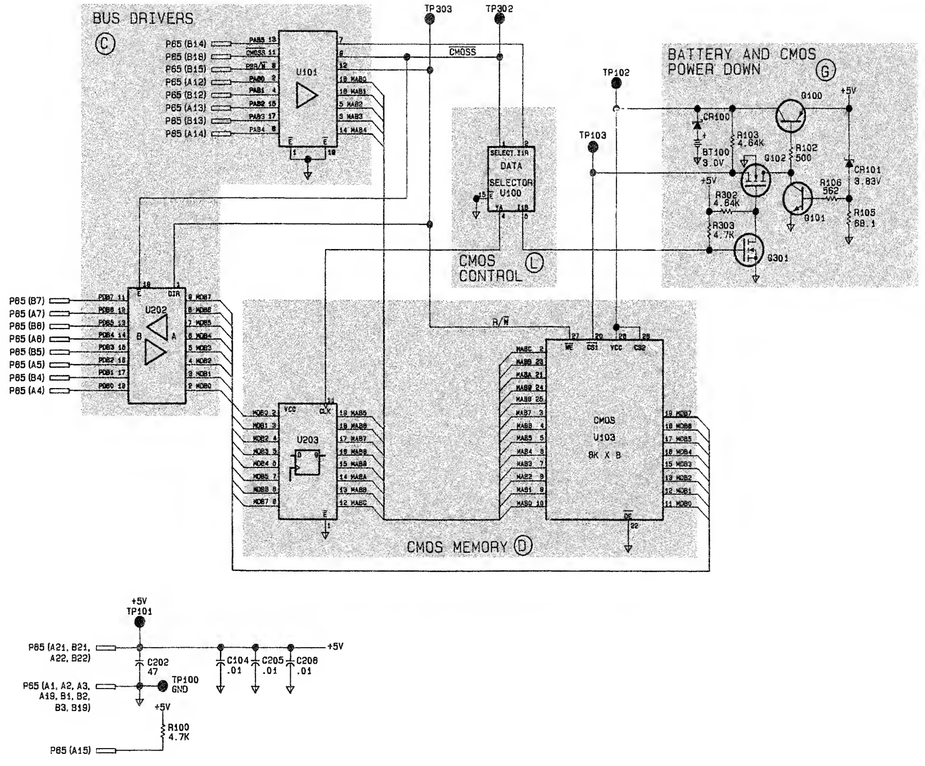


	+5V	GND
U103	28	22

A66 CMOS MEMORY ASSEMBLY

03561-66566

REV B



7-28 A70, A71, A72 POWER SUPPLY ASSEMBLIES AND PART OF A99 MOTHERBOARD ASSEMBLY

7-29 Power Supply Circuit Description

GENERAL

The -hp-3561A power supply is a Master/Slave switching supply. That is, one supply is used as the control (master) and the other supplies are "slaved" to the master. It uses two power MOS-FET transistors in a half-bridge configuration to drive the main power transformer at a frequency of 128 kHz. The duty-cycle of the drive is determined by the pulse-width control circuits which monitor the output of the master supply. The +5V master supply is used as the logic supply. Nine slave supplies, which are independently L-C filtered and post-regulated by 3-terminal regulators, are used by analog and isolated ground logic circuits.

There are two control feedback loops in the main +5V supply. A voltage feedback loop provides control of the supply output during normal operation. During an over-current condition, another loop takes control and provides current limiting.

The power supply has protection circuits which monitor the supply outputs. These circuits are connected to a latching fault supervisor circuit which turns off the gate drive of the power FETs. An LED is is turned on when a fault is detected to indicate the fault condition. Any supply can cause a fault condition which would shut down all supplies.

A separate bias supply provides ±12V to the control circuits of the master supply. This supply uses 3-terminal linear regulators and derive its power from a separate power transformer. This supply must be present for operation of the power supply.

[A] START UP CONTROL

This circuit prevents the main supply from turning on until the bias supply voltage exceeds +11V. U101 compares the +5V reference voltage to a divided down +12V bias voltage. The output disables the "Over Current Sense Pulse Width Control" and "Fault Supervisor" circuits and sends the Start Up Enable signal to the SHUT input on the Pulse Width Modulator.

[B] OVER CURRENT SENSE PULSE WIDTH CONTROL

The over current control circuitry monitors the current through resistor R200. The voltage developed across R200 is input to comparator U401. As the current reaches maximum, U401 starts to turn Q1 and Q400 on. This causes the Pulse Width Modulator IC to reduce the duty-cycle of the switching FETs which reduces the supply current.

[C] CLOCK SYNC CONTROL

This circuit buffers the 256kHz clock from the A20 Assembly and drives the SYNC input of the Pulse Width Modulator. It also monitors the +5V main supply and inhibits the clock to the Pulse Width Modulator until the supply reaches 4.75 volts.

[D] VOLTAGE SENSE PULSE WIDTH CONTROL

This circuit compares the +5V main supply with the +5V reference. As the main supply starts to exceed the reference, this circuit pulls the COMP line lower causing the Pulse Width Modulator to reduce the duty-cycle of the drive to the switching FETs which reduces the main voltage.

[E] PULSE WIDTH MODULATOR

The Pulse Width Modulator is the controller for the -hp-3561A power supply. It drives the switching circuits in a manner which maintains a constant voltage at the supply output. It does this by varying the on-off time (duty cycle) of the switching FETs. The on-off time is controlled by the COMP input at U1(3). As this voltage level lowers, the on time becomes narrower.

[F] SHUT DOWN DRIVER

Signals from the Primary Current Sensor [K] and Fault Supervisor [L] are ORed at the input of the Shut Down Driver. Either of these two signals enable the Shut Down Driver to disable the Pulse Width Modulator IC and trun off the power supply.

[G] POWER SUPPLY OVERVOLTAGE COMPARATORS
[H] ISOLATED POWER SUPPLY OVERVOLTAGE COMPARATORS

These two circuits monitor the isolated and chassis-referenced supplies. If an overvoltage condition occurs in any one of the supplies, the overvoltage circuit will trigger the Fault Supervisor [L] and turn off the power supply.

[I] VMOS DRIVER

The VMOS Driver buffers the drive signals from the Pulse Width Modulator [E] and drives the switching FETs through transformer T200.

[J] +5V OVERVOLTAGE COMPARATOR

This circuit compares the +5V main supply with the +5V reference. If an overvoltage condition occurs, this circuit will activate the Fault Supervisor [L] to turn off the power supply.

[K] PRIMARY CURRENT SENSOR

Current transformer A70T600 senses the primary current of the main transformer A71T300. CR500, CR501 and U501c/d convert this current to a voltage at U501a/b pins 11 and 14. When a primary overcurrent condition is sensed, this circuit enables the Shut Down Driver [F] and turns off the power supply.

[L] FAULT SUPERVISOR

All fault-detecting-circuit outputs are latched by the Fault Supervisor. This latch turns off the Pulse Width Modulator through the Shut Down Driver [F] and lights a fault indicating LED during any fault condition. The four LEDs indicate which fault-detecting circuit was activated. These four LEDs are off during normal operation.

CR1 — Primary Overcurrent Indicator
CR2 — +5V Overvoltage Indicator
CR3 — Power Supply Overvoltage Indicator (ground referenced slave supplies)
CR4 — Isolated Power Supply Overvoltage Indicator (isolated slave supplies)

[M] RECTIFIER/FILTER

This Full-Wave bridge rectifier and R-C filter network convert the ac power input to approximately 170Vdc which is then supplied to the switching transistors [O]. When S2 is set to 115V, the Rectifier/Filter circuit functions as a voltage doubler. When S2 is set to 230V, the Rectifier/Filter circuit functions as a full-wave bridge.

[N] BIAS TRANSFORMER

The ac Line voltage is stepped down by the bias transformer and sent to the bias power supply circuitry [Q].

[O] SWITCHERS

The Switcher circuit consists of two switching power FETs and transient protection circuitry. The FETs are driven by the VMOS Driver [I] and switch the rectified line power to the power transformer.

[P] LINE SYNC CONTROL

The ac line signal taken from the secondary of the bias transformer is buffered and shaped by the Line Sync Control circuit. The sync output is used by the display circuitry as scan synchronization.

[Q] BIAS VOLTAGE POWER SUPPLY

The secondary voltage of the bias transformer is rectified and filtered to provide the ± 12V bias supplies which are used by the various power supply control circuits.

[R] LOW VOLTAGE DETECTOR

This circuitry monitors the line voltage through the secondary of the bias transformer. If the line voltage drops below minimum level, this circuit sends a power fail signal to the A40 Processor Assembly.

[S] +5V RECTIFIER

This circuit rectifies and filters the +5V main supply. This supply powers the logic circuits.

[T] INSTRUMENT GROUND RECTIFIERS

This circuit rectifies one of the two multi-tap secondary windings of the power transformer to produce three supply voltages which are referenced to chassis ground.

[U] ISOLATED GROUND RECTIFIERS

This circuit rectifies one of the two multi-tap secondary windings of the power transformer to produce four supply voltages whose grounds are not referenced to the chassis (floating).

[V] PS FILTER

This is the L-C filtering circuitry for all slave supplies. The Zener diodes in this circuit provide overvoltage protection for the input of the three-pin regulators [W,X].

[W] INSTRUMENT GROUND POWER SUPPLY

These four linear regulators are on the A99 Motherboard Assembly. They provide the four regulated supplies which are chassis grounded.

[X] ISOLATED GROUND POWER SUPPLY

These five linear regulators are on the A99 Motherboard Assembly. They provide the five regulated supplies which are not referenced to chassis ground (floating ground).

7-30 Troubleshooting The Power Supply

WARNING

The -hp-3561A Power Supply A70, A71 and A99 Assemblies contain exposed ±170 primary voltages. Read the following safety consideration before attempting to troubleshoot the Power Supply assemblies. Contact with these voltages can cause serious personal injury.

SAFETY CONSIDERATION

The -hp-3561A power supply has many exposed areas which contain Primary voltage. These areas are shaded in red on the schematic and component locator. Extra care must be exercised when troubleshooting in these areas.

GENERAL

The power supply in the -hp-3561A is a Master/Slave type. The troubleshooting procedure will be to determine:

A. If the problem is in the Master or Slave power supply.
B. Which functional circuit(s) of the power supply failed.

The power supply circuits between the A70, A71 and A72 Assemblies are interactive so the troubleshooting will be to isolate the problem to a functional circuit rather than to an assembly. The approach will be to verify which particular circuits are operating properly.

There are four LEDs on the A70 Assembly which are normally not lighted. When an LED is on, it indicates that a fault condition was detected and which monitoring circuit was involved. This will turn off the drive from the Pulse Width Modulator (shut down condition). However, the power supply can have a failure without an LED lit. For example, the Bias Supply can be bad which would not allow the power supply to operate, or there could be a low voltage condition which would not be detected by the power supply protect circuitry.

WARNING

The heat sinks on the A70 Assembly are connected to ±170 primary voltage. Exercise extreme caution when troubleshooting in this area. Contact with these voltages can cause serious personal injury.

WARNING

Wait at least three (3) minutes after power has been turned off before disconnecting the power supply cables W70 and W71, or removing the A70 or A71 Assemblies. A ±170 Vdc charge is retained in the A99 Motherboard Assembly capacitors and a sudden discharge may occur if the wait-time is not observed.

REMOVING THE A20 ASSEMBLY

In normal operation, the A20 Assembly provides the 256 kHz switching clock to the power supply. However, when the A20 Assembly is removed the power supply pulse width modulation circuit will generate its own clock. To prevent the A20 Assembly Clock from interfering with power supply troubleshooting, remove the A20 Assembly before troubleshooting any part of the power supply.

ISOLATING THE PROBLEM TO THE MASTER OR SLAVE SUPPLY

CAUTION

When removing or inserting any PC Assembly, the ac Line switch must be in the OFF position. Otherwise, PC Assembly damage may occur.

There are four protection circuits which will light the LEDs on the A70 Assembly. They are primary overcurrent, +5V master overvoltage, power supply overvoltage and isolated power supply overvoltage. If any of these LEDs are on and the power supply is shut down, turn the main power off and remove the A72 Assembly. Turn the main power on. If none of the LEDs light, the master +5V supply is working and the problem is in the slave supply. Troubleshoot the slave supply.

If any of the LEDs light, and the power supply is shut down, turn the main power off and disconnect W71 from A70J300. This will disable the main power transformer and rectifiers. Turn the main power switch on. If any of the LEDs light, there is a problem in the protection circuitry. Troubleshoot the protection circuits.

If none of the LEDs light, there is a problem in the main power transformer (A71T300) or the rectifier circuits [S],[T], or [U] blocks on the power supply schematic.

TROUBLESHOOTING THE SLAVE SUPPLY

Isolate the problem to one or more of the slave supplies by lifting one of the legs of the input inductors on the A72 Assembly (PS Filter block [V]). Troubleshoot the faulty slave supply. Note that switching the front panel input reference switch to CHASSIS connects the isolated ground to the chassis.

TROUBLESHOOTING THE MASTER SUPPLY

There are three supplies needed in order for the master supply to operate. They are the ±12V Bias and the +5V reference. The Bias supply circuitry is on the A71 Assembly [Q], with its transformer on the A99 Assembly. The +5V reference is generated by the PWM IC U1(18) on the A70 Assembly. Also needed is the Sync signal coming into the PWM IC at U1(12). Before troubleshooting the master supply, verify that the bias and reference supplies and sync signal are operating.

WARNING

This setup procedure exposes ±170 Vdc primary voltage on the large heat sinks and other parts of the A70 Assembly. Extreme caution must be exercised when troubleshooting during this condition. Contact with the high voltage can cause serious personal injury.

A70 [G],[H],[J],[K],[L] TROUBLESHOOTING

Place the A70 Assembly on an extender board and remove cable W70 from A70J700 (to the A99 Motherboard Assembly). This removes the ± 170Vdc primary voltage from the A70 and A71 Assemblies. Turn on the AC Line power switch. If one of the A70 LEDs comes on and the main power supply is shut down, there may be problem in the protection circuit. Troubleshoot the indicated protection circuit.

A70 [B],[D] TROUBLESHOOTING

With the cable removed from A70J700, turn on the main power switch. If no LEDs light, and the main supply is shut down, the problem may be in the pulse-width feedback control or the primary switching circuits. To verify proper operation of the feedback pulse-width control circuits [B] and [D]:

1. Adjust a dc power supply to 5V ±.2V and connect it to A70TP105 (+ to TP105, - to TP130).

2. Monitor the pulse width signal at A70TP100 and A70TP101.

3. Increase the dc supply voltage to +6V. The pulse width should change width to minimum. If it does not, troubleshoot the Voltage Sense Pulse Width Control circuit [D].

4. Monitor the pulse width at A70TP100 and TP101 (drive signal).

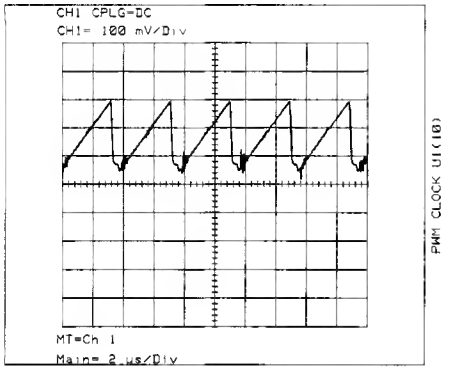
5. Connect a clip lead to TP400. Ground the other end of the clip lead. The pulse width should change width to minimum. If it does not, troubleshoot the Overcurrent Sense Pulse Width Control [B].

If these two pulse width control circuits are working, troubleshoot the primary switching circuits [O] and [I].

OSCILLOSCOPE SIGNAL PICTURES

The oscilloscope plots are used for troubleshooting the power supply. Note that all measurements are taken with a 10:1 probe. Other notes unique to the measurement are written next to the plot. Figure 7-49 gives those waveforms necessary for troubleshooting circuits on the A70 Assembly and Figure 7-50 gives those waveforms necessary for troubleshooting circuits on the A71 Assembly.

Figure 7-49 A70 Assembly Troubleshooting Waveforms

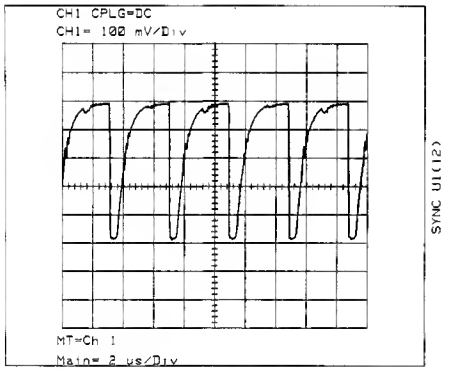


Probe: 10:1

Ch1: Connection- A70U1(10)
Coupling- dc
Ground- Center Graticule

Trigger: Internal-Ch1
Slope: Positive

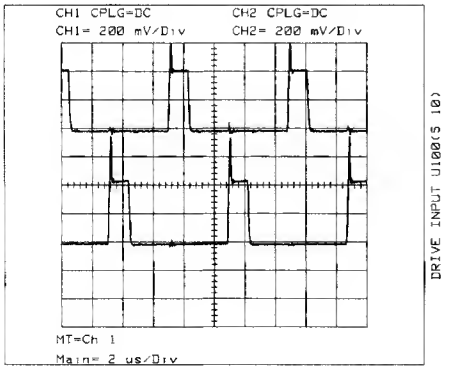
Bandwidth Limit: On



Probe: 10:1
Ch1: Connection- A70U1(12)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On



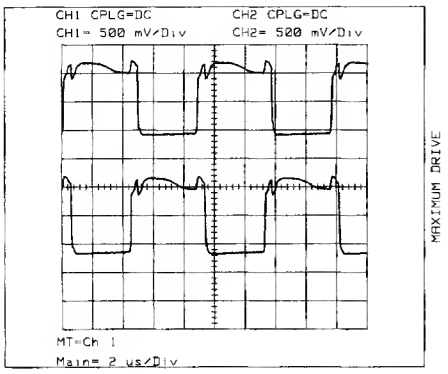
Probe: 10:1

Ch1: Connection- A70U100(10)
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A70U100(5)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On



Probe: 10:1

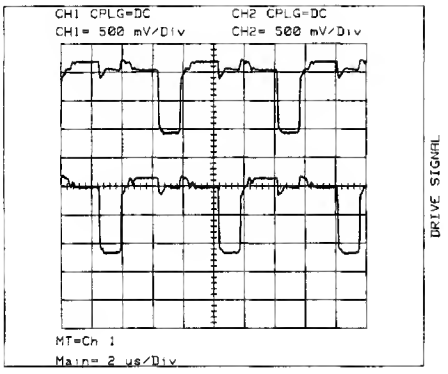
Ch1: Connection- A70 TP100
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A70 TP101
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On

This is the drive signal at maximum duty cycle (cable removed from A70J700)



Probe: 10:1
Ch1: Connection- A70 TP100
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A70 TP101
Coupling- dc
Ground- Third Graticule From Bottom

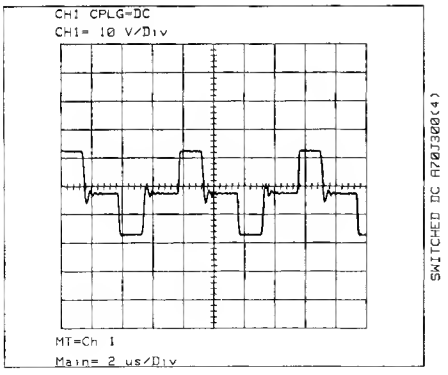
Trigger: Internal- Ch1
Slope: Positive

Bandwidth Limit: On

This is the drive signal at normal duty cycle (all assemblies installed).

WARNING

WARNING! THIS MEASUREMENT CONTACTS 300VP-P PRIMARY DC VOLTAGE. USE EXTREME CAUTION WHEN PROBING THIS SIGNAL!

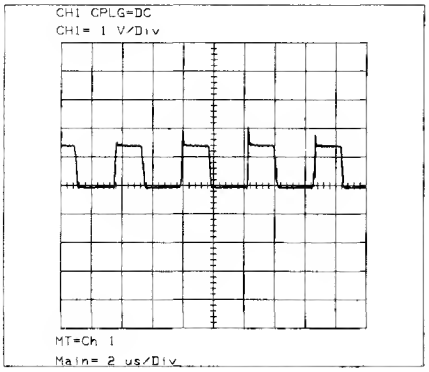


Probe: 10:1, 10MΩ, 600V Maximum Voltage (-hp-10014A)

Ch1: Connection- A70J300(4)
Coupling- dc
Ground- Center Graticule

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On



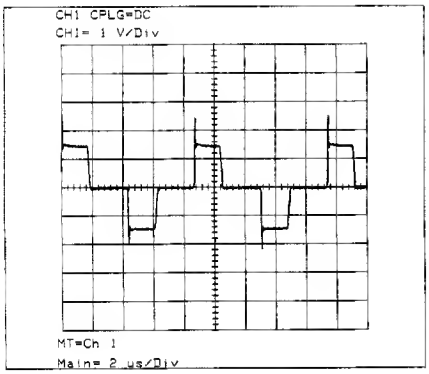
Probe: 10:1

Ch1: Connection- Cathode of A70CR100
Coupling- dc
Ground- Center Graticule

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On

Figure 7-50 Correct Waveform At A71CR100

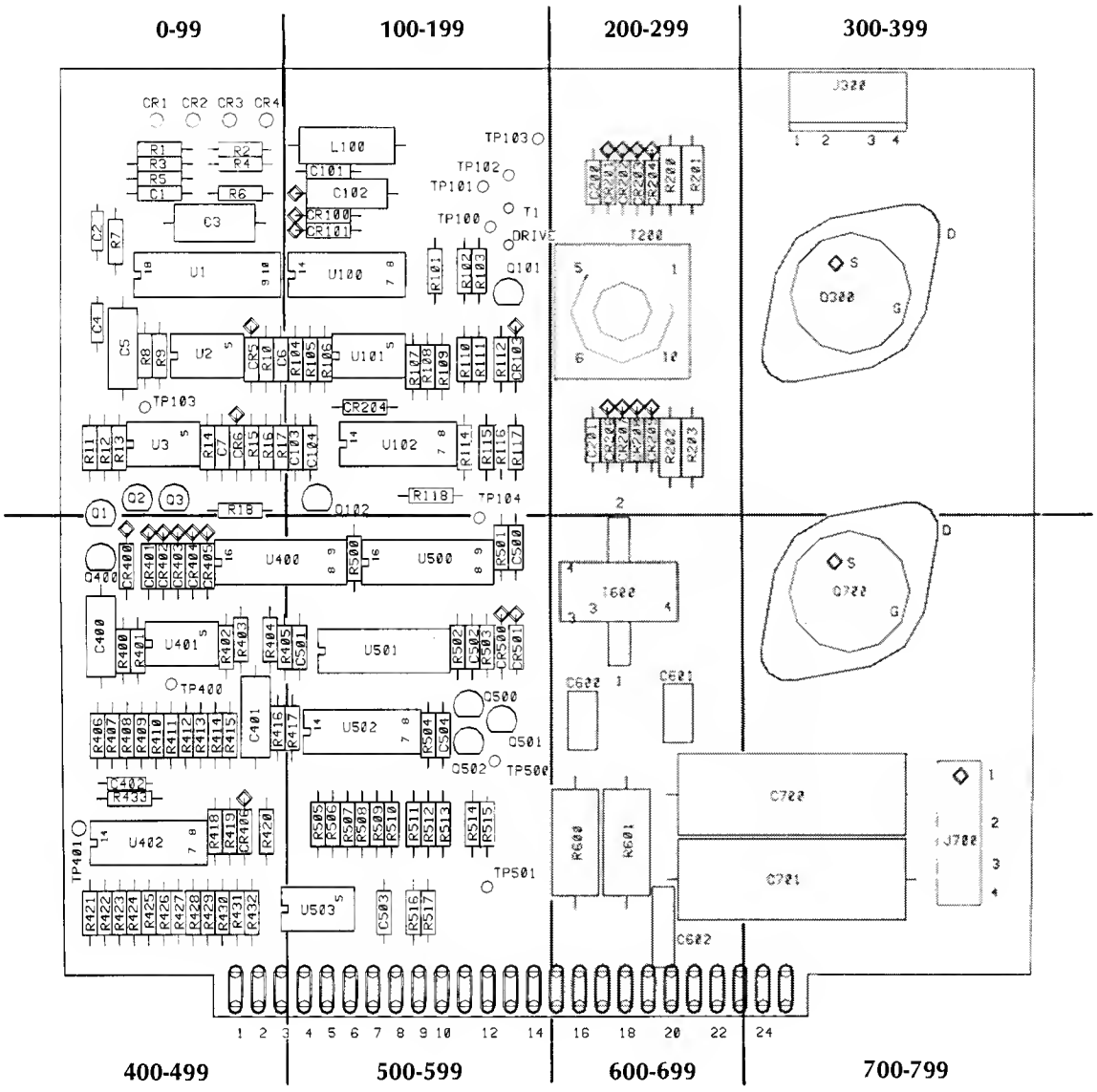


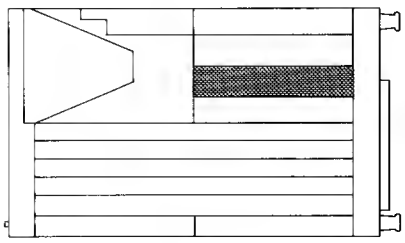
Probe: 10:1

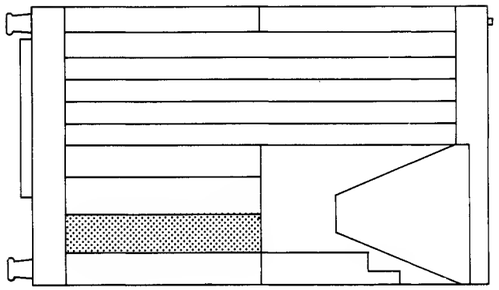
Ch1: Connection- Junction Of A71CR100
and A71R203
Coupling- dc
Ground- Center Graticule

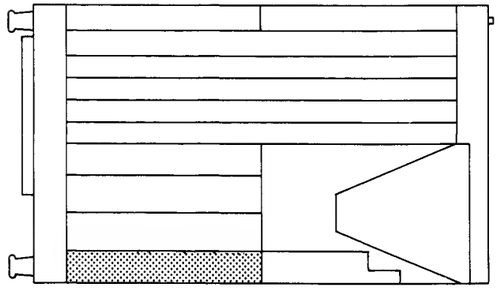
Trigger: Internal-Ch1
Slope: Positive

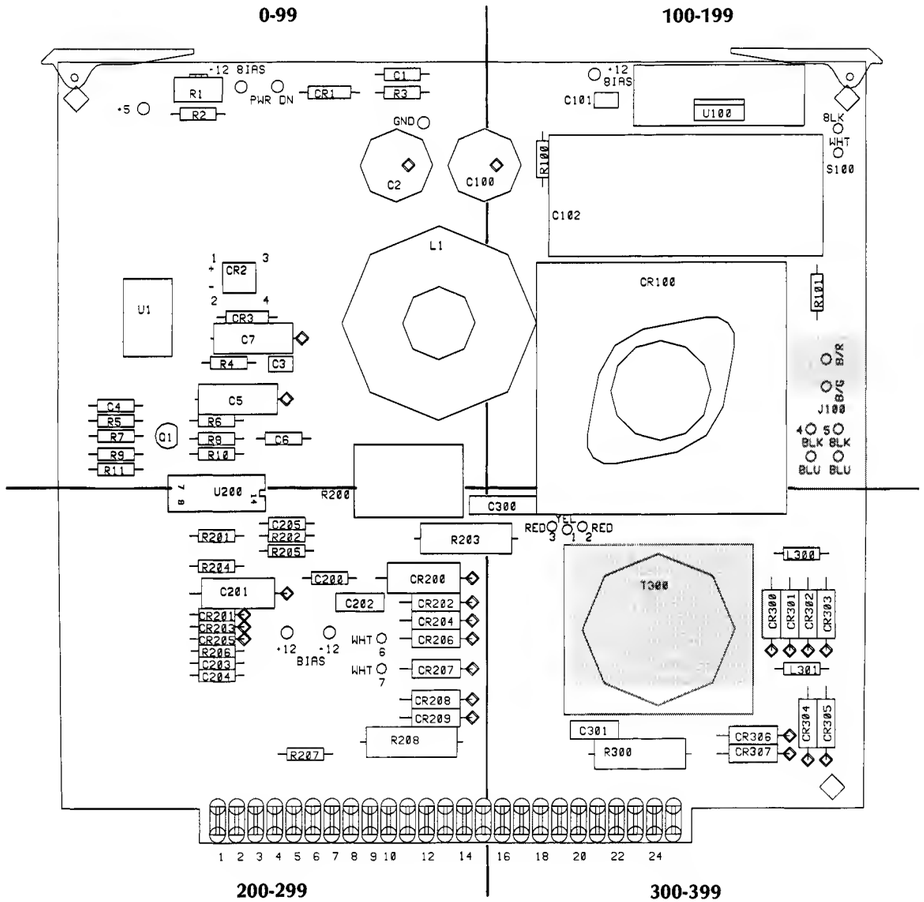
Bandwidth Limit: On


0-99
100-199
200-299
300-399
400-499
500-599
600-699
700-799

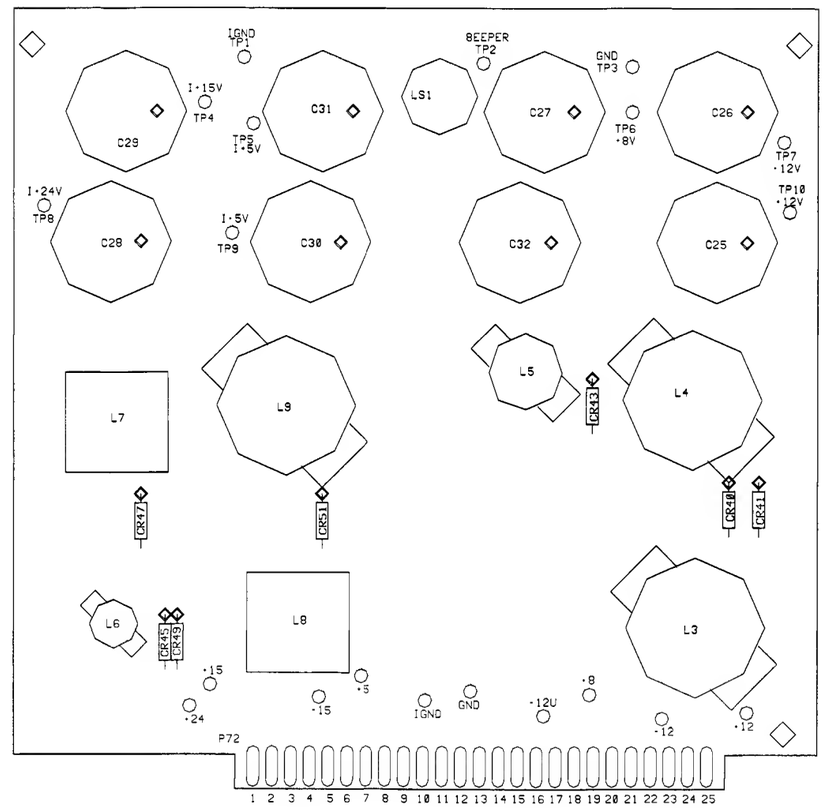







0-99
100-199
200-299
300-399
+12 BIAS
PWR ON
CR1
R1
R2
C1
R3
+5
GND
C2
C100
C101
+12 BIAS
U100
BLK
WHT
S100
R100
C102
L1
CR100
R101
J100
B/R
B/G
BLK BLK
BLU BLU
U1
CR2
CR3
C7
R4
C3
C5
C4
R5
R7
R9
R11
Q1
R6
R8
R10
C6
U200
R200
C300
R201
R202
R205
R204
C201
C200
C202
CR200
CR202
CR204
CR206
CR207
CR208
CR209
CR201
CR203
CR205
R206
C203
C204
+12 BIAS
+12
WHT
WHT
R203
RED
RED
T300
L300
L301
CR300
CR301
CR302
CR303
CR304
CR305
CR306
CR307
C301
R300
R208
R207
1 2 3 4 5 6 7 8 9 10 12 14 16 18 20 22 24

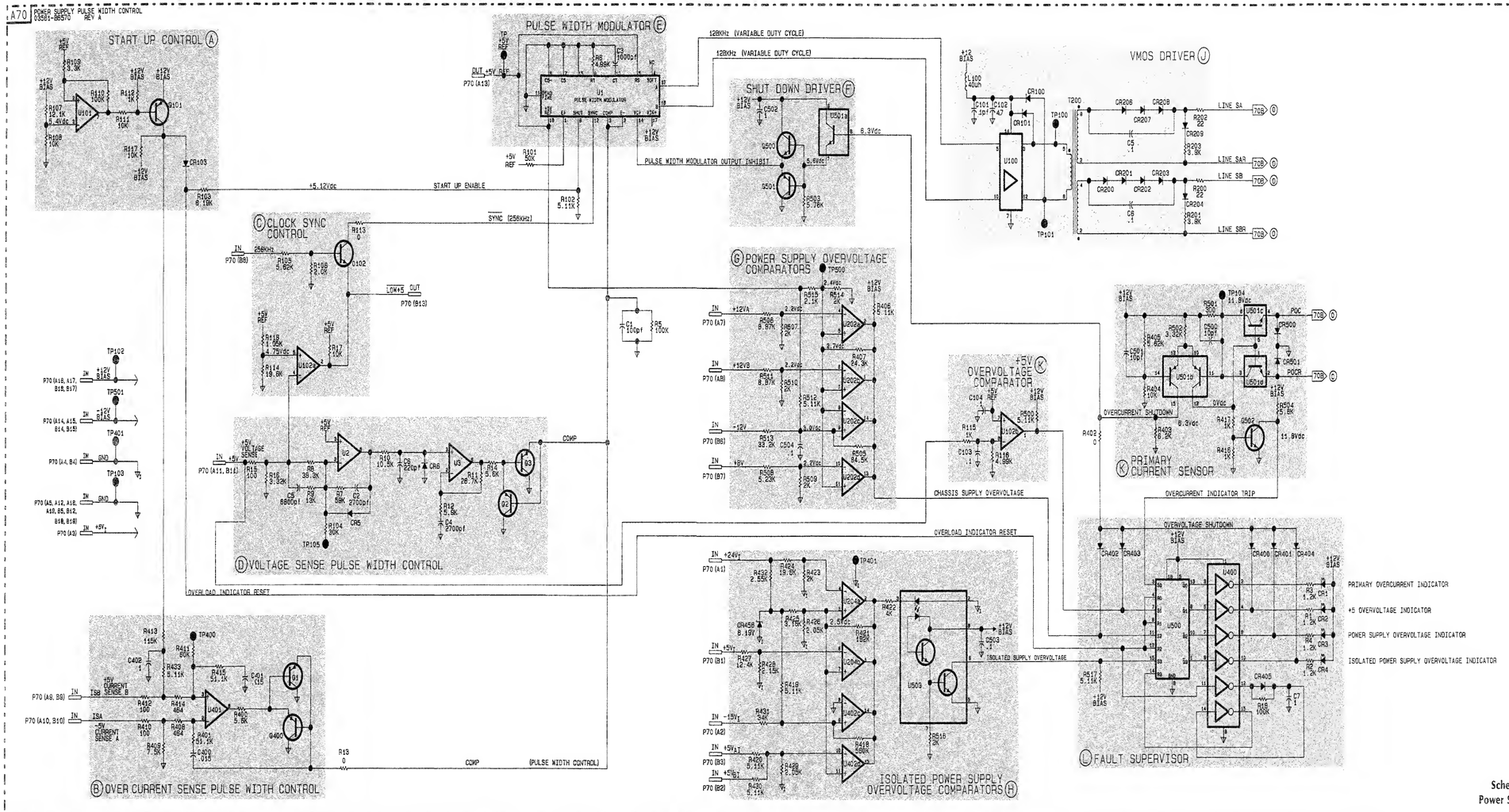
A71


IGND
TP1
BEEPER
TP2
GND
TP3
+15
TP4
TP5
+5V
TP6
+8V
TP7
+12V
+24V
TP8
+5V
TP9
TP10
+12V
C29
C31
LS1
C27
C26
C28
C30
C32
C25
L7
L9
L5
L4
CR43
CR47
CR51
CR40
CR41
L6
L8
L3
CR45
CR49
+15
+24
+5
IGND
GND
-12V
+8
+12
+12
P72
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25

A72

A70 Assembly

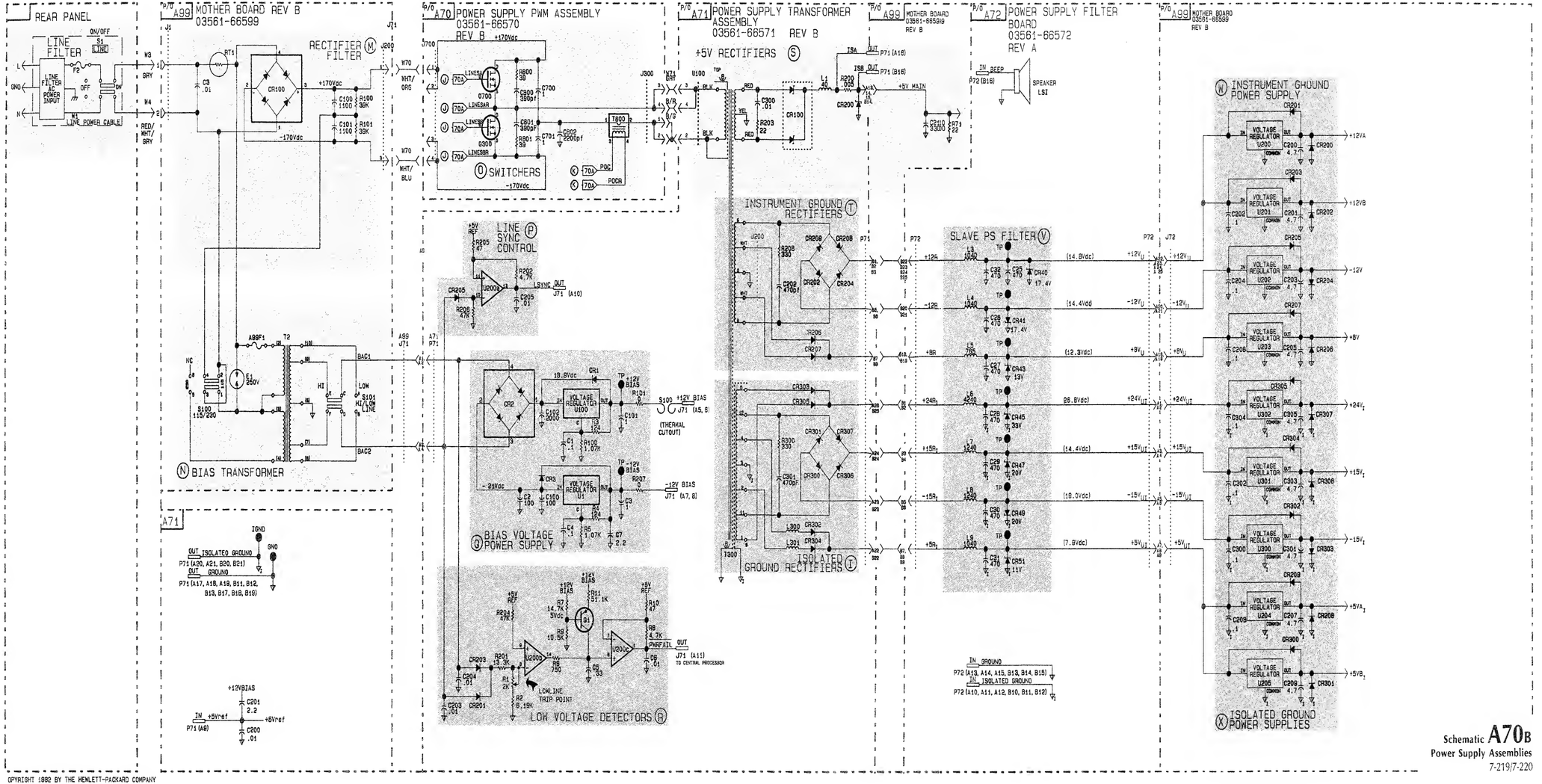
	+12VBIAS	-12VBIAS	$+5V_{IN}$	-15_{V1}	GND
U1	17				15
U2	7	4			
U3	7	4			
U101	8	1,4			
U400	1				8
U401	7	4			
U402			3	12	
U500	16				8
U502	3				12



Schematic **A70A**
Power Supply Assemblies
7-217/7-218

A71 Assembly

	+12VBIAS	GND
U200	3	12



7-31 A80 AND A81 KEYBOARD ASSEMBLIES

7-32 Keyboard Driver Circuit Descriptions

GENERAL

The front panel switches and LED's communicate with the processor over data lines PDB0 through PDB7. The processor can write to or read from the keyboard assembly. The processor periodically scans the keyboard to see if a switch has been pressed rather than working with an interrupt scheme. The individual blocks are explained in the text that follows.

[A] ADDRESS I/O DECODING

This circuitry is used to enable the various latches and drivers to accept or transmit data onto the front panel's internal bus. Processor address bits 0 and 1 are decoded by a 1 of 4 circuit. The four output lines are the enable lines for the functional blocks [C], [D] and [E].

[B] PROCESSOR DATA BUS BUFFER

This is a bi-directional 3-state device which interfaces the front panel with bits 0 through 7 of the data bus. The data direction and enable signals are PBR/$\overline{W}$ (read/not write) and FPS (front panel scan).

[C] SWITCH COLUMN DRIVE

This circuitry contains an octal latch and eight inverting buffers. The 8-bit bus is applied to the column switch poles through these devices. When a switch is depressed, the column data is transferred to the row circuitry and read by the processor.

[D] SWITCH ROW READ

The switch row read is an octal receiver. When a switch is depressed, the column data is applied to the input. When the processor wants to read the key, it will enable the receiver to output via the switch row select. This output then goes through the processor data bus buffer to the processor's data bus.

[E] LED DRIVE

Two octal D-flops store the LED data sent from the processor board. This data is output through two resistor packs to the cathodes of the LED's. The LED's are not multiplexed but rather enabled continuously.

7-33 Removing The Front Panel

WARNING

Disconnect the main power cord before attempting to remove the front panel.

The following procedure outlines the steps necessary to remove the front panel.

1. Remove the instrument's top and bottom covers.

WARNING

+8000 Vdc is present at all times in the flyback transformer and CRT EVEN WITH THE MAIN POWER CORD REMOVED. Be extremely careful when working in proximity to this area. The high voltage could cause serious personal injury or death if contacted.

2. Remove the four screws which secure the dress panel to the front panel casting. Refer to Figure 7-51 for their location.

3. Press the top dress panel tab on either side to remove the dress panel from the front panel casting.

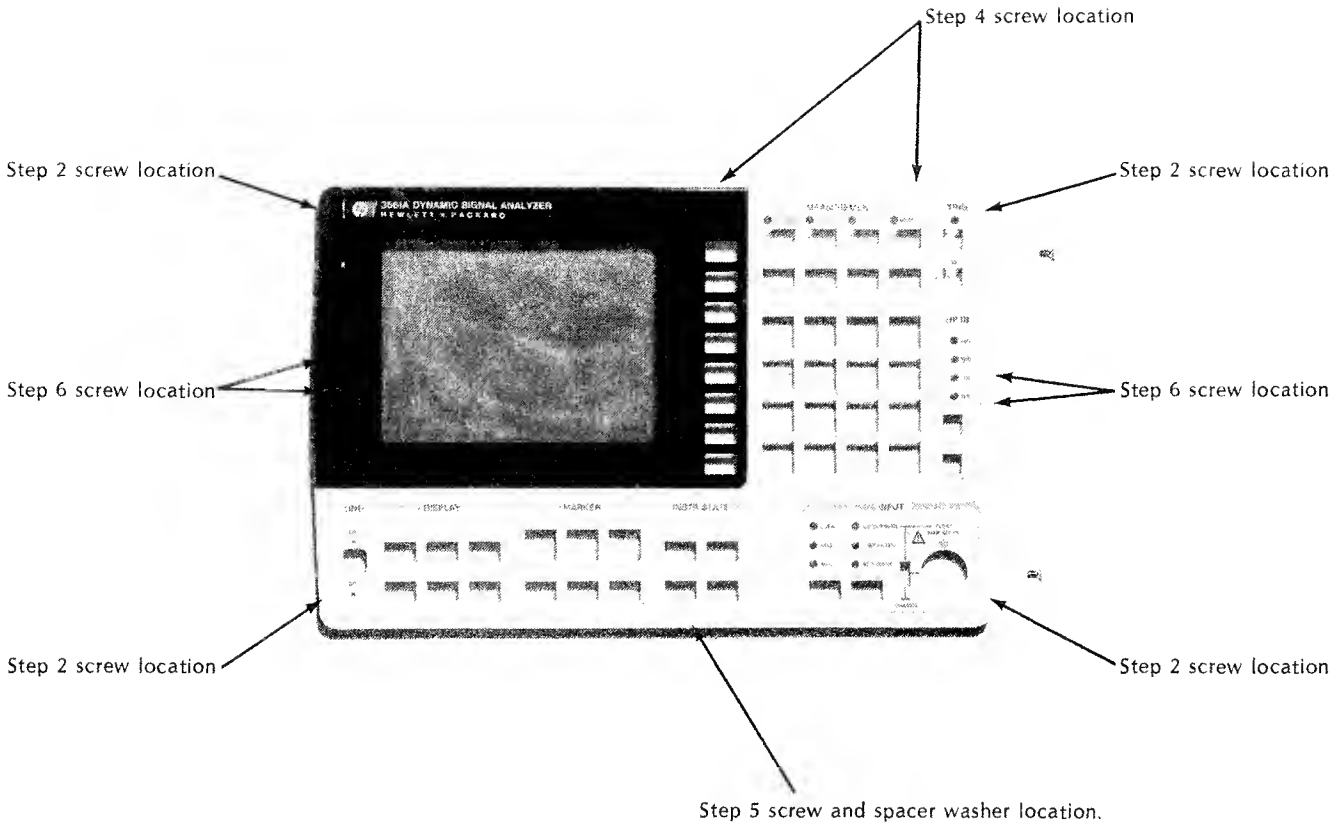
4. Remove the two screws on the top right of the front panel casting which hold it to the aluminum board guide bracket. The location is shown in Figure 7-51. Do not remove the two screws over the CRT. These screws hold the CRT shield to the front panel.

5. Remove the screw and spacer washer from the bottom center of the front panel casting. The location is shown in Figure 7-51.

6. Remove the four screws holding the front panel casting to the left and right side rails as shown in Figure 7-51.

7. Remove the input cable W10 from the A10 Input Amplifier Assembly by pulling the A10 connector away from the A10 Assembly toward the front of the instrument.

Figure 7-51 Front Panel Disassembly Screw Locations



The front panel can now be pulled away from the instrument frame. If the black and white wire assembly going from the Motherboard Assembly to the CRT yoke is removed from the motherboard connector, the front panel can be placed flat in front of the instrument frame.

WARNING

Do not damage or remove the green grounding wire which connects the front panel casting to the instrument's aluminum frame. Removing this wire will allow the front panel casting to float up to +8000 Vdc.

CAUTION

Be careful not to damage the ribbon cable W81 which connects the front panel circuitry with the instrument's motherboard assembly.

7-34 Troubleshooting the A80 and A81 Keyboard Assemblies

GENERAL

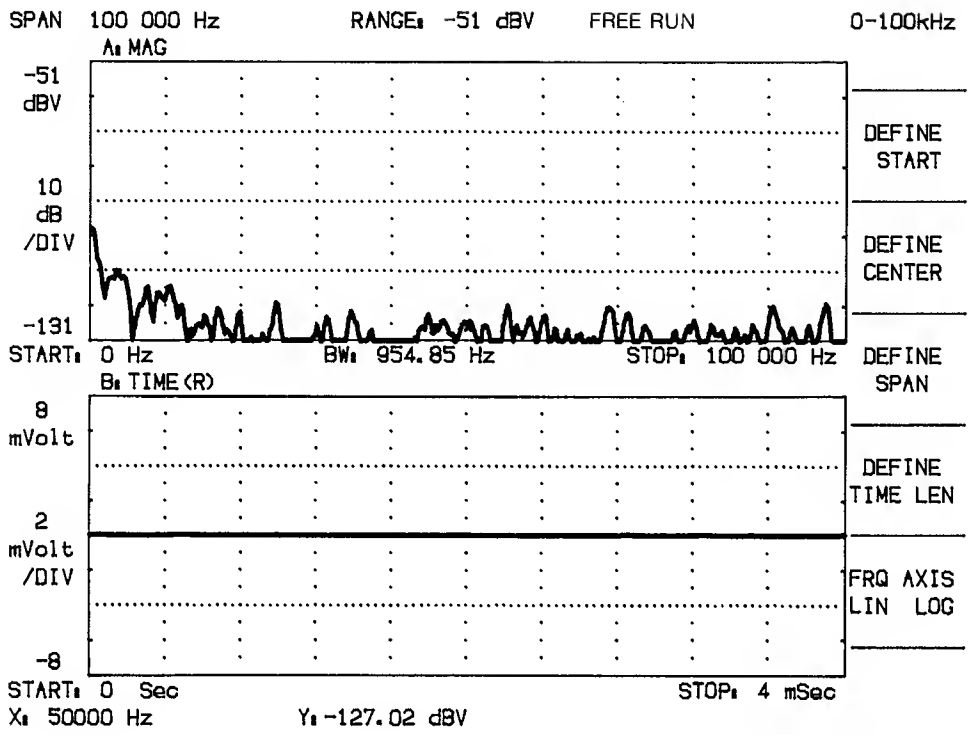
Failures on the A80 or A81 Keyboard Assemblies are not detected by the power-up test routine. There are also no built-in diagnostics which will test the keyboard assemblies and display an ERROR RETURN CODE should a failure exist. For these reasons, a list of keyboard failure symptoms is given in Table 7-58.

Signature analysis is used to troubleshoot the A81 Keyboard Driver Assembly.

Table 7-58 Keyboard Failure Symptoms

The following symptoms may occur if there is a failure on the keyboard assemblies:	
1.	During the power-up routine, the front panel LEDs should go through two lamp tests during which all LEDs should illuminate. If any of the LEDs do not illuminate, the failure may be on the A80 Keyboard Assembly. If none of the LEDs illuminate, the problem may be on the A81 Keyboard Driver Assembly.
2.	Immediately after the 10 second power-up routine, only the MEAS and AUTO LEDs should be illuminated. If either is not, the problem may be on the A80 Keyboard Assembly. If both are not, or there are any others illuminated, the problem may be on the A81 Keyboard Driver Assembly.
3.	Immediately after the 10 second power-up routine, the display shown in Figure 7-52 should appear on the CRT. Note particularly the definitions of the softkey menu. If the display does not match, there may be a stuck key on the A80 Keyboard Assembly. Check all keys and make sure that none are stuck in. There may also may be a shorted trace on the A80 Keyboard Assembly traces.
4.	Immediately after the 10 second power-up routine, if the CRT display continually flashes and the internal beeper continually sounds, there may be a stuck key or shorted trace on the A80 Keyboard Assembly.
5.	During instrument operation, pressing one of the front panel keys has no affect.
6.	During operation, pressing one of the front panel keys does not illuminate the correct LED indicator.
7.	Some or all of the HP-IB LED indicators does not illuminate during HP-IB operation and the instrument is operating properly under remote control.

Figure 7-52 Correct Power-up CRT Display



A81 KEYBOARD TROUBLESHOOTING

To troubleshoot the A80 and A81 Keyboard Assemblies, the front panel must be removed by following the instructions in Paragraph 7-33. However, to repair or replace either of the two assemblies, they must be removed from the front panel casting and separated.

With the front panel removed, the A81 Keyboard Driver Assembly is exposed. The A80 Keyboard Assembly is between the A81 Assembly and the front panel casting. The two assemblies make electrical contact through W80 which is a foam pressure cable. The foam supports one plane of fine wires. If these assemblies are pulled apart for repair, make certain that W80 is oriented properly with the fine wires making contact with the assembly connectors. Otherwise no contact will be made and the A80 Keyboard Assembly will not function.

To verify that the keyboard assemblies are causing symptoms 3 and 4, remove the keyboard interconnect cable W81 from the Motherboard Assembly and turn the instrument LINE switch ON.

WARNING

The green grounding wire which connects the front panel casting to the mainframe sheet metal must be connected and making good contact. If this wire is missing or not making good contact, the front panel will float up to +8000 Vdc!

If the instrument powers-up correctly, there is a problem with the Keyboard Assemblies. If however, the instrument still exhibits symptoms 3 and 4, there is a problem elsewhere in the instrument and you should refer to the fault isolation information in Section 6. Refer to Table 7-59 for the keyboard DSA troubleshooting information.

1. With the power turned OFF, remove the A60 Digital Display Driver Assembly (this disables the internal beeper which is activated during this test).

2. Move A40W1 from the left position to the right position as shown:

3. Turn the instrument ON and wait approximately 10 seconds before checking the signatures in Table 7-59.

Table 7-59 Keyboard DSA Troubleshooting Information

Connect the Signature Analyzer as follows:

Signal	Polarity	Connection
Clock		A81 TP FPS
Start		A40 CR1 (Green LED Cathode)
Stop		A40 CR1 (Green LED Cathode)

+5 V Signature - 5UAH

[A] Address I/O Decoding

U7(11)	5UAH
U7(13)	47P6
U7(14)	9HU7
U7(15)	P553

[B] Processor Data Bus Buffer

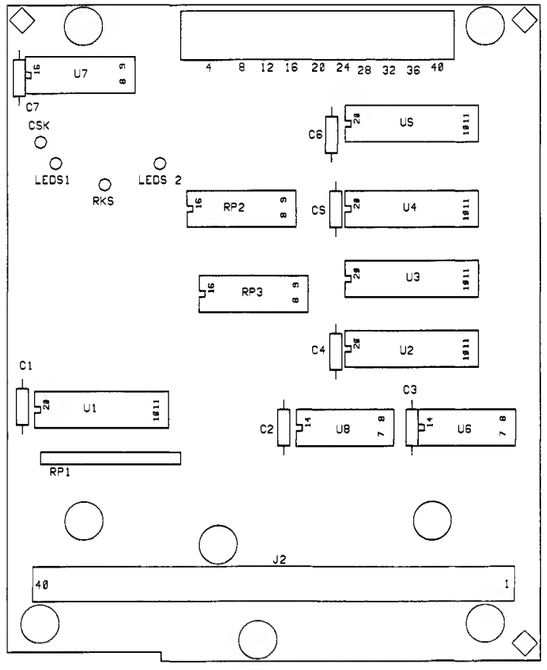
U5(2)	0836
U5(3)	A925
U5(4)	C17U
U5(5)	106F
U5(6)	524A
U5(7)	8209
U5(8)	F02U
U5(9)	A495

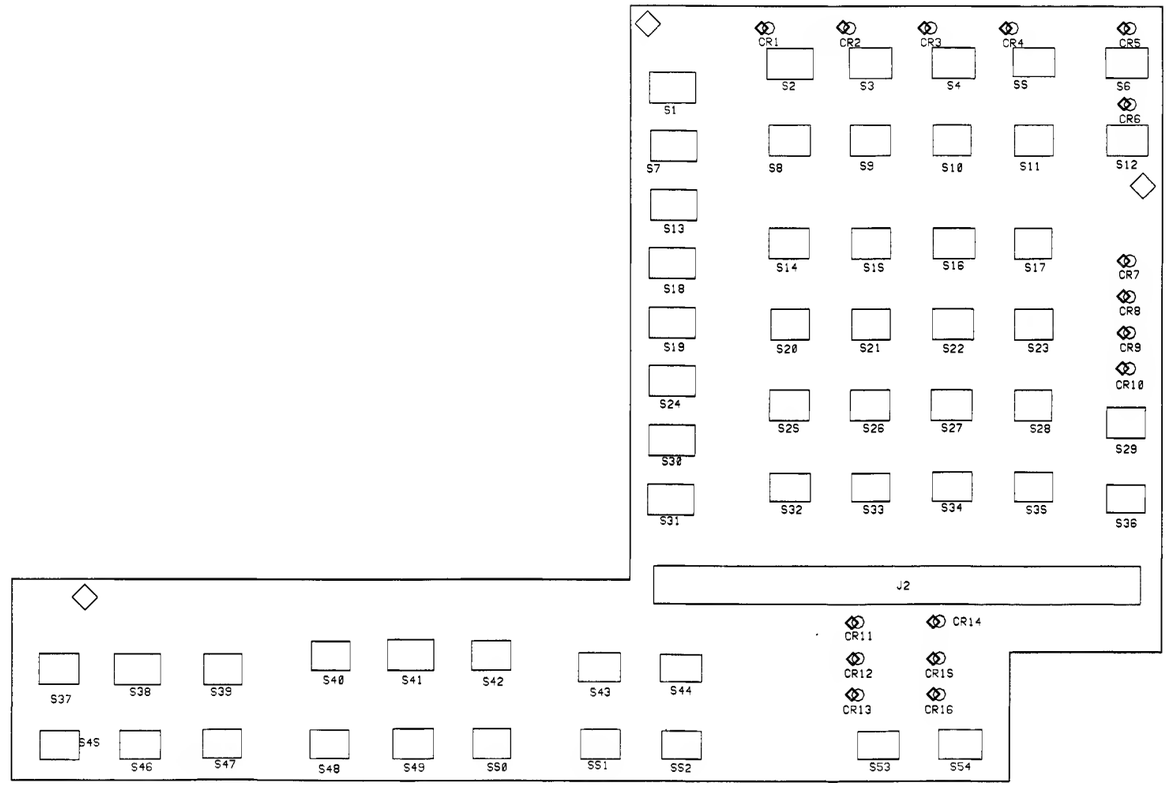
[C] Switch Column Drive

U2(2)	9968
U2(5)	5UAH (HIGH)
U2(6)	0000 (LOW)
U2(9)	9968
U2(11)	P553
U2(12)	H416
U2(15)	8CCC
U2(16)	4H7P
U2(19)	8CCC
U6(2)	0000 (LOW)
U6(4)	0000 (LOW)
U6(6)	0000 (LOW)
U6(8)	5UAH
U6(10)	0000 (LOW)
U6(12)	0000 (LOW)
U8(2)	0000 (LOW)
U8(4)	0000 (LOW)

[E] LED Drive

U3(2)	82H3
U3(5)	3FP5
U3(6)	5UAH (HIGH)
U3(9)	P19C
U3(11)	9HU7
U3(12)	P19C
U3(15)	3FP5
U3(16)	CP36
U3(19)	CP36
U4(2)	4402
U4(5)	4402
U4(6)	PF69
U4(9)	A86C
U4(11)	47P6
U4(12)	A86C
U4(15)	A86C
U4(16)	C3F4
U4(19)	U7F6


4 8 12 16 20 24 28 32 36 40
U7
C7
CSK
LEDS1
RKS
LEDS 2
C6
U5
RP2
C5
U4
U3
RP3
U2
C4
C1
U1
C2
U8
C3
U6
RP1
J2
40
1


CR1
CR2
CR3
CR4
CR5
CR6
CR7
CR8
CR9
CR10
CR11
CR12
CR13
CR14
CR15
CR16
S1
S2
S3
S4
S5
S6
S7
S8
S9
S10
S11
S12
S13
S14
S15
S16
S17
S18
S19
S20
S21
S22
S23
S24
S25
S26
S27
S28
S29
S30
S31
S32
S33
S34
S35
S36
S37
S38
S39
S40
S41
S42
S43
S44
S45
S46
S47
S48
S49
S50
S51
S52
S53
S54
J2

A81 KEYBOARD DRIVER ASSEMBLY

03561-66581

REV A

A80 KEYBOARD

03561-66580

REV A

INPUT

SIGNAL NAME	FUNCTIONAL BLOCK	CONN# PIN#	ORIGIN
FPS	A	J1 (13)	A40
PAB0	A	J1 (19)	A40
PAB1	A	J1 (20)	A40
PBR/W	A	J1 (15)	A40
+5V		J1 (1, 2 3, 4)	A70
GND		J1 (5, 6 11, 12 14, 16, 21, 22)	A70

I/O

SIGNAL NAME	FUNC. BLOCK	CONN# PIN#	ORIGIN
POB0	B	J1 (29)	A40
POB1	B	J1 (30)	A40
POB2	B	J1 (27)	A40
POB3	B	J1 (28)	A40
POB4	B	J1 (25)	A40
POB5	B	J1 (26)	A40
POB6	B	J1 (23)	A40
POB7	B	J1 (24)	A40

SWITCH COLUMN DRIVE (C)

SWITCH ROW READ (D)

ADDRESS I/O DECODING (A)

PROCESSOR DATA BUS BUFFER (B)

LED DRIVE (E)

SCS

SRS

LEDS2

LEDS1

SWITCH COLUMN SELECT

SWITCH ROW SELECT

LED SELECT2

LED SELECT1

TO A99 J81

WB1

J1

J2

WB0

U1 U2 U3 U4 U5 U6 U7 U8

RP1 10K

RP2 150

RP3 150

CR1 EXT SAMP

CR2 AVG

CR13 AUTO

CR16 AC CPL

CR15 AWT FILTER

CR12 HALF

CR11 OVER

CR14 ICP CURRENT

CR3 TIME BUFFER

CR4 MEAS HALT

CR5 TRIG SEL

CR6 ARM

CR7 REM

CR8 SRQ

CR9 LTN

CR10 TLK

SOFT KEY 1	NEXT TRACE	STORE/ RECALL	MODE	AVG	TIME BUFFER	START	TRIG SEL
S1	S37	S45	S2	S3	S4	S5	S6
SOFT KEY 2	DEFINE TRACE	UNITS	FREQ	WINDOW	SOURCE	PHASE /CONT	ARM
S7	S38	S46	S8	S9	S10	S11	S12
SOFT KEY 3	VERT SCALE	FORMAT	↑	7	8	9	LCL
S13	S39	S47	S14	S15	S16	S17	S29
SOFT KEY 4	←	MKR	↓	4	5	6	PLOT
S18	S40	S48	S20	S21	S22	S23	S36
SOFT KEY 5	FAST	SPCL MKR	MKR VALUE	1	2	3	
S19	S41	S49	S25	S26	S27	S28	
SOFT KEY 6	→	REL MKR	BACK SPACE	⌫	.	+/-	
S24	S42	S50	S32	S33	S34	S35	
SOFT KEY 7	SAVE	VIEW ON/OFF					RANGE
S30	S43	S51					S53
RETURN	RECALL	PRESET					INPUT
S31	S44	S52					S54

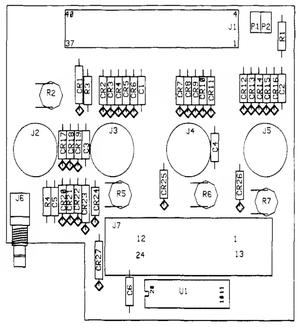
POWER AND GROUND CONNECTIONS

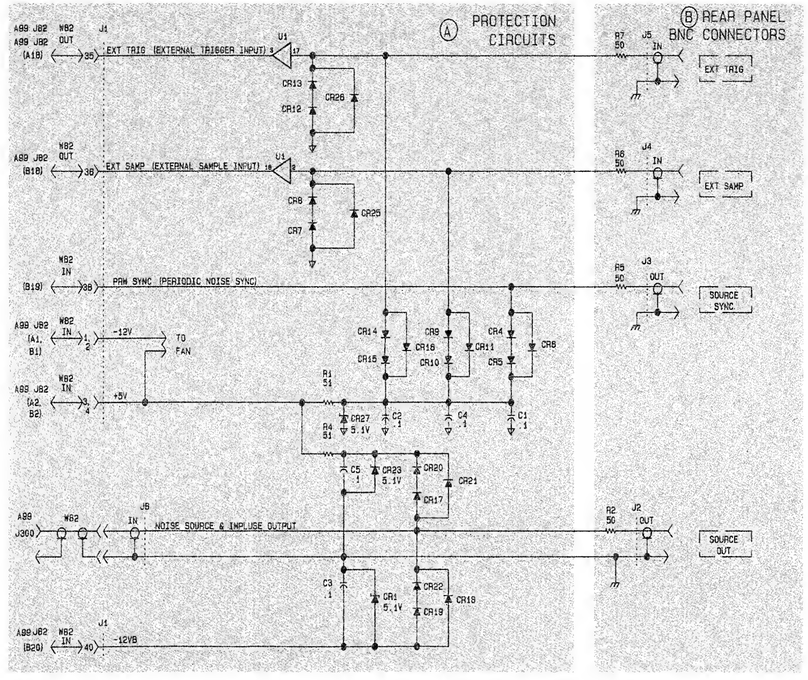
IC	+5V PIN#	GND PIN#	BI-PASS CAPACITOR
U1	20	10	C1
U2	20	10	C4
U3	20	10	
U4	20	10	C5
U5	20	10	C6
U8	14	7	C3
U7	16	8	C7
U8	14	7	C2

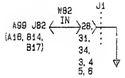
C1 .1 C2 .1 C3 .1 C4 .1 C5 .1 C6 .1 C7 .1

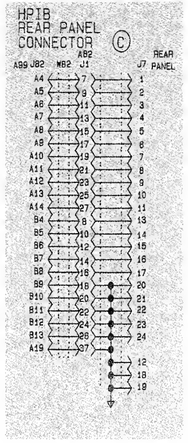
Schematic **A80**
Keyboard Assembly
Keyboard Driver Assembly
7-231/7-232

A82 REAR PANEL ASSEMBLY
03561-66582
REV B









7-36 A90 ANALOG DISPLAY DRIVER ASSEMBLY AND PART OF A99 MOTHERBOARD ASSEMBLY

7-37 Analog Display Driver Circuit Description

GENERAL

The main function of the analog display driver is to provide the CRT bias voltages and drive signals. The -hp-3561A uses a magnetic deflection CRT with a raster scan CRT sweep pattern. The raster scan pattern consists of a 512 horizontal by 256 vertical grid on the CRT screen. Each grid position is called a pixel. A pixel is illuminated when it is hit by the electron beam inside the CRT. This beam is turned on and off by the cathode drive signal and can be moved to any part of the CRT by a magnetic field created by the yoke. The yoke has two control inputs; vertical position control and horizontal position control. With the horizontal and vertical beam controls, the beam is swept down each vertical column of pixels, starting with the left most column and moving to the right. When all 512 columns of pixels have been covered, the beam is blanked and retraces to the start position. With this sweep pattern there are 512 vertical sweeps for each horizontal sweep, thus the vertical sweep is called the fast sweep and the horizontal sweep is called the slow sweep. The slow sweep operates at the power line frequency when jumper A60J200 is in the SYNC position and at 62.8 Hz when jumper A60J200 is in the 60 Hz position. The fast sweep operates at 36 kHz.

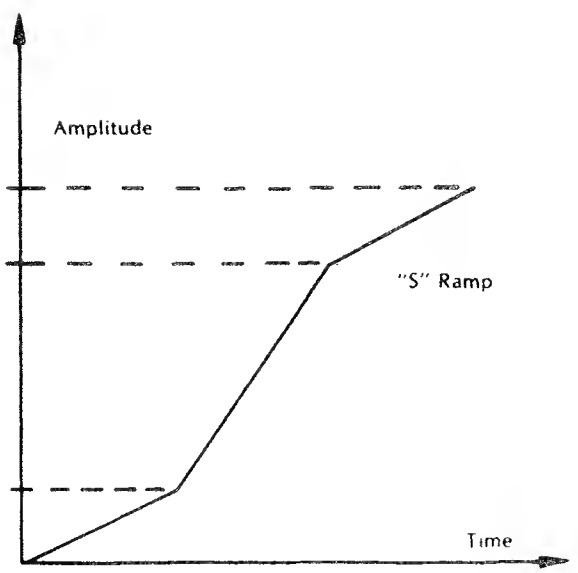
[A] VIDEO DRIVE

The video drive circuit provides the cathode drive signal (CATHD) which turns the CRT beam on or off. When the VIDH and the VIDF signals are both high, the CATHD signal is pulled high to +14.8 Vdc through Q203. This turns the CRT beam off. When the VIDF (video full bright) signal goes low, the CATHD signal is pulled low to -12 Vdc through Q202. This turns CRT beam on full intensity. When the VIDH (video half bright) goes low, the CATHD signal is pulled low to -9 Vdc ± 3 Vdc, (depending on the position of the half bright adjustment), through Q205. This turns the CRT beam on half intensity. The $+12V_U$ volt supply is an unregulated supply and may vary in voltage around +14.8 Vdc.

[B] SLOW SWEEP HORIZONTAL DRIVE

The slow sweep circuit generates an "S" shaped ramp signal used to drive the horizontal position of the yoke. This ramp is generated from the SSYNC signal which is output from the A60 Assembly. When SSYNC is high, Q400 is turned off allowing the current source (Q3) to charge C400 creating a ramp at TP100. When SSYNC goes low, Q400 is turned on pulling the voltage across C400 to ground. Feedback around C400 is provided to put an "S" shape into the ramp. This feedback loop uses CR1 and CR2 to divide the ramp into three sections. The "S" shape is created by giving the center section a larger gain as shown in Figure 7-53.

Figure 7-53 "S" Ramp



[D] FAST SWEEP VERTICAL DRIVE, [E] FLYBACK TRANSFORMER

The fast sweep circuit works in conjunction with the flyback transformer to generate a ramp signal to drive the vertical control of the yoke. The FSYNC (fast sync) signal generated on the A60 Assembly establishes the frequency of the vertical ramp. At power-on, capacitors C9, C102, and C103 all charge up to approximately +30 Vdc. These capacitors then provide constant voltages to power the flyback transformer. When PDRIVE goes high, Q1 on the A99 Assembly is turned on, shorting pin three of the flyback transformer to ground. This causes C102 to discharge through the vertical yoke coil, creating a ramp. When PDRIVE goes low, Q1 on the A99 Assembly is turned off causing a large current surge from the flyback transformer. The current surge charges C102 through the vertical yoke coil causing the CRT beam to retrace. Feedback of the retrace pulse is provided through the PSENSE signal. This feedback works to align the rising edge of PSENSE with the falling edge of FSYNC by changing the ON time of the PDRIVE signal. If the edges of the FSYNC and PDRIVE signals are not aligned, the display pattern will not be vertically centered on the CRT screen.

The matching between the flyback transformer, T100, and capacitors A99 C5, C6, C7, and C8 determines the retrace pulse width and the value of the CRT anode voltage. Whenever T100 is replaced, these capacitors must be re-selected using the procedures given in Section 7-38.

[F] HIGH VOLTAGE

The high voltage circuit uses two taps from the flyback transformer to generate the grid bias voltages for the CRT. When the PDRIVE signal goes low, a current surge is generated in the flyback transformer which causes a +450 Volt peak and a -150 Volt peak voltage spike. These voltages are low pass filtered and divided down to drive the CRT grids.

Table 7-60 A90 Assembly Signal Descriptions

Signal	Description
CATHD	CATHode Drive: Turns the CRT beam on or off; the voltage of this signal relative to the voltage of the BRIGHTNESS signal determines the intensity of the CRT beam.
FDRIVE	Fast Sweep Yoke DRIVE: Powers the vertical yoke coil.
FDRIVER	Fast Sweep Yoke DRIVE Return: Current return from the vertical yoke coil.
FSYNC	Fast Sweep SYNCronizer: This signal syncronizes the fast sweep trace with the slow sweep trace and the cathode drive signal.
PDRIVE	Pulse Drive: Initiates a retrace pulse on falling edge of PDRIVE.
PSENSE	Pulse SENSE: Detects a retrace pulse. Provides feedback to vertically center the display on the CRT screen.
RTRC	ReTRaCe: This signal is the PSENSE signal clipped to +5 Volts and indicates when a retrace is occurring.
SDRIVE	Slow Sweep Yoke DRIVE: Powers the horizontal yoke coil.
SDRIVER	Slow Sweep Yoke DRIVE Return: Current return from the horizontal yoke coil.
SSHAPE	S SHAPE: Provides feedback to put an "S" shape into the slow sweep ramp.
SSYNC	Slow Sweep SYNCronizer: This signal syncronizes the slow sweep trace with the fast sweep trace and the cathode drive signal.
VIDH	VIDeo Drive Half Bright: Turns the CRT beam on half intensity.
VIDF	VIDeo Drive Full Bright: Turns the CRT beam on full intensity.

7-38 Troubleshooting the Analog Display Driver

SAFETY CONSIDERATIONS

Troubleshooting the analog display driver may require placing the A90 Assembly on an extender board or removing the plastic shield from the bottom of the A99 Motherboard Assembly exposing dangerous voltages. Service should only be performed by service trained personnel who are aware af the hazards involved. voltages. Hazardous voltage areas are outlined in red on the schematic diagram and component locators. Use extreme care when troubleshooting in these areas.

WARNING

8000 Vdc are present at all times in the flyback transformer and CRT EVEN WHEN THE INSTRUMENT IS TURNED OFF. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

WARNING

Power Supply Capacitors on the A99 Motherboard Assembly will remain charged to ±170 Vdc for at least three (3) minutes after power is removed from the instrument. These voltages are exposed when the protective plastic shield is removed. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

WARNING

+450 and -150 Volts are present on the A90 Analog Display Driver Assembly and the A99 Motherboard Assembly. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

TROUBLESHOOTING AND REPLACING PARTS ON THE A99 MOTHERBOARD ASSEMBLY

All parts on the A99 Assembly should be checked by removing the protective plastic shield covering the bottom of the A99 Motherboard Assembly. The front panel should not be removed while power is applied to the instrument. Once a faulty component is isolated, the front panel can then be removed and the component replaced. Instructions for removing the front panel are given in Section 7-35 "A80 AND A81 KEYBOARD ASSEMBLIES"

WARNING

Disconnect the power cord before removing the front panel and replace the front panel before re-applying power. Do not disconnect the green grounding wire connecting the front panel the the chasis. If this grounding wire is disconnected the front panel can charge up to 8000 Vdc.

General Troubleshooting

By observing the characteristics of a display failure, the problem can usually be isolated to either the A90 Analog Display Driver Assembly or the A60 Digital Display Driver Assembly. If the CRT screen is completely blank, the failure could be related to any -hp-3561A assembly. Start the fault isolation procedure at TEST A to isolate these types of failures. The following display symptoms most likely indicate a failure in the A90 or A99 Analog Display Driver Assemblies:

- Vertical Position Incorrect
- Vertical Size Incorrect
- Horizontal Position Incorrect
- Horizontal Size Incorrect
- Brightness Will Not Adjust Correctly
- Focus Will Not Adjust Correctly
- Excessive Background Light

The following display symptoms most likely indicate a failure in the A60 Digital Display Driver Assembly, however, these symptoms can also be caused by the main processor. For information on isolating a failure to either the digital display driver or the main processor, see the fault isolation section of this manual.

- Random Dots Appear on the Screen
- Random Dots Missing on the Screen
- Failure Appearing Only on the Alpha Numerics
- Failure Appearing Only on the Graphics
- Graticule has Missing Lines, Missing Dots, or Extra Dots

The following display symptoms most likely indicate a failure in the CRT or yoke.

- Display Pattern Trapezoidal
- Display Pattern Tilted to one side or the other

The display adjustment procedures given in Section 2 of this manual should always be performed both before and after troubleshooting the A90 or A99 Assemblies.

A60 ASSEMBLY TEST SETUP

The A60 Assembly must be setup as shown below before troubleshooting the A90 and A99 Assemblies.

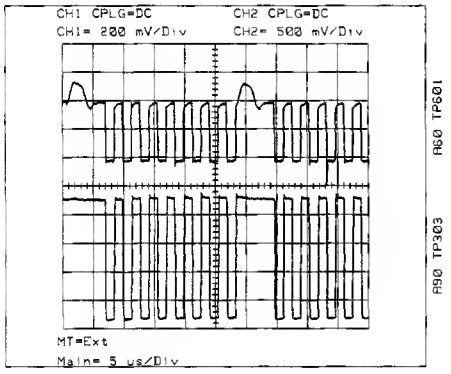
1. Turn the -hp-3561A LINE power switch OFF.

2. Move test jumper A60J100 to the PLANE2 position and jumper A60J200 to the 60 Hz position as shown on the A60 Assembly Component Locator.

[A] VIDEO DRIVE

With Jumper A60J100 in the PLANE2 test position, turn the -hp-3561A LINE power switch ON and check the waveforms given in Figure 7-54. Move test Jumper A60J100 to the PLANE1 test position and check the waveforms given in Figure 7-55.

Figure 7-54 PLANE2 Video Drive Waveforms



Probe: 10:1

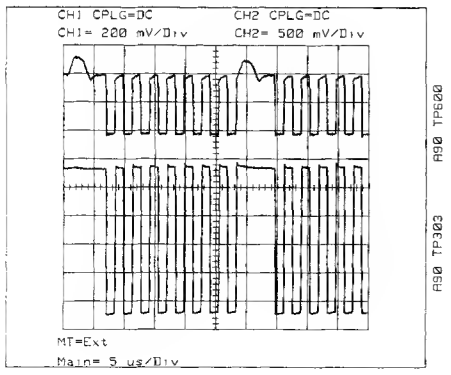
Ch1: Connection- A90 TP601 "VIDH"
Coupling- dc
Ground- Fourth Graticule From Top

Ch1: Connection- A90 TP303 "CATHD"
Coupling- dc
Ground- Second Graticule From Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

Bandwidth Limit: OFF

Figure 7-55 PLANE1 Video Drive Waveforms



Probe: 10:1
Ch1- Connection- A90 TP600 "VIDF"
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A90 TP303 "CATHD"
Coupling- dc
Ground- Third Graticule From Bottom

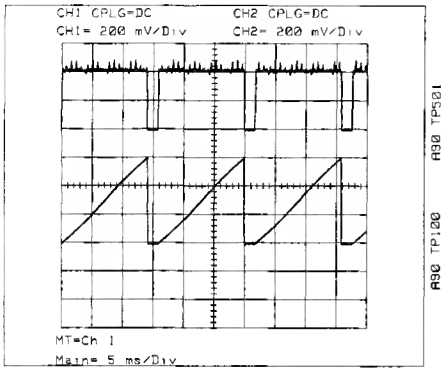
Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

Bandwidth Limit: OFF

[B] SLOW SWEEP HORIZONTAL DRIVE

Check the waveforms given in Figure 7-56 in the order given. Due to feedback, a failure in the voltage to current driver may cause an incorrect signal at the test point TP102.

Figure 7-56 Slow Sweep Horizontal Drive Waveforms



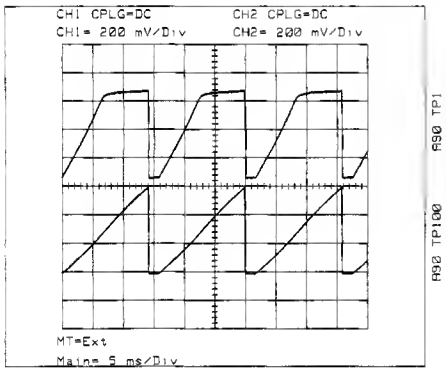
Probe: 10:1

Ch1: Connection- A90 TP501 "SSYNC"
Coupling- dc
Ground- Third Graticule from Top

Ch2- Connection- A90 TP100 "S Ramp"
Coupling- dc
Ground- Third Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



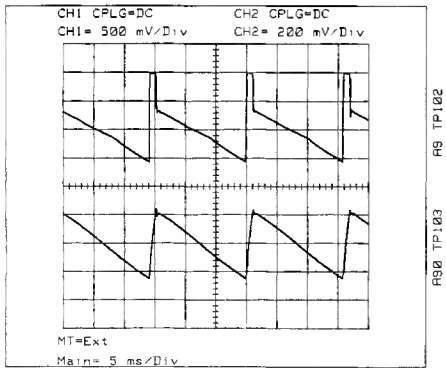
Probe: 10:1

Ch1: Connection- A90 TP1 "S Feedback"
Coupling- dc
Ground- Third Graticule from Top

Ch2: Connection- A90 TP100 "S Ramp"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1
Ch1: Connection- A90 TP102
Coupling- dc
Ground- Third Graticule from Top

Ch2: Connection- A90 TP103 "SYDRIVER"
Coupling- dc
Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

Bandwidth Limit: ON

Note: The amplitude and dc offset of these signals will vary with the horizontal gain adjustment and the horizontal position adjustment.

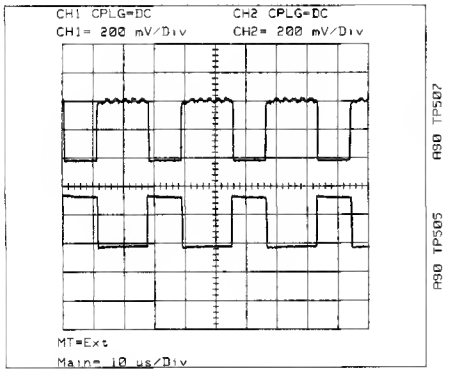
[D] FAST SWEEP VERTICAL DRIVE, [E] FLYBACK TRANSFORMER

The fast sweep vertical drive circuit should be tested first in open loop mode and then in closed loop mode. To break the PSENSE feedback loop, use a clip lead to short the two pins of A90J400 together. With A90J400 shorted, check the waveforms given in Figure 7-57 in the order given. If all of the waveforms in Figure 7-57 are correct, close the feedback loop by removing the clip lead shorting A90J400 and check the waveforms given in Figure 7-58.

NOTE

When A90 J400 is shorted, the display will appear to be vertically off center and will appear to wrap around the end of the screen.

Figure 7-57 Fast Sweep Waveforms in Open Loop Mode



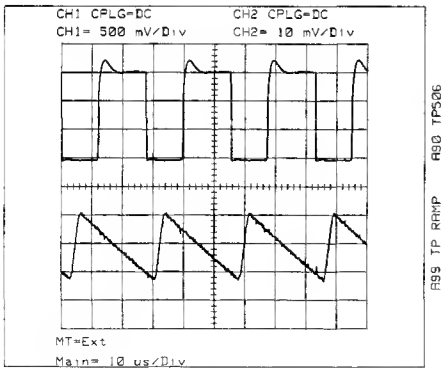
Probe: 10:1

Ch1: Connection- A90 TP507 "FSYNC"
Coupling- dc
Ground- Fourth Graticule from Top

Ch2: Connection- A90 TP505 "LOW PDRIVE"
Coupling- dc
Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

Bandwidth Limit: ON

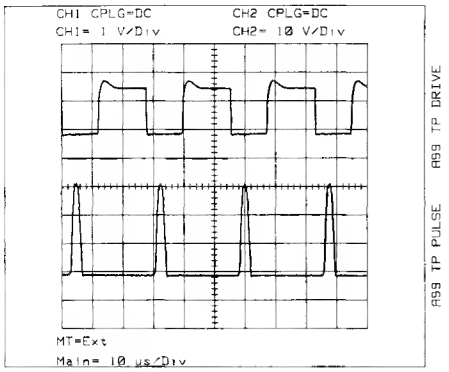


Probe: 10:1
Ch1: Connection- A90 TP506 "PDRIVE"
Coupling- dc
Ground- Fourth Graticule from Top

Ch2: Connection- A99 TP"RAMP"
Coupling- dc
Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope: Positive

Bandwidth Limit: ON



Probe: Ch1- 10:1 Probe on Ch1
Ch2- 10:1, 10 MΩ, Maximum Voltage ≥ 600 Vdc (-hp-10014A)

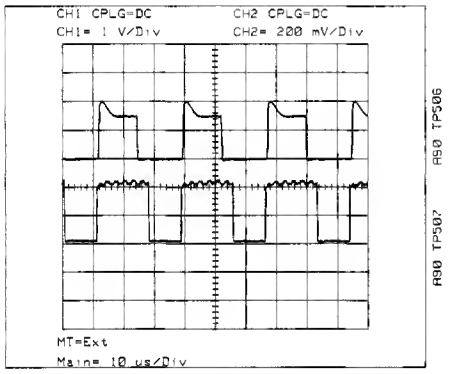
Ch1: Connection- A99 TP"DRIVE"
Coupling- dc
Ground- Third Graticule from Top

Ch2: Connection- A99 TP"PULSE"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

Bandwidth Limit: ON

Figure 7-58 Fast Sweep Waveforms In Closed Loop Mode



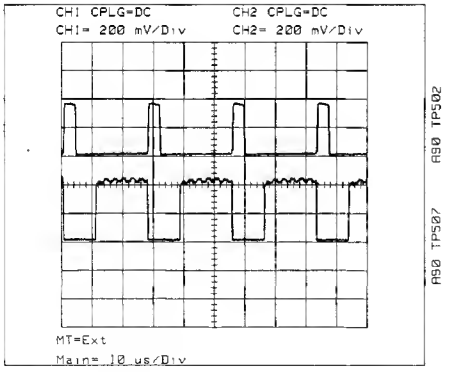
Probe: 10:1

Ch1: Connection- A90 TP506 "PDRIVE"
Coupling- dc
Ground- Fourth Graticule from Top

Ch2: Connection- A90 TP507 "FSYNC"
Coupling- dc
Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1 Probe on Ch1 and Ch2

Ch1: Connection- A90 TP502 "LOW PSENSE"
Coupling- dc
Ground- Fourth Graticule from Top

Ch2: Connection- A90 TP507 "FSYNC"
Coupling: Dc
Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC"
Slope- Positive

[F] HIGH VOLTAGE, [C] CATHODE RAY TUBE

WARNING

8000 Vdc present at all times in the flyback transformer and CRT EVEN WHEN THE INSTRUMENT IS TURNED OFF. Be extremely careful when working in proximity to this area. The high voltage could cause serious personal injury if contacted.

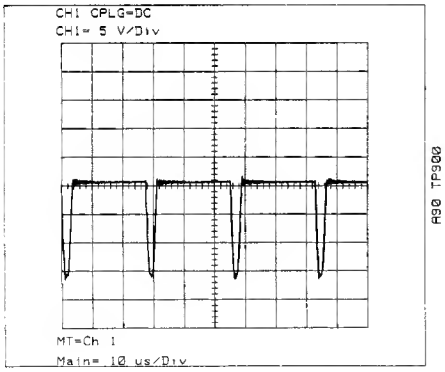
Use only high voltage probes with the specified characteristics when troubleshooting the high voltage circuits.

Before checking the high voltage signals, check for proper operation of the CRT heater. If the heater is operating correctly, there will be an orange glow at the back of the CRT.

A 10 MΩ 10:1 probe (-hp-10014A) which meets the required characteristics listed in Table 1-5 is required to check the +450 Vpeak and the -150 Vpeak waveforms of the flyback transformer. Lower impedance probes will load the high voltage circuit down, changing its operating characteristics. Check the high voltage waveforms given in Figure 7-59.

A 1000 MΩ, 1000:1 high voltage probe (-hp-34111A) which meets the required characteristics listed in Table 1-5 is required to check the 8000 Vdc CRT anode voltage. To measure this voltage, touch the tip of the probe to the anode cap as shown in Figure 7-60. The voltage should be 8200 Vdc ± 820 Vdc.

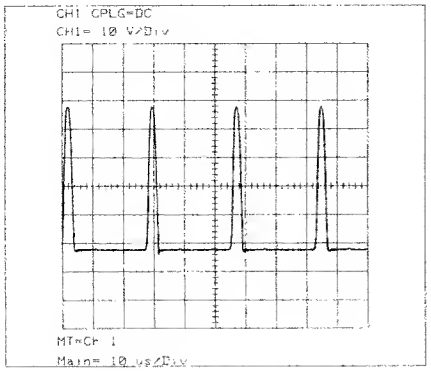
Figure 7-59 High Voltage Waveforms



Probe: 10:1, 10 MΩ, Maximum Voltage
≥ 600 Vdc
(-hp-10014A)

Ch1: Connection- A90 TP900 "-150 Vpeak"
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Negative

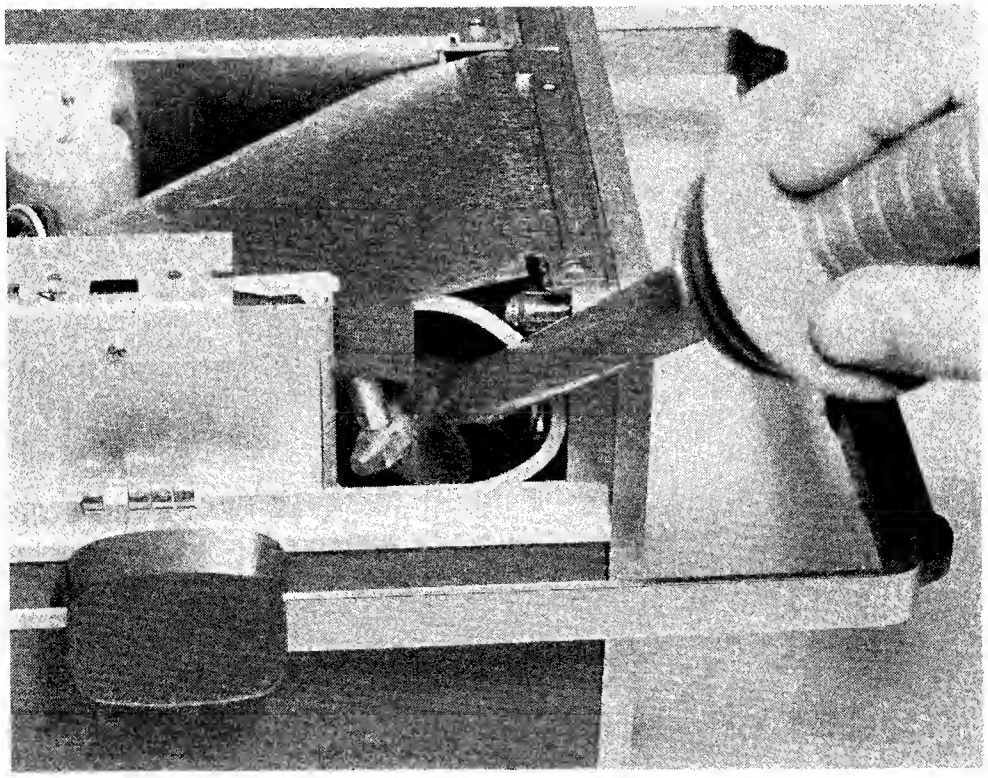


Probe: 10:1, 10 MΩ, Maximum Voltage
≥ 600 Vdc
(-hp-10014A)

Ch1: Connection- A90 TP304 "+450 Vpeak"
Coupling- dc
Ground- Third Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Figure 7-60 Measuring the CRT Anode Voltage



SELECTING A99 C5, C6, C7, AND C8

WARNING

Review the "Safety Considerations" and "Troubleshooting and Replacing Parts on the A99 Motherboard Assembly" paragraphs in this section before performing these procedures.

The matching between the flyback transformer, T100, and capacitors A99 C5, C6, C7, C8 determines the retrace pulse width and the CRT anode voltage. Whenever T100 is replaced, these capacitors must be reselected using the procedures given below. Capacitors C5, C6, C7, and C8 can each be loaded with any of the capacitor values given in Table 7-61, with the optimum loaded values given in Table 7-62. The optimum values will be correct for most transformers and is the usual factory loaded configuration.

Table 7-61 Possible Values for A99 C5, C6, C7, C8

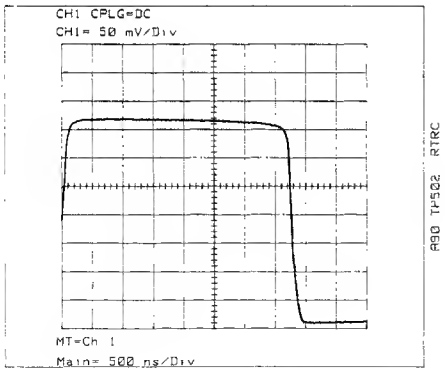
Capacitor Value	Maximum Voltage	-hp-Part Number
not loaded		
220 pF	1000 Vdc	0160-3454
470 pF	1000 Vdc	0160-3455
1000 pF	1000 Vdc	0160-3466

Table 7-62 Optimum Loaded Values for A99 C5, C6, C7, C8

Capacitor	Optimum Value
C5	1000 pF
C6	1000 pF
C7	not loaded
C8	not loaded

1. Connect the oscilloscope probe to A90TP502, turn the -hp-3561A LINE power switch ON, and set the oscilloscope to obtain the waveform given in Figure 7-61. Set the oscilloscope ground to the bottom graticule.

Figure 7-61 Retrace Pulse Width Measurement



Probe: 10:1

Ch1: Connection- A90 TP502 "RTRC"
Coupling- dc
Ground- Bottom Graticule

Trigger: Internal- Ch1
Slope- Positive

2. Measure the width of the "RTRC" pulse at the center horizontal graticule. The pulse width should be 3.7 microseconds ± .15 microseconds (± 1.5 minor division).

3. If the pulse width is too narrow, increase the total capacitance of C5 + C6 + C7 + C8 by by adding 230 pF for every .1 microseconds that the pulse width is too narrow. (e.g., If the pulse width is 3.5 microseconds wide, add a 470 pF capacitor to any one of the unloaded positions to bring the pulse width up to 3.7 microseconds.)

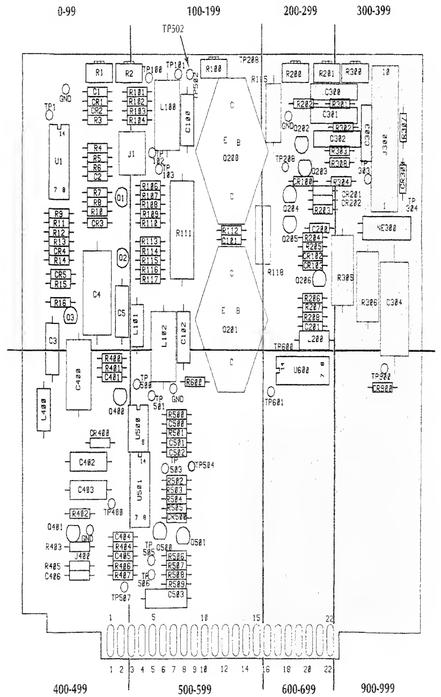
   If the pulse width is too wide, decrease the total capacitance of C5 + C6 + C7 + C8 by deleting 230 pF for every .1 microseconds that the pulse width is too wide. (eg., If the pulse width is 3.9 microseconds wide, replace one of the 1000 pF capacitors with a 470 pF capacitor to bring the pulse width down to 3.7 microseconds.

Table 7-63 A90 Assembly Signal Connections
INPUTS

Signal Name	Functional Block	Connector Number	Origin Assemblies
FSYNC	D	P90(B6)	A60
SSYNC	B	P90(A4)	A60
VIDF	A	P90(A18)	A60
VIDH	A	P90(19)	A60

A90 Assembly

	$+12_{V1}$	-12_{V1}	+5V	GND
U1	4	11		
U501			14	7
U600			14	7



A90 ANALOG DISPLAY DRIVER
03561-66590
REV A

VIDEO DRIVE (A)

SLOW SWEEP HORIZONTAL DRIVE (B)

FAST SWEEP VERTICAL DRIVE (D)

CATHODE RAY TUBE (C)

FLYBACK TRANSFORMER (E)

HIGH VOLTAGE (F)

P/O A99 MOTHERBOARD
03561-66599
REV B

NOTE:
SEE THE A90, A99 TROUBLESHOOTING PROCEDURES FOR INSTRUCTIONS ON SELECTING CAPACITORS C5, C6, C7, AND C8.

CAPACITORS C5, C6, C7 AND C8 ARE RESELECTED WHENEVER T100 IS REPLACED.

Schematic **A90**
Analog Display Driver Assembly
7-249/7-250

7-39 A99 MOTHERBOARD ASSEMBLY

7-40 Motherboard Circuit Description

The primary function of the motherboard assembly is to interconnect the signals of all -hp-3561A circuit assemblies. In addition to signal interconnect, the Motherboard Assembly contains part of the power supply circuits and part of the analog display driver circuits. Troubleshooting information for the power supply circuits is included with the A70, A71, and A72 Assemblies troubleshooting information. Troubleshooting information for the analog display circuits is included with the A90 Assembly troubleshooting information. Table 7-64 lists all inter-assembly signal connections.

Table 7-64 Signal Interconnect

Connector Number →	**J15**	J62
Pin Number —→	**B13**	A13
	↑ Signal Origin (Shown in bold)	↑ Signal Destination

Control and I/O Signals

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
A/D DATA		**J15**	J22												
		B13	A2												
ATN						J52							J82		
I/O						A18							A14		
BEEP							**J62**				J72				
							B8				B16				
$\overline{\text{BUBI}}$					J41			**J65**							
					A6			**A15**							
$\overline{\text{BUBS}}$					**J41**			J65							
					A10			B16							
$\overline{\text{CMOSS}}$					**J41**			J65							
					B10			B18							
COMP	**J10**	J15													
	B25	B1													
CONVERT		J15	**J22**												
		B16	**B2**												
COSINE			J21			**J51**									
			A19			**B8**									
DAV						J52							J82		
I/O						B16							A9		
$\overline{\text{DATAREQ}}$		J15	**J22**												
		B14	**B3**												
$\overline{\text{DMAI}}$			**J21**		J41										
			B16		A7										
$\overline{\text{DSPH}}$					J41		**J61**								
					B5		**A7**								
$\overline{\text{DSPS}}$					**J41**		J61								
					A9		A8								
$\overline{\text{DF1BG}}$			J22	**J32**											
			A11	**B12**											
$\overline{\text{DF2BG}}$			J22	**J32**											
			A10	**B13**											
$\overline{\text{DF3BG}}$			J22	**J32**											
			A9	**B14**											
$\overline{\text{DF1BR}}$			**J22**	J32											
			B11	A12											
$\overline{\text{DF2BR}}$			**J22**	J32											
			B10	A13											
$\overline{\text{DF3BR}}$			**J22**	J32											
			B9	A14											
ESR*4			**J21**			J51									
			A23			B3									
EOI						J52							J82		
I/O						B15							A8		

Control and I/O Signals

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
EXT SAMP			J22 A7										**J82 B18**		
EXT TRIG						J52 A8							**J82 A18**		
FECAL	J10 A15		**J21 B12**												
$\overline{\text{FECLKI}}$	**J10 A24**	J15 A2													
FECLK	J10 A16		**J21 B11**												
FEDATA	J10 B16		**J21 A11**												
FEDATAIC	J10 A25	**J15 A1**													
$\overline{\text{FEISO}}$			J21 B14												
FELATCHI	**J10 A23**	J15 A3													
FELATCH	J10 B15		**J21 A12**												
FETRIG		**J15 A13**	J22 B5												
$\overline{\text{FFTI}}$				**J31 B4**	J41 A8										
$\overline{\text{FPS}}$					**J41 B8**							J81 B14			
FSYNC							**J61 B4**								J90 B6
$\overline{\text{HPCI}}$					J41 B7	**J51 A7**									
$\overline{\text{HPDI}}$					J41 B6	**J51 A6**									
$\overline{\text{HPIBS}}$					**J41 B11**	J51 A11									
IFC						J52							J82		
I/O						A16							A12		
ISA									J70 A10 B10	**J71 A16**					
ISB									J70 A9 B9	**J71 B16**					
ISM	**J10 B23**	J15 A6													
$\overline{\text{LOS}}$					**J41 A11**	J51 A10									
$\overline{\text{LOW+5}}$					J42 B13				**J70 B13**						
LSYNC							J62 B9			**J71 A10**					
NDAC I/O						J52 B18							J82 A11		

Control and I/O Signals

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
NRFD						J52							J82		
I/O						B17							A11		
NOISE						**J52**							J6		J300
						B21									
$\overline{\text{PBG}}$				**J32**	J42										
				B16	B16										
$\overline{\text{PBLDS}}$				J31	**J41**										
				A6	**A12**										
$\overline{\text{PBR}}$				J32	**J42**										
				A16	**A16**										
PBR/$\overline{\text{W}}$				J31	**J41**	J51	J61	J65				J81			
				B7	**B13**	A13	**A13**	B15				B13			
$\overline{\text{PBUDS}}$				J31	**J41**	J51									
				B6	**A13**	B13									
PDRIVE														**J90**	A99
														A9	T1
														B9	
$\overline{\text{PRAMRE}}$				J31	**J41**										
				A7	**A4**										
$\overline{\text{PRIOS}}$				J32	**J42**										
				B17	**B17**										
PRN SYNC						**J52**							J82		
						A21							B19		
PSENSE														J90	**A99**
														A11	**T100**
														B11	
RBR/$\overline{\text{W}}$			J21	**J31**											
			A10	**B16**											
$\overline{\text{PWR FAIL}}$					J41					**J71**					
					A4					**A11**					
REN						J52							J82		
I/O						A15							B8		
$\overline{\text{RESET}}$			J21	J31	**J41**	J51	J61	J65				J81			
			A21	B3	**B3**	A3	A3	B17				B17			
$\overline{\text{RIOS}}$			J21	**J31**											
			B10	**A16**											
$\overline{\text{SINT}}$					J41	**J51**									
					B12	**A12**									
-SINE			J21			**J51**									
			B19			**A8**									
SRQ						J52							J82		
I/O						A17							A13		
SSTAT		**J15**	J22												
		A14	B4												
SSYNC							**J61**							J90	
							B5							B4	
SYNC2			**J21**			J51									
			B18			A5									
TRIG LVL	**J10**	J15													
	B24	B2													
VIDF							**J61**							J90	
							B3							A18	

Control and I/O Signals

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
VIDH							**J61**							J90	
							B2							A19	
ZPHTRIG			**J21**			J51									
			A17			A9									
1/3TRIG			J22			**J52**									
			B7			**A6**									
Data and Address Bus Signals															
DIO1						J52							J82		
I/O						B11							A4		
DIO2						J52							J82		
I/O						B12							A5		
DIO3						J52							J82		
I/O						B13							A6		
DIO4						J52							J82		
I/O						B14							A7		
DIO5						J52							J82		
I/O						A11							B4		
DIO6						J52							J82		
I/O						A12							B5		
DIO7						J52							J82		
I/O						A13							B6		
DIO8						J52							J82		
I/O						A14							B7		
PAB0					**J41**	J51	J61	J65				J81			
					B16	B16	B16	A12				B11			
PAB1					**J41**	J51	J61	J65				J81			
					A16	A16	A16	B12				A11			
PAB2					**J41**	J51	J61	J65							
					B15	B15	B15	A13							
PAB3					**J41**		J61	J65							
					A15		A15	B13							
PAB4					**J41**			J65							
					B14			A14							
PAB5					**J41**			J65							
					A14			B14							
PDB0				J31	J41	J51	J61	J65				J81			
I/O				B15	B24	B24	B24	A4				B6			
PDB1				J31	J41	J51	J61	J65				J81			
I/O				A15	A24	A24	A24	B4				A6			
PDB2				J31	J41	J51	J61	J65				J81			
I/O				B14	B23	B23	B23	A5				B7			
PDB3				J31	J41	J51	J61	J65				J81			
I/O				A14	A23	A23	A23	B5				A7			
PDB4				J31	J41	J51	J61	J65				J81			
I/O				B13	B22	B22	B22	A6				B8			
PDB5				J31	J41	J51	J61	J65				J81			
I/O				A13	A22	A22	A22	B6				A8			
PDB6				J31	J41	J51	J61	J65				J81			
I/O				B12	B21	B21	B21	A7				B9			
PDB7				J31	J41	J51	J61	J65				J81			
I/O				A12	A21	A21	A21	B7				A9			
PDB8				J31	J41	J51	J61	J65							
I/O				B11	B20	B20	B20	A8							

Data and Address Bus Signals

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
PDB9				J31	J41	J51	J61								
I/O				A11	A20	A20	A20								
PDBA				J31	J41	J51	J61								
I/O				B10	B19	B19	B19								
PDBB				J31	J41	J51	J61								
I/O				A10	A19	A19	A19								
PDBC				J31	J41	J51	J61								
I/O				B9	B18	B18	B18								
PDBD				J31	J41	J51	J61								
I/O				A9	A18	A18	A18								
PDBE				J31	J41	J51	J61								
I/O				B8	B17	B17	B17								
PDBF				J31	J41	J51	J61	J65							
I/O				A8	A17	A17	A17	B11							
RAB0			J21	J31	J42										
I/O			A2	B24	B11										
RAB1			J21	J31	J42										
I/O			B2	A24	A11										
RAB2			J21	J31	J42										
I/O			A3	B23	B10										
RAB3			J21	J31	J42										
I/O			B3	A23	A10										
RAB4			J21	J31	J42										
I/O			A4	B22	B9										
RAB5			J21	J31	J42										
I/O			B4	A22	A9										
RAB6			J21	J31	J42										
I/O			A5	B21	B8										
RAB7			J21	J31	J42										
I/O			B5	A21	A8										
RAB8			J21	J31	J42										
I/O			A6	B20	B7										
RAB9			J21	J31	J42										
I/O			B6	A20	A7										
RABA			J21	J31	J42										
I/O			A7	B19	B6										
RABB			J21	J31	J42										
I/O			B7	A19	A6										
RABC			J21	J31	J42										
I/O			A8	B18	B5										
RABD			J21	J31	J42										
I/O			B8	A18	A5										
RABE			J21	J31	J42										
I/O			A9	B17	B4										
RABF			J21	J31	J42										
I/O			B9	A17	A4										
RDB0			J22	J32											
I/O			A12	B11											
RDB1			J22	J32											
I/O			B12	A11											

Data and Address Bus Signals

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
RDB2			J22	J32											
I/O			A13	B10											
RDB3			J22	J32											
I/O			B13	A10											
RDB4			J22	J32											
I/O			A14	B9											
RDB5			J22	J32											
I/O			B14	A9											
RDB6			J22	J32											
I/O			A15	B8											
RDB7			J22	J32											
I/O			B15	A8											
RDB8			J22	J32											
I/O			A16	B7											
RDB9			J22	J32											
I/O			B16	A7											
RDBA			J22	J32											
I/O			A17	B6											
RDBB			J22	J32											
I/O			B17	A6											
RDBC			J22	J32											
I/O			A18	B5											
RDBD			J22	J32											
I/O			B18	A5											
RDBE			J22	J32											
I/O			A19	B4											
RDBF			J22	J32											
I/O			B19	A4											
Clocks															
100 kHz				J31	**J41**										
				B2	**A3**										
256 kHz			**J21**						J70						
			B23						B8						
4 MHz					**J41**	J51		J65							
					B2	A2		A17							
10.24 MHz		J15	**J21**			J51									
		A15	**A24**			B2									
20.48 MHz		J15	J21	J31	**J41**										
		B15	B24	A2	**A2**										
Common Ground Power Supplies															
+5V	J10	J15	J22	J32	J42	J52	J62	J65	J70	**J71**		J81	J82	J90	
	A13	A8	A21	A1	A1	A1	A1	A21	A11	**A13**		A19	A2	A4	
	B13	B8	B22	B1	B1	B1	B1	A22	B11	**A14**		A20	B2	B7	
			B22	B2	B2		B2	B21		**A15**		B19		B19	
								B22		**B14**		B20			
										B15					
+8V			J22												**A99**
			B21												**U203**

Common Ground Power Supplies

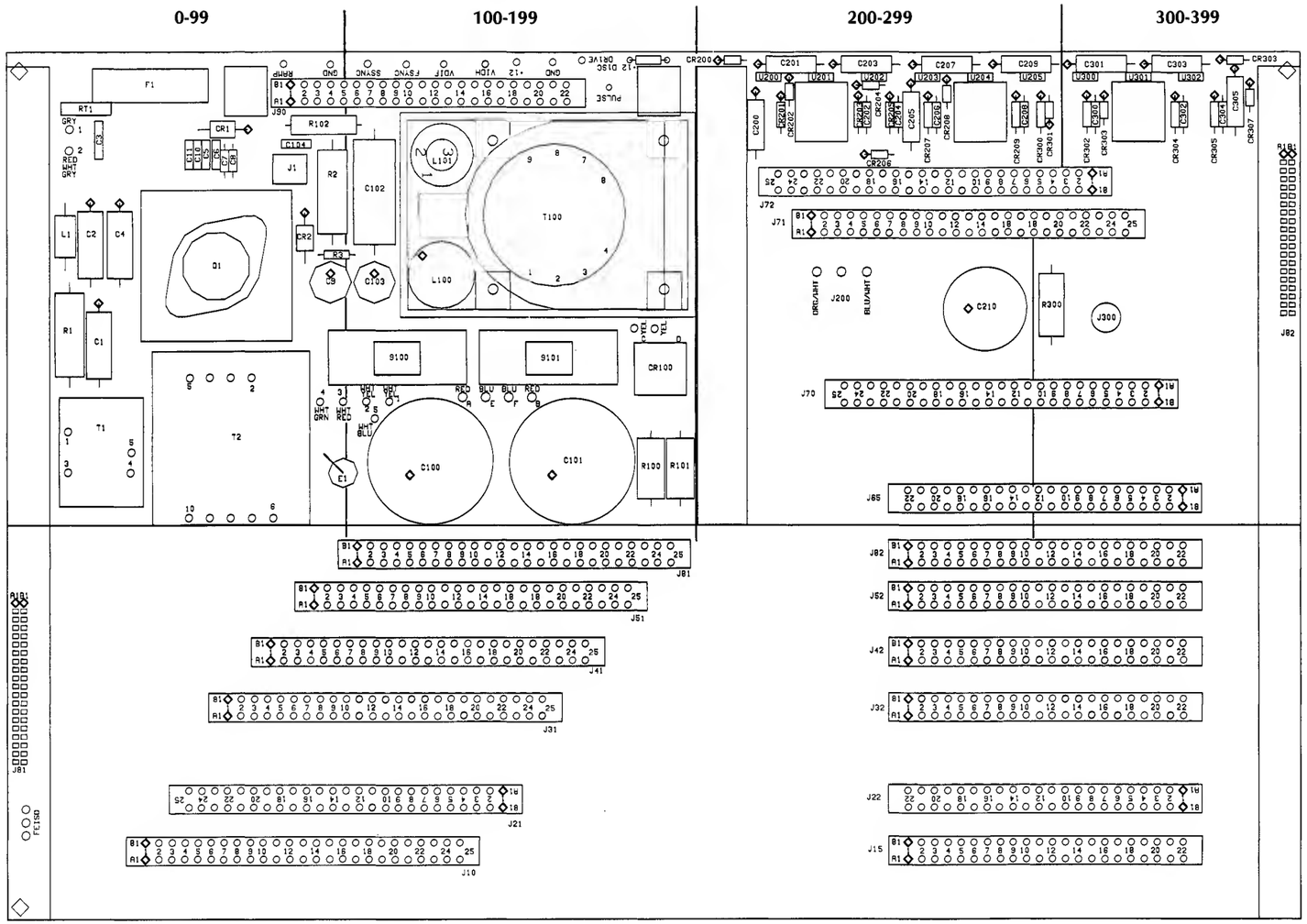
Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
$+12V_A$									J70 A7					J90 A2 A7 A21 B2 B21	**A99** **U200**
$+12V_B$		J15 A9 B9	J22 A20		J42 B3	J52 B3	J62 B3	J65 A20	J70 A8						**A99** **U201**
-12V		J15 A10 B10	J22 B20		 A3	J52			J70 B6				J82 B20	J90 A3 A20 B3 B20	**A99** **U202**
$+5V_{ref}$									**J70** **A13**	J71 A9					
+12VBIAS									J70 A16 A17 B16 B17	**J71** **A5** **A6**					
-12VBIAS									J70 A14 A15 B14 B15	**J71** **A7** **A8**					
+450 Vpeak														J90 B15	**A99** **T100**
-150 Vpeak														J90 A15	**A99** **T100**
Isolated Ground Power Supplies															
$+5V_{AI}$		J15 A21 B21							J70 B3						**A99** **U204**
$+5V_{BI}$	J10 A21 B21								J70 B2						**A99** **U205**
$+15V_I$	J10 A18 B18	J15 A18 B18							J70 B1						**A99** **U301**
$+24V_I$	J10 A11 B11								J70 A1						**A99** **U302**
$-15V_I$	J10 A17 B17	J15 A19 B19							J70 A2						**A99** **U300**

Unregulated Power Supplies

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
$+8V_U$ (+12V)											**J72**				A99
											A18				U203
											A19				
$+12V_U$ (+15V)											**J72**			J90	A99
											A22			B18	U200
											A23				U201
											A24				
											A25				
$-12V_U$ (-15V)											**J72**		J82		A99
											A16		A1		U202
											A17		B1		
											A20				
											A21				
$+5V_{UI}$ (+8VI)									J70		**J72**				A99
									A3		**A7**				U204
											A8				U205
											A9				
$+15V_{UI}$ (+19VI)											**J72**				A99
											A3				U301
											A4				
$+24V_{UI}$ (+27VI)											**J72**				A99
											A1				U302
											A2				
$-15V_{UI}$ (-19VI)											**J72**				A99
											A5				U300
											A6				
Raw Power Supplies (unfiltered)															
$+8V_R$										**J71**	J72				
										B7	B18				
										B8	B19				
$+12V_R$										**J71**	J72				
										B1	B22				
										B2	B23				
										B3	B24				
										B4	B25				
$-12V_R$										**J71**	J72				
										B5	B20				
										B6	B21				
$+5VI_R$										**J71**	J72				
										A22	B7				
										B22	B8				
											B9				
$+15V_{IR}$										**J71**	J72				
										A24	B3				
										B24	B4				
$+24V_{IR}$										J71	**J72**				
										A25	**B1**				
										B25	**B2**				
$-15V_{IR}$										**J71**	J72				
										A23	B5				
										B23	B6				

Line power supplies

Signal Name	Assemblies														
	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
BIAS AC1										J71 A1 A2					**A99 T2**
BIAS AC2										J71 A3 A4					**A99 T2**
+170 Vdc									J700 1						**J200 1 2**
-170 Vdc									J700 3						**J200 3 4**


0-99
100-199
200-299
300-399
J90
J1
J81
J72
J71
J70
J65
J82
J52
J42
J32
J22
J15
J51
J41
J31
J21
J10
J200
J300
C210
R300
CR100
CR200
CR303
T100
L100
T1
T2
C100
C101
R100
R101
Q1
Q9
CR1
CR2
R102
C102
C103
C124
L1
C2
C4
R1
C1
R2
R3
C3
RT1
F1
9100
9101
C201
C203
C207
C209
C301
C303
U200
U201
U202
U203
U204
U205
U300
U301
U302
C200
C205
C206
C208
C300
C302
C304
C305
CR200
CR201
CR202
CR203
CR204
CR205
CR206
CR207
CR208
CR209
CR300
CR301
CR302
CR303
CR304
CR305
CR307
J81
J82
FC150

APPENDIX A QUICK REFERENCE

This quick reference contains abbreviated operating information for the -hp-3561A. Included in this section is a brief description of the -hp-3561A front and rear panels, and a map illustrating the -hp-3561A menus.

MENU DEFINED KEYS
The menu defined keys are defined by the display menu entries. Menus are selected and displayed by pressing a labeled front panel key.

MEASUREMENT KEY GROUP
The measurement group indicators illuminate when a measurement is in progress, or measurement options are selected or enabled. The measurement group keys control the measurement and select menus for altering measurement parameters and options.

EXT SAMP indicator illuminates when the external sampling mode is enabled.

AVG key indicator illuminates when an averaging process is selected.

TIME BUFFER key indicator illuminates when the time capture mode is selected.

MEAS indicator illuminates when a measurement is in progress.

MODE key displays a menu for selecting the instrument measurement mode (narrow band, third octave, full octave, time capture, external sample, or test modes).

AVG key displays a menu for selecting the type of averaging process applied to the measurement.

TIME BUFFER key displays a menu for initiating a time capture operation and defining the time capture mode parameters.

START key clears the time record and accumulated average results, and initiates a measurement.

FREQ key displays a menu for defining the measurement frequency parameters.

WINDOW key displays a menu for selecting the window applied to the input signal.

SOURCE key displays a menu for enabling the -hp-3561A noise source and selecting the noise type.

PAUSE/CONT key suspends an in progress measurement or continues a suspended measurement.

TRIGGER KEY GROUP
The trigger group keys control the trigger function. The trigger indicators illuminate to indicate the trigger status.

TRIG SEL key indicator illuminates when the -hp-3561A is triggered.

TRIG SEL key displays a menu for selecting and defining the trigger used for starting a measurement.

ARM key indicator illuminates when the -hp-3561A is armed and waiting for a valid trigger.

ARM key resets the trigger circuits when the manual arm trigger mode is selected.

HP-IB KEY GROUP

HP-IB group keys control the HP-IB and plotting functions. HP-IB indicators illuminate to indicate the HP-IB status.

RMT indicator illuminates when the -hp-3561A is operating under HP-IB control. In the remote mode, (and the **LCL** key is not locked out by the controller), only the **LCL** key is recognized by the -hp-3561A.

SRQ indicator illuminates when the -hp-3561A generates an HP-IB service request.

LTN indicator illuminates when the -hp-3561A is addressed to listen over the HP-IB.

TLK indicator illuminates when the -hp-3561A is addressed to talk over the HP-IB.

LCL key displays a menu for setting the HP-IB address, enabling the talk only mode, and enabling the HP-IB power on service request.

PLOT key displays a menu for selecting and defining plotter options.

LINE KEY

LINE key applies power to the -hp-3561A circuits.

DISPLAY KEY GROUP
The display group keys affect the display format.

NEXT TRACE key selects the active trace on the display. For a single trace format **NEXT TRACE** toggles the display between the two available traces. The active trace is the trace displayed. For an upper/lower trace format, the active trace is identified by an intensified label over the trace graticule. For a front/back trace format or map format, the active trace is intensified.

DEFINE TRACE key displays a menu for selecting the magnitude, phase, time, or math trace functions.

VERT SCALE key displays a menu for scaling the vertical display axis.

STORE/RECALL key displays a menu for storing traces in memory, recalling traces from memory, and entering trace labels.

UNITS key displays a menu for selecting and defining the vertical and horizontal axis units of the display.

FORMAT key displays a menu for selecting a single trace, upper/lower trace, front/back trace, or map display format.

MARKER GROUP KEYS
The marker group keys affect the operation of the marker. The ◀ , **FAST**, and ▶ keys position the marker on the active trace. **FAST**, when used with the arrow keys, moves the marker at a faster rate.

MKR key displays a menu for selecting absolute marker functions.

SPCL MKR key displays a menu for selecting band marking, harmonic marker, and sideband marker measurements.

REL MKR key displays a menu for enabling the relative marker function and defining the reference values for the relative measurements.

INSTRUMENT STATE KEY GROUP
The instrument state group keys affect the instrument setup configuration.

SAVE key displays a menu for storing the current instrument state in nonvolatile memory.

RECALL key displays a menu for recalling an instrument state from nonvolatile memory.

VIEW ON/OFF key toggles the display between a graphic trace display and a tabular text display of the instrument state.

PRESET key initializes the -hp-3561A to the most commonly required setup.

INPUT KEY GROUP
The input group keys control the -hp-3561A input circuits. The input group indicators provide an indication of the input circuit status.

OVER indicator illuminates when the input signal amplitude exceeds the maximum range of the signal processing circuits.

HALF indicator illuminates when the input signal level is greater than one-half the maximum input range value. An optimum input level illuminates the **HALF** indicator without illuminating the **OVER** indicator.

AUTO indicator illuminates when the -hp-3561A auto-ranging circuits are enabled.

ICP CURRENT indicator illuminates when the -hp-3561A ICP current source is enabled.

A WT FILTER indicator illuminates when an internal A-weighting filter is in the -hp-3561A input signal path.

AC COUPLE indicator illuminates when ac coupling is selected.

RANGE key displays a menu for setting the input range or selecting auto-range.

INPUT key displays a menu for selecting the -hp-3561A input circuits (ac/dc coupling, A-weighting filter, or ICP current source) or calibration circuits.

FLOAT-CHASSIS switch connects the input circuit ground reference to chassis ground or isolates (floats) it from chassis ground.

WARNING

Do not isolate the -hp-3561A from earth ground by interrupting the protective earth conductor inside or outside the -hp-3561A. Interruption of the protective earth conductor can subject the operator to lethal voltages.

INPUT connector provides a high impedance input (1 MΩ).

REAR PANEL CONNECTORS

SOURCE OUTPUT connector is the output for the -hp-3561A pseudo-random noise source or impulse generator. This output is enabled through the **SOURCE** key menu.

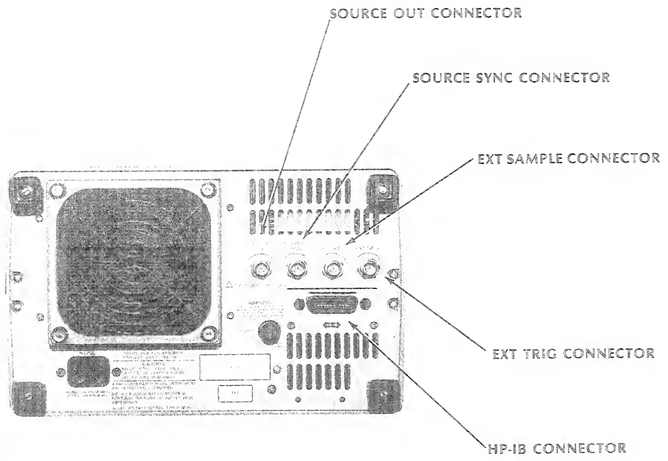
A positive **SOURCE SYNC** output marks a time record that coincides with an impulse or pseudo-random noise output. The output occurs at the start of the time record. If the trigger is derived from the internal noise source or impulse generator, the output is synchronized to the source trigger signal. The **SOURCE SYNC** output is a TTL level pulse.

The -hp-3561A sampling frequency is controlled through the **EXT SAMPLE** connector when the external sampling mode is enabled through the **MODE** key. The **EXT SAMPLE** input is TTL compatible.

External trigger sources connect to the -hp-3561A through the **EXT TRIGGER** input connector. The -hp-3561A trigger circuits sense this connector when **EXTERNAL TRIGGER** is selected through the **TRIG SEL** key menu. The trigger input is TTL compatible.

External HP-IB devices communicate with the -hp-3561A through the rear panel HP-IB connector. The -hp-3561A controls a printer or plotter through this connector.

CROSS REFERENCE TO CHAPER II OPERATOR'S REFERENCE



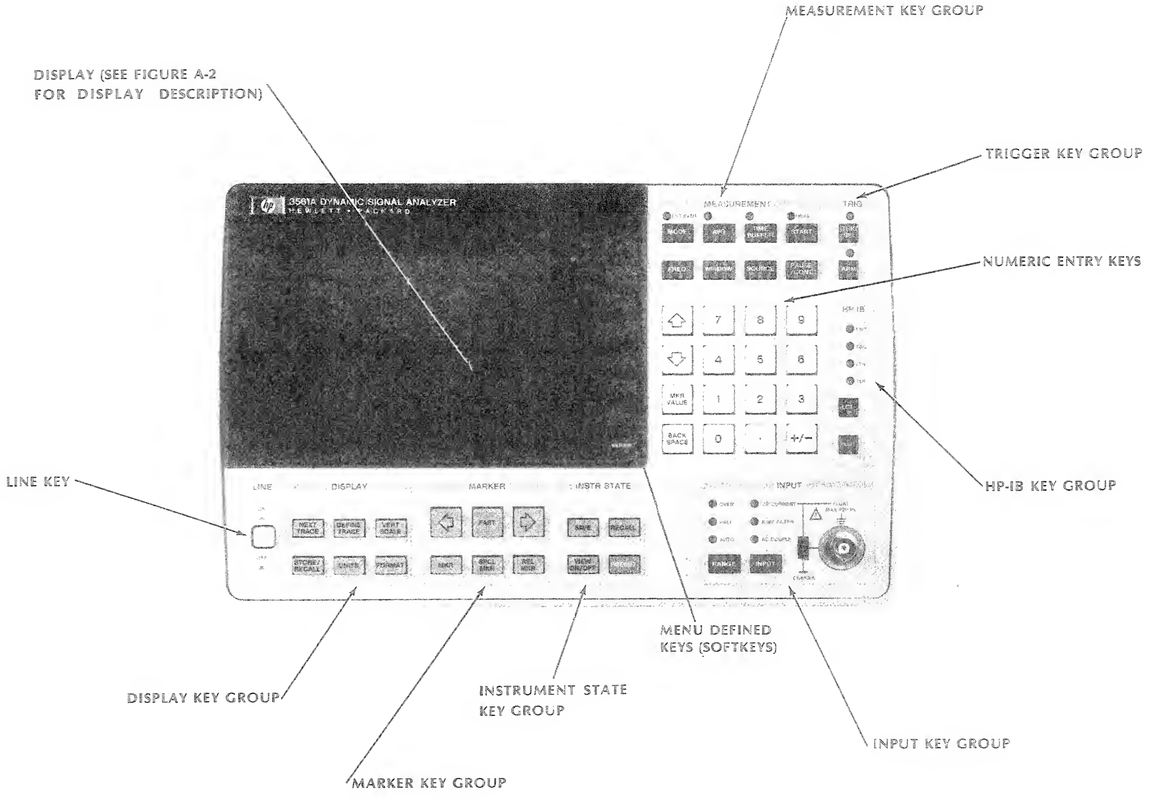


Figure A-1. -hp-3561A Front and Rear Panels.

DISPLAY DESCRIPTION

ENTRY AREA displays the alphanumeric characters used in defining a parameter. The current entry for a key requiring a numeric or character input is displayed here when the key is selected.

INPUT RANGE area displays the full scale input range.

STATUS AREA displays the current status of the -hp-3561A.

TRACE DESCRIPTION indicates the trace function. An intensified trace description indicates the active trace.

TRACE LABEL displays the trace annotation entered through the **DEFINE TRACELBL** menu entry when the trace label display is enabled. If the trace label display is disabled, a detailed description of the trace function is displayed in this area.

AVERAGE STATUS area provides information regarding the averaging process applied to the measurement.

OVERLOAD STATUS area indicates overloads occuring during a measurement.

Y-AXIS LABEL displays the annotation for the graticule vertical axis.

X-AXIS LABEL displays the annotation for the graticule horizontal axis

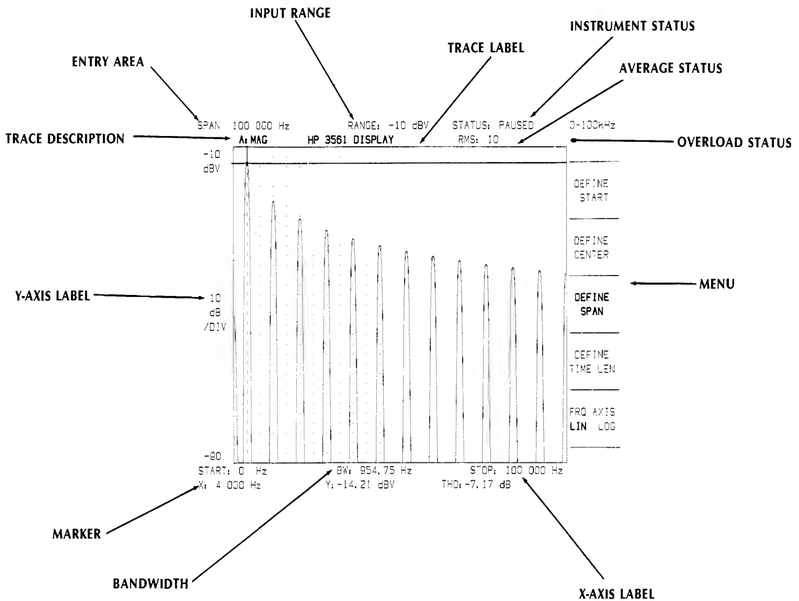
BANDWIDTH display area displays the measurement bandwidth.

X MARKER area displays the horizontal axis coordinate value of the marker.

Y MARKER area displays the vertical axis coordinate value of the marker.

MENU area displays the menu defining the unlabeled keys to the right of the menu.

SINGLE TRACE AND MAP MODE DISPLAY FORMAT



DUAL TRACE DISPLAY FORMAT

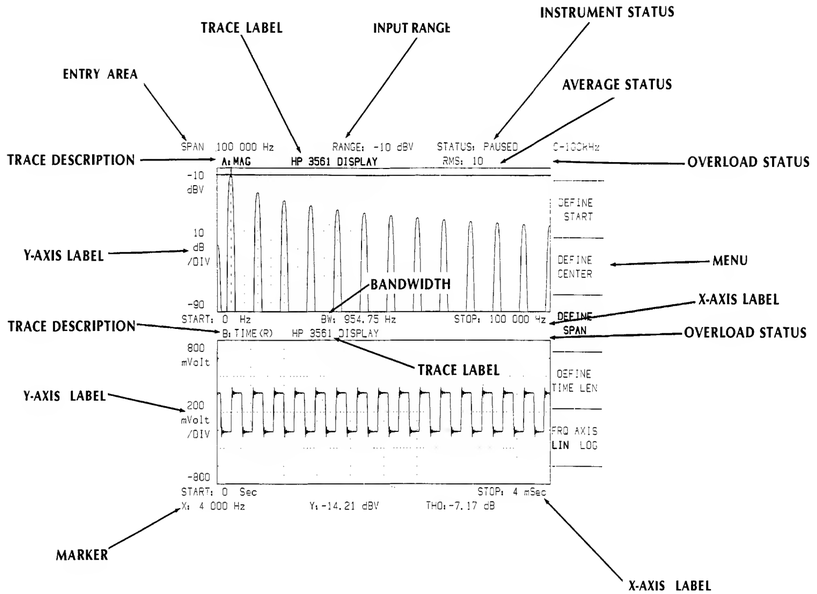
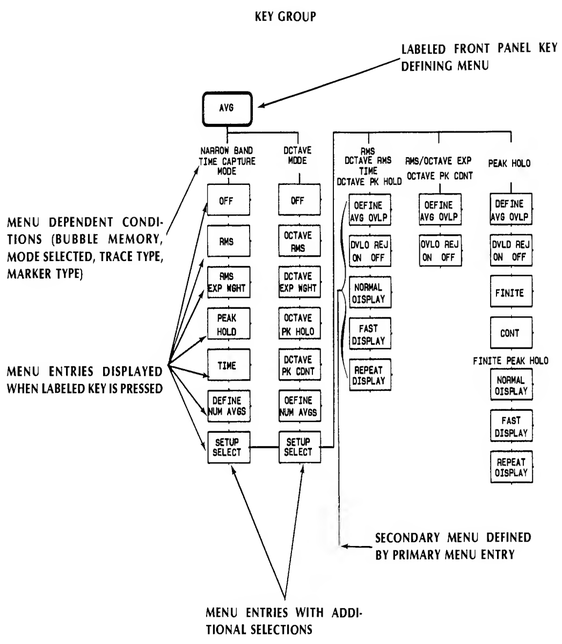
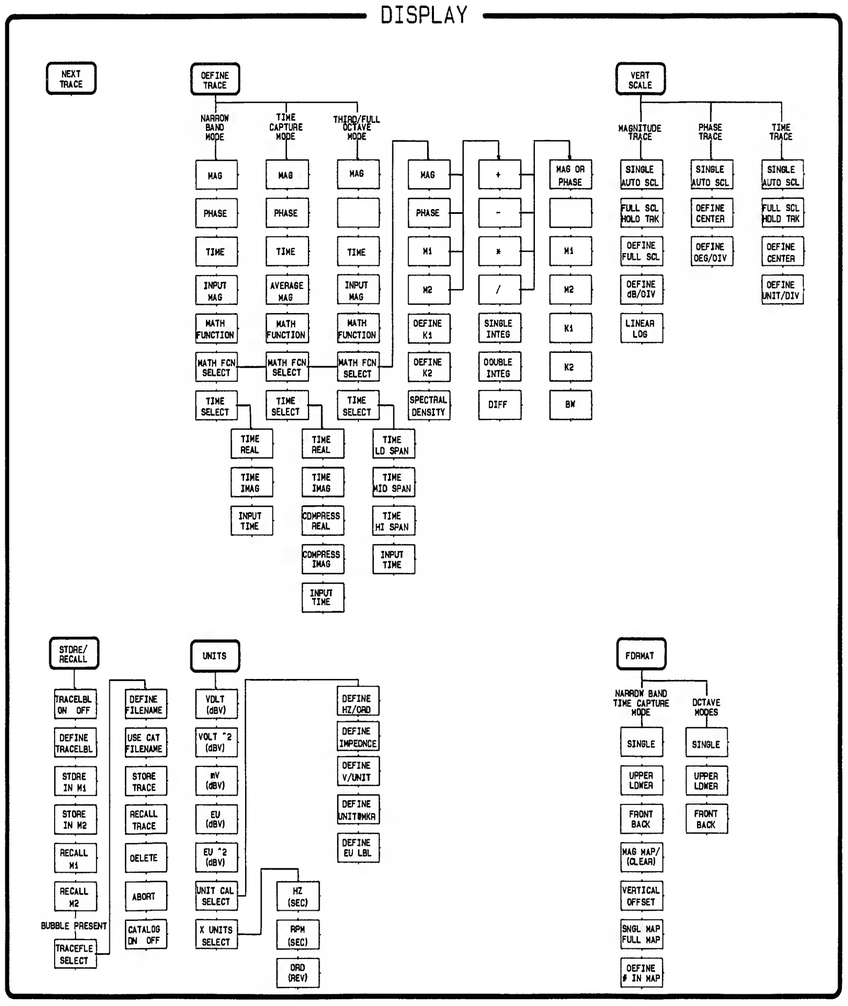


Figure A-2. Display Annotation II

HOW TO INTERPRET THE KEY MAP





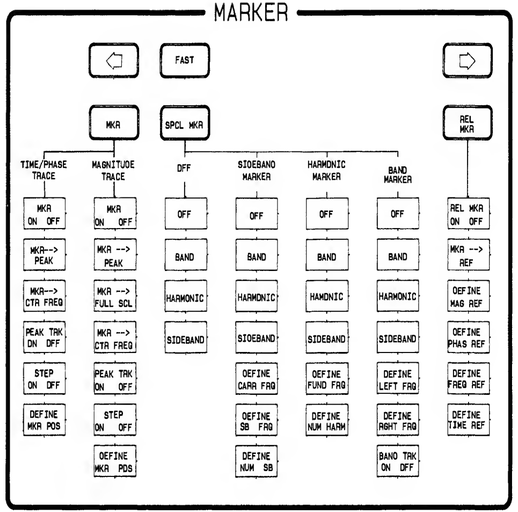


Figure A-3. -hp-3561A Menus
Sheet 1

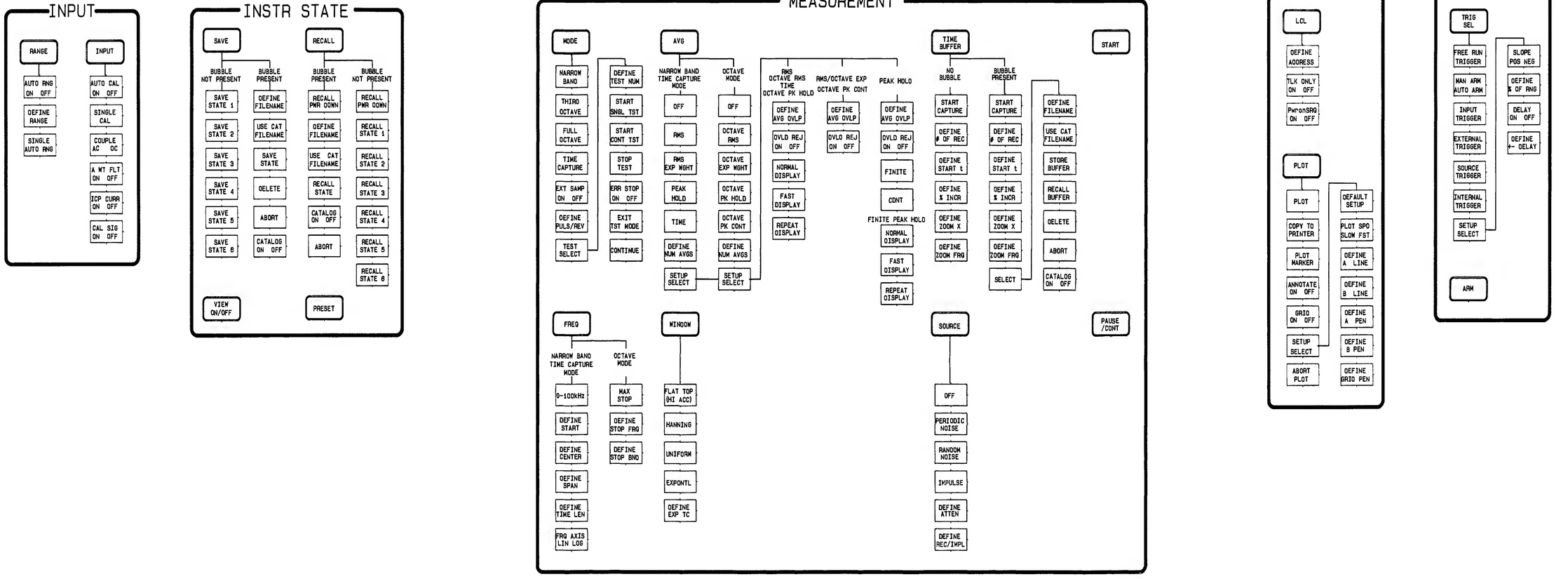


Figure A-3. -hp-3561A Menus
Sheet 2

03561-90010

Printed in U.S.A.